TPS7A4501-SP Total Ionizing Dose Radiation Report

This report discusses the results of the Total Ionizing Dose (TID) testing for the Radiation Hardness Assured (RHA), QML Class V certified Texas Instrument’s TPS7A4501-SP (5962R1222403VXC and 5962R1222403V9A). The RHA qualified TPS7A4501-SP passes up to 100 krad(Si) Low Dose Rate and 100 krad(Si) High Dose Rate TID.

NOTE: For questions or comments, contact hirelmarketing@list.ti.com.

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1 Device Information

1.1 *Product Description*

The TPS7A4501-SP is a wide VIN (2.3-20 V), 100 krad (Si) Radiation Hardness Assured (RHA) Low Dropout (LDO) linear regulator. It uses a PNP pass element that offers optimal performance at higher voltage and temperature under heavy ion exposure. The TPS7A4501-SP provides a very small form factor, low noise power solution with excellent Power Supply Rejection Ratio (PSRR). The device includes internal protection circuitry for reverse-polarity and reverse-current protection, current and thermal limits, and an enable input for power sequencing. The ideal package is offered in the thermally enhanced HKU package utilizing a thermal pad and thermal vias for optimal junction to case cooling in vacuum environments such as space. It has been RHA qualified to 100 krad (Si) under both LDR and HDR. It is orderable under SMD 5962R1222403VXC in our thermally enhanced 10 pin HKU ceramic flat pack package and as Known Good Die (KGD) under SMD 5962R1222403V9A.

Unlike a CMOS-based LDO, the TPS7A4501-SP is built in an all bipolar technology and exhibits ground current based on the output current. This minor additional current should be added to the output load current when performing overall power dissipation calculations.

1.2 *Device Details*

Table 1 lists the device information used in the initial RHA TID characterization and qualification of HDR tests. Current production lot RLAT data can always be found in the Group E report shipped. The process for pulling the group E report from TI is described

Table 1. Device and Exposure Details

TID HDR/LDR Details: up to 150 krad(Si)	
TI Device Number	TPS7A4501-SP (5962R1222403VXC)
Package	10 Pin Ceramic Flatpack (HKU)
Technology	Bipolar Process (J1 Bipolar)
Die Lot Number	3305886SHE
A/T Lot Number / Date Code	4001298 (LTC: 1407C), 4001299 (LTC: 1407A), 4001300(LTC: 1407B)
Quantity Tested	95 device including 1 control device
Lot Accept/Reject	Devices passed 3 krad (Si), 10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si) and 150 krad(Si)(1)
HDR Radiation Facility	Texas Instruments SVA Group, Santa Clara, CA
LDR Radiation Facility	RAD/Aeroflex in Colorado Springs, Colorado
HDR Dose Level	3 krad(Si), 10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si) and 150 krad(Si)(1)
HDR Dose Rate	84 rad/s
LDR Dose Level	50 krad(Si), 100 krad(Si)
LDR Dose Rate	0.01 rad/s
HDR Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
LDR Radiation Source	Gammacell JLSA 81-24 Co-60
Irradiation Temperature	Ambient, room temperature

(1) 150 krad(Si) units pass, per MIL-STD-883 1019.9, Condition A and section 3.12 acceleration annealing test.

Figure 1. Device Used in Exposure

2 Total Dose Test Setup

2.1 Test Overview

The TPS7A4501-SP was tested according to MIL-STD-883J, Test Method 1019.9. For this testing, Condition A was used. For this test, the product was irradiated up to 1.5x the rated radiation level and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). The device was functional and passed all parametric tests within (guard bands) of the Standard Microcircuit Drawing (SMD) electrical specification limits.

The TPS7A4501-SP J1 Bipolar technology contains only bipolar components; therefore, an Enhanced Low Dose Rate Sensitivity (ELDRS) study was performed to determine if the device has a Low Dose Rate (LDR) sensitivity.

2.2 Test Description and Facilities

The TPS7A4501-SP LDR exposure was performed on biased and unbiased devices in a Co60 gamma cell under a 10 mrad(Si)/sec exposure rate. The dose rate of the irradiator used in the exposure ranges from < 10 mrad(Si)/sec to a maximum of approximately 65 rad(Si)/sec, determined by the distance from the source. For the LDR (10mrad(Si)/sec) exposure, the test box was positioned approximately 2m from the source. The exposure boards are housed in a lead-aluminum box (as specified in MIL-STD-883 TM 1019.9) to harden the gamma spectrum and minimize dose enhancement effects. The irradiator calibration is maintained by Logmire Laboratories using Thermoluminescence Dosimeters (TLDs) traceable to the National Institute of Standards and Technology (NIST) and the dosimetry was verified using TLDs prior to the radiation exposures. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and returned to TI Dallas for a full post radiation electrical evaluation using Texas Instruments production Automated Test Equipment (ATE). ATE guard band test limits are set within SMD electrical limits to ensure a minimum Cpk and test error margin based on initial qualification and characterization data. Post radiation measurements were taken within 30 minutes of removal of the devices form the dry ice container. The devices were allowed to reach room temperature prior to electrical post radiation measurements.

The TPS7A4501-SP HDR exposure was performed on biased and unbiased devices in a Co-60 gamma cell at TI SVA facility in Santa Clara California. The un-attenuated dose rate of this cell is 65rad(Si)/sec. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and returned to TI Dallas for a full post radiation electrical evaluation using Texas Instruments Automated Test Equipment (ATE). ATE guard band test limits are set within SMD electrical limits to ensure a minimum Cpk and test error margin based on initial qualification and characterization data. Post radiation measurements were taken within 30 minutes of removal of the devices form the dry ice container. The devices were allowed to reach room temperature prior to electrical post radiation measurements.

2.3 Test Setup Details

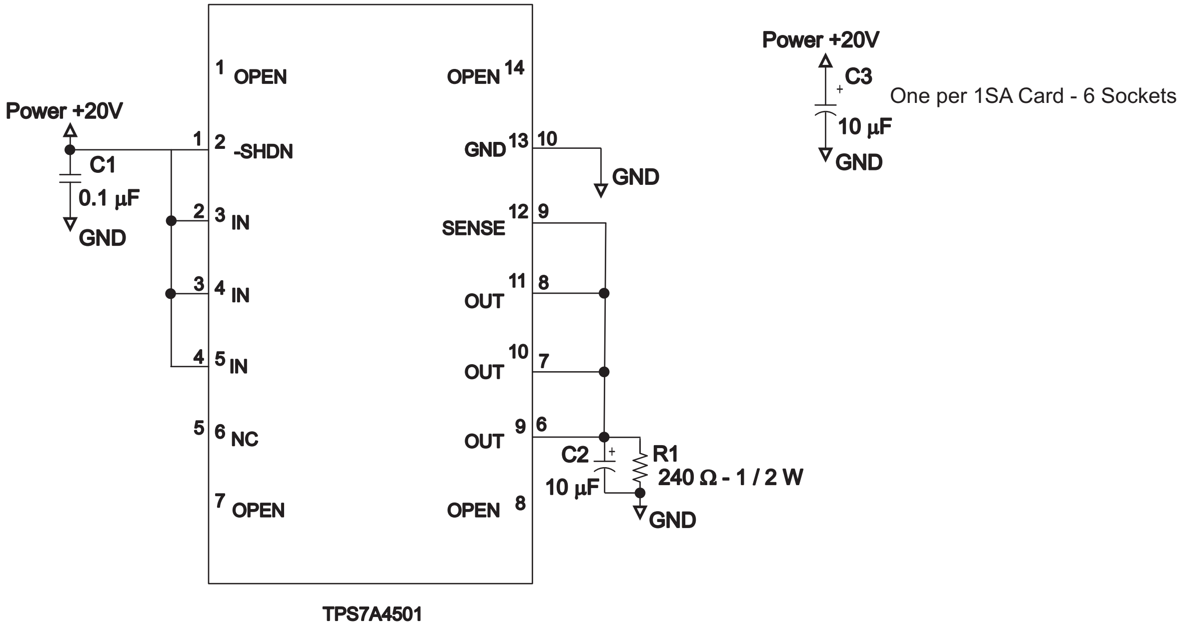
The devices under HDR and LDR exposure were tested in both biased and unbiased conditions in two conditions as described as follows.

2.3.1 Unbiased

For the unbiased HDR and LDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Figure 2 shows the diagram for HDR and LDR exposure.



This is a 10-pin flatpack in a 14-pin carrier/socket

Figure 2. Bias Diagram Used in TID Exposure

2.4 Test Configuration and Condition

A step-stress (3k, 10k, 30k, 50k, 100 krad) test method was used to determine the TID hardness level. That is, after a predetermined TID level was reached, an electrical test was performed on a given sample of parts to verify that the units are within specified SMD electrical test limits. MIL-STD-883, Test Method 1019.9, Condition A and D was used in this case. If this passes, then the wafer lot can be certified as an RHA wafer lot.

Table 2 to Table 3 list the samples that used during the RHA characterization

Table 2. HDR ≤ 50 - 100 rad(Si)/sec Biased Device Information

Total Samples: 5/dose rate (5 biased)					
Exposure Duration and Level:					
3k	10k	30k	50k	100k (RLAT Included)	150k
1 (wafer 8)	3 (wafer 8)	5 (wafer 8)	6 (wafer 8)	8, 9, 10, 11, 12, 13, 14 (wafer 8) 8, 9, 10, 11, 12, 13, 14 (wafer 9) 7, 8, 9, 10, 11, 12, 13, 14 (wafer 10)	15 (wafer 8)
2 (wafer 8)	4 (wafer 8)	4 (wafer 9)	7 (wafer 8)		15 (wafer 9)
1 (wafer 9)	3 (wafer 9)	5 (wafer 9)	6 (wafer 9)		16 (wafer 9)
2 (wafer 9)	2 (wafer 10)	4 (wafer 10)	7 (wafer 9)		15 (wafer 10)
1 (wafer 10)	3 (wafer 10)	5 (wafer 10)	6 (wafer 10)		16 (wafer 10)

Control Unit: 25 (wafer 8), 45 (wafer 9), 17 (wafer 10)

Table 3. HDR ≤ 50 - 100 rad(Si)/sec UnBiased Device Information

Total Samples: 5 Unbiased/TID level					
Exposure Levels:					
3k	10k	30k	50k	100k (RLAT Included)	150k
26 (wafer 8)	28 (wafer 8)	30 (wafer 8)	31 (wafer 8)	33, 34, 35, 36, 37, 38, 39 (wafer 8) 33, 34, 35, 36, 37, 38, 39 (wafer 9) 32, 33, 34, 35, 36, 37, 38, 39 (wafer 10)	40 (wafer 8)
27 (wafer 8)	29 (wafer 8)	29 (wafer 9)	32 (wafer 8)		40 (wafer 8)
26 (wafer 9)	28 (wafer 9)	30 (wafer 9)	31 (wafer 9)		41 (wafer 9)
27 (wafer 9)	27 (wafer 10)	29 (wafer 10)	32 (wafer 9)		41 (wafer 10)
26 (wafer 10)	28 (wafer 10)	30 (wafer 10)	31 (wafer 10)		43 (wafer 10)

Control Unit: 25 (wafer 8), 45 (wafer 9), 17 (wafer 10)

Table 4. HDR ≤ 50 - 100 rad(Si)/sec Segment Testing (HDR)

Exposure Duration and Level: 100 krad(Si
Unit / Wafer Number Biased
S1 - 16, 17
S2 - 19, 20
S3 - 10,12
S4 - 7, 8
S5 - 2, 3

Control Unit: Correlation - S5-1

Table 5. LDR = 10 mrad(Si)/sec Device and Exposure Information (LDR)

Total Samples: 10/dose rate (5 biased + 5 unbiased)	
Unit / Wafer Number Biased	
50 krad(Si)	**100 krad(Si)**
Biased	**Biased**
16, 17 (wafer 9)	18,19, 20 (wafer 9)
17, 18, 19 (wafer 10)	20, 21 (wafer 10)
UnBiased	**UnBiased**
22 (wafer 8)	23, 24, 25 (wafer 8)
22, 23 (wafer 9)	24 (wafer 9)
23, 24 (wafer 10)	25 (wafer 10)

Control Unit: 21 (wafer 9)

Table 6. HDR ≤ 50 - 100 rad(Si)/sec Package Extension Exposure Information

Exposure Type: 100krad(Si) HDR
Unit / Wafer Number Biased
2, 3, 4, 5, 6, 7, 8, 9, 10, 11 (Wafer 8)

Control Unit: 1 (wafer 8)

3 Total Ionizing Dose (RHA) Characterization Test Results

3.1 *Total Ionizing Dose RHA Characterization Summary Results*

The parametric data for the TPS7A4501-SP passes up to 100 krad(Si) Low Dose Rate and 100 krad(Si) High Dose Rate TID.

Segment-level testing across one wafer from all five sections (top, bottom, mid, left, and right) at 100 krad (Si) yielded passing results for all SMD electrical parameters. Data shows very minimal drift among each segment. Hence the device does not exhibit any wafer level variability effect.

The drift of SMD electrical parameters through low dose rate (LDR) and high dose rate (HDR). were within the pre-rad characterization limits. The device does exhibit a slight Low Dose Rate Sensitivity in the Vadj parameter, but remains within the pre-radiation electrical limits at 100 krad Total Dose Level, as allowed by MIL-STD-883, TM1019. The device is tested to maximum total dose of 100 krad(Si) per MIL-TD-883, TM1090 condition A and condition D.

The TPS7A4501-SP passed post electrical test over all the conditions below indicating that this lot can be certified as 100 krad RHA.

- HDR (100 rad/sec) unbiased: Post 3 krad(Si), 10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si), 150 krad(Si)
- HDR (100 rad/sec) biased: Post 3 krad(Si), 10 krad(Si), 30 krad(Si), 50 krad(Si), 100 krad(Si), 150 krad(Si)
- LDR (0.01 rad/sec) unbiased: Post 50 krad(Si), 100 krad(Si)
- LDR (0.01 rad/sec) biased: Post 50 krad(Si), 100 krad(Si)

NOTE: 150krad(Si) units pass, per MIL-STD-883 1019.9, Condition A, section 3.12 accelerated annealing test

3.2 *Group E Full RHA Radiation Lot Acceptance (RLAT) Report*

The Group E RHA RLAT summary is shipped with each TI RHA QMLV product. To see the full list of all documents shipped with TI QMLV products review our TI QMLV Lot Documents Summary SBOA140. This document also has instructions on how to pull the full RHA (Group E) report.

4 Applicable and Reference Documents

4.1 *Applicable Documents*

TPS7A4501-SP 2.3- to 20-V, 1.5-A Low-Dropout Voltage Regulator Datasheet (SLVSC31)

TPS7A4501-SP Evaluation Module

TPS7A4501-SP Evaluation Module User's Guide (SLVUAM1)

TPS7A4501-SP Single Event Effects Radiation Report (SLAK014)

4.2 *Reference Documents*

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Original (June 2016) to A Revision	**Page**
• CMS: C1703033 — Changed device name used in the *Test Description and Facilities* section from TPS7H3301-SP to TPS7A4501-SP.	3

TPS7A4501-RHA

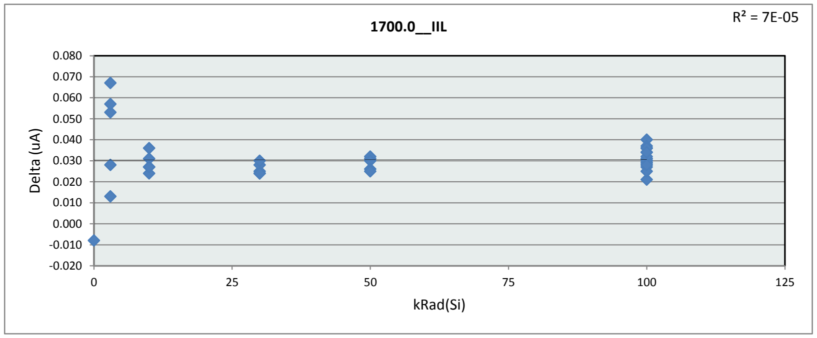
TID HDR Report 100 KRad (Unbiased)

All units passed SMD specification limits.

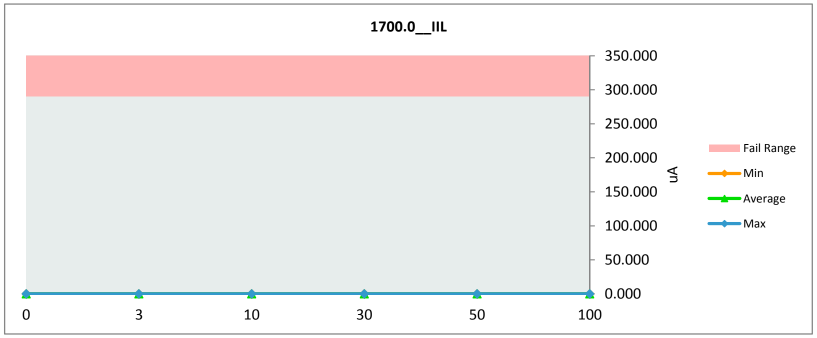
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		1700.0__IIL		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	290	290	
	Min Limit			
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	0.067	0.075	-0.008
3	HDR_L1_D26_UnBias	0.060	0.032	0.028
3	HDR_L1_D27_UnBias	0.067	0.000	0.067
3	HDR_L2_D26_UnBias	0.051	0.038	0.013
3	HDR_L2_D27_UnBias	0.059	0.006	0.053
3	HDR_L3_D26_UnBias	0.064	0.007	0.057
10	HDR_L1_D28_UnBias	0.060	0.036	0.024
10	HDR_L1_D29_UnBias	0.074	0.038	0.036
10	HDR_L2_D28_UnBias	0.058	0.031	0.027
10	HDR_L3_D27_UnBias	0.066	0.035	0.031
10	HDR_L3_D28_UnBias	0.059	0.032	0.027
30	HDR_L1_D30_UnBias	0.060	0.036	0.024
30	HDR_L2_D29_nUBias	0.061	0.036	0.025
30	HDR_L2_D30_UnBias	0.061	0.033	0.028
30	HDR_L3_D29_UnBias	0.066	0.036	0.030
30	HDR_L3_D30_UnBias	0.061	0.037	0.024
50	HDR_L1_D31_UnBias	0.066	0.035	0.031
50	HDR_L1_D32_UnBias	0.066	0.034	0.032
50	HDR_L2_D31_UnBias	0.062	0.032	0.030
50	HDR_L2_D32_UnBias	0.058	0.032	0.026
50	HDR_L3_D31_UnBias	0.061	0.036	0.025
100	HDR_L1_D33_UnBias	0.065	0.037	0.028
100	HDR_L1_D34_UnBias	0.069	0.029	0.040
100	HDR_L1_D35_UnBias	0.064	0.034	0.030
100	HDR_L1_D36_UnBias	0.060	0.033	0.027
100	HDR_L1_D37_UnBias	0.064	0.034	0.030
100	HDR_L1_D38_UnBias	0.066	0.037	0.029
100	HDR_L1_D39_UnBias	0.055	0.034	0.021
100	HDR_L2_D33_UnBias	0.064	0.027	0.037
100	HDR_L2_D34_UnBias	0.066	0.030	0.036
100	HDR_L2_D35_UnBias	0.064	0.034	0.030
100	HDR_L2_D36_UnBias	0.060	0.031	0.029
100	HDR_L2_D37_UnBias	0.061	0.030	0.031
100	HDR_L2_D38_UnBias	0.063	0.029	0.034
100	HDR_L2_D39_UnBias	0.057	0.032	0.025
100	HDR_L3_D32_UnBias	0.064	0.028	0.036
100	HDR_L3_D33_UnBias	0.060	0.031	0.029
100	HDR_L3_D34_UnBias	0.062	0.031	0.031
100	HDR_L3_D35_UnBias	0.065	0.035	0.030
100	HDR_L3_D36_UnBias	0.067	0.031	0.036
100	HDR_L3_D37_UnBias	0.063	0.031	0.032
100	HDR_L3_D38_UnBias	0.065	0.031	0.034
100	HDR_L3_D39_UnBias	0.062	0.034	0.028
	Max	0.074	0.075	0.067
	Average	0.063	0.032	0.031
	Min	0.051	0.000	-0.008
	Std Dev	0.004	0.010	0.011



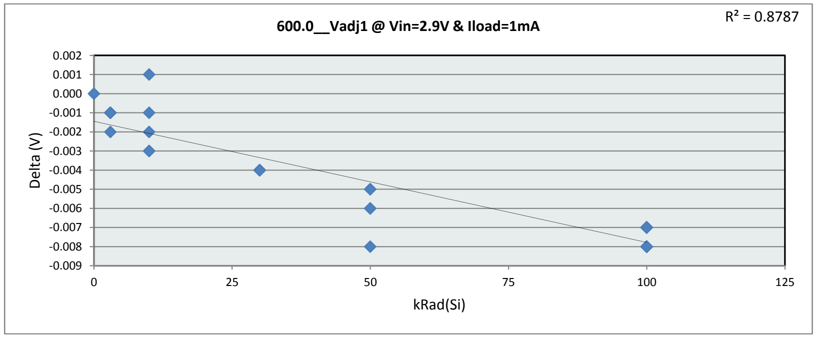
	1700.0__IIL					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	290	uA				
Min Limit		uA				
kRad(Si)	0	3	10	30	50	100
LL						
Min	0.075	0.006	0.031	0.033	0.032	0.027
Average	0.075	0.017	0.034	0.036	0.034	0.032
Max	0.075	0.038	0.038	0.037	0.036	0.037
UL	290.000	290.000	290.000	290.000	290.000	290.000



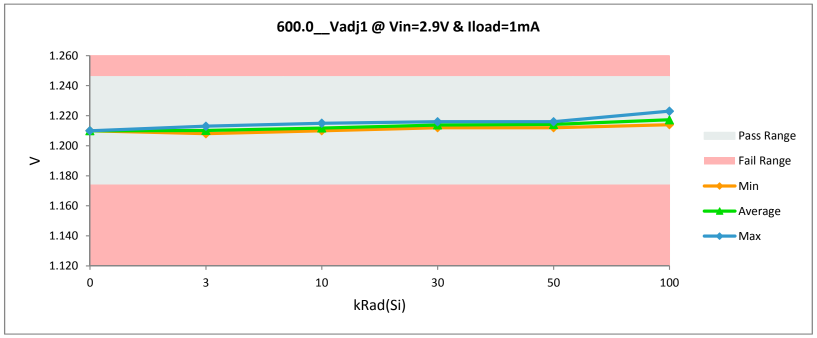
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		600.0__Vadj1 @ Vin=2.9V & Iload=1mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	1.246	1.246	
	Min Limit	1.174	1.174	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	1.210	1.210	0.000
3	HDR_L1_D26_UnBias	1.209	1.211	-0.002
3	HDR_L1_D27_UnBias	1.207	1.208	-0.001
3	HDR_L2_D26_UnBias	1.209	1.210	-0.001
3	HDR_L2_D27_UnBias	1.208	1.209	-0.001
3	HDR_L3_D26_UnBias	1.212	1.213	-0.001
10	HDR_L1_D28_UnBias	1.214	1.215	-0.001
10	HDR_L1_D29_UnBias	1.209	1.211	-0.002
10	HDR_L2_D28_UnBias	1.207	1.210	-0.003
10	HDR_L3_D27_UnBias	1.211	1.210	0.001
10	HDR_L3_D28_UnBias	1.210	1.213	-0.003
30	HDR_L1_D30_UnBias	1.208	1.212	-0.004
30	HDR_L2_D29_nUBias	1.211	1.215	-0.004
30	HDR_L2_D30_UnBias	1.210	1.214	-0.004
30	HDR_L3_D29_UnBias	1.208	1.212	-0.004
30	HDR_L3_D30_UnBias	1.212	1.216	-0.004
50	HDR_L1_D31_UnBias	1.206	1.212	-0.006
50	HDR_L1_D32_UnBias	1.206	1.214	-0.008
50	HDR_L2_D31_UnBias	1.211	1.216	-0.005
50	HDR_L2_D32_UnBias	1.208	1.214	-0.006
50	HDR_L3_D31_UnBias	1.210	1.215	-0.005
100	HDR_L1_D33_UnBias	1.208	1.216	-0.008
100	HDR_L1_D34_UnBias	1.208	1.215	-0.007
100	HDR_L1_D35_UnBias	1.210	1.218	-0.008
100	HDR_L1_D36_UnBias	1.209	1.217	-0.008
100	HDR_L1_D37_UnBias	1.211	1.218	-0.007
100	HDR_L1_D38_UnBias	1.208	1.216	-0.008
100	HDR_L1_D39_UnBias	1.210	1.217	-0.007
100	HDR_L2_D33_UnBias	1.212	1.220	-0.008
100	HDR_L2_D34_UnBias	1.211	1.219	-0.008
100	HDR_L2_D35_UnBias	1.211	1.219	-0.008
100	HDR_L2_D36_UnBias	1.211	1.218	-0.007
100	HDR_L2_D37_UnBias	1.211	1.219	-0.008
100	HDR_L2_D38_UnBias	1.210	1.217	-0.007
100	HDR_L2_D39_UnBias	1.210	1.217	-0.007
100	HDR_L3_D32_UnBias	1.207	1.215	-0.008
100	HDR_L3_D33_UnBias	1.215	1.223	-0.008
100	HDR_L3_D34_UnBias	1.208	1.216	-0.008
100	HDR_L3_D35_UnBias	1.208	1.216	-0.008
100	HDR_L3_D36_UnBias	1.211	1.219	-0.008
100	HDR_L3_D37_UnBias	1.208	1.215	-0.007
100	HDR_L3_D38_UnBias	1.207	1.214	-0.007
100	HDR_L3_D39_UnBias	1.209	1.216	-0.007
	Max	1.215	1.223	0.001
	Average	1.210	1.215	-0.005
	Min	1.206	1.208	-0.008
	Std Dev	0.002	0.003	0.003



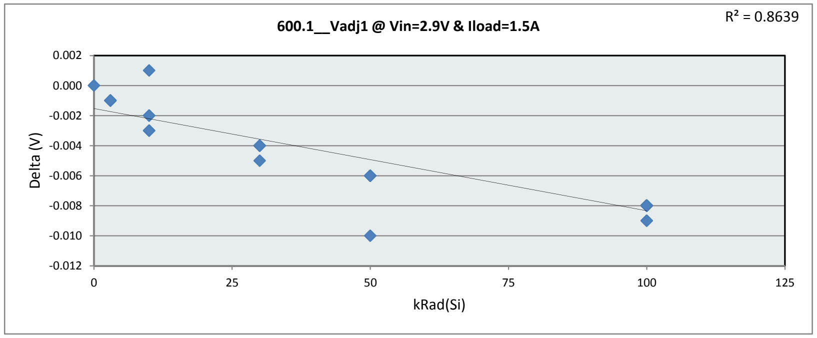
	600.0__Vadj1 @ Vin=2.					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1.246	V				
Min Limit	1.174	V				
kRad(Si)	0	3	10	30	50	100
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.210	1.208	1.210	1.212	1.212	1.214
Average	1.210	1.210	1.212	1.214	1.214	1.217
Max	1.210	1.213	1.215	1.216	1.216	1.223
UL	1.246	1.246	1.246	1.246	1.246	1.246



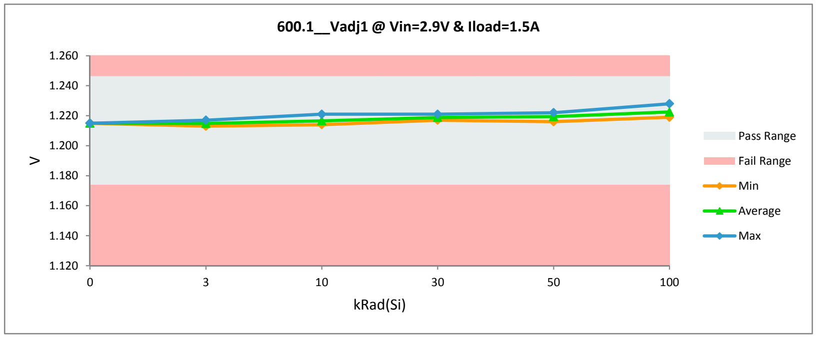
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		600.1__Vadj1 @ Vin=2.9V & Iload=1.5A		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	1.246	1.246	
	Min Limit	1.174	1.174	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	1.215	1.215	0.000
3	HDR_L1_D26_UnBias	1.214	1.215	-0.001
3	HDR_L1_D27_UnBias	1.212	1.213	-0.001
3	HDR_L2_D26_UnBias	1.214	1.215	-0.001
3	HDR_L2_D27_UnBias	1.213	1.214	-0.001
3	HDR_L3_D26_UnBias	1.216	1.217	-0.001
10	HDR_L1_D28_UnBias	1.219	1.221	-0.002
10	HDR_L1_D29_UnBias	1.213	1.216	-0.003
10	HDR_L2_D28_UnBias	1.212	1.214	-0.002
10	HDR_L3_D27_UnBias	1.215	1.214	0.001
10	HDR_L3_D28_UnBias	1.215	1.218	-0.003
30	HDR_L1_D30_UnBias	1.212	1.217	-0.005
30	HDR_L2_D29_nUBias	1.216	1.220	-0.004
30	HDR_L2_D30_UnBias	1.215	1.219	-0.004
30	HDR_L3_D29_UnBias	1.213	1.217	-0.004
30	HDR_L3_D30_UnBias	1.217	1.221	-0.004
50	HDR_L1_D31_UnBias	1.210	1.216	-0.006
50	HDR_L1_D32_UnBias	1.210	1.220	-0.010
50	HDR_L2_D31_UnBias	1.216	1.222	-0.006
50	HDR_L2_D32_UnBias	1.213	1.219	-0.006
50	HDR_L3_D31_UnBias	1.214	1.220	-0.006
100	HDR_L1_D33_UnBias	1.213	1.221	-0.008
100	HDR_L1_D34_UnBias	1.213	1.221	-0.008
100	HDR_L1_D35_UnBias	1.215	1.223	-0.008
100	HDR_L1_D36_UnBias	1.214	1.222	-0.008
100	HDR_L1_D37_UnBias	1.215	1.223	-0.008
100	HDR_L1_D38_UnBias	1.213	1.221	-0.008
100	HDR_L1_D39_UnBias	1.214	1.222	-0.008
100	HDR_L2_D33_UnBias	1.217	1.225	-0.008
100	HDR_L2_D34_UnBias	1.216	1.224	-0.008
100	HDR_L2_D35_UnBias	1.216	1.225	-0.009
100	HDR_L2_D36_UnBias	1.216	1.224	-0.008
100	HDR_L2_D37_UnBias	1.216	1.224	-0.008
100	HDR_L2_D38_UnBias	1.215	1.223	-0.008
100	HDR_L2_D39_UnBias	1.215	1.223	-0.008
100	HDR_L3_D32_UnBias	1.211	1.220	-0.009
100	HDR_L3_D33_UnBias	1.220	1.228	-0.008
100	HDR_L3_D34_UnBias	1.213	1.221	-0.008
100	HDR_L3_D35_UnBias	1.213	1.221	-0.008
100	HDR_L3_D36_UnBias	1.216	1.224	-0.008
100	HDR_L3_D37_UnBias	1.212	1.220	-0.008
100	HDR_L3_D38_UnBias	1.211	1.219	-0.008
100	HDR_L3_D39_UnBias	1.213	1.221	-0.008
	Max	1.220	1.228	0.001
	Average	1.214	1.220	-0.006
	Min	1.210	1.213	-0.010
	Std Dev	0.002	0.004	0.003



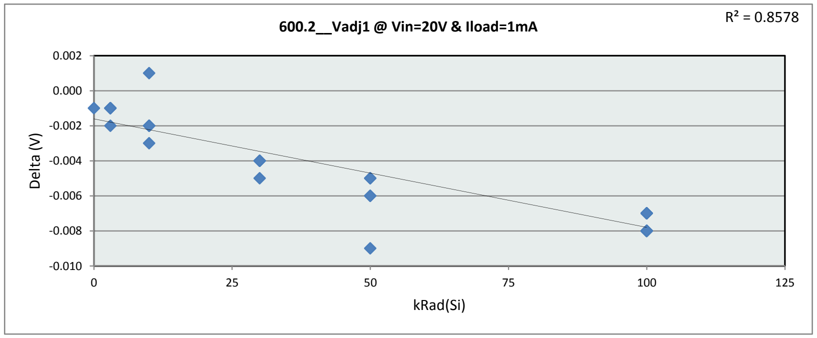
	600.1__Vadj1 @ Vin=2.					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1.246	V				
Min Limit	1.174	V				
kRad(Si)	0	3	10	30	50	100
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.215	1.213	1.214	1.217	1.216	1.219
Average	1.215	1.215	1.217	1.219	1.219	1.223
Max	1.215	1.217	1.221	1.221	1.222	1.228
UL	1.246	1.246	1.246	1.246	1.246	1.246



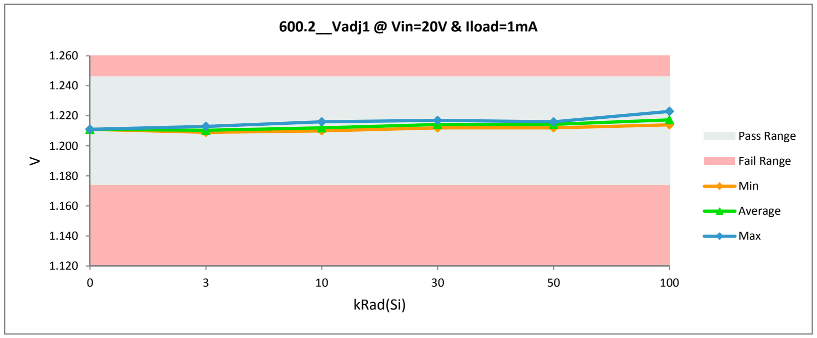
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		600.2__Vadj1 @ Vin=20V & Iload=1mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	1.246	1.246	
	Min Limit	1.174	1.174	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	1.210	1.211	-0.001
3	HDR_L1_D26_UnBias	1.210	1.211	-0.001
3	HDR_L1_D27_UnBias	1.207	1.209	-0.002
3	HDR_L2_D26_UnBias	1.209	1.210	-0.001
3	HDR_L2_D27_UnBias	1.208	1.209	-0.001
3	HDR_L3_D26_UnBias	1.212	1.213	-0.001
10	HDR_L1_D28_UnBias	1.214	1.216	-0.002
10	HDR_L1_D29_UnBias	1.209	1.211	-0.002
10	HDR_L2_D28_UnBias	1.207	1.210	-0.003
10	HDR_L3_D27_UnBias	1.211	1.210	0.001
10	HDR_L3_D28_UnBias	1.211	1.213	-0.002
30	HDR_L1_D30_UnBias	1.208	1.212	-0.004
30	HDR_L2_D29_nUBias	1.211	1.215	-0.004
30	HDR_L2_D30_UnBias	1.210	1.214	-0.004
30	HDR_L3_D29_UnBias	1.208	1.213	-0.005
30	HDR_L3_D30_UnBias	1.213	1.217	-0.004
50	HDR_L1_D31_UnBias	1.206	1.212	-0.006
50	HDR_L1_D32_UnBias	1.206	1.215	-0.009
50	HDR_L2_D31_UnBias	1.211	1.216	-0.005
50	HDR_L2_D32_UnBias	1.208	1.214	-0.006
50	HDR_L3_D31_UnBias	1.210	1.215	-0.005
100	HDR_L1_D33_UnBias	1.209	1.217	-0.008
100	HDR_L1_D34_UnBias	1.208	1.215	-0.007
100	HDR_L1_D35_UnBias	1.210	1.218	-0.008
100	HDR_L1_D36_UnBias	1.210	1.217	-0.007
100	HDR_L1_D37_UnBias	1.211	1.218	-0.007
100	HDR_L1_D38_UnBias	1.208	1.216	-0.008
100	HDR_L1_D39_UnBias	1.210	1.218	-0.008
100	HDR_L2_D33_UnBias	1.212	1.220	-0.008
100	HDR_L2_D34_UnBias	1.211	1.219	-0.008
100	HDR_L2_D35_UnBias	1.211	1.219	-0.008
100	HDR_L2_D36_UnBias	1.211	1.218	-0.007
100	HDR_L2_D37_UnBias	1.211	1.219	-0.008
100	HDR_L2_D38_UnBias	1.210	1.217	-0.007
100	HDR_L2_D39_UnBias	1.210	1.217	-0.007
100	HDR_L3_D32_UnBias	1.207	1.215	-0.008
100	HDR_L3_D33_UnBias	1.215	1.223	-0.008
100	HDR_L3_D34_UnBias	1.208	1.216	-0.008
100	HDR_L3_D35_UnBias	1.208	1.216	-0.008
100	HDR_L3_D36_UnBias	1.211	1.219	-0.008
100	HDR_L3_D37_UnBias	1.208	1.215	-0.007
100	HDR_L3_D38_UnBias	1.207	1.214	-0.007
100	HDR_L3_D39_UnBias	1.209	1.216	-0.007
	Max	1.215	1.223	0.001
	Average	1.210	1.215	-0.005
	Min	1.206	1.209	-0.009
	Std Dev	0.002	0.003	0.003



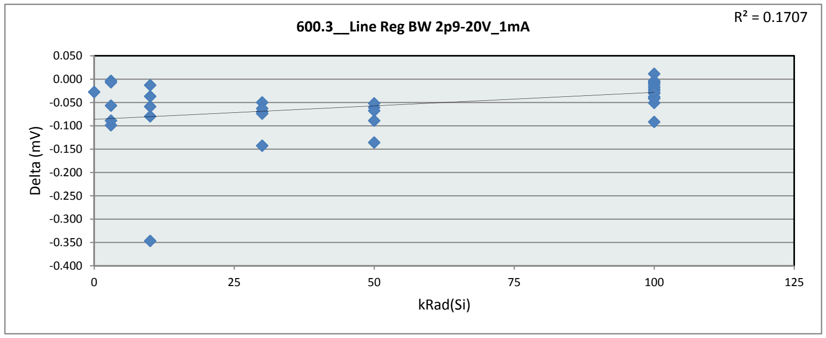
	600.2__Vadj1 @ Vin=2					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1.246	V				
Min Limit	1.174	V				
kRad(Si)	0	3	10	30	50	100
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.211	1.209	1.210	1.212	1.212	1.214
Average	1.211	1.210	1.212	1.214	1.214	1.217
Max	1.211	1.213	1.216	1.217	1.216	1.223
UL	1.246	1.246	1.246	1.246	1.246	1.246



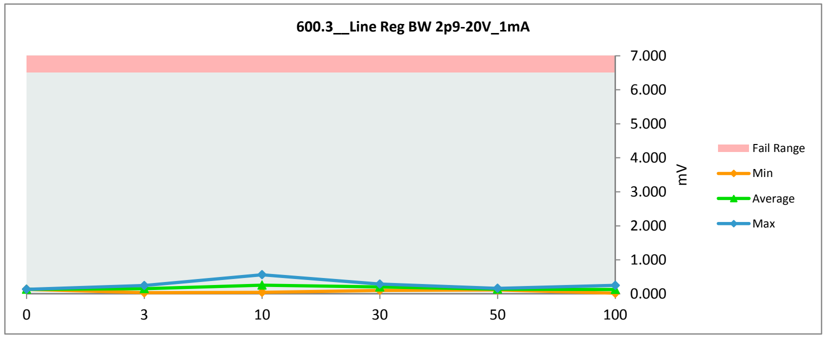
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		600.3__Line Reg BW 2p9-20V_1mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	6.5	6.5	
	Min Limit			
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	0.106	0.134	-0.028
3	HDR_L1_D26_UnBias	0.139	0.196	-0.057
3	HDR_L1_D27_UnBias	0.063	0.162	-0.099
3	HDR_L2_D26_UnBias	0.047	0.136	-0.089
3	HDR_L2_D27_UnBias	0.031	0.035	-0.004
3	HDR_L3_D26_UnBias	0.239	0.246	-0.007
10	HDR_L1_D28_UnBias	0.217	0.564	-0.347
10	HDR_L1_D29_UnBias	0.079	0.159	-0.080
10	HDR_L2_D28_UnBias	0.033	0.046	-0.013
10	HDR_L3_D27_UnBias	0.221	0.258	-0.037
10	HDR_L3_D28_UnBias	0.200	0.259	-0.059
30	HDR_L1_D30_UnBias	0.105	0.248	-0.143
30	HDR_L2_D29_nUBias	0.135	0.205	-0.070
30	HDR_L2_D30_UnBias	0.053	0.103	-0.050
30	HDR_L3_D29_UnBias	0.100	0.174	-0.074
30	HDR_L3_D30_UnBias	0.225	0.288	-0.063
50	HDR_L1_D31_UnBias	0.028	0.117	-0.089
50	HDR_L1_D32_UnBias	0.028	0.164	-0.136
50	HDR_L2_D31_UnBias	0.054	0.115	-0.061
50	HDR_L2_D32_UnBias	0.077	0.145	-0.068
50	HDR_L3_D31_UnBias	0.112	0.164	-0.052
100	HDR_L1_D33_UnBias	0.172	0.223	-0.051
100	HDR_L1_D34_UnBias	0.050	0.054	-0.004
100	HDR_L1_D35_UnBias	0.118	0.210	-0.092
100	HDR_L1_D36_UnBias	0.197	0.235	-0.038
100	HDR_L1_D37_UnBias	0.095	0.137	-0.042
100	HDR_L1_D38_UnBias	0.127	0.150	-0.023
100	HDR_L1_D39_UnBias	0.139	0.170	-0.031
100	HDR_L2_D33_UnBias	0.110	0.118	-0.008
100	HDR_L2_D34_UnBias	0.049	0.073	-0.024
100	HDR_L2_D35_UnBias	0.070	0.088	-0.018
100	HDR_L2_D36_UnBias	0.055	0.061	-0.006
100	HDR_L2_D37_UnBias	0.115	0.145	-0.030
100	HDR_L2_D38_UnBias	0.047	0.056	-0.009
100	HDR_L2_D39_UnBias	0.092	0.116	-0.024
100	HDR_L3_D32_UnBias	0.013	0.020	-0.007
100	HDR_L3_D33_UnBias	0.211	0.200	0.011
100	HDR_L3_D34_UnBias	0.087	0.127	-0.040
100	HDR_L3_D35_UnBias	0.079	0.092	-0.013
100	HDR_L3_D36_UnBias	0.232	0.250	-0.018
100	HDR_L3_D37_UnBias	0.064	0.083	-0.019
100	HDR_L3_D38_UnBias	0.082	0.106	-0.024
100	HDR_L3_D39_UnBias	0.105	0.134	-0.029
	Max	0.239	0.564	0.011
	Average	0.107	0.157	-0.050
	Min	0.013	0.020	-0.347
	Std Dev	0.064	0.093	0.058



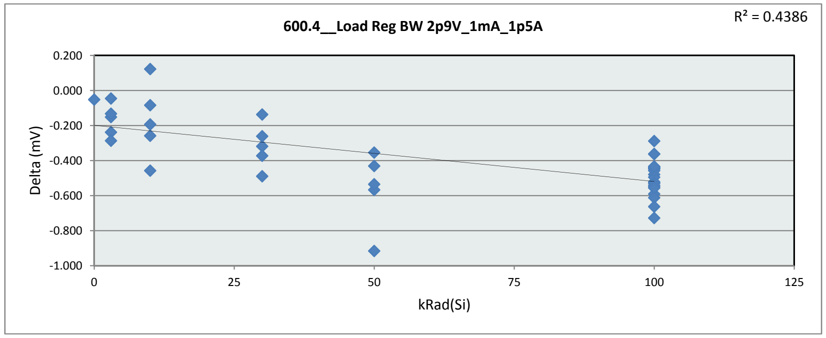
	600.3__Line Reg BW 2p					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	6.5	mV				
Min Limit		mV				
kRad(Si)	0	3	10	30	50	100
LL						
Min	0.134	0.035	0.046	0.103	0.115	0.020
Average	0.134	0.155	0.257	0.204	0.141	0.129
Max	0.134	0.246	0.564	0.288	0.164	0.250
UL	6.500	6.500	6.500	6.500	6.500	6.500



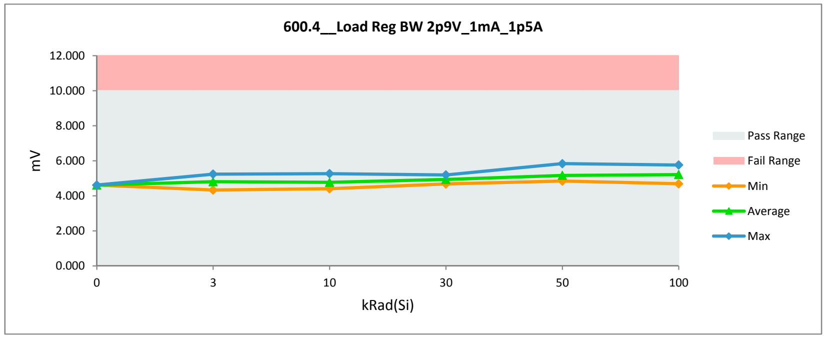
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		600.4__Load Reg BW 2p9V_1mA_1p5A		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	10	10	
	Min Limit	0	0	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	4.560	4.612	-0.052
3	HDR_L1_D26_UnBias	4.521	4.760	-0.239
3	HDR_L1_D27_UnBias	4.498	4.650	-0.152
3	HDR_L2_D26_UnBias	5.106	5.239	-0.133
3	HDR_L2_D27_UnBias	4.757	5.044	-0.287
3	HDR_L3_D26_UnBias	4.284	4.330	-0.046
10	HDR_L1_D28_UnBias	5.008	5.267	-0.259
10	HDR_L1_D29_UnBias	4.488	4.682	-0.194
10	HDR_L2_D28_UnBias	4.688	4.772	-0.084
10	HDR_L3_D27_UnBias	4.527	4.405	0.122
10	HDR_L3_D28_UnBias	4.265	4.723	-0.458
30	HDR_L1_D30_UnBias	4.604	4.923	-0.319
30	HDR_L2_D29_nUBias	4.682	4.943	-0.261
30	HDR_L2_D30_UnBias	5.057	5.194	-0.137
30	HDR_L3_D29_UnBias	4.544	4.917	-0.373
30	HDR_L3_D30_UnBias	4.185	4.675	-0.490
50	HDR_L1_D31_UnBias	4.411	4.842	-0.431
50	HDR_L1_D32_UnBias	4.411	5.327	-0.916
50	HDR_L2_D31_UnBias	5.267	5.834	-0.567
50	HDR_L2_D32_UnBias	4.553	4.908	-0.355
50	HDR_L3_D31_UnBias	4.380	4.915	-0.535
100	HDR_L1_D33_UnBias	4.372	4.963	-0.591
100	HDR_L1_D34_UnBias	4.850	5.462	-0.612
100	HDR_L1_D35_UnBias	4.804	5.353	-0.549
100	HDR_L1_D36_UnBias	4.709	5.072	-0.363
100	HDR_L1_D37_UnBias	4.705	5.151	-0.446
100	HDR_L1_D38_UnBias	4.344	4.866	-0.522
100	HDR_L1_D39_UnBias	4.481	4.923	-0.442
100	HDR_L2_D33_UnBias	4.883	5.332	-0.449
100	HDR_L2_D34_UnBias	5.278	5.758	-0.480
100	HDR_L2_D35_UnBias	4.944	5.672	-0.728
100	HDR_L2_D36_UnBias	5.183	5.678	-0.495
100	HDR_L2_D37_UnBias	4.887	5.322	-0.435
100	HDR_L2_D38_UnBias	4.959	5.248	-0.289
100	HDR_L2_D39_UnBias	4.929	5.457	-0.528
100	HDR_L3_D32_UnBias	4.503	4.961	-0.458
100	HDR_L3_D33_UnBias	4.942	5.381	-0.439
100	HDR_L3_D34_UnBias	4.652	5.182	-0.530
100	HDR_L3_D35_UnBias	4.662	5.096	-0.434
100	HDR_L3_D36_UnBias	4.381	4.923	-0.542
100	HDR_L3_D37_UnBias	4.540	5.203	-0.663
100	HDR_L3_D38_UnBias	4.392	4.948	-0.556
100	HDR_L3_D39_UnBias	4.321	4.684	-0.363
	Max	5.278	5.834	0.122
	Average	4.663	5.060	-0.397
	Min	4.185	4.330	-0.916
	Std Dev	0.283	0.346	0.201



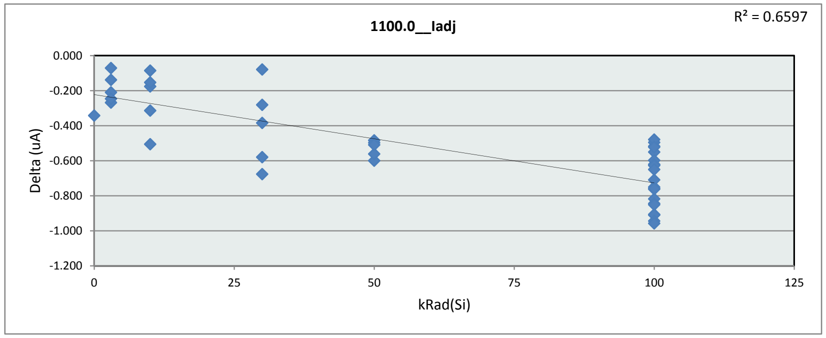
	600.4__Load Reg BW 2					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	10	mV				
Min Limit	0	mV				
kRad(Si)	0	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000	0.000
Min	4.612	4.330	4.405	4.675	4.842	4.684
Average	4.612	4.805	4.770	4.930	5.165	5.211
Max	4.612	5.239	5.267	5.194	5.834	5.758
UL	10.000	10.000	10.000	10.000	10.000	10.000



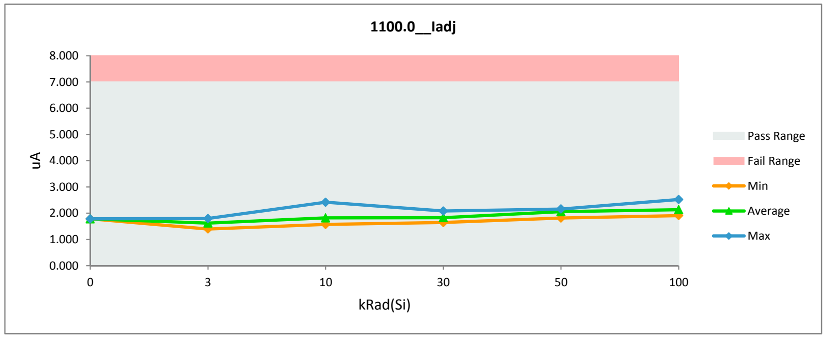
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		1100.0__Iadj		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	7	7	
	Min Limit	0	0	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	1.443	1.786	-0.343
3	HDR_L1_D26_UnBias	1.482	1.554	-0.072
3	HDR_L1_D27_UnBias	1.400	1.610	-0.210
3	HDR_L2_D26_UnBias	1.487	1.756	-0.269
3	HDR_L2_D27_UnBias	1.549	1.796	-0.247
3	HDR_L3_D26_UnBias	1.259	1.398	-0.139
10	HDR_L1_D28_UnBias	1.359	1.673	-0.314
10	HDR_L1_D29_UnBias	2.241	2.418	-0.177
10	HDR_L2_D28_UnBias	1.508	1.662	-0.154
10	HDR_L3_D27_UnBias	1.270	1.776	-0.506
10	HDR_L3_D28_UnBias	1.487	1.573	-0.086
30	HDR_L1_D30_UnBias	1.436	2.016	-0.580
30	HDR_L2_D29_nUBias	1.463	1.745	-0.282
30	HDR_L2_D30_UnBias	1.407	2.084	-0.677
30	HDR_L3_D29_UnBias	1.566	1.646	-0.080
30	HDR_L3_D30_UnBias	1.273	1.658	-0.385
50	HDR_L1_D31_UnBias	1.558	2.158	-0.600
50	HDR_L1_D32_UnBias	1.558	2.120	-0.562
50	HDR_L2_D31_UnBias	1.606	2.090	-0.484
50	HDR_L2_D32_UnBias	1.609	2.107	-0.498
50	HDR_L3_D31_UnBias	1.304	1.814	-0.510
100	HDR_L1_D33_UnBias	1.430	1.981	-0.551
100	HDR_L1_D34_UnBias	1.404	2.222	-0.818
100	HDR_L1_D35_UnBias	1.318	2.163	-0.845
100	HDR_L1_D36_UnBias	1.734	2.332	-0.598
100	HDR_L1_D37_UnBias	1.352	1.976	-0.624
100	HDR_L1_D38_UnBias	1.451	2.072	-0.621
100	HDR_L1_D39_UnBias	1.385	2.292	-0.907
100	HDR_L2_D33_UnBias	1.345	2.255	-0.910
100	HDR_L2_D34_UnBias	1.574	2.070	-0.496
100	HDR_L2_D35_UnBias	1.538	2.056	-0.518
100	HDR_L2_D36_UnBias	1.610	2.520	-0.910
100	HDR_L2_D37_UnBias	1.377	2.005	-0.628
100	HDR_L2_D38_UnBias	1.414	2.165	-0.751
100	HDR_L2_D39_UnBias	1.502	2.265	-0.763
100	HDR_L3_D32_UnBias	1.259	1.909	-0.650
100	HDR_L3_D33_UnBias	1.274	1.984	-0.710
100	HDR_L3_D34_UnBias	1.277	2.128	-0.851
100	HDR_L3_D35_UnBias	1.536	2.016	-0.480
100	HDR_L3_D36_UnBias	1.411	1.934	-0.523
100	HDR_L3_D37_UnBias	1.336	2.280	-0.944
100	HDR_L3_D38_UnBias	1.257	2.215	-0.958
100	HDR_L3_D39_UnBias	1.380	2.139	-0.759
	Max	2.241	2.520	-0.072
	Average	1.452	1.986	-0.535
	Min	1.257	1.398	-0.958
	Std Dev	0.170	0.257	0.258



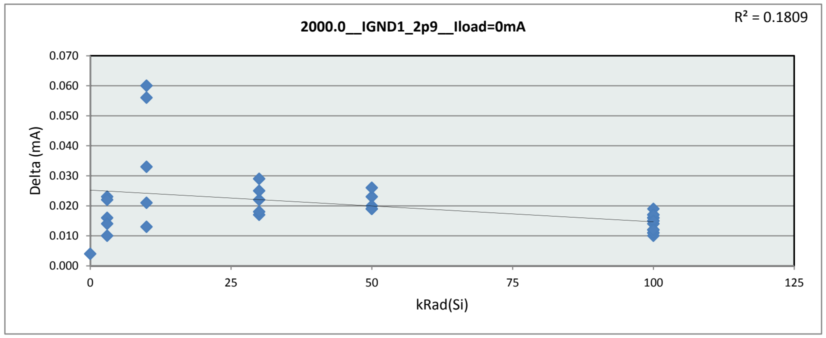
	1100.0__Iadj					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	7	uA				
Min Limit	0	uA				
kRad(Si)	0	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000	0.000
Min	1.786	1.398	1.573	1.646	1.814	1.909
Average	1.786	1.623	1.820	1.830	2.058	2.135
Max	1.786	1.796	2.418	2.084	2.158	2.520
UL	7.000	7.000	7.000	7.000	7.000	7.000



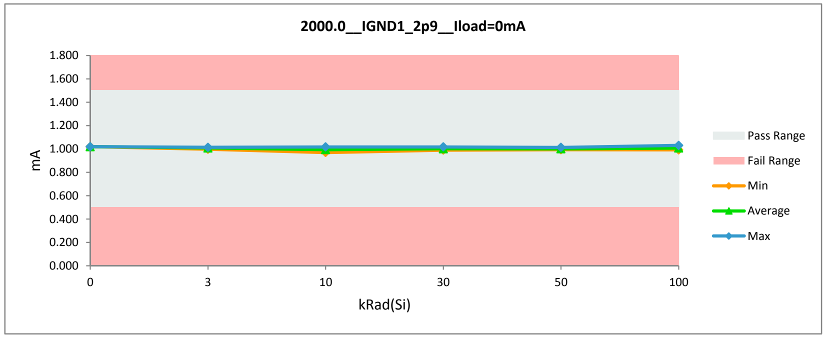
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2000.0__IGND1_2p9__Iload=0mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	1.5	1.5	
	Min Limit	0.5	0.5	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	1.023	1.019	0.004
3	HDR_L1_D26_UnBias	1.027	1.011	0.016
3	HDR_L1_D27_UnBias	1.030	1.007	0.023
3	HDR_L2_D26_UnBias	1.019	0.997	0.022
3	HDR_L2_D27_UnBias	1.024	1.014	0.010
3	HDR_L3_D26_UnBias	1.027	1.013	0.014
10	HDR_L1_D28_UnBias	1.025	0.969	0.056
10	HDR_L1_D29_UnBias	1.019	0.998	0.021
10	HDR_L2_D28_UnBias	1.026	1.013	0.013
10	HDR_L3_D27_UnBias	1.032	0.972	0.060
10	HDR_L3_D28_UnBias	1.050	1.017	0.033
30	HDR_L1_D30_UnBias	1.022	0.993	0.029
30	HDR_L2_D29_nUBias	1.026	1.004	0.022
30	HDR_L2_D30_UnBias	1.021	1.004	0.017
30	HDR_L3_D29_UnBias	1.015	0.990	0.025
30	HDR_L3_D30_UnBias	1.035	1.017	0.018
50	HDR_L1_D31_UnBias	1.019	0.996	0.023
50	HDR_L1_D32_UnBias	1.019	0.993	0.026
50	HDR_L2_D31_UnBias	1.023	1.003	0.020
50	HDR_L2_D32_UnBias	1.032	1.013	0.019
50	HDR_L3_D31_UnBias	1.016	0.997	0.019
100	HDR_L1_D33_UnBias	1.039	1.020	0.019
100	HDR_L1_D34_UnBias	1.018	1.004	0.014
100	HDR_L1_D35_UnBias	1.046	1.030	0.016
100	HDR_L1_D36_UnBias	1.031	1.014	0.017
100	HDR_L1_D37_UnBias	1.028	1.012	0.016
100	HDR_L1_D38_UnBias	1.023	1.008	0.015
100	HDR_L1_D39_UnBias	1.037	1.021	0.016
100	HDR_L2_D33_UnBias	1.027	1.010	0.017
100	HDR_L2_D34_UnBias	1.021	1.005	0.016
100	HDR_L2_D35_UnBias	1.025	1.009	0.016
100	HDR_L2_D36_UnBias	1.029	1.012	0.017
100	HDR_L2_D37_UnBias	1.026	1.012	0.014
100	HDR_L2_D38_UnBias	1.022	1.007	0.015
100	HDR_L2_D39_UnBias	1.031	1.016	0.015
100	HDR_L3_D32_UnBias	1.004	0.992	0.012
100	HDR_L3_D33_UnBias	1.008	0.997	0.011
100	HDR_L3_D34_UnBias	1.012	1.001	0.011
100	HDR_L3_D35_UnBias	1.007	0.997	0.010
100	HDR_L3_D36_UnBias	1.021	1.010	0.011
100	HDR_L3_D37_UnBias	1.015	1.003	0.012
100	HDR_L3_D38_UnBias	1.005	0.993	0.012
100	HDR_L3_D39_UnBias	1.009	0.997	0.012
	Max	1.050	1.030	0.060
	Average	1.024	1.005	0.019
	Min	1.004	0.969	0.004
	Std Dev	0.010	0.012	0.010



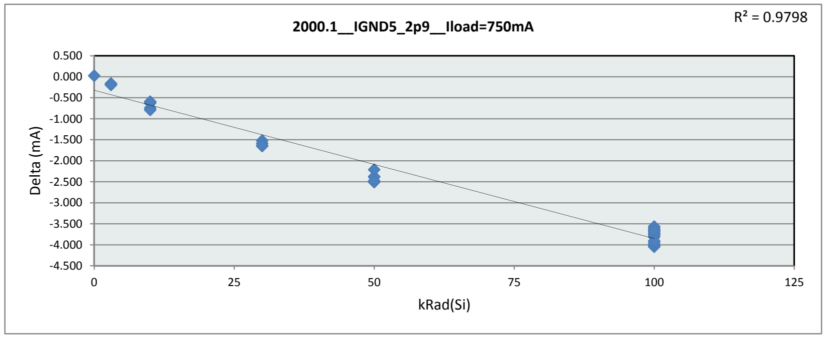
	2000.0__IGND1_2p9__					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1.5	mA				
Min Limit	0.5	mA				
kRad(Si)	0	3	10	30	50	100
LL	0.500	0.500	0.500	0.500	0.500	0.500
Min	1.019	0.997	0.969	0.990	0.993	0.992
Average	1.019	1.008	0.994	1.002	1.000	1.008
Max	1.019	1.014	1.017	1.017	1.013	1.030
UL	1.500	1.500	1.500	1.500	1.500	1.500



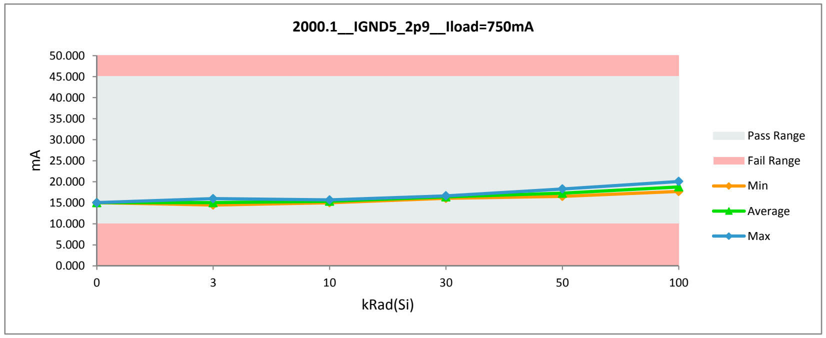
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2000.1__IGND5_2p9__Iload=750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	45	45	
	Min Limit	10	10	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	15.056	15.032	0.024
3	HDR_L1_D26_UnBias	14.296	14.463	-0.167
3	HDR_L1_D27_UnBias	14.265	14.460	-0.195
3	HDR_L2_D26_UnBias	15.812	15.986	-0.174
3	HDR_L2_D27_UnBias	14.993	15.158	-0.165
3	HDR_L3_D26_UnBias	14.918	15.111	-0.193
10	HDR_L1_D28_UnBias	14.684	15.428	-0.744
10	HDR_L1_D29_UnBias	14.519	15.146	-0.627
10	HDR_L2_D28_UnBias	14.424	15.018	-0.594
10	HDR_L3_D27_UnBias	14.889	15.679	-0.790
10	HDR_L3_D28_UnBias	14.940	15.549	-0.609
30	HDR_L1_D30_UnBias	14.409	16.055	-1.646
30	HDR_L2_D29_nUBias	14.857	16.379	-1.522
30	HDR_L2_D30_UnBias	15.029	16.619	-1.590
30	HDR_L3_D29_UnBias	15.009	16.655	-1.646
30	HDR_L3_D30_UnBias	14.705	16.352	-1.647
50	HDR_L1_D31_UnBias	14.393	16.772	-2.379
50	HDR_L1_D32_UnBias	14.393	16.905	-2.512
50	HDR_L2_D31_UnBias	15.904	18.291	-2.387
50	HDR_L2_D32_UnBias	14.305	16.517	-2.212
50	HDR_L3_D31_UnBias	15.423	17.904	-2.481
100	HDR_L1_D33_UnBias	14.057	17.689	-3.632
100	HDR_L1_D34_UnBias	14.496	18.184	-3.688
100	HDR_L1_D35_UnBias	14.816	18.543	-3.727
100	HDR_L1_D36_UnBias	14.251	17.820	-3.569
100	HDR_L1_D37_UnBias	14.654	18.397	-3.743
100	HDR_L1_D38_UnBias	14.250	17.845	-3.595
100	HDR_L1_D39_UnBias	14.279	17.953	-3.674
100	HDR_L2_D33_UnBias	14.965	18.617	-3.652
100	HDR_L2_D34_UnBias	15.332	19.058	-3.726
100	HDR_L2_D35_UnBias	15.273	19.044	-3.771
100	HDR_L2_D36_UnBias	16.262	20.078	-3.816
100	HDR_L2_D37_UnBias	14.956	18.635	-3.679
100	HDR_L2_D38_UnBias	15.856	19.630	-3.774
100	HDR_L2_D39_UnBias	15.761	19.430	-3.669
100	HDR_L3_D32_UnBias	15.133	19.177	-4.044
100	HDR_L3_D33_UnBias	15.133	19.155	-4.022
100	HDR_L3_D34_UnBias	15.049	19.097	-4.048
100	HDR_L3_D35_UnBias	15.162	19.197	-4.035
100	HDR_L3_D36_UnBias	14.818	18.803	-3.985
100	HDR_L3_D37_UnBias	15.138	19.116	-3.978
100	HDR_L3_D38_UnBias	14.924	18.853	-3.929
100	HDR_L3_D39_UnBias	14.998	18.908	-3.910
	Max	16.262	20.078	0.024
	Average	14.902	17.412	-2.510
	Min	14.057	14.460	-4.048
	Std Dev	0.507	1.646	1.480



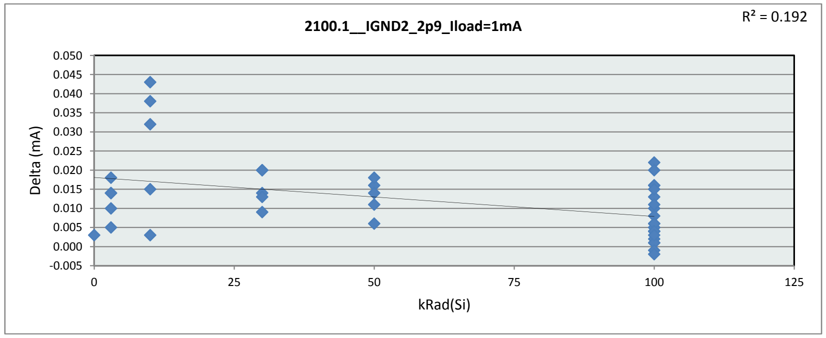
	2000.1__IGND5_2p9__				
Test Site	CLAB				
Tester	ETS#3				
Test Number	EF556000				
Max Limit	45	mA			
Min Limit	10	mA			
kRad(Si)	0	3	10	30	50	100
LL	10.000	10.000	10.000	10.000	10.000	10.000
Min	15.032	14.460	15.018	16.055	16.517	17.689
Average	15.032	15.036	15.364	16.412	17.278	18.783
Max	15.032	15.986	15.679	16.655	18.291	20.078
UL	45.000	45.000	45.000	45.000	45.000	45.000



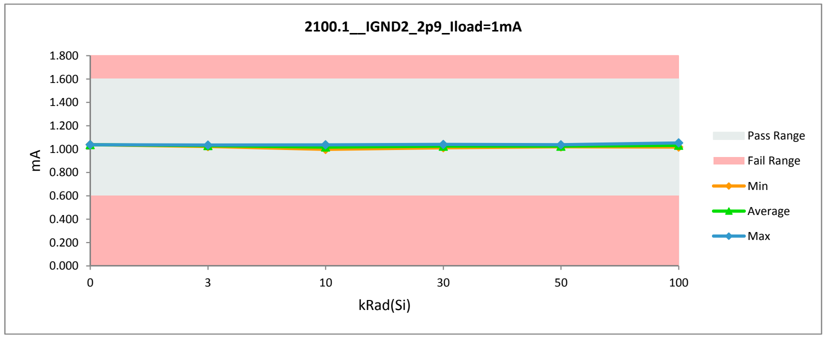
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2100.1__IGND2_2p9_Iload=1mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mA	mA	
Max Limit		1.6	1.6	
Min Limit		0.6	0.6	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	1.041	1.038	0.003
3	HDR_L1_D26_UnBias	1.036	1.031	0.005
3	HDR_L1_D27_UnBias	1.047	1.029	0.018
3	HDR_L2_D26_UnBias	1.036	1.022	0.014
3	HDR_L2_D27_UnBias	1.044	1.034	0.010
3	HDR_L3_D26_UnBias	1.046	1.032	0.014
10	HDR_L1_D28_UnBias	1.035	0.997	0.038
10	HDR_L1_D29_UnBias	1.036	1.021	0.015
10	HDR_L2_D28_UnBias	1.037	1.034	0.003
10	HDR_L3_D27_UnBias	1.040	0.997	0.043
10	HDR_L3_D28_UnBias	1.068	1.036	0.032
30	HDR_L1_D30_UnBias	1.038	1.018	0.020
30	HDR_L2_D29_nUBias	1.043	1.029	0.014
30	HDR_L2_D30_UnBias	1.035	1.026	0.009
30	HDR_L3_D29_UnBias	1.032	1.012	0.020
30	HDR_L3_D30_UnBias	1.053	1.040	0.013
50	HDR_L1_D31_UnBias	1.037	1.021	0.016
50	HDR_L1_D32_UnBias	1.037	1.019	0.018
50	HDR_L2_D31_UnBias	1.033	1.027	0.006
50	HDR_L2_D32_UnBias	1.048	1.037	0.011
50	HDR_L3_D31_UnBias	1.035	1.021	0.014
100	HDR_L1_D33_UnBias	1.058	1.045	0.013
100	HDR_L1_D34_UnBias	1.034	1.029	0.005
100	HDR_L1_D35_UnBias	1.075	1.053	0.022
100	HDR_L1_D36_UnBias	1.042	1.038	0.004
100	HDR_L1_D37_UnBias	1.053	1.037	0.016
100	HDR_L1_D38_UnBias	1.041	1.035	0.006
100	HDR_L1_D39_UnBias	1.056	1.046	0.010
100	HDR_L2_D33_UnBias	1.054	1.034	0.020
100	HDR_L2_D34_UnBias	1.047	1.031	0.016
100	HDR_L2_D35_UnBias	1.035	1.033	0.002
100	HDR_L2_D36_UnBias	1.047	1.036	0.011
100	HDR_L2_D37_UnBias	1.041	1.036	0.005
100	HDR_L2_D38_UnBias	1.047	1.032	0.015
100	HDR_L2_D39_UnBias	1.049	1.041	0.008
100	HDR_L3_D32_UnBias	1.019	1.018	0.001
100	HDR_L3_D33_UnBias	1.024	1.023	0.001
100	HDR_L3_D34_UnBias	1.033	1.027	0.006
100	HDR_L3_D35_UnBias	1.025	1.021	0.004
100	HDR_L3_D36_UnBias	1.038	1.034	0.004
100	HDR_L3_D37_UnBias	1.025	1.026	-0.001
100	HDR_L3_D38_UnBias	1.020	1.017	0.003
100	HDR_L3_D39_UnBias	1.020	1.022	-0.002
	Max	1.075	1.053	0.043
	Average	1.040	1.029	0.012
	Min	1.019	0.997	-0.002
	Std Dev	0.012	0.011	0.010



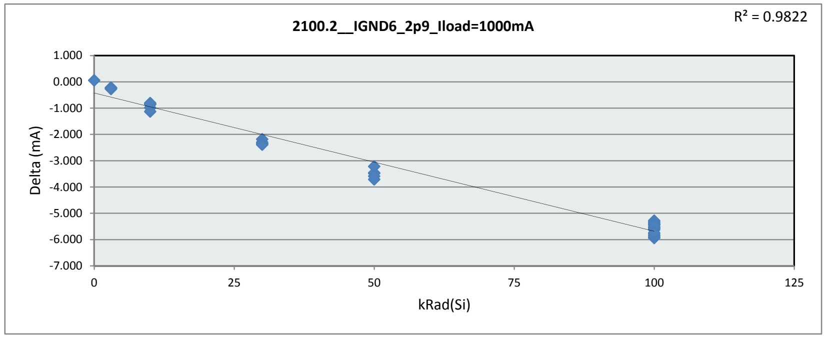
	2100.1__IGND2_2p9_I					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1.6	mA				
Min Limit	0.6	mA				
kRad(Si)	0	3	10	30	50	100
LL	0.600	0.600	0.600	0.600	0.600	0.600
Min	1.038	1.022	0.997	1.012	1.019	1.017
Average	1.038	1.030	1.017	1.025	1.025	1.032
Max	1.038	1.034	1.036	1.040	1.037	1.053
UL	1.600	1.600	1.600	1.600	1.600	1.600



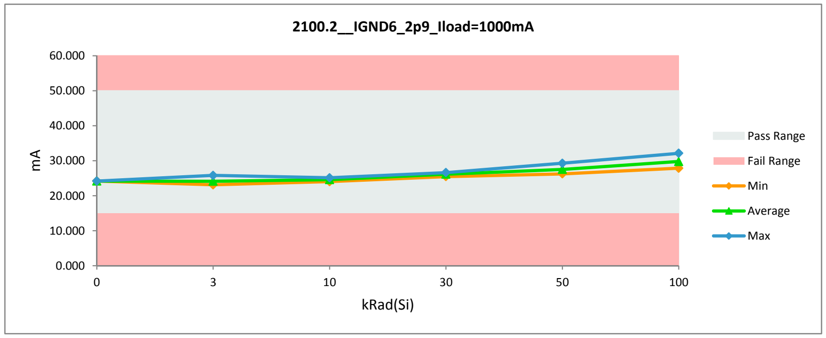
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2100.2__IGND6_2p9_Iload=1000mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	50	50	
	Min Limit	15	15	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	24.242	24.188	0.054
3	HDR_L1_D26_UnBias	22.927	23.165	-0.238
3	HDR_L1_D27_UnBias	22.830	23.107	-0.277
3	HDR_L2_D26_UnBias	25.571	25.793	-0.222
3	HDR_L2_D27_UnBias	24.140	24.384	-0.244
3	HDR_L3_D26_UnBias	24.031	24.276	-0.245
10	HDR_L1_D28_UnBias	23.653	24.638	-0.985
10	HDR_L1_D29_UnBias	23.356	24.215	-0.859
10	HDR_L2_D28_UnBias	23.169	24.020	-0.851
10	HDR_L3_D27_UnBias	23.990	25.123	-1.133
10	HDR_L3_D28_UnBias	24.118	24.927	-0.809
30	HDR_L1_D30_UnBias	23.104	25.455	-2.351
30	HDR_L2_D29_nUBias	23.884	26.068	-2.184
30	HDR_L2_D30_UnBias	24.164	26.465	-2.301
30	HDR_L3_D29_UnBias	24.245	26.590	-2.345
30	HDR_L3_D30_UnBias	23.702	26.092	-2.390
50	HDR_L1_D31_UnBias	23.063	26.525	-3.462
50	HDR_L1_D32_UnBias	23.063	26.779	-3.716
50	HDR_L2_D31_UnBias	25.787	29.272	-3.485
50	HDR_L2_D32_UnBias	23.019	26.237	-3.218
50	HDR_L3_D31_UnBias	25.179	28.772	-3.593
100	HDR_L1_D33_UnBias	22.475	27.852	-5.377
100	HDR_L1_D34_UnBias	23.258	28.703	-5.445
100	HDR_L1_D35_UnBias	23.907	29.426	-5.519
100	HDR_L1_D36_UnBias	22.951	28.232	-5.281
100	HDR_L1_D37_UnBias	23.571	29.104	-5.533
100	HDR_L1_D38_UnBias	22.863	28.188	-5.325
100	HDR_L1_D39_UnBias	22.869	28.301	-5.432
100	HDR_L2_D33_UnBias	24.137	29.550	-5.413
100	HDR_L2_D34_UnBias	24.695	30.216	-5.521
100	HDR_L2_D35_UnBias	24.610	30.193	-5.583
100	HDR_L2_D36_UnBias	26.484	32.116	-5.632
100	HDR_L2_D37_UnBias	24.039	29.488	-5.449
100	HDR_L2_D38_UnBias	25.662	31.239	-5.577
100	HDR_L2_D39_UnBias	25.594	31.022	-5.428
100	HDR_L3_D32_UnBias	24.397	30.334	-5.937
100	HDR_L3_D33_UnBias	24.432	30.360	-5.928
100	HDR_L3_D34_UnBias	24.293	30.235	-5.942
100	HDR_L3_D35_UnBias	24.477	30.404	-5.927
100	HDR_L3_D36_UnBias	23.867	29.740	-5.873
100	HDR_L3_D37_UnBias	24.489	30.339	-5.850
100	HDR_L3_D38_UnBias	24.011	29.804	-5.793
100	HDR_L3_D39_UnBias	24.223	29.969	-5.746
	Max	26.484	32.116	0.054
	Average	24.013	27.695	-3.683
	Min	22.475	23.107	-5.942
	Std Dev	0.908	2.528	2.203



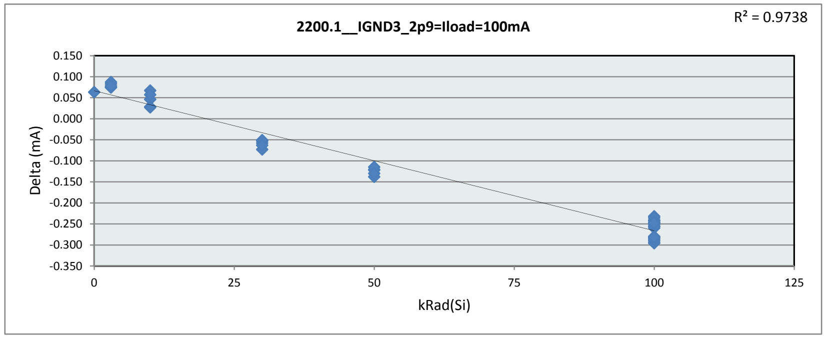
	2100.2__IGND6_2p9_I					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	50	mA				
Min Limit	15	mA				
kRad(Si)	0	3	10	30	50	100
LL	15.000	15.000	15.000	15.000	15.000	15.000
Min	24.188	23.107	24.020	25.455	26.237	27.852
Average	24.188	24.145	24.585	26.134	27.517	29.764
Max	24.188	25.793	25.123	26.590	29.272	32.116
UL	50.000	50.000	50.000	50.000	50.000	50.000



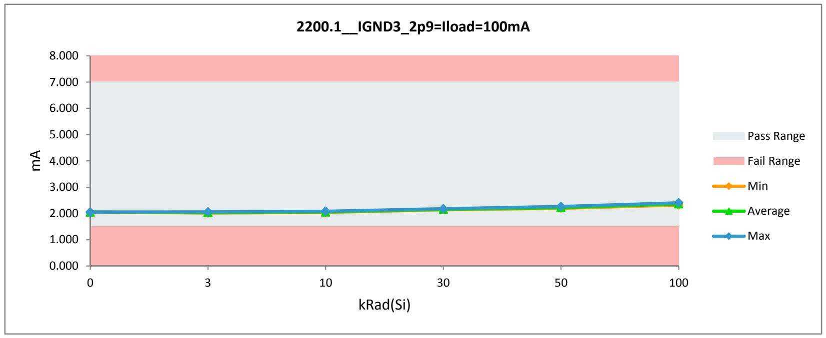
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2200.1__IGND3_2p9=Iload=100mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	7	7	
	Min Limit	1.5	1.5	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	2.113	2.050	0.063
3	HDR_L1_D26_UnBias	2.092	2.017	0.075
3	HDR_L1_D27_UnBias	2.088	2.014	0.074
3	HDR_L2_D26_UnBias	2.142	2.059	0.083
3	HDR_L2_D27_UnBias	2.133	2.046	0.087
3	HDR_L3_D26_UnBias	2.117	2.039	0.078
10	HDR_L1_D28_UnBias	2.085	2.039	0.046
10	HDR_L1_D29_UnBias	2.083	2.055	0.028
10	HDR_L2_D28_UnBias	2.088	2.061	0.027
10	HDR_L3_D27_UnBias	2.108	2.041	0.067
10	HDR_L3_D28_UnBias	2.142	2.085	0.057
30	HDR_L1_D30_UnBias	2.087	2.145	-0.058
30	HDR_L2_D29_nUBias	2.107	2.160	-0.053
30	HDR_L2_D30_UnBias	2.105	2.178	-0.073
30	HDR_L3_D29_UnBias	2.087	2.138	-0.051
30	HDR_L3_D30_UnBias	2.103	2.166	-0.063
50	HDR_L1_D31_UnBias	2.093	2.214	-0.121
50	HDR_L1_D32_UnBias	2.093	2.215	-0.122
50	HDR_L2_D31_UnBias	2.127	2.265	-0.138
50	HDR_L2_D32_UnBias	2.086	2.201	-0.115
50	HDR_L3_D31_UnBias	2.094	2.224	-0.130
100	HDR_L1_D33_UnBias	2.104	2.345	-0.241
100	HDR_L1_D34_UnBias	2.092	2.343	-0.251
100	HDR_L1_D35_UnBias	2.130	2.373	-0.243
100	HDR_L1_D36_UnBias	2.091	2.323	-0.232
100	HDR_L1_D37_UnBias	2.112	2.359	-0.247
100	HDR_L1_D38_UnBias	2.086	2.322	-0.236
100	HDR_L1_D39_UnBias	2.101	2.356	-0.255
100	HDR_L2_D33_UnBias	2.115	2.358	-0.243
100	HDR_L2_D34_UnBias	2.120	2.376	-0.256
100	HDR_L2_D35_UnBias	2.128	2.388	-0.260
100	HDR_L2_D36_UnBias	2.159	2.406	-0.247
100	HDR_L2_D37_UnBias	2.118	2.374	-0.256
100	HDR_L2_D38_UnBias	2.148	2.397	-0.249
100	HDR_L2_D39_UnBias	2.138	2.386	-0.248
100	HDR_L3_D32_UnBias	2.084	2.364	-0.280
100	HDR_L3_D33_UnBias	2.079	2.370	-0.291
100	HDR_L3_D34_UnBias	2.075	2.371	-0.296
100	HDR_L3_D35_UnBias	2.078	2.373	-0.295
100	HDR_L3_D36_UnBias	2.087	2.372	-0.285
100	HDR_L3_D37_UnBias	2.083	2.365	-0.282
100	HDR_L3_D38_UnBias	2.068	2.356	-0.288
100	HDR_L3_D39_UnBias	2.073	2.355	-0.282
	Max	2.159	2.406	0.087
	Average	2.103	2.243	-0.140
	Min	2.068	2.014	-0.296
	Std Dev	0.023	0.139	0.140



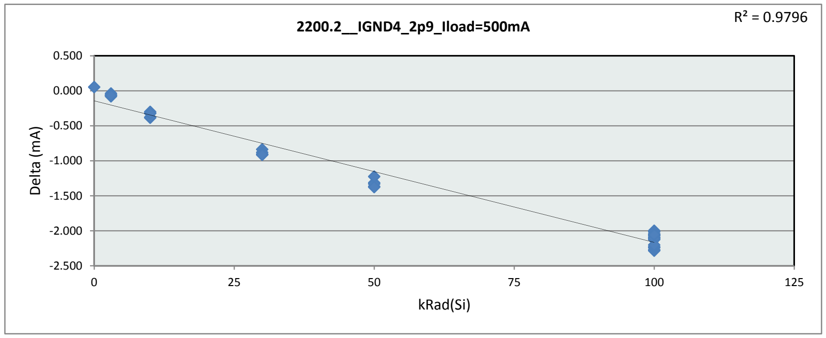
	2200.1__IGND3_2p9=I					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	7	mA				
Min Limit	1.5	mA				
kRad(Si)	0	3	10	30	50	100
LL	1.500	1.500	1.500	1.500	1.500	1.500
Min	2.050	2.014	2.039	2.138	2.201	2.322
Average	2.050	2.035	2.056	2.157	2.224	2.365
Max	2.050	2.059	2.085	2.178	2.265	2.406
UL	7.000	7.000	7.000	7.000	7.000	7.000



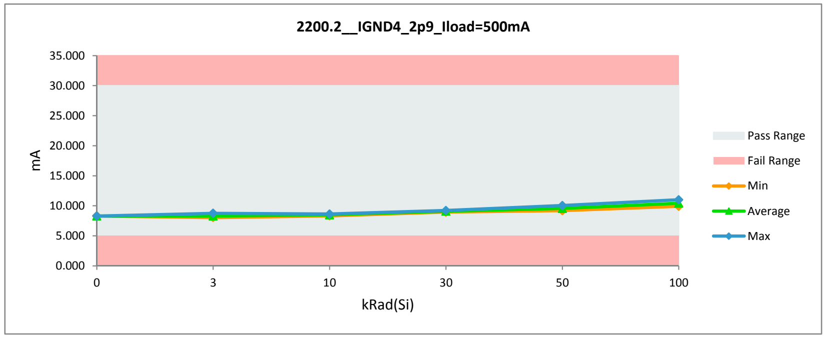
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2200.2__IGND4_2p9_Iload=500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	5	5	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	8.347	8.296	0.051
3	HDR_L1_D26_UnBias	7.972	8.032	-0.060
3	HDR_L1_D27_UnBias	7.965	8.045	-0.080
3	HDR_L2_D26_UnBias	8.686	8.748	-0.062
3	HDR_L2_D27_UnBias	8.314	8.353	-0.039
3	HDR_L3_D26_UnBias	8.276	8.342	-0.066
10	HDR_L1_D28_UnBias	8.135	8.521	-0.386
10	HDR_L1_D29_UnBias	8.070	8.392	-0.322
10	HDR_L2_D28_UnBias	8.026	8.329	-0.303
10	HDR_L3_D27_UnBias	8.254	8.634	-0.380
10	HDR_L3_D28_UnBias	8.280	8.602	-0.322
30	HDR_L1_D30_UnBias	8.043	8.949	-0.906
30	HDR_L2_D29_nUBias	8.253	9.092	-0.839
30	HDR_L2_D30_UnBias	8.338	9.220	-0.882
30	HDR_L3_D29_UnBias	8.281	9.190	-0.909
30	HDR_L3_D30_UnBias	8.159	9.075	-0.916
50	HDR_L1_D31_UnBias	8.036	9.352	-1.316
50	HDR_L1_D32_UnBias	8.036	9.405	-1.369
50	HDR_L2_D31_UnBias	8.717	10.048	-1.331
50	HDR_L2_D32_UnBias	7.964	9.191	-1.227
50	HDR_L3_D31_UnBias	8.432	9.810	-1.378
100	HDR_L1_D33_UnBias	7.875	9.920	-2.045
100	HDR_L1_D34_UnBias	8.078	10.146	-2.068
100	HDR_L1_D35_UnBias	8.206	10.299	-2.093
100	HDR_L1_D36_UnBias	7.916	9.917	-2.001
100	HDR_L1_D37_UnBias	8.149	10.244	-2.095
100	HDR_L1_D38_UnBias	7.941	9.956	-2.015
100	HDR_L1_D39_UnBias	7.979	10.044	-2.065
100	HDR_L2_D33_UnBias	8.284	10.331	-2.047
100	HDR_L2_D34_UnBias	8.473	10.571	-2.098
100	HDR_L2_D35_UnBias	8.445	10.563	-2.118
100	HDR_L2_D36_UnBias	8.873	11.002	-2.129
100	HDR_L2_D37_UnBias	8.305	10.375	-2.070
100	HDR_L2_D38_UnBias	8.720	10.831	-2.111
100	HDR_L2_D39_UnBias	8.638	10.696	-2.058
100	HDR_L3_D32_UnBias	8.358	10.632	-2.274
100	HDR_L3_D33_UnBias	8.358	10.631	-2.273
100	HDR_L3_D34_UnBias	8.296	10.582	-2.286
100	HDR_L3_D35_UnBias	8.364	10.643	-2.279
100	HDR_L3_D36_UnBias	8.214	10.457	-2.243
100	HDR_L3_D37_UnBias	8.335	10.575	-2.240
100	HDR_L3_D38_UnBias	8.252	10.481	-2.229
100	HDR_L3_D39_UnBias	8.279	10.482	-2.203
	Max	8.873	11.002	0.051
	Average	8.254	9.651	-1.397
	Min	7.875	8.032	-2.286
	Std Dev	0.234	0.914	0.848



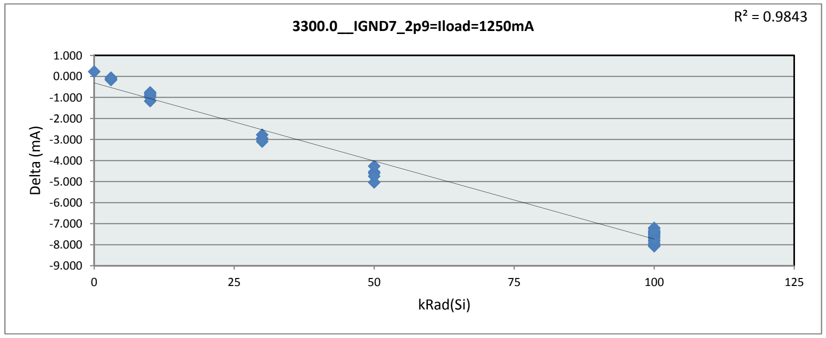
	2200.2__IGND4_2p9_I					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	30	mA				
Min Limit	5	mA				
kRad(Si)	0	3	10	30	50	100
LL	5.000	5.000	5.000	5.000	5.000	5.000
Min	8.296	8.032	8.329	8.949	9.191	9.917
Average	8.296	8.304	8.496	9.105	9.561	10.426
Max	8.296	8.748	8.634	9.220	10.048	11.002
UL	30.000	30.000	30.000	30.000	30.000	30.000



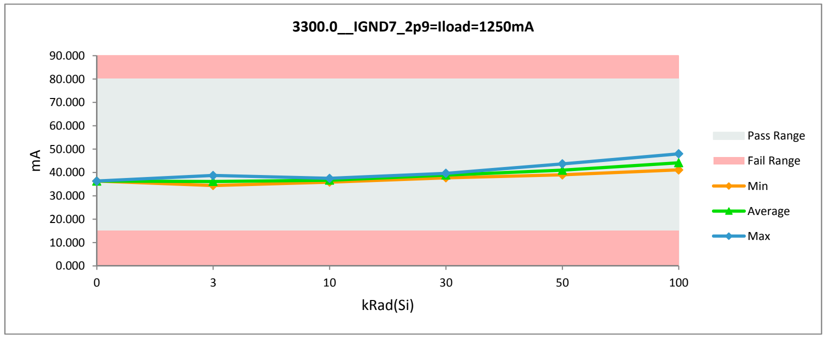
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		3300.0__IGND7_2p9=Iload=1250mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	80	80	
	Min Limit	15	15	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	36.541	36.314	0.227
3	HDR_L1_D26_UnBias	34.505	34.618	-0.113
3	HDR_L1_D27_UnBias	34.283	34.432	-0.149
3	HDR_L2_D26_UnBias	38.633	38.693	-0.060
3	HDR_L2_D27_UnBias	36.389	36.556	-0.167
3	HDR_L3_D26_UnBias	36.345	36.463	-0.118
10	HDR_L1_D28_UnBias	35.796	36.625	-0.829
10	HDR_L1_D29_UnBias	35.230	36.146	-0.916
10	HDR_L2_D28_UnBias	34.883	35.877	-0.994
10	HDR_L3_D27_UnBias	36.283	37.458	-1.175
10	HDR_L3_D28_UnBias	36.593	37.351	-0.758
30	HDR_L1_D30_UnBias	34.708	37.697	-2.989
30	HDR_L2_D29_nUBias	35.988	38.768	-2.780
30	HDR_L2_D30_UnBias	36.390	39.358	-2.968
30	HDR_L3_D29_UnBias	36.681	39.624	-2.943
30	HDR_L3_D30_UnBias	35.900	38.994	-3.094
50	HDR_L1_D31_UnBias	34.655	39.200	-4.545
50	HDR_L1_D32_UnBias	34.655	39.695	-5.040
50	HDR_L2_D31_UnBias	39.069	43.674	-4.605
50	HDR_L2_D32_UnBias	34.696	38.963	-4.267
50	HDR_L3_D31_UnBias	38.622	43.369	-4.747
100	HDR_L1_D33_UnBias	33.756	41.098	-7.342
100	HDR_L1_D34_UnBias	34.990	42.428	-7.438
100	HDR_L1_D35_UnBias	36.215	43.724	-7.509
100	HDR_L1_D36_UnBias	34.699	41.901	-7.202
100	HDR_L1_D37_UnBias	35.592	43.141	-7.549
100	HDR_L1_D38_UnBias	34.409	41.648	-7.239
100	HDR_L1_D39_UnBias	34.417	41.786	-7.369
100	HDR_L2_D33_UnBias	36.512	43.876	-7.364
100	HDR_L2_D34_UnBias	37.265	44.778	-7.513
100	HDR_L2_D35_UnBias	37.133	44.777	-7.644
100	HDR_L2_D36_UnBias	40.269	47.975	-7.706
100	HDR_L2_D37_UnBias	36.238	43.679	-7.441
100	HDR_L2_D38_UnBias	38.819	46.427	-7.608
100	HDR_L2_D39_UnBias	38.873	46.288	-7.415
100	HDR_L3_D32_UnBias	36.830	44.886	-8.056
100	HDR_L3_D33_UnBias	37.024	45.094	-8.070
100	HDR_L3_D34_UnBias	36.748	44.807	-8.059
100	HDR_L3_D35_UnBias	36.999	45.044	-8.045
100	HDR_L3_D36_UnBias	36.071	44.059	-7.988
100	HDR_L3_D37_UnBias	37.097	45.022	-7.925
100	HDR_L3_D38_UnBias	36.198	44.023	-7.825
100	HDR_L3_D39_UnBias	36.642	44.430	-7.788
	Max	40.269	47.975	0.227
	Average	36.271	41.181	-4.910
	Min	33.756	34.432	-8.070
	Std Dev	1.475	3.672	3.108



	3300.0__IGND7_2p9=I					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	80	mA				
Min Limit	15	mA				
kRad(Si)	0	3	10	30	50	100
LL	15.000	15.000	15.000	15.000	15.000	15.000
Min	36.314	34.432	35.877	37.697	38.963	41.098
Average	36.314	36.152	36.691	38.888	40.980	44.131
Max	36.314	38.693	37.458	39.624	43.674	47.975
UL	80.000	80.000	80.000	80.000	80.000	80.000

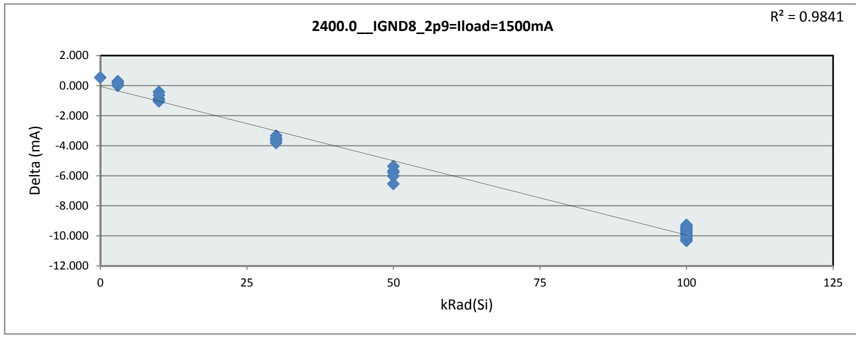


TPS7A4501-RHA

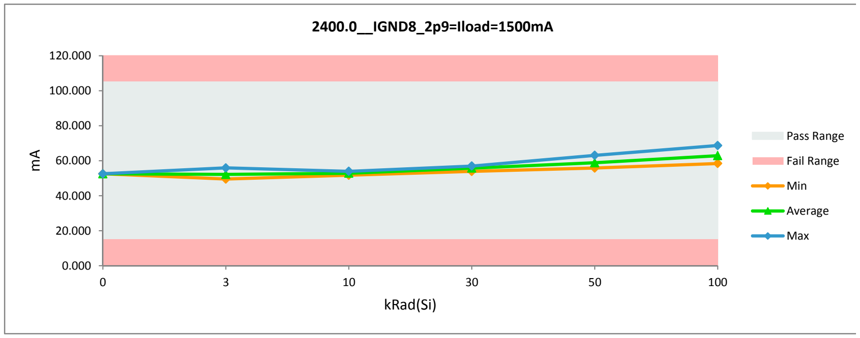
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2400.0__IGND8_2p9=Iload=1500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	105	105	
	Min Limit	15	15	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	53.038	52.500	0.538
3	HDR_L1_D26_UnBias	50.096	49.917	0.179
3	HDR_L1_D27_UnBias	49.695	49.505	0.190
3	HDR_L2_D26_UnBias	56.170	55.877	0.293
3	HDR_L2_D27_UnBias	52.820	52.823	-0.003
3	HDR_L3_D26_UnBias	52.854	52.720	0.134
10	HDR_L1_D28_UnBias	52.173	52.592	-0.419
10	HDR_L1_D29_UnBias	51.190	52.058	-0.868
10	HDR_L2_D28_UnBias	50.653	51.684	-1.031
10	HDR_L3_D27_UnBias	52.786	53.834	-1.048
10	HDR_L3_D28_UnBias	53.283	53.915	-0.632
30	HDR_L1_D30_UnBias	50.292	53.865	-3.573
30	HDR_L2_D29_nUBias	52.223	55.569	-3.346
30	HDR_L2_D30_UnBias	52.783	56.438	-3.655
30	HDR_L3_D29_UnBias	53.393	56.924	-3.531
30	HDR_L3_D30_UnBias	52.275	56.092	-3.817
50	HDR_L1_D31_UnBias	50.206	55.898	-5.692
50	HDR_L1_D32_UnBias	50.206	56.754	-6.548
50	HDR_L2_D31_UnBias	56.884	62.665	-5.781
50	HDR_L2_D32_UnBias	50.426	55.796	-5.370
50	HDR_L3_D31_UnBias	57.050	63.079	-6.029
100	HDR_L1_D33_UnBias	48.951	58.415	-9.464
100	HDR_L1_D34_UnBias	50.759	60.396	-9.637
100	HDR_L1_D35_UnBias	52.833	62.509	-9.676
100	HDR_L1_D36_UnBias	50.597	59.873	-9.276
100	HDR_L1_D37_UnBias	51.774	61.496	-9.722
100	HDR_L1_D38_UnBias	49.950	59.320	-9.370
100	HDR_L1_D39_UnBias	49.946	59.451	-9.505
100	HDR_L2_D33_UnBias	53.138	62.606	-9.468
100	HDR_L2_D34_UnBias	54.111	63.773	-9.662
100	HDR_L2_D35_UnBias	53.909	63.770	-9.861
100	HDR_L2_D36_UnBias	58.790	68.683	-9.893
100	HDR_L2_D37_UnBias	52.615	62.187	-9.572
100	HDR_L2_D38_UnBias	56.459	66.233	-9.774
100	HDR_L2_D39_UnBias	56.736	66.261	-9.525
100	HDR_L3_D32_UnBias	53.473	63.814	-10.341
100	HDR_L3_D33_UnBias	53.877	64.165	-10.288
100	HDR_L3_D34_UnBias	53.454	63.783	-10.329
100	HDR_L3_D35_UnBias	53.790	64.104	-10.314
100	HDR_L3_D36_UnBias	52.448	62.671	-10.223
100	HDR_L3_D37_UnBias	54.008	64.169	-10.161
100	HDR_L3_D38_UnBias	52.519	62.571	-10.052
100	HDR_L3_D39_UnBias	53.314	63.280	-9.966
	Max	58.790	68.683	0.538
	Average	52.743	58.931	-6.188
	Min	48.951	49.505	-10.341
	Std Dev	2.242	5.046	4.141



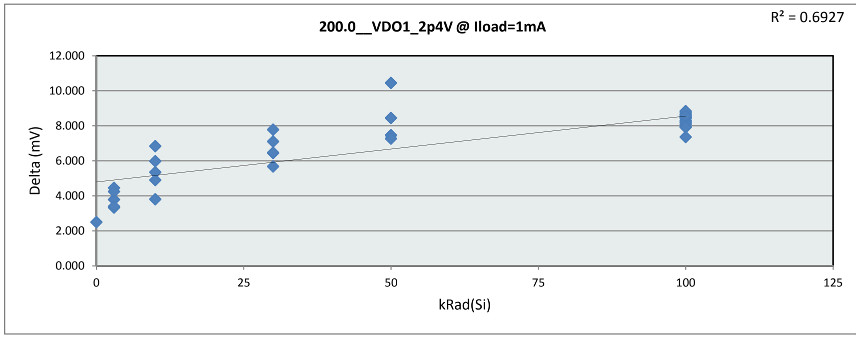
	2400.0__IGND8_2p9=I					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	105	mA				
Min Limit	15	mA				
kRad(Si)	0	3	10	30	50	100
LL	15.000	15.000	15.000	15.000	15.000	15.000
Min	52.500	49.505	51.684	53.865	55.796	58.415
Average	52.500	52.168	52.817	55.778	58.838	62.888
Max	52.500	55.877	53.915	56.924	63.079	68.683
UL	105.000	105.000	105.000	105.000	105.000	105.000



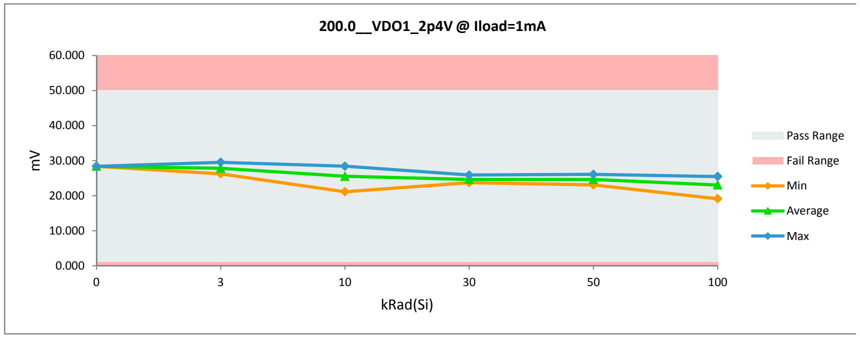
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.0__VDO1_2p4V @ Iload=1mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	50	50	
	Min Limit	1	1	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	30.871	28.376	2.495
3	HDR_L1_D26_UnBias	31.071	27.288	3.783
3	HDR_L1_D27_UnBias	33.100	28.649	4.451
3	HDR_L2_D26_UnBias	31.600	27.357	4.243
3	HDR_L2_D27_UnBias	32.839	29.514	3.325
3	HDR_L3_D26_UnBias	29.617	26.229	3.388
10	HDR_L1_D28_UnBias	27.961	21.125	6.836
10	HDR_L1_D29_UnBias	30.619	25.271	5.348
10	HDR_L2_D28_UnBias	33.306	28.412	4.894
10	HDR_L3_D27_UnBias	30.564	26.761	3.803
10	HDR_L3_D28_UnBias	32.097	26.121	5.976
30	HDR_L1_D30_UnBias	32.737	24.962	7.775
30	HDR_L2_D29_nUBias	30.264	23.821	6.443
30	HDR_L2_D30_UnBias	31.176	24.715	6.461
30	HDR_L3_D29_UnBias	32.999	25.904	7.095
30	HDR_L3_D30_UnBias	29.389	23.716	5.673
50	HDR_L1_D31_UnBias	34.520	26.074	8.446
50	HDR_L1_D32_UnBias	34.520	24.075	10.445
50	HDR_L2_D31_UnBias	30.523	23.066	7.457
50	HDR_L2_D32_UnBias	32.686	25.231	7.455
50	HDR_L3_D31_UnBias	31.946	24.687	7.259
100	HDR_L1_D33_UnBias	32.219	23.497	8.722
100	HDR_L1_D34_UnBias	32.717	24.080	8.637
100	HDR_L1_D35_UnBias	31.164	22.700	8.464
100	HDR_L1_D36_UnBias	31.233	22.819	8.414
100	HDR_L1_D37_UnBias	30.491	22.229	8.262
100	HDR_L1_D38_UnBias	32.282	23.790	8.492
100	HDR_L1_D39_UnBias	31.240	22.769	8.471
100	HDR_L2_D33_UnBias	29.135	21.048	8.087
100	HDR_L2_D34_UnBias	30.005	21.710	8.295
100	HDR_L2_D35_UnBias	29.899	21.814	8.085
100	HDR_L2_D36_UnBias	30.217	22.307	7.910
100	HDR_L2_D37_UnBias	30.252	22.038	8.214
100	HDR_L2_D38_UnBias	30.986	22.813	8.173
100	HDR_L2_D39_UnBias	31.174	23.239	7.935
100	HDR_L3_D32_UnBias	34.149	25.359	8.790
100	HDR_L3_D33_UnBias	26.469	19.114	7.355
100	HDR_L3_D34_UnBias	32.632	24.172	8.460
100	HDR_L3_D35_UnBias	32.972	24.442	8.530
100	HDR_L3_D36_UnBias	30.030	22.107	7.923
100	HDR_L3_D37_UnBias	33.743	25.117	8.626
100	HDR_L3_D38_UnBias	34.282	25.450	8.832
100	HDR_L3_D39_UnBias	32.929	24.358	8.571
	Max	34.520	29.514	10.445
	Average	31.503	24.380	7.123
	Min	26.469	19.114	2.495
	Std Dev	1.743	2.259	1.877



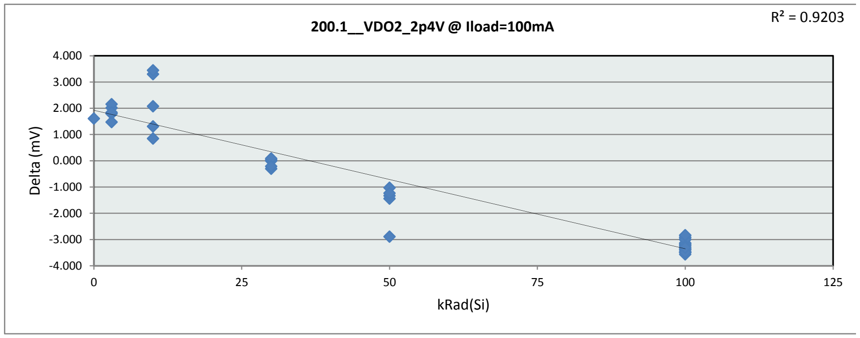
	200.0__VDO1_2p4V @					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	50	mV				
Min Limit	1	mV				
kRad(Si)	0	3	10	30	50	100
LL	1.000	1.000	1.000	1.000	1.000	1.000
Min	28.376	26.229	21.125	23.716	23.066	19.114
Average	28.376	27.807	25.538	24.624	24.627	23.044
Max	28.376	29.514	28.412	25.904	26.074	25.450
UL	50.000	50.000	50.000	50.000	50.000	50.000



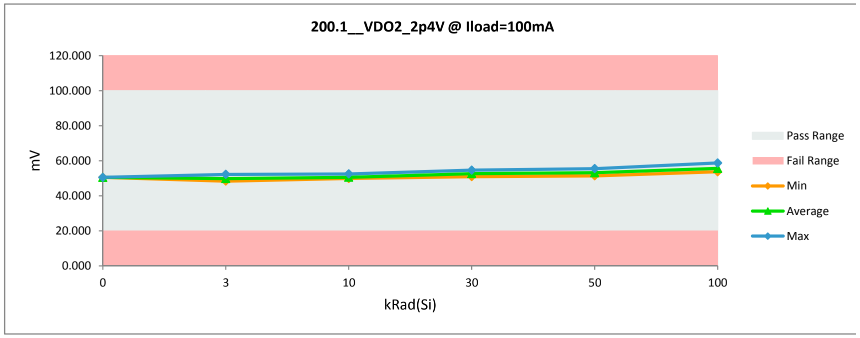
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.1__VDO2_2p4V @ Iload=100mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		100	100	
Min Limit		20	20	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	52.097	50.494	1.603
3	HDR_L1_D26_UnBias	51.171	49.384	1.787
3	HDR_L1_D27_UnBias	50.361	48.345	2.016
3	HDR_L2_D26_UnBias	51.782	49.626	2.156
3	HDR_L2_D27_UnBias	51.062	49.590	1.472
3	HDR_L3_D26_UnBias	54.015	52.178	1.837
10	HDR_L1_D28_UnBias	53.229	49.929	3.300
10	HDR_L1_D29_UnBias	51.633	50.324	1.309
10	HDR_L2_D28_UnBias	50.700	49.854	0.846
10	HDR_L3_D27_UnBias	53.607	50.165	3.442
10	HDR_L3_D28_UnBias	54.531	52.458	2.073
30	HDR_L1_D30_UnBias	50.921	50.929	-0.008
30	HDR_L2_D29_nUBias	52.370	52.335	0.035
30	HDR_L2_D30_UnBias	52.145	52.452	-0.307
30	HDR_L3_D29_UnBias	52.950	52.865	0.085
30	HDR_L3_D30_UnBias	54.408	54.621	-0.213
50	HDR_L1_D31_UnBias	49.930	51.375	-1.445
50	HDR_L1_D32_UnBias	49.930	52.825	-2.895
50	HDR_L2_D31_UnBias	52.650	53.677	-1.027
50	HDR_L2_D32_UnBias	50.968	52.301	-1.333
50	HDR_L3_D31_UnBias	54.262	55.501	-1.239
100	HDR_L1_D33_UnBias	50.260	53.725	-3.465
100	HDR_L1_D34_UnBias	50.735	54.301	-3.566
100	HDR_L1_D35_UnBias	51.485	54.703	-3.218
100	HDR_L1_D36_UnBias	51.074	54.400	-3.326
100	HDR_L1_D37_UnBias	52.100	55.298	-3.198
100	HDR_L1_D38_UnBias	50.527	53.920	-3.393
100	HDR_L1_D39_UnBias	51.266	54.627	-3.361
100	HDR_L2_D33_UnBias	53.118	55.970	-2.852
100	HDR_L2_D34_UnBias	52.907	55.844	-2.937
100	HDR_L2_D35_UnBias	52.621	55.773	-3.152
100	HDR_L2_D36_UnBias	52.881	55.797	-2.916
100	HDR_L2_D37_UnBias	52.564	55.699	-3.135
100	HDR_L2_D38_UnBias	52.667	55.661	-2.994
100	HDR_L2_D39_UnBias	52.266	55.272	-3.006
100	HDR_L3_D32_UnBias	52.555	56.045	-3.490
100	HDR_L3_D33_UnBias	55.892	58.728	-2.836
100	HDR_L3_D34_UnBias	52.996	56.496	-3.500
100	HDR_L3_D35_UnBias	53.015	56.493	-3.478
100	HDR_L3_D36_UnBias	53.606	56.866	-3.260
100	HDR_L3_D37_UnBias	52.875	56.274	-3.399
100	HDR_L3_D38_UnBias	52.284	55.775	-3.491
100	HDR_L3_D39_UnBias	53.084	56.397	-3.313
	Max	55.892	58.728	3.442
	Average	52.267	53.611	-1.344
	Min	49.930	48.345	-3.566
	Std Dev	1.340	2.583	2.283



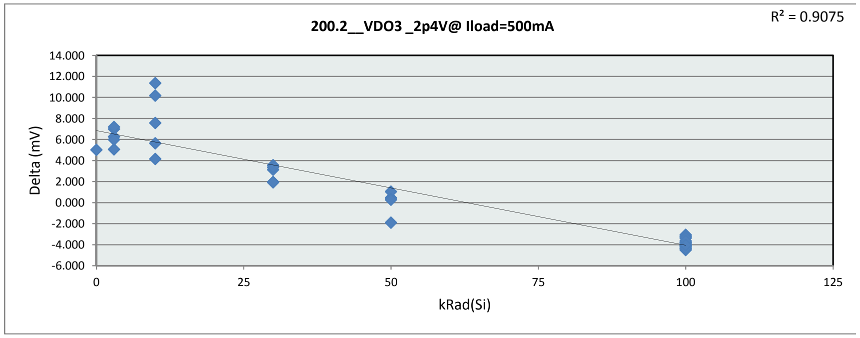
	200.1__VDO2_2p4V @					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	100	mV				
Min Limit	20	mV				
kRad(Si)	0	3	10	30	50	100
LL	20.000	20.000	20.000	20.000	20.000	20.000
Min	50.494	48.345	49.854	50.929	51.375	53.725
Average	50.494	49.825	50.546	52.640	53.136	55.639
Max	50.494	52.178	52.458	54.621	55.501	58.728
UL	100.000	100.000	100.000	100.000	100.000	100.000



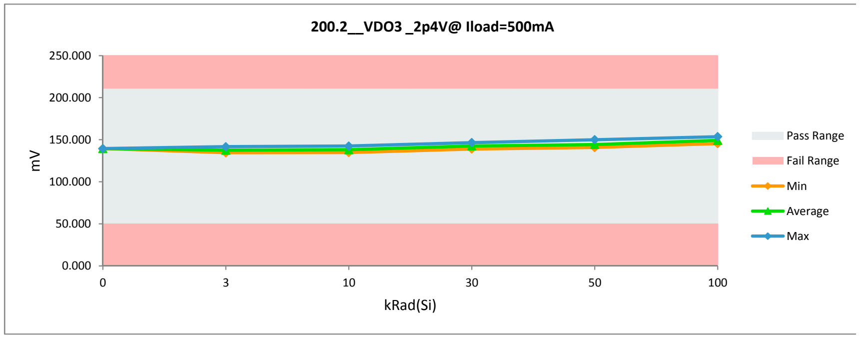
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.2__VDO3 _2p4V@ Iload=500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	210	210	
	Min Limit	50	50	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	144.443	139.427	5.016
3	HDR_L1_D26_UnBias	142.729	136.462	6.267
3	HDR_L1_D27_UnBias	141.543	134.543	7.000
3	HDR_L2_D26_UnBias	144.220	137.032	7.188
3	HDR_L2_D27_UnBias	142.937	137.880	5.057
3	HDR_L3_D26_UnBias	147.731	141.740	5.991
10	HDR_L1_D28_UnBias	146.162	134.805	11.357
10	HDR_L1_D29_UnBias	143.774	138.134	5.640
10	HDR_L2_D28_UnBias	142.417	138.272	4.145
10	HDR_L3_D27_UnBias	147.135	136.967	10.168
10	HDR_L3_D28_UnBias	150.053	142.474	7.579
30	HDR_L1_D30_UnBias	142.553	139.004	3.549
30	HDR_L2_D29_nUBias	144.713	141.579	3.134
30	HDR_L2_D30_UnBias	144.407	142.450	1.957
30	HDR_L3_D29_UnBias	146.532	143.168	3.364
30	HDR_L3_D30_UnBias	148.559	146.633	1.926
50	HDR_L1_D31_UnBias	141.288	140.830	0.458
50	HDR_L1_D32_UnBias	141.288	143.188	-1.900
50	HDR_L2_D31_UnBias	145.960	144.918	1.042
50	HDR_L2_D32_UnBias	142.777	142.486	0.291
50	HDR_L3_D31_UnBias	150.265	149.979	0.286
100	HDR_L1_D33_UnBias	141.312	145.444	-4.132
100	HDR_L1_D34_UnBias	142.577	146.950	-4.373
100	HDR_L1_D35_UnBias	144.503	148.251	-3.748
100	HDR_L1_D36_UnBias	143.389	147.368	-3.979
100	HDR_L1_D37_UnBias	144.693	148.505	-3.812
100	HDR_L1_D38_UnBias	141.931	146.003	-4.072
100	HDR_L1_D39_UnBias	142.922	147.026	-4.104
100	HDR_L2_D33_UnBias	146.133	149.313	-3.180
100	HDR_L2_D34_UnBias	145.778	148.848	-3.070
100	HDR_L2_D35_UnBias	145.025	148.924	-3.899
100	HDR_L2_D36_UnBias	146.756	150.047	-3.291
100	HDR_L2_D37_UnBias	145.096	148.906	-3.810
100	HDR_L2_D38_UnBias	146.135	149.338	-3.203
100	HDR_L2_D39_UnBias	146.062	149.447	-3.385
100	HDR_L3_D32_UnBias	145.849	150.128	-4.279
100	HDR_L3_D33_UnBias	149.947	153.584	-3.637
100	HDR_L3_D34_UnBias	146.589	151.005	-4.416
100	HDR_L3_D35_UnBias	146.396	150.907	-4.511
100	HDR_L3_D36_UnBias	146.938	151.128	-4.190
100	HDR_L3_D37_UnBias	146.754	150.883	-4.129
100	HDR_L3_D38_UnBias	145.178	149.535	-4.357
100	HDR_L3_D39_UnBias	146.775	150.819	-4.044
	Max	150.265	153.584	11.357
	Average	145.075	144.984	0.091
	Min	141.288	134.543	-4.511
	Std Dev	2.365	5.302	4.752



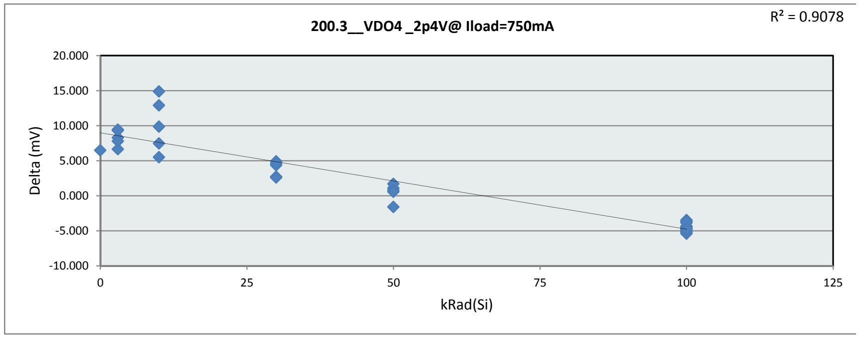
	200.2__VDO3 _2p4V@					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	210	mV				
Min Limit	50	mV				
kRad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	139.427	134.543	134.805	139.004	140.830	145.444
Average	139.427	137.531	138.130	142.567	144.280	149.198
Max	139.427	141.740	142.474	146.633	149.979	153.584
UL	210.000	210.000	210.000	210.000	210.000	210.000



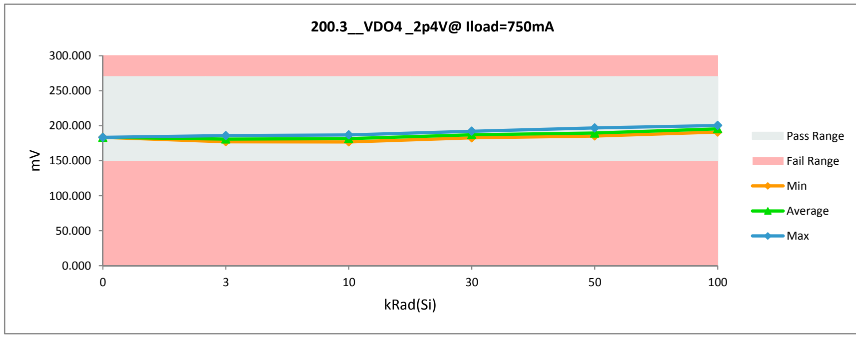
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.3__VDO4 _2p4V@ Iload=750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	270	270	
	Min Limit	150	150	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	189.804	183.319	6.485
3	HDR_L1_D26_UnBias	187.752	179.477	8.275
3	HDR_L1_D27_UnBias	186.411	177.096	9.315
3	HDR_L2_D26_UnBias	189.879	180.467	9.412
3	HDR_L2_D27_UnBias	188.137	181.490	6.647
3	HDR_L3_D26_UnBias	193.659	185.881	7.778
10	HDR_L1_D28_UnBias	191.741	176.866	14.875
10	HDR_L1_D29_UnBias	189.068	181.611	7.457
10	HDR_L2_D28_UnBias	187.544	182.051	5.493
10	HDR_L3_D27_UnBias	192.974	180.081	12.893
10	HDR_L3_D28_UnBias	196.728	186.876	9.852
30	HDR_L1_D30_UnBias	187.597	182.684	4.913
30	HDR_L2_D29_nUBias	189.994	185.634	4.360
30	HDR_L2_D30_UnBias	189.688	186.979	2.709
30	HDR_L3_D29_UnBias	192.405	187.814	4.591
30	HDR_L3_D30_UnBias	194.698	192.104	2.594
50	HDR_L1_D31_UnBias	186.339	185.240	1.099
50	HDR_L1_D32_UnBias	186.339	187.934	-1.595
50	HDR_L2_D31_UnBias	191.899	190.213	1.686
50	HDR_L2_D32_UnBias	187.838	187.046	0.792
50	HDR_L3_D31_UnBias	197.345	196.766	0.579
100	HDR_L1_D33_UnBias	186.057	190.843	-4.786
100	HDR_L1_D34_UnBias	187.794	192.834	-5.040
100	HDR_L1_D35_UnBias	190.445	194.778	-4.333
100	HDR_L1_D36_UnBias	188.850	193.478	-4.628
100	HDR_L1_D37_UnBias	190.240	194.656	-4.416
100	HDR_L1_D38_UnBias	186.925	191.598	-4.673
100	HDR_L1_D39_UnBias	187.932	192.740	-4.808
100	HDR_L2_D33_UnBias	191.721	195.444	-3.723
100	HDR_L2_D34_UnBias	191.397	194.869	-3.472
100	HDR_L2_D35_UnBias	190.355	194.984	-4.629
100	HDR_L2_D36_UnBias	193.060	196.896	-3.836
100	HDR_L2_D37_UnBias	190.500	194.967	-4.467
100	HDR_L2_D38_UnBias	192.209	195.826	-3.617
100	HDR_L2_D39_UnBias	192.391	196.255	-3.864
100	HDR_L3_D32_UnBias	191.637	196.672	-5.035
100	HDR_L3_D33_UnBias	195.823	200.323	-4.500
100	HDR_L3_D34_UnBias	192.455	197.752	-5.297
100	HDR_L3_D35_UnBias	192.172	197.587	-5.415
100	HDR_L3_D36_UnBias	192.609	197.690	-5.081
100	HDR_L3_D37_UnBias	192.774	197.666	-4.892
100	HDR_L3_D38_UnBias	190.692	195.877	-5.185
100	HDR_L3_D39_UnBias	192.695	197.524	-4.829
	Max	197.345	200.323	14.875
	Average	190.664	190.207	0.458
	Min	186.057	176.866	-5.415
	Std Dev	2.817	6.661	5.983



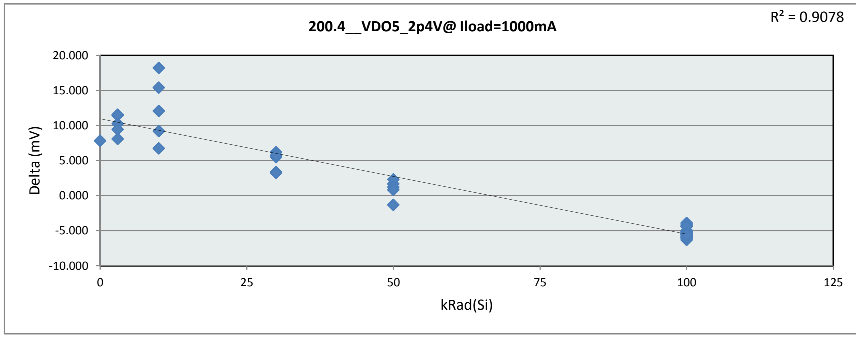
	200.3__VDO4 _2p4V@					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	270	mV				
Min Limit	150	mV				
kRad(Si)	0	3	10	30	50	100
LL	150.000	150.000	150.000	150.000	150.000	150.000
Min	183.319	177.096	176.866	182.684	185.240	190.843
Average	183.319	180.882	181.497	187.043	189.440	195.512
Max	183.319	185.881	186.876	192.104	196.766	200.323
UL	270.000	270.000	270.000	270.000	270.000	270.000



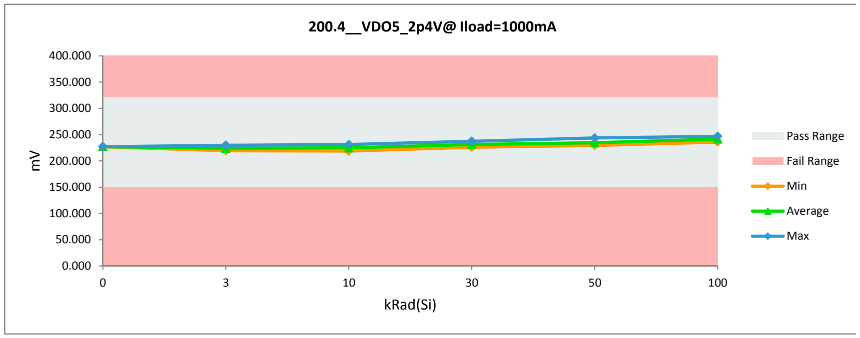
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.4__VDO5_2p4V@ Iload=1000mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	320	320	
	Min Limit	150	150	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	234.947	227.115	7.832
3	HDR_L1_D26_UnBias	232.570	222.332	10.238
3	HDR_L1_D27_UnBias	230.959	219.518	11.441
3	HDR_L2_D26_UnBias	235.416	223.874	11.542
3	HDR_L2_D27_UnBias	233.064	224.984	8.080
3	HDR_L3_D26_UnBias	239.333	229.879	9.454
10	HDR_L1_D28_UnBias	237.005	218.787	18.218
10	HDR_L1_D29_UnBias	234.065	224.867	9.198
10	HDR_L2_D28_UnBias	232.425	225.684	6.741
10	HDR_L3_D27_UnBias	238.593	223.187	15.406
10	HDR_L3_D28_UnBias	243.197	231.124	12.073
30	HDR_L1_D30_UnBias	232.290	226.112	6.178
30	HDR_L2_D29_nUBias	234.955	229.473	5.482
30	HDR_L2_D30_UnBias	234.711	231.366	3.345
30	HDR_L3_D29_UnBias	238.031	232.287	5.744
30	HDR_L3_D30_UnBias	240.593	237.358	3.235
50	HDR_L1_D31_UnBias	231.102	229.440	1.662
50	HDR_L1_D32_UnBias	231.102	232.440	-1.338
50	HDR_L2_D31_UnBias	237.748	235.444	2.304
50	HDR_L2_D32_UnBias	232.636	231.421	1.215
50	HDR_L3_D31_UnBias	244.429	243.603	0.826
100	HDR_L1_D33_UnBias	230.443	235.889	-5.446
100	HDR_L1_D34_UnBias	232.732	238.514	-5.782
100	HDR_L1_D35_UnBias	236.185	241.131	-4.946
100	HDR_L1_D36_UnBias	234.133	239.450	-5.317
100	HDR_L1_D37_UnBias	235.465	240.570	-5.105
100	HDR_L1_D38_UnBias	231.629	236.963	-5.334
100	HDR_L1_D39_UnBias	232.617	238.147	-5.530
100	HDR_L2_D33_UnBias	237.077	241.383	-4.306
100	HDR_L2_D34_UnBias	236.743	240.658	-3.915
100	HDR_L2_D35_UnBias	235.446	240.849	-5.403
100	HDR_L2_D36_UnBias	239.332	243.753	-4.421
100	HDR_L2_D37_UnBias	235.712	240.890	-5.178
100	HDR_L2_D38_UnBias	238.179	242.247	-4.068
100	HDR_L2_D39_UnBias	238.635	243.009	-4.374
100	HDR_L3_D32_UnBias	237.282	243.080	-5.798
100	HDR_L3_D33_UnBias	241.457	246.833	-5.376
100	HDR_L3_D34_UnBias	238.144	244.297	-6.153
100	HDR_L3_D35_UnBias	237.774	244.102	-6.328
100	HDR_L3_D36_UnBias	238.055	244.011	-5.956
100	HDR_L3_D37_UnBias	238.722	244.349	-5.627
100	HDR_L3_D38_UnBias	235.993	241.993	-6.000
100	HDR_L3_D39_UnBias	238.498	244.105	-5.607
	Max	244.429	246.833	18.218
	Average	236.033	235.268	0.765
	Min	230.443	218.787	-6.328
	Std Dev	3.336	8.021	7.173



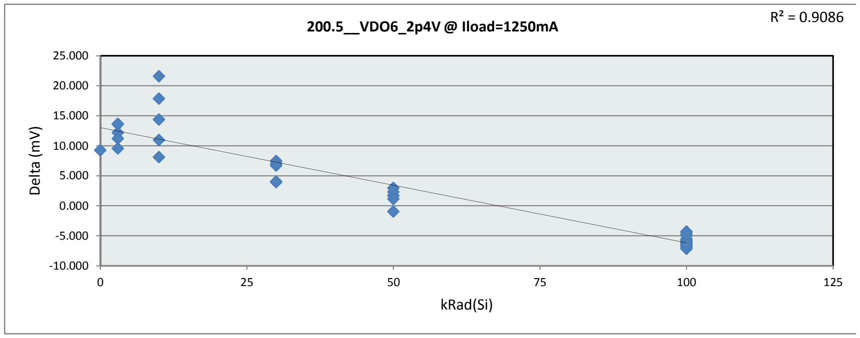
	200.4__VDO5_2p4V@ I					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	320	mV				
Min Limit	150	mV				
kRad(Si)	0	3	10	30	50	100
LL	150.000	150.000	150.000	150.000	150.000	150.000
Min	227.115	219.518	218.787	226.112	229.440	235.889
Average	227.115	224.117	224.730	231.319	234.470	241.647
Max	227.115	229.879	231.124	237.358	243.603	246.833
UL	320.000	320.000	320.000	320.000	320.000	320.000



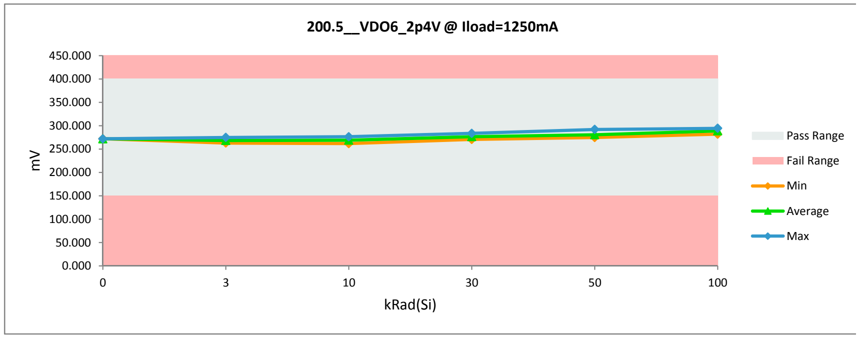
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.5__VDO6_2p4V @ Iload=1250mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		400	400	
Min Limit		150	150	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	281.185	271.932	9.253
3	HDR_L1_D26_UnBias	278.389	266.205	12.184
3	HDR_L1_D27_UnBias	276.479	262.901	13.578
3	HDR_L2_D26_UnBias	282.060	268.421	13.639
3	HDR_L2_D27_UnBias	279.022	269.473	9.549
3	HDR_L3_D26_UnBias	286.097	274.896	11.201
10	HDR_L1_D28_UnBias	283.299	261.707	21.592
10	HDR_L1_D29_UnBias	280.052	269.092	10.960
10	HDR_L2_D28_UnBias	278.379	270.282	8.097
10	HDR_L3_D27_UnBias	285.310	267.456	17.854
10	HDR_L3_D28_UnBias	290.772	276.404	14.368
30	HDR_L1_D30_UnBias	277.946	270.470	7.476
30	HDR_L2_D29_nUBias	280.928	274.239	6.689
30	HDR_L2_D30_UnBias	280.784	276.750	4.034
30	HDR_L3_D29_UnBias	284.791	277.782	7.009
30	HDR_L3_D30_UnBias	287.560	283.634	3.926
50	HDR_L1_D31_UnBias	276.890	274.598	2.292
50	HDR_L1_D32_UnBias	276.890	277.873	-0.983
50	HDR_L2_D31_UnBias	284.743	281.769	2.974
50	HDR_L2_D32_UnBias	278.498	276.796	1.702
50	HDR_L3_D31_UnBias	293.005	291.887	1.118
100	HDR_L1_D33_UnBias	275.731	281.818	-6.087
100	HDR_L1_D34_UnBias	278.712	285.171	-6.459
100	HDR_L1_D35_UnBias	283.022	288.545	-5.523
100	HDR_L1_D36_UnBias	280.512	286.453	-5.941
100	HDR_L1_D37_UnBias	281.715	287.423	-5.708
100	HDR_L1_D38_UnBias	277.331	283.302	-5.971
100	HDR_L1_D39_UnBias	278.256	284.488	-6.232
100	HDR_L2_D33_UnBias	283.461	288.313	-4.852
100	HDR_L2_D34_UnBias	283.103	287.417	-4.314
100	HDR_L2_D35_UnBias	281.606	287.727	-6.121
100	HDR_L2_D36_UnBias	286.862	291.836	-4.974
100	HDR_L2_D37_UnBias	281.990	287.812	-5.822
100	HDR_L2_D38_UnBias	285.339	289.821	-4.482
100	HDR_L2_D39_UnBias	286.122	290.966	-4.844
100	HDR_L3_D32_UnBias	284.037	290.609	-6.572
100	HDR_L3_D33_UnBias	288.128	294.378	-6.250
100	HDR_L3_D34_UnBias	284.950	291.935	-6.985
100	HDR_L3_D35_UnBias	284.524	291.711	-7.187
100	HDR_L3_D36_UnBias	284.560	291.370	-6.810
100	HDR_L3_D37_UnBias	285.833	292.155	-6.322
100	HDR_L3_D38_UnBias	282.378	289.150	-6.772
100	HDR_L3_D39_UnBias	285.420	291.806	-6.386
	Max	293.005	294.378	21.592
	Average	282.481	281.367	1.114
	Min	275.731	261.707	-7.187
	Std Dev	3.939	9.423	8.359



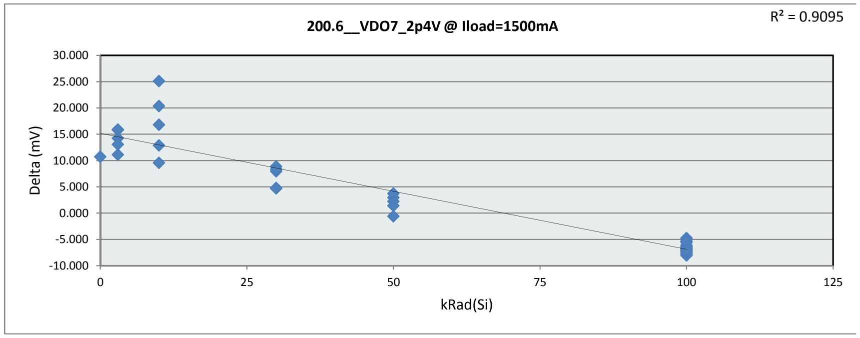
	200.5__VDO6_2p4V @					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	400	mV				
Min Limit	150	mV				
kRad(Si)	0	3	10	30	50	100
LL	150.000	150.000	150.000	150.000	150.000	150.000
Min	271.932	262.901	261.707	270.470	274.598	281.818
Average	271.932	268.379	268.988	276.575	280.585	288.828
Max	271.932	274.896	276.404	283.634	291.887	294.378
UL	400.000	400.000	400.000	400.000	400.000	400.000



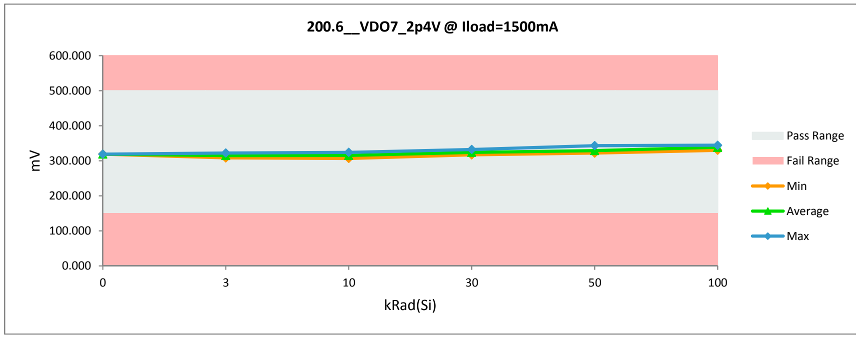
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
		200.6__VDO7_2p4V @ Iload=1500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	500	500	
	Min Limit	150	150	
0	CORR_L2_D45	329.684	318.955	10.729
3	HDR_L1_D26_UnBias	326.451	312.193	14.258
3	HDR_L1_D27_UnBias	324.128	308.302	15.826
3	HDR_L2_D26_UnBias	331.094	315.208	15.886
3	HDR_L2_D27_UnBias	327.167	316.062	11.105
3	HDR_L3_D26_UnBias	335.148	322.066	13.082
10	HDR_L1_D28_UnBias	331.775	306.650	25.125
10	HDR_L1_D29_UnBias	328.236	315.351	12.885
10	HDR_L2_D28_UnBias	326.523	316.965	9.558
10	HDR_L3_D27_UnBias	334.343	313.977	20.366
10	HDR_L3_D28_UnBias	340.706	323.882	16.824
30	HDR_L1_D30_UnBias	325.731	316.850	8.881
30	HDR_L2_D29_nUBias	329.053	321.085	7.968
30	HDR_L2_D30_UnBias	329.063	324.277	4.786
30	HDR_L3_D29_UnBias	333.834	325.476	8.358
30	HDR_L3_D30_UnBias	336.830	332.137	4.693
50	HDR_L1_D31_UnBias	324.818	321.851	2.967
50	HDR_L1_D32_UnBias	324.818	325.424	-0.606
50	HDR_L2_D31_UnBias	334.144	330.418	3.726
50	HDR_L2_D32_UnBias	326.562	324.327	2.235
50	HDR_L3_D31_UnBias	344.454	343.054	1.400
100	HDR_L1_D33_UnBias	323.078	329.811	-6.733
100	HDR_L1_D34_UnBias	326.848	334.023	-7.175
100	HDR_L1_D35_UnBias	332.172	338.265	-6.093
100	HDR_L1_D36_UnBias	329.166	335.763	-6.597
100	HDR_L1_D37_UnBias	330.155	336.506	-6.351
100	HDR_L1_D38_UnBias	325.240	331.821	-6.581
100	HDR_L1_D39_UnBias	326.052	332.969	-6.917
100	HDR_L2_D33_UnBias	332.121	337.542	-5.421
100	HDR_L2_D34_UnBias	331.680	336.420	-4.740
100	HDR_L2_D35_UnBias	330.005	336.898	-6.893
100	HDR_L2_D36_UnBias	336.861	342.413	-5.552
100	HDR_L2_D37_UnBias	330.509	337.050	-6.541
100	HDR_L2_D38_UnBias	334.882	339.821	-4.939
100	HDR_L2_D39_UnBias	336.040	341.362	-5.322
100	HDR_L3_D32_UnBias	333.114	340.447	-7.333
100	HDR_L3_D33_UnBias	337.085	344.208	-7.123
100	HDR_L3_D34_UnBias	334.035	341.856	-7.821
100	HDR_L3_D35_UnBias	333.586	341.625	-8.039
100	HDR_L3_D36_UnBias	333.315	340.982	-7.667
100	HDR_L3_D37_UnBias	335.295	342.318	-7.023
100	HDR_L3_D38_UnBias	330.987	338.523	-7.536
100	HDR_L3_D39_UnBias	334.679	341.839	-7.160
	Max	344.454	344.208	25.125
	Average	331.197	329.697	1.500
	Min	323.078	306.650	-8.039
	Std Dev	4.664	10.938	9.604



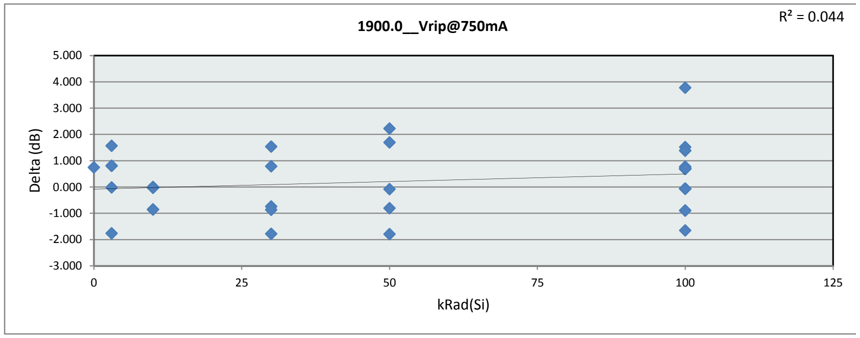
kRad(Si)	0	3	10	30	50	100
	200.6__VDO7_2p4V @					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	500	mV				
Min Limit	150	mV				
LL	150.000	150.000	150.000	150.000	150.000	150.000
Min	318.955	308.302	306.650	316.850	321.851	329.811
Average	318.955	314.766	315.365	323.965	329.015	338.294
Max	318.955	322.066	323.882	332.137	343.054	344.208
UL	500.000	500.000	500.000	500.000	500.000	500.000



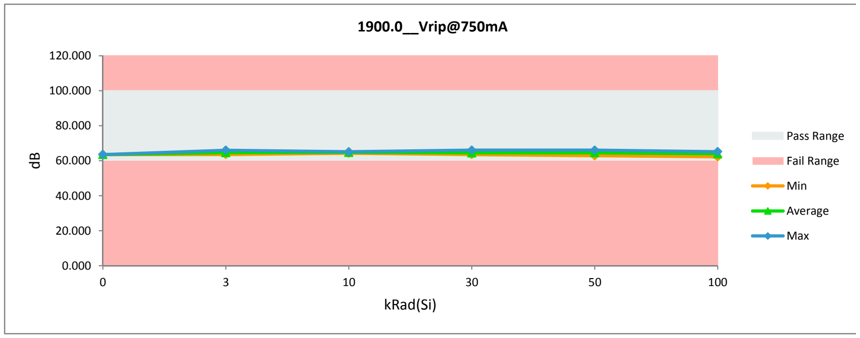
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		1900.0__Vrip@750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	dB	dB	
	Max Limit	100	100	
	Min Limit	60	60	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	64.244	63.500	0.744
3	HDR_L1_D26_UnBias	65.065	64.258	0.807
3	HDR_L1_D27_UnBias	65.050	64.243	0.807
3	HDR_L2_D26_UnBias	65.061	65.081	-0.020
3	HDR_L2_D27_UnBias	64.224	65.986	-1.762
3	HDR_L3_D26_UnBias	65.086	63.521	1.565
10	HDR_L1_D28_UnBias	64.276	65.134	-0.858
10	HDR_L1_D29_UnBias	64.231	65.090	-0.859
10	HDR_L2_D28_UnBias	64.219	64.247	-0.028
10	HDR_L3_D27_UnBias	65.080	65.081	-0.001
10	HDR_L3_D28_UnBias	64.248	64.278	-0.030
30	HDR_L1_D30_UnBias	65.051	63.516	1.535
30	HDR_L2_D29_nUBias	62.800	63.539	-0.739
30	HDR_L2_D30_UnBias	65.069	64.285	0.784
30	HDR_L3_D29_UnBias	64.229	65.100	-0.871
30	HDR_L3_D30_UnBias	64.264	66.048	-1.784
50	HDR_L1_D31_UnBias	65.035	62.814	2.221
50	HDR_L1_D32_UnBias	65.035	65.118	-0.083
50	HDR_L2_D31_UnBias	64.248	66.044	-1.796
50	HDR_L2_D32_UnBias	65.970	64.279	1.691
50	HDR_L3_D31_UnBias	63.482	64.290	-0.808
100	HDR_L1_D33_UnBias	64.233	63.547	0.686
100	HDR_L1_D34_UnBias	64.224	65.122	-0.898
100	HDR_L1_D35_UnBias	65.075	64.313	0.762
100	HDR_L1_D36_UnBias	63.481	63.548	-0.067
100	HDR_L1_D37_UnBias	64.248	65.145	-0.897
100	HDR_L1_D38_UnBias	65.971	62.200	3.771
100	HDR_L1_D39_UnBias	64.242	63.554	0.688
100	HDR_L2_D33_UnBias	64.264	63.575	0.689
100	HDR_L2_D34_UnBias	65.083	63.566	1.517
100	HDR_L2_D35_UnBias	63.499	65.151	-1.652
100	HDR_L2_D36_UnBias	65.081	64.316	0.765
100	HDR_L2_D37_UnBias	64.250	62.868	1.382
100	HDR_L2_D38_UnBias	64.244	63.554	0.690
100	HDR_L2_D39_UnBias	65.071	65.136	-0.065
100	HDR_L3_D32_UnBias	64.218	63.530	0.688
100	HDR_L3_D33_UnBias	65.119	65.183	-0.064
100	HDR_L3_D34_UnBias	65.061	64.298	0.763
100	HDR_L3_D35_UnBias	64.228	62.845	1.383
100	HDR_L3_D36_UnBias	64.257	64.322	-0.065
100	HDR_L3_D37_UnBias	63.469	63.534	-0.065
100	HDR_L3_D38_UnBias	64.216	63.528	0.688
100	HDR_L3_D39_UnBias	64.229	63.540	0.689
	Max	65.971	66.048	3.771
	Average	64.505	64.229	0.277
	Min	62.800	62.200	-1.796
	Std Dev	0.648	0.914	1.139



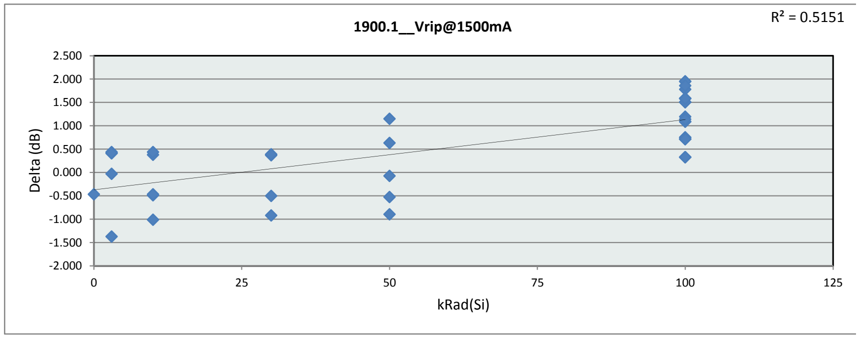
	1900.0__Vrip@750mA					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	100	dB				
Min Limit	60	dB				
kRad(Si)	0	3	10	30	50	100
LL	60.000	60.000	60.000	60.000	60.000	60.000
Min	63.500	63.521	64.247	63.516	62.814	62.200
Average	63.500	64.618	64.766	64.498	64.509	63.926
Max	63.500	65.986	65.134	66.048	66.044	65.183
UL	100.000	100.000	100.000	100.000	100.000	100.000



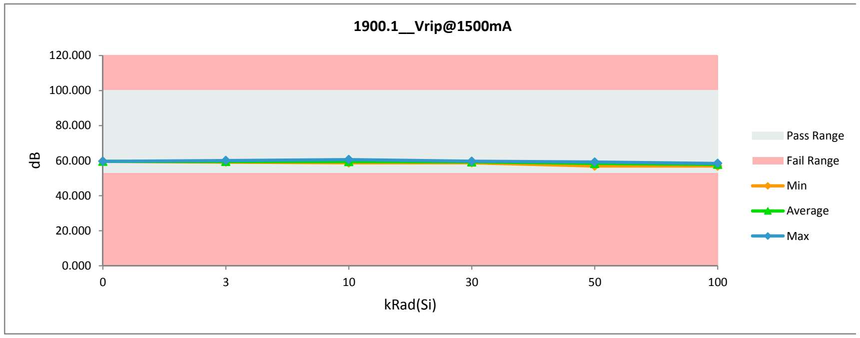
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		1900.1__Vrip@1500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	dB	dB	
	Max Limit	100	100	
	Min Limit	53	53	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	59.111	59.580	-0.469
3	HDR_L1_D26_UnBias	58.680	60.052	-1.372
3	HDR_L1_D27_UnBias	60.004	59.568	0.436
3	HDR_L2_D26_UnBias	59.545	59.137	0.408
3	HDR_L2_D27_UnBias	59.537	59.123	0.414
3	HDR_L3_D26_UnBias	59.572	59.601	-0.029
10	HDR_L1_D28_UnBias	59.592	60.604	-1.012
10	HDR_L1_D29_UnBias	59.099	59.589	-0.490
10	HDR_L2_D28_UnBias	59.084	58.705	0.379
10	HDR_L3_D27_UnBias	59.567	59.132	0.435
10	HDR_L3_D28_UnBias	58.691	59.161	-0.470
30	HDR_L1_D30_UnBias	59.536	59.154	0.382
30	HDR_L2_D29_nUBias	59.122	58.754	0.368
30	HDR_L2_D30_UnBias	59.556	59.167	0.389
30	HDR_L3_D29_UnBias	59.097	59.601	-0.504
30	HDR_L3_D30_UnBias	58.709	59.630	-0.921
50	HDR_L1_D31_UnBias	58.646	58.719	-0.073
50	HDR_L1_D32_UnBias	58.646	59.173	-0.527
50	HDR_L2_D31_UnBias	58.290	59.185	-0.895
50	HDR_L2_D32_UnBias	59.093	57.944	1.149
50	HDR_L3_D31_UnBias	57.514	56.884	0.630
100	HDR_L1_D33_UnBias	59.547	58.355	1.192
100	HDR_L1_D34_UnBias	59.537	57.589	1.948
100	HDR_L1_D35_UnBias	58.692	58.367	0.325
100	HDR_L1_D36_UnBias	58.680	57.968	0.712
100	HDR_L1_D37_UnBias	59.563	57.613	1.950
100	HDR_L1_D38_UnBias	59.092	57.587	1.505
100	HDR_L1_D39_UnBias	59.108	58.361	0.747
100	HDR_L2_D33_UnBias	59.134	58.384	0.750
100	HDR_L2_D34_UnBias	58.703	58.378	0.325
100	HDR_L2_D35_UnBias	59.125	57.619	1.506
100	HDR_L2_D36_UnBias	58.697	57.611	1.086
100	HDR_L2_D37_UnBias	59.118	57.613	1.505
100	HDR_L2_D38_UnBias	58.686	56.907	1.779
100	HDR_L2_D39_UnBias	58.688	57.602	1.086
100	HDR_L3_D32_UnBias	59.081	57.222	1.859
100	HDR_L3_D33_UnBias	59.609	58.023	1.586
100	HDR_L3_D34_UnBias	58.678	58.350	0.328
100	HDR_L3_D35_UnBias	58.672	57.959	0.713
100	HDR_L3_D36_UnBias	59.572	57.987	1.585
100	HDR_L3_D37_UnBias	58.667	57.953	0.714
100	HDR_L3_D38_UnBias	59.528	57.947	1.581
100	HDR_L3_D39_UnBias	59.093	57.956	1.137
	Max	60.004	60.604	1.950
	Average	59.069	58.507	0.562
	Min	57.514	56.884	-1.372
	Std Dev	0.467	0.878	0.870



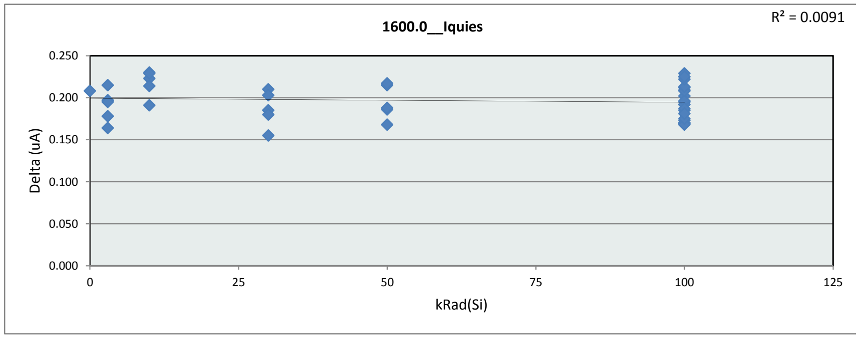
	1900.1__Vrip@1500mA					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	100	dB				
Min Limit	53	dB				
kRad(Si)	0	3	10	30	50	100
LL	53.000	53.000	53.000	53.000	53.000	53.000
Min	59.580	59.123	58.705	58.754	56.884	56.907
Average	59.580	59.496	59.438	59.261	58.381	57.880
Max	59.580	60.052	60.604	59.630	59.185	58.384
UL	100.000	100.000	100.000	100.000	100.000	100.000



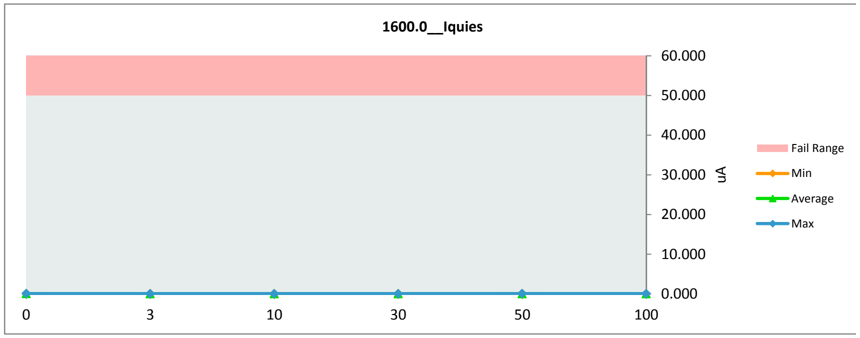
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		1600.0__Iquies		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		uA	uA	
Max Limit		50	50	
Min Limit				
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	0.269	0.061	0.208
3	HDR_L1_D26_UnBias	0.231	0.034	0.197
3	HDR_L1_D27_UnBias	0.202	0.024	0.178
3	HDR_L2_D26_UnBias	0.237	0.022	0.215
3	HDR_L2_D27_UnBias	0.235	0.040	0.195
3	HDR_L3_D26_UnBias	0.197	0.033	0.164
10	HDR_L1_D28_UnBias	0.235	0.012	0.223
10	HDR_L1_D29_UnBias	0.230	0.016	0.214
10	HDR_L2_D28_UnBias	0.272	0.042	0.230
10	HDR_L3_D27_UnBias	0.203	0.012	0.191
10	HDR_L3_D28_UnBias	0.257	0.028	0.229
30	HDR_L1_D30_UnBias	0.214	0.029	0.185
30	HDR_L2_D29_nUBias	0.248	0.038	0.210
30	HDR_L2_D30_UnBias	0.248	0.045	0.203
30	HDR_L3_D29_UnBias	0.203	0.023	0.180
30	HDR_L3_D30_UnBias	0.198	0.043	0.155
50	HDR_L1_D31_UnBias	0.232	0.046	0.186
50	HDR_L1_D32_UnBias	0.232	0.044	0.188
50	HDR_L2_D31_UnBias	0.265	0.050	0.215
50	HDR_L2_D32_UnBias	0.281	0.064	0.217
50	HDR_L3_D31_UnBias	0.218	0.050	0.168
100	HDR_L1_D33_UnBias	0.218	0.033	0.185
100	HDR_L1_D34_UnBias	0.234	0.042	0.192
100	HDR_L1_D35_UnBias	0.223	0.028	0.195
100	HDR_L1_D36_UnBias	0.258	0.046	0.212
100	HDR_L1_D37_UnBias	0.230	0.028	0.202
100	HDR_L1_D38_UnBias	0.250	0.041	0.209
100	HDR_L1_D39_UnBias	0.229	0.037	0.192
100	HDR_L2_D33_UnBias	0.251	0.026	0.225
100	HDR_L2_D34_UnBias	0.222	0.026	0.196
100	HDR_L2_D35_UnBias	0.247	0.039	0.208
100	HDR_L2_D36_UnBias	0.265	0.036	0.229
100	HDR_L2_D37_UnBias	0.255	0.042	0.213
100	HDR_L2_D38_UnBias	0.264	0.042	0.222
100	HDR_L2_D39_UnBias	0.260	0.035	0.225
100	HDR_L3_D32_UnBias	0.203	0.033	0.170
100	HDR_L3_D33_UnBias	0.195	0.026	0.169
100	HDR_L3_D34_UnBias	0.197	0.027	0.170
100	HDR_L3_D35_UnBias	0.206	0.033	0.173
100	HDR_L3_D36_UnBias	0.202	0.034	0.168
100	HDR_L3_D37_UnBias	0.216	0.029	0.187
100	HDR_L3_D38_UnBias	0.203	0.028	0.175
100	HDR_L3_D39_UnBias	0.214	0.033	0.181
	Max	0.281	0.064	0.230
	Average	0.231	0.035	0.196
	Min	0.195	0.012	0.155
	Std Dev	0.024	0.011	0.021



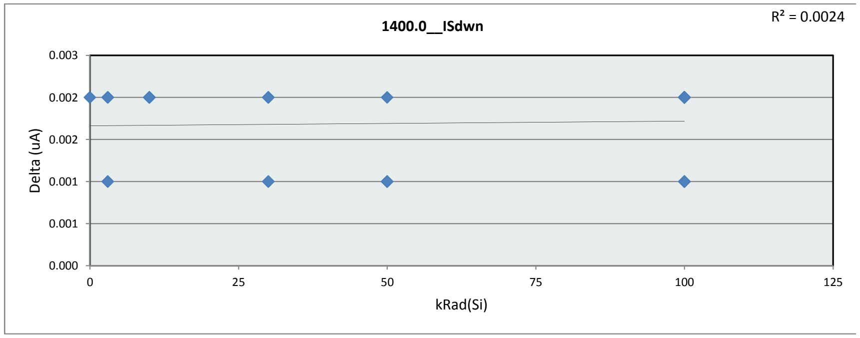
	1600.0__Iquies					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	50	uA				
Min Limit		uA				
kRad(Si)	0	3	10	30	50	100
LL						
Min	0.061	0.022	0.012	0.023	0.044	0.026
Average	0.061	0.031	0.022	0.036	0.051	0.034
Max	0.061	0.040	0.042	0.045	0.064	0.046
UL	50.000	50.000	50.000	50.000	50.000	50.000



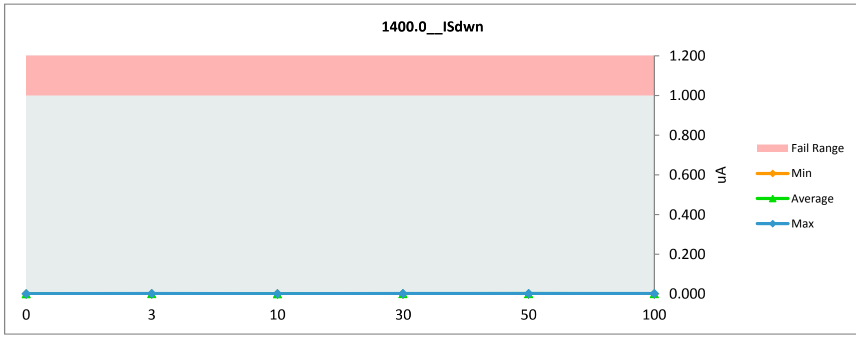
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		1400.0__ISdwn		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	1	1	
	Min Limit			
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	0.003	0.001	0.002
3	HDR_L1_D26_UnBias	0.003	0.002	0.001
3	HDR_L1_D27_UnBias	0.003	0.002	0.001
3	HDR_L2_D26_UnBias	0.003	0.001	0.002
3	HDR_L2_D27_UnBias	0.003	0.001	0.002
3	HDR_L3_D26_UnBias	0.003	0.001	0.002
10	HDR_L1_D28_UnBias	0.003	0.001	0.002
10	HDR_L1_D29_UnBias	0.003	0.001	0.002
10	HDR_L2_D28_UnBias	0.003	0.001	0.002
10	HDR_L3_D27_UnBias	0.003	0.001	0.002
10	HDR_L3_D28_UnBias	0.003	0.001	0.002
30	HDR_L1_D30_UnBias	0.003	0.001	0.002
30	HDR_L2_D29_nUBias	0.003	0.002	0.001
30	HDR_L2_D30_UnBias	0.003	0.001	0.002
30	HDR_L3_D29_UnBias	0.003	0.001	0.002
30	HDR_L3_D30_UnBias	0.003	0.002	0.001
50	HDR_L1_D31_UnBias	0.003	0.002	0.001
50	HDR_L1_D32_UnBias	0.003	0.002	0.001
50	HDR_L2_D31_UnBias	0.003	0.002	0.001
50	HDR_L2_D32_UnBias	0.003	0.001	0.002
50	HDR_L3_D31_UnBias	0.003	0.002	0.001
100	HDR_L1_D33_UnBias	0.003	0.002	0.001
100	HDR_L1_D34_UnBias	0.003	0.001	0.002
100	HDR_L1_D35_UnBias	0.003	0.001	0.002
100	HDR_L1_D36_UnBias	0.003	0.001	0.002
100	HDR_L1_D37_UnBias	0.003	0.001	0.002
100	HDR_L1_D38_UnBias	0.003	0.001	0.002
100	HDR_L1_D39_UnBias	0.003	0.001	0.002
100	HDR_L2_D33_UnBias	0.003	0.001	0.002
100	HDR_L2_D34_UnBias	0.003	0.001	0.002
100	HDR_L2_D35_UnBias	0.003	0.001	0.002
100	HDR_L2_D36_UnBias	0.003	0.001	0.002
100	HDR_L2_D37_UnBias	0.003	0.002	0.001
100	HDR_L2_D38_UnBias	0.003	0.001	0.002
100	HDR_L2_D39_UnBias	0.003	0.002	0.001
100	HDR_L3_D32_UnBias	0.003	0.001	0.002
100	HDR_L3_D33_UnBias	0.003	0.001	0.002
100	HDR_L3_D34_UnBias	0.003	0.001	0.002
100	HDR_L3_D35_UnBias	0.003	0.002	0.001
100	HDR_L3_D36_UnBias	0.003	0.001	0.002
100	HDR_L3_D37_UnBias	0.003	0.002	0.001
100	HDR_L3_D38_UnBias	0.003	0.001	0.002
100	HDR_L3_D39_UnBias	0.003	0.001	0.002
	Max	0.003	0.002	0.002
	Average	0.003	0.001	0.002
	Min	0.003	0.001	0.001
	Std Dev	0.000	0.000	0.000



	1400.0__ISdwn					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1	uA				
Min Limit		uA				
kRad(Si)	0	3	10	30	50	100
LL						
Min	0.001	0.001	0.001	0.001	0.001	0.001
Average	0.001	0.001	0.001	0.001	0.002	0.001
Max	0.001	0.002	0.001	0.002	0.002	0.002
UL	1.000	1.000	1.000	1.000	1.000	1.000

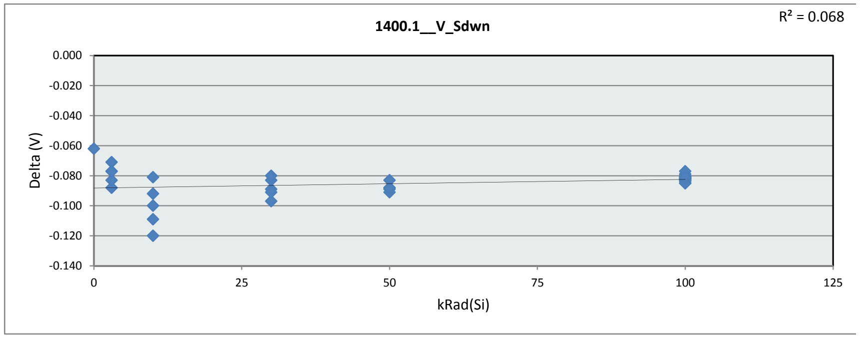


TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

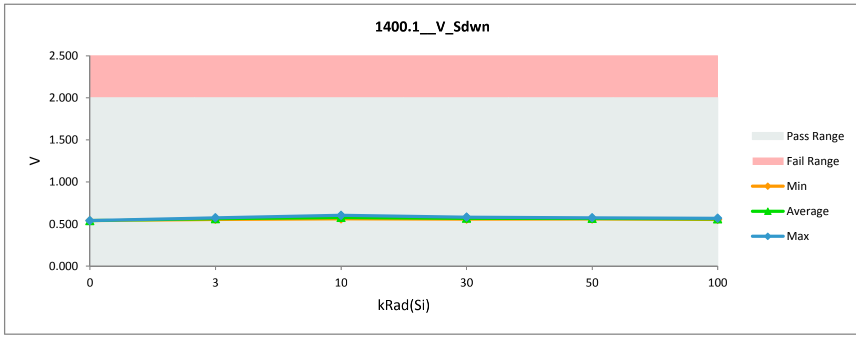
All units passed SMD specification limits up to 100kRAD HDR.

	1400.1__V_Sdwn	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	V	V
Max Limit	2	2
Min Limit	0	0

kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	0.479	0.541	-0.062
3	HDR_L1_D26_UnBias	0.484	0.561	-0.077
3	HDR_L1_D27_UnBias	0.485	0.573	-0.088
3	HDR_L2_D26_UnBias	0.491	0.574	-0.083
3	HDR_L2_D27_UnBias	0.484	0.555	-0.071
3	HDR_L3_D26_UnBias	0.478	0.555	-0.077
10	HDR_L1_D28_UnBias	0.483	0.603	-0.120
10	HDR_L1_D29_UnBias	0.483	0.575	-0.092
10	HDR_L2_D28_UnBias	0.481	0.562	-0.081
10	HDR_L3_D27_UnBias	0.477	0.586	-0.109
10	HDR_L3_D28_UnBias	0.462	0.562	-0.100
30	HDR_L1_D30_UnBias	0.485	0.582	-0.097
30	HDR_L2_D29_nUBias	0.479	0.568	-0.089
30	HDR_L2_D30_UnBias	0.484	0.567	-0.083
30	HDR_L3_D29_UnBias	0.477	0.568	-0.091
30	HDR_L3_D30_UnBias	0.478	0.558	-0.080
50	HDR_L1_D31_UnBias	0.480	0.571	-0.091
50	HDR_L1_D32_UnBias	0.480	0.568	-0.088
50	HDR_L2_D31_UnBias	0.485	0.574	-0.089
50	HDR_L2_D32_UnBias	0.477	0.560	-0.083
50	HDR_L3_D31_UnBias	0.472	0.560	-0.088
100	HDR_L1_D33_UnBias	0.484	0.565	-0.081
100	HDR_L1_D34_UnBias	0.479	0.561	-0.082
100	HDR_L1_D35_UnBias	0.477	0.561	-0.084
100	HDR_L1_D36_UnBias	0.478	0.561	-0.083
100	HDR_L1_D37_UnBias	0.483	0.565	-0.082
100	HDR_L1_D38_UnBias	0.479	0.561	-0.082
100	HDR_L1_D39_UnBias	0.483	0.564	-0.081
100	HDR_L2_D33_UnBias	0.479	0.564	-0.085
100	HDR_L2_D34_UnBias	0.485	0.568	-0.083
100	HDR_L2_D35_UnBias	0.485	0.566	-0.081
100	HDR_L2_D36_UnBias	0.484	0.567	-0.083
100	HDR_L2_D37_UnBias	0.480	0.561	-0.081
100	HDR_L2_D38_UnBias	0.484	0.567	-0.083
100	HDR_L2_D39_UnBias	0.484	0.563	-0.079
100	HDR_L3_D32_UnBias	0.477	0.559	-0.082
100	HDR_L3_D33_UnBias	0.479	0.561	-0.082
100	HDR_L3_D34_UnBias	0.480	0.560	-0.080
100	HDR_L3_D35_UnBias	0.477	0.558	-0.081
100	HDR_L3_D36_UnBias	0.477	0.554	-0.077
100	HDR_L3_D37_UnBias	0.472	0.557	-0.085
100	HDR_L3_D38_UnBias	0.475	0.557	-0.082
100	HDR_L3_D39_UnBias	0.476	0.557	-0.081
	Max	0.491	0.603	-0.062
	Average	0.480	0.565	-0.085
	Min	0.462	0.541	-0.120
	Std Dev	0.005	0.010	0.009



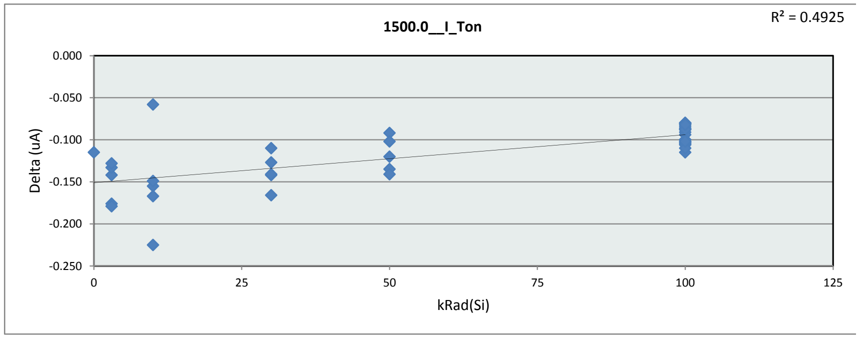
	1400.1__V_Sdwn					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	2	V				
Min Limit	0	V				
kRad(Si)	0	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000	0.000
Min	0.541	0.555	0.562	0.558	0.560	0.554
Average	0.541	0.564	0.578	0.569	0.567	0.562
Max	0.541	0.574	0.603	0.582	0.574	0.568
UL	2.000	2.000	2.000	2.000	2.000	2.000



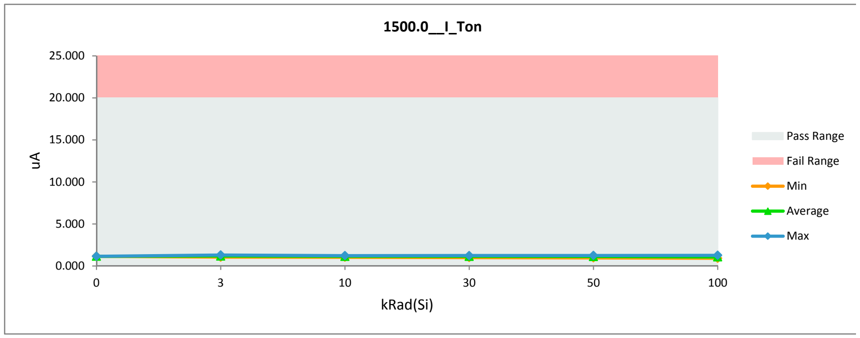
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		1500.0__I_Ton		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	20	20	
	Min Limit	0	0	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	1.040	1.155	-0.115
3	HDR_L1_D26_UnBias	0.979	1.121	-0.142
3	HDR_L1_D27_UnBias	1.100	1.276	-0.176
3	HDR_L2_D26_UnBias	1.130	1.309	-0.179
3	HDR_L2_D27_UnBias	1.016	1.149	-0.133
3	HDR_L3_D26_UnBias	0.923	1.051	-0.128
10	HDR_L1_D28_UnBias	1.005	1.230	-0.225
10	HDR_L1_D29_UnBias	0.949	1.104	-0.155
10	HDR_L2_D28_UnBias	1.058	1.207	-0.149
10	HDR_L3_D27_UnBias	0.987	1.045	-0.058
10	HDR_L3_D28_UnBias	0.961	1.128	-0.167
30	HDR_L1_D30_UnBias	1.077	1.243	-0.166
30	HDR_L2_D29_nUBias	1.032	1.174	-0.142
30	HDR_L2_D30_UnBias	1.100	1.241	-0.141
30	HDR_L3_D29_UnBias	0.875	1.002	-0.127
30	HDR_L3_D30_UnBias	0.952	1.062	-0.110
50	HDR_L1_D31_UnBias	1.033	1.168	-0.135
50	HDR_L1_D32_UnBias	1.033	1.125	-0.092
50	HDR_L2_D31_UnBias	1.113	1.254	-0.141
50	HDR_L2_D32_UnBias	1.026	1.146	-0.120
50	HDR_L3_D31_UnBias	0.859	0.961	-0.102
100	HDR_L1_D33_UnBias	1.140	1.246	-0.106
100	HDR_L1_D34_UnBias	0.970	1.061	-0.091
100	HDR_L1_D35_UnBias	0.946	1.040	-0.094
100	HDR_L1_D36_UnBias	0.924	1.012	-0.088
100	HDR_L1_D37_UnBias	1.042	1.144	-0.102
100	HDR_L1_D38_UnBias	0.922	1.009	-0.087
100	HDR_L1_D39_UnBias	1.105	1.209	-0.104
100	HDR_L2_D33_UnBias	0.981	1.081	-0.100
100	HDR_L2_D34_UnBias	1.158	1.273	-0.115
100	HDR_L2_D35_UnBias	1.094	1.194	-0.100
100	HDR_L2_D36_UnBias	1.081	1.186	-0.105
100	HDR_L2_D37_UnBias	1.087	1.190	-0.103
100	HDR_L2_D38_UnBias	1.133	1.243	-0.110
100	HDR_L2_D39_UnBias	1.064	1.166	-0.102
100	HDR_L3_D32_UnBias	0.898	0.984	-0.086
100	HDR_L3_D33_UnBias	0.876	0.957	-0.081
100	HDR_L3_D34_UnBias	0.921	1.002	-0.081
100	HDR_L3_D35_UnBias	0.914	0.998	-0.084
100	HDR_L3_D36_UnBias	0.903	0.983	-0.080
100	HDR_L3_D37_UnBias	0.894	0.982	-0.088
100	HDR_L3_D38_UnBias	0.836	0.916	-0.080
100	HDR_L3_D39_UnBias	0.868	0.950	-0.082
	Max	1.158	1.309	-0.058
	Average	1.000	1.116	-0.116
	Min	0.836	0.916	-0.225
	Std Dev	0.089	0.107	0.034



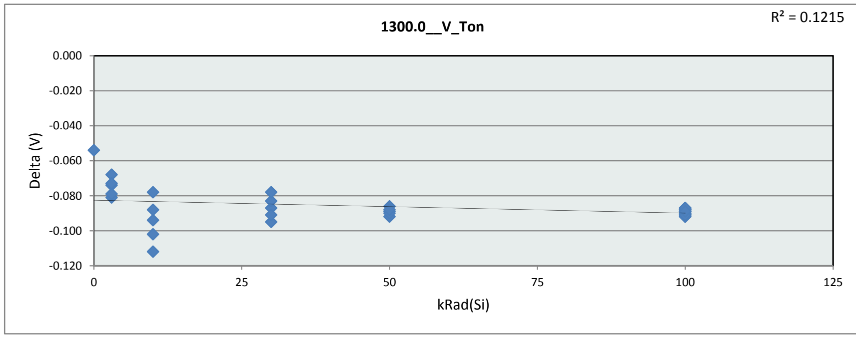
	1500.0__I_Ton					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	20	uA				
Min Limit	0	uA				
kRad(Si)	0	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000	0.000
Min	1.155	1.051	1.045	1.002	0.961	0.916
Average	1.155	1.181	1.143	1.144	1.131	1.083
Max	1.155	1.309	1.230	1.243	1.254	1.273
UL	20.000	20.000	20.000	20.000	20.000	20.000



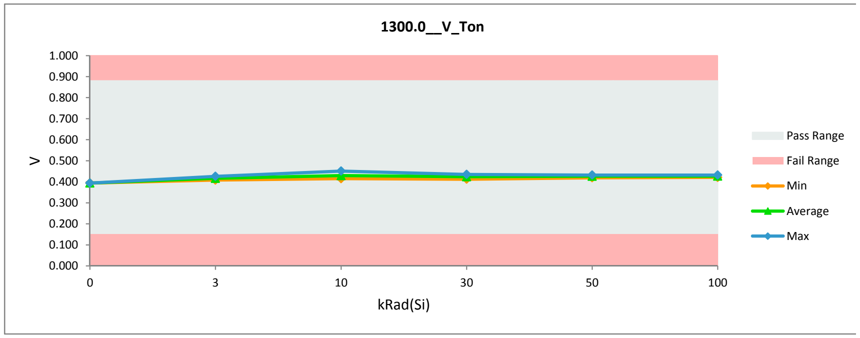
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		1300.0__V_Ton		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	0.88	0.88	
	Min Limit	0.15	0.15	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	0.340	0.394	-0.054
3	HDR_L1_D26_UnBias	0.343	0.417	-0.074
3	HDR_L1_D27_UnBias	0.342	0.423	-0.081
3	HDR_L2_D26_UnBias	0.347	0.426	-0.079
3	HDR_L2_D27_UnBias	0.340	0.408	-0.068
3	HDR_L3_D26_UnBias	0.335	0.408	-0.073
10	HDR_L1_D28_UnBias	0.339	0.451	-0.112
10	HDR_L1_D29_UnBias	0.339	0.427	-0.088
10	HDR_L2_D28_UnBias	0.338	0.416	-0.078
10	HDR_L3_D27_UnBias	0.336	0.438	-0.102
10	HDR_L3_D28_UnBias	0.321	0.415	-0.094
30	HDR_L1_D30_UnBias	0.340	0.435	-0.095
30	HDR_L2_D29_nUBias	0.338	0.425	-0.087
30	HDR_L2_D30_UnBias	0.341	0.424	-0.083
30	HDR_L3_D29_UnBias	0.333	0.424	-0.091
30	HDR_L3_D30_UnBias	0.334	0.412	-0.078
50	HDR_L1_D31_UnBias	0.339	0.431	-0.092
50	HDR_L1_D32_UnBias	0.339	0.428	-0.089
50	HDR_L2_D31_UnBias	0.342	0.432	-0.090
50	HDR_L2_D32_UnBias	0.336	0.422	-0.086
50	HDR_L3_D31_UnBias	0.331	0.419	-0.088
100	HDR_L1_D33_UnBias	0.340	0.428	-0.088
100	HDR_L1_D34_UnBias	0.339	0.428	-0.089
100	HDR_L1_D35_UnBias	0.333	0.425	-0.092
100	HDR_L1_D36_UnBias	0.338	0.427	-0.089
100	HDR_L1_D37_UnBias	0.338	0.429	-0.091
100	HDR_L1_D38_UnBias	0.338	0.426	-0.088
100	HDR_L1_D39_UnBias	0.340	0.428	-0.088
100	HDR_L2_D33_UnBias	0.338	0.429	-0.091
100	HDR_L2_D34_UnBias	0.342	0.432	-0.090
100	HDR_L2_D35_UnBias	0.343	0.430	-0.087
100	HDR_L2_D36_UnBias	0.341	0.431	-0.090
100	HDR_L2_D37_UnBias	0.340	0.428	-0.088
100	HDR_L2_D38_UnBias	0.342	0.432	-0.090
100	HDR_L2_D39_UnBias	0.339	0.427	-0.088
100	HDR_L3_D32_UnBias	0.333	0.424	-0.091
100	HDR_L3_D33_UnBias	0.336	0.425	-0.089
100	HDR_L3_D34_UnBias	0.337	0.424	-0.087
100	HDR_L3_D35_UnBias	0.334	0.423	-0.089
100	HDR_L3_D36_UnBias	0.334	0.421	-0.087
100	HDR_L3_D37_UnBias	0.330	0.422	-0.092
100	HDR_L3_D38_UnBias	0.331	0.422	-0.091
100	HDR_L3_D39_UnBias	0.332	0.421	-0.089
	Max	0.347	0.451	-0.054
	Average	0.337	0.425	-0.087
	Min	0.321	0.394	-0.112
	Std Dev	0.005	0.009	0.009



	1300.0__V_Ton					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	0.88	V				
Min Limit	0.15	V				
kRad(Si)	0	3	10	30	50	100
LL	0.150	0.150	0.150	0.150	0.150	0.150
Min	0.394	0.408	0.415	0.412	0.419	0.421
Average	0.394	0.416	0.429	0.424	0.426	0.426
Max	0.394	0.426	0.451	0.435	0.432	0.432
UL	0.880	0.880	0.880	0.880	0.880	0.880

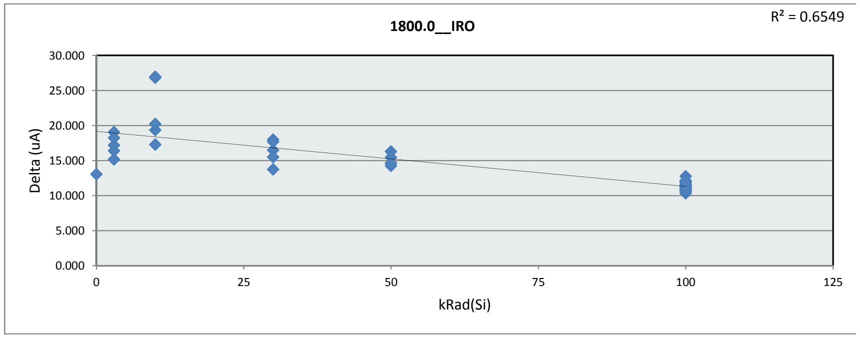


TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

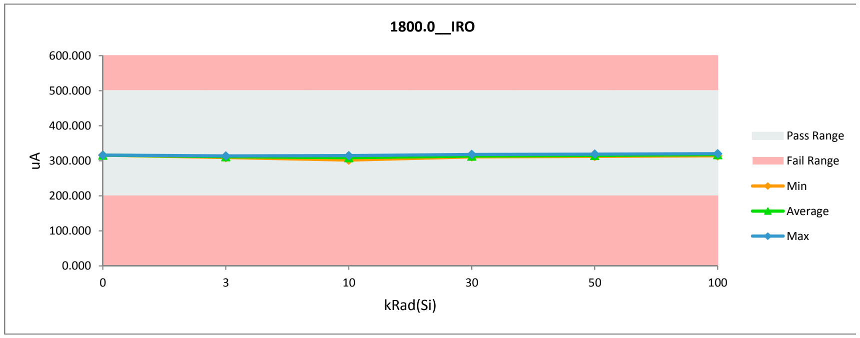
All units passed SMD specification limits up to 100kRAD HDR.

	1800.0__IRO	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	uA	uA
Max Limit	500	500
Min Limit	200	200

kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	329.122	316.067	13.055
3	HDR_L1_D26_UnBias	329.215	312.038	17.177
3	HDR_L1_D27_UnBias	329.648	310.583	19.065
3	HDR_L2_D26_UnBias	327.380	309.152	18.228
3	HDR_L2_D27_UnBias	328.855	313.701	15.154
3	HDR_L3_D26_UnBias	328.524	312.137	16.387
10	HDR_L1_D28_UnBias	328.695	301.880	26.815
10	HDR_L1_D29_UnBias	328.830	309.471	19.359
10	HDR_L2_D28_UnBias	331.951	314.671	17.280
10	HDR_L3_D27_UnBias	330.574	303.621	26.953
10	HDR_L3_D28_UnBias	333.666	313.448	20.218
30	HDR_L1_D30_UnBias	329.203	311.224	17.979
30	HDR_L2_D29_nUBias	329.438	312.955	16.483
30	HDR_L2_D30_UnBias	328.399	312.901	15.498
30	HDR_L3_D29_UnBias	328.803	311.115	17.688
30	HDR_L3_D30_UnBias	331.841	318.109	13.732
50	HDR_L1_D31_UnBias	328.898	314.243	14.655
50	HDR_L1_D32_UnBias	328.898	312.596	16.302
50	HDR_L2_D31_UnBias	329.519	314.069	15.450
50	HDR_L2_D32_UnBias	333.219	318.977	14.242
50	HDR_L3_D31_UnBias	329.740	315.130	14.610
100	HDR_L1_D33_UnBias	329.310	318.988	10.322
100	HDR_L1_D34_UnBias	328.731	318.104	10.627
100	HDR_L1_D35_UnBias	330.733	318.994	11.739
100	HDR_L1_D36_UnBias	331.641	320.105	11.536
100	HDR_L1_D37_UnBias	327.986	316.846	11.140
100	HDR_L1_D38_UnBias	330.271	319.311	10.960
100	HDR_L1_D39_UnBias	329.682	318.845	10.837
100	HDR_L2_D33_UnBias	329.601	317.674	11.927
100	HDR_L2_D34_UnBias	326.833	315.293	11.540
100	HDR_L2_D35_UnBias	327.689	317.153	10.536
100	HDR_L2_D36_UnBias	330.345	318.903	11.442
100	HDR_L2_D37_UnBias	328.374	317.369	11.005
100	HDR_L2_D38_UnBias	328.182	316.880	11.302
100	HDR_L2_D39_UnBias	331.240	320.064	11.176
100	HDR_L3_D32_UnBias	326.035	314.626	11.409
100	HDR_L3_D33_UnBias	325.507	314.093	11.414
100	HDR_L3_D34_UnBias	327.795	316.977	10.818
100	HDR_L3_D35_UnBias	326.615	315.625	10.990
100	HDR_L3_D36_UnBias	328.793	317.793	11.000
100	HDR_L3_D37_UnBias	330.173	317.422	12.751
100	HDR_L3_D38_UnBias	327.486	315.354	12.132
100	HDR_L3_D39_UnBias	328.158	316.141	12.017
	Max	333.666	320.105	26.953
	Average	329.200	314.899	14.301
	Min	325.507	301.880	10.322
	Std Dev	1.708	3.979	4.027



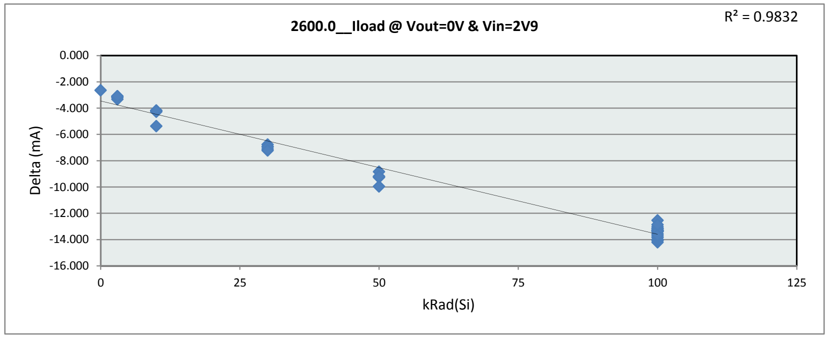
	1800.0__IRO					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	500	uA				
Min Limit	200	uA				
kRad(Si)	0	3	10	30	50	100
LL	200.000	200.000	200.000	200.000	200.000	200.000
Min	316.067	309.152	301.880	311.115	312.596	314.093
Average	316.067	311.522	308.618	313.261	315.003	317.389
Max	316.067	313.701	314.671	318.109	318.977	320.105
UL	500.000	500.000	500.000	500.000	500.000	500.000



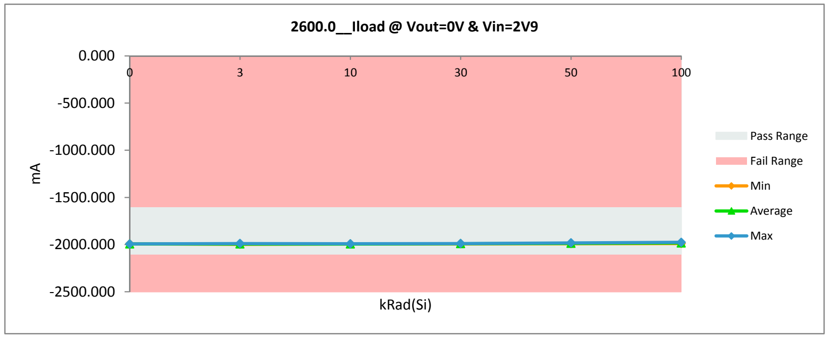
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2600.0__Iload @ Vout=0V & Vin=2V9		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	-1600	-1600	
	Min Limit	-2100	-2100	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	-1995.722	-1993.072	-2.650
3	HDR_L1_D26_UnBias	-1999.900	-1996.710	-3.190
3	HDR_L1_D27_UnBias	-2000.132	-1996.805	-3.327
3	HDR_L2_D26_UnBias	-1991.543	-1988.441	-3.102
3	HDR_L2_D27_UnBias	-1995.878	-1992.722	-3.156
3	HDR_L3_D26_UnBias	-1996.299	-1993.205	-3.094
10	HDR_L1_D28_UnBias	-1997.671	-1993.397	-4.274
10	HDR_L1_D29_UnBias	-1998.575	-1994.398	-4.177
10	HDR_L2_D28_UnBias	-1998.934	-1994.731	-4.203
10	HDR_L3_D27_UnBias	-1996.471	-1991.100	-5.371
10	HDR_L3_D28_UnBias	-1996.307	-1992.089	-4.218
30	HDR_L1_D30_UnBias	-1999.298	-1992.182	-7.116
30	HDR_L2_D29_nUBias	-1997.068	-1990.290	-6.778
30	HDR_L2_D30_UnBias	-1995.995	-1989.063	-6.932
30	HDR_L3_D29_UnBias	-1995.226	-1988.275	-6.951
30	HDR_L3_D30_UnBias	-1997.492	-1990.263	-7.229
50	HDR_L1_D31_UnBias	-1999.254	-1989.985	-9.269
50	HDR_L1_D32_UnBias	-1999.254	-1989.291	-9.963
50	HDR_L2_D31_UnBias	-1990.847	-1981.631	-9.216
50	HDR_L2_D32_UnBias	-1999.370	-1990.531	-8.839
50	HDR_L3_D31_UnBias	-1992.264	-1983.065	-9.199
100	HDR_L1_D33_UnBias	-2001.616	-1988.281	-13.335
100	HDR_L1_D34_UnBias	-1998.796	-1985.446	-13.350
100	HDR_L1_D35_UnBias	-1996.608	-1983.426	-13.182
100	HDR_L1_D36_UnBias	-1999.549	-1987.012	-12.537
100	HDR_L1_D37_UnBias	-1997.780	-1984.466	-13.314
100	HDR_L1_D38_UnBias	-1999.855	-1986.828	-13.027
100	HDR_L1_D39_UnBias	-2000.180	-1986.848	-13.332
100	HDR_L2_D33_UnBias	-1996.227	-1983.076	-13.151
100	HDR_L2_D34_UnBias	-1994.368	-1980.984	-13.384
100	HDR_L2_D35_UnBias	-1994.737	-1981.173	-13.564
100	HDR_L2_D36_UnBias	-1988.570	-1975.381	-13.189
100	HDR_L2_D37_UnBias	-1996.468	-1983.176	-13.292
100	HDR_L2_D38_UnBias	-1991.326	-1977.935	-13.391
100	HDR_L2_D39_UnBias	-1991.409	-1978.537	-12.872
100	HDR_L3_D32_UnBias	-1994.700	-1980.485	-14.215
100	HDR_L3_D33_UnBias	-1995.129	-1981.050	-14.079
100	HDR_L3_D34_UnBias	-1995.029	-1981.025	-14.004
100	HDR_L3_D35_UnBias	-1994.478	-1980.451	-14.027
100	HDR_L3_D36_UnBias	-1996.768	-1982.770	-13.998
100	HDR_L3_D37_UnBias	-1994.349	-1980.514	-13.835
100	HDR_L3_D38_UnBias	-1995.960	-1982.157	-13.803
100	HDR_L3_D39_UnBias	-1995.346	-1981.671	-13.675
	Max	-1988.570	-1975.381	-2.650
	Average	-1996.343	-1986.603	-9.740
	Min	-2001.616	-1996.805	-14.215
	Std Dev	2.901	5.558	4.248



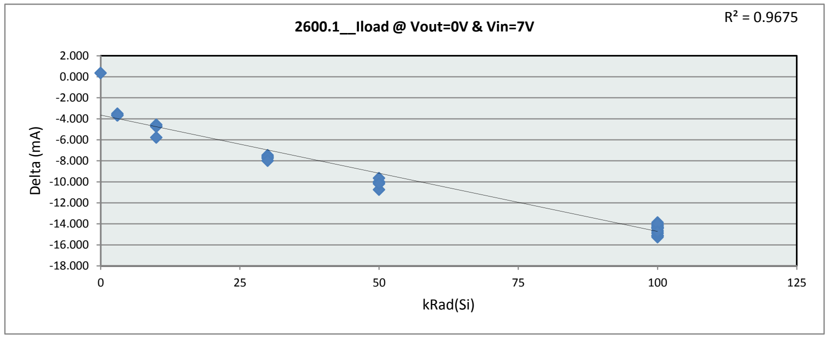
	2600.0__Iload @ Vout=					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	-1600	mA				
Min Limit	-2100	mA				
kRad(Si)	0	3	10	30	50	100
LL	-2100.000	-2100.000	-2100.000	-2100.000	-2100.000	-2100.000
Min	-1993.072	-1996.805	-1994.731	-1992.182	-1990.531	-1988.281
Average	-1993.072	-1993.577	-1993.143	-1990.015	-1986.901	-1982.395
Max	-1993.072	-1988.441	-1991.100	-1988.275	-1981.631	-1975.381
UL	-1600.000	-1600.000	-1600.000	-1600.000	-1600.000	-1600.000



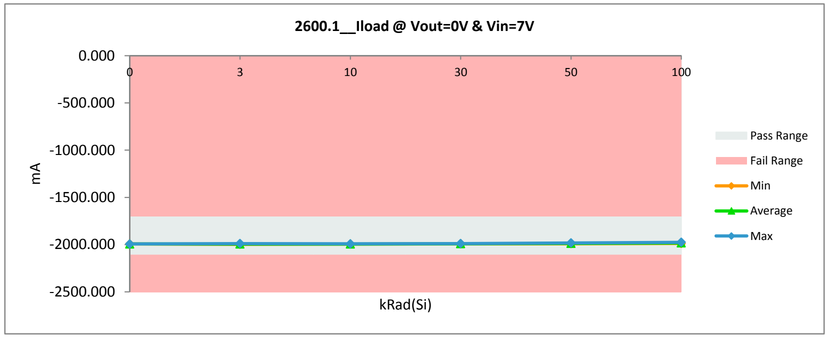
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2600.1__Iload @ Vout=0V & Vin=7V		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	-1700	-1700	
	Min Limit	-2100	-2100	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	-1992.674	-1993.017	0.343
3	HDR_L1_D26_UnBias	-2000.322	-1996.644	-3.678
3	HDR_L1_D27_UnBias	-2000.669	-1997.001	-3.668
3	HDR_L2_D26_UnBias	-1992.012	-1988.496	-3.516
3	HDR_L2_D27_UnBias	-1996.367	-1992.677	-3.690
3	HDR_L3_D26_UnBias	-1996.850	-1993.204	-3.646
10	HDR_L1_D28_UnBias	-1998.169	-1993.596	-4.573
10	HDR_L1_D29_UnBias	-1999.088	-1994.353	-4.735
10	HDR_L2_D28_UnBias	-1999.325	-1994.585	-4.740
10	HDR_L3_D27_UnBias	-1996.911	-1991.123	-5.788
10	HDR_L3_D28_UnBias	-1996.670	-1991.933	-4.737
30	HDR_L1_D30_UnBias	-1999.866	-1992.106	-7.760
30	HDR_L2_D29_nUBias	-1997.559	-1990.082	-7.477
30	HDR_L2_D30_UnBias	-1996.455	-1988.827	-7.628
30	HDR_L3_D29_UnBias	-1995.780	-1988.130	-7.650
30	HDR_L3_D30_UnBias	-1997.972	-1989.974	-7.998
50	HDR_L1_D31_UnBias	-1999.730	-1989.659	-10.071
50	HDR_L1_D32_UnBias	-1999.730	-1988.986	-10.744
50	HDR_L2_D31_UnBias	-1991.325	-1981.317	-10.008
50	HDR_L2_D32_UnBias	-1999.763	-1990.104	-9.659
50	HDR_L3_D31_UnBias	-1992.965	-1982.777	-10.188
100	HDR_L1_D33_UnBias	-2002.138	-1987.755	-14.383
100	HDR_L1_D34_UnBias	-1999.300	-1984.904	-14.396
100	HDR_L1_D35_UnBias	-1997.076	-1982.862	-14.214
100	HDR_L1_D36_UnBias	-1999.933	-1986.054	-13.879
100	HDR_L1_D37_UnBias	-1998.281	-1983.863	-14.418
100	HDR_L1_D38_UnBias	-2000.292	-1986.213	-14.079
100	HDR_L1_D39_UnBias	-2000.687	-1986.316	-14.371
100	HDR_L2_D33_UnBias	-1996.661	-1982.496	-14.165
100	HDR_L2_D34_UnBias	-1994.864	-1980.440	-14.424
100	HDR_L2_D35_UnBias	-1995.241	-1980.604	-14.637
100	HDR_L2_D36_UnBias	-1989.086	-1974.770	-14.316
100	HDR_L2_D37_UnBias	-1996.877	-1982.512	-14.365
100	HDR_L2_D38_UnBias	-1991.800	-1977.358	-14.442
100	HDR_L2_D39_UnBias	-1991.907	-1977.918	-13.989
100	HDR_L3_D32_UnBias	-1995.156	-1979.889	-15.267
100	HDR_L3_D33_UnBias	-1995.606	-1980.424	-15.182
100	HDR_L3_D34_UnBias	-1995.564	-1980.453	-15.111
100	HDR_L3_D35_UnBias	-1994.982	-1979.826	-15.156
100	HDR_L3_D36_UnBias	-1997.263	-1982.138	-15.125
100	HDR_L3_D37_UnBias	-1994.816	-1979.925	-14.891
100	HDR_L3_D38_UnBias	-1996.450	-1981.537	-14.913
100	HDR_L3_D39_UnBias	-1995.803	-1981.053	-14.750
	Max	-1989.086	-1974.770	0.343
	Average	-1996.744	-1986.230	-10.514
	Min	-2002.138	-1997.001	-15.267
	Std Dev	2.956	5.780	4.675



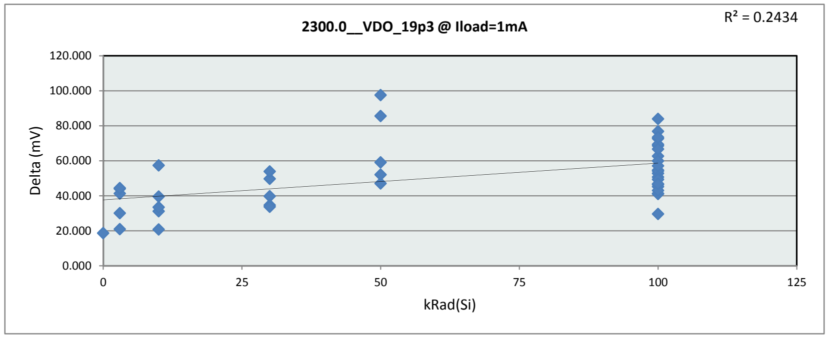
	2600.1__Iload @ Vout=					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	-1700 mA					
Min Limit	-2100 mA					
kRad(Si)	0	3	10	30	50	100
LL	-2100.000	-2100.000	-2100.000	-2100.000	-2100.000	-2100.000
Min	-1993.017	-1997.001	-1994.585	-1992.106	-1990.104	-1987.755
Average	-1993.017	-1993.604	-1993.118	-1989.824	-1986.569	-1981.787
Max	-1993.017	-1988.496	-1991.123	-1988.130	-1981.317	-1974.770
UL	-1700.000	-1700.000	-1700.000	-1700.000	-1700.000	-1700.000



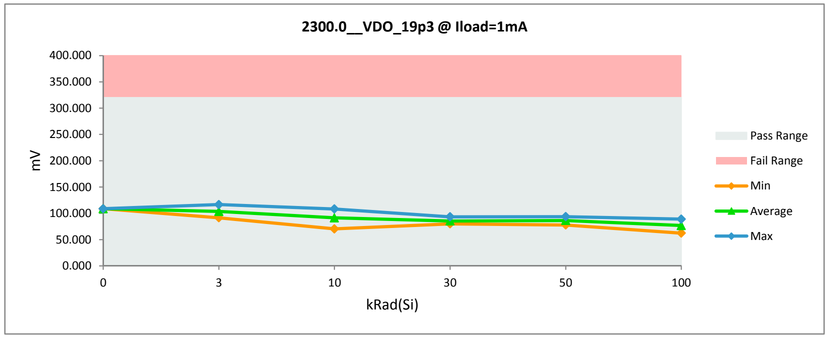
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.0__VDO_19p3 @ Iload=1mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	320	320	
	Min Limit	1	1	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	127.313	108.729	18.584
3	HDR_L1_D26_UnBias	129.839	99.764	30.075
3	HDR_L1_D27_UnBias	149.449	108.164	41.285
3	HDR_L2_D26_UnBias	145.708	101.724	43.984
3	HDR_L2_D27_UnBias	160.953	116.585	44.368
3	HDR_L3_D26_UnBias	112.395	91.509	20.886
10	HDR_L1_D28_UnBias	101.587	70.451	31.136
10	HDR_L1_D29_UnBias	124.225	84.668	39.557
10	HDR_L2_D28_UnBias	165.508	108.212	57.296
10	HDR_L3_D27_UnBias	123.958	103.239	20.719
10	HDR_L3_D28_UnBias	123.340	89.964	33.376
30	HDR_L1_D30_UnBias	136.895	87.215	49.680
30	HDR_L2_D29_nUBias	119.717	79.961	39.756
30	HDR_L2_D30_UnBias	120.077	85.517	34.560
30	HDR_L3_D29_UnBias	147.211	93.388	53.823
30	HDR_L3_D30_UnBias	114.509	80.812	33.697
50	HDR_L1_D31_UnBias	179.129	93.603	85.526
50	HDR_L1_D32_UnBias	179.129	81.659	97.470
50	HDR_L2_D31_UnBias	124.834	77.779	47.055
50	HDR_L2_D32_UnBias	150.871	91.846	59.025
50	HDR_L3_D31_UnBias	138.690	86.687	52.003
100	HDR_L1_D33_UnBias	138.157	75.536	62.621
100	HDR_L1_D34_UnBias	152.986	80.355	72.631
100	HDR_L1_D35_UnBias	131.203	76.619	54.584
100	HDR_L1_D36_UnBias	134.402	74.530	59.872
100	HDR_L1_D37_UnBias	125.148	72.387	52.761
100	HDR_L1_D38_UnBias	151.059	82.489	68.570
100	HDR_L1_D39_UnBias	127.597	73.436	54.161
100	HDR_L2_D33_UnBias	113.048	67.814	45.234
100	HDR_L2_D34_UnBias	112.447	71.442	41.005
100	HDR_L2_D35_UnBias	110.994	69.760	41.234
100	HDR_L2_D36_UnBias	125.087	74.383	50.704
100	HDR_L2_D37_UnBias	119.822	70.513	49.309
100	HDR_L2_D38_UnBias	122.563	76.159	46.404
100	HDR_L2_D39_UnBias	122.154	79.146	43.008
100	HDR_L3_D32_UnBias	164.122	87.377	76.745
100	HDR_L3_D33_UnBias	91.959	62.382	29.577
100	HDR_L3_D34_UnBias	138.563	81.517	57.046
100	HDR_L3_D35_UnBias	152.040	82.774	69.266
100	HDR_L3_D36_UnBias	120.079	73.330	46.749
100	HDR_L3_D37_UnBias	152.178	85.576	66.602
100	HDR_L3_D38_UnBias	172.834	88.938	83.896
100	HDR_L3_D39_UnBias	155.490	82.090	73.400
	Max	179.129	116.585	97.470
	Average	135.099	84.419	50.680
	Min	91.959	62.382	18.584
	Std Dev	20.501	12.409	17.715



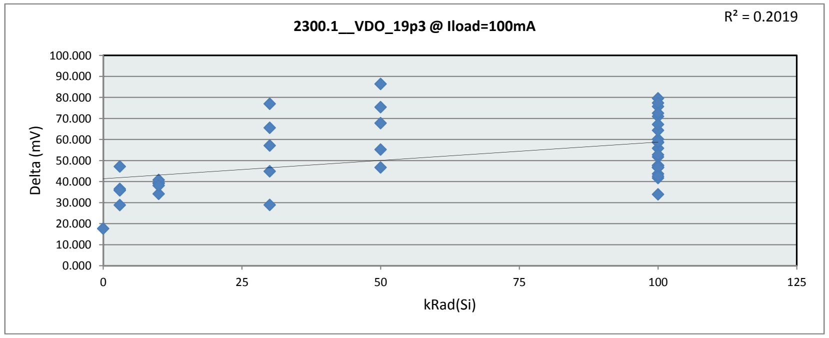
	2300.0__VDO_19p3 @					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	320	mV				
Min Limit	1	mV				
kRad(Si)	0	3	10	30	50	100
LL	1.000	1.000	1.000	1.000	1.000	1.000
Min	108.729	91.509	70.451	79.961	77.779	62.382
Average	108.729	103.549	91.307	85.379	86.315	76.752
Max	108.729	116.585	108.212	93.388	93.603	88.938
UL	320.000	320.000	320.000	320.000	320.000	320.000



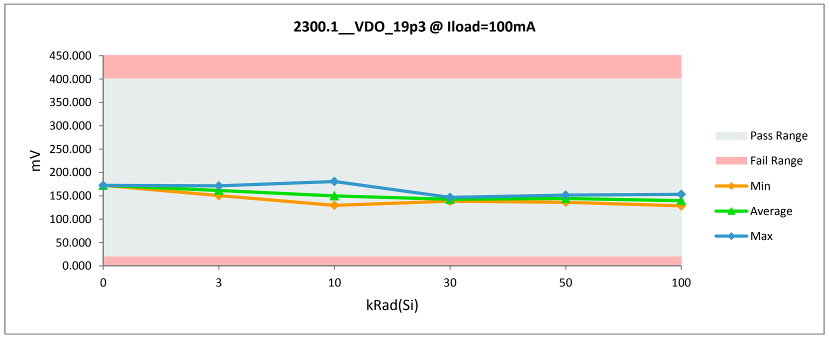
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.1__VDO_19p3 @ Iload=100mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	20	20	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	190.000	172.331	17.669
3	HDR_L1_D26_UnBias	189.797	153.311	36.486
3	HDR_L1_D27_UnBias	218.119	170.932	47.187
3	HDR_L2_D26_UnBias	197.833	161.942	35.891
3	HDR_L2_D27_UnBias	207.175	171.343	35.832
3	HDR_L3_D26_UnBias	179.256	150.384	28.872
10	HDR_L1_D28_UnBias	168.774	129.637	39.137
10	HDR_L1_D29_UnBias	179.738	140.317	39.421
10	HDR_L2_D28_UnBias	221.449	180.638	40.811
10	HDR_L3_D27_UnBias	184.366	150.183	34.183
10	HDR_L3_D28_UnBias	186.818	148.678	38.140
30	HDR_L1_D30_UnBias	216.844	139.882	76.962
30	HDR_L2_D29_nUBias	183.334	138.424	44.910
30	HDR_L2_D30_UnBias	197.937	140.827	57.110
30	HDR_L3_D29_UnBias	211.875	146.328	65.547
30	HDR_L3_D30_UnBias	175.682	146.777	28.905
50	HDR_L1_D31_UnBias	226.912	151.548	75.364
50	HDR_L1_D32_UnBias	226.912	140.494	86.418
50	HDR_L2_D31_UnBias	182.837	136.154	46.683
50	HDR_L2_D32_UnBias	212.337	144.569	67.768
50	HDR_L3_D31_UnBias	204.312	149.082	55.230
100	HDR_L1_D33_UnBias	197.601	137.401	60.200
100	HDR_L1_D34_UnBias	208.729	137.742	70.987
100	HDR_L1_D35_UnBias	187.591	139.966	47.625
100	HDR_L1_D36_UnBias	192.467	136.646	55.821
100	HDR_L1_D37_UnBias	181.687	134.878	46.809
100	HDR_L1_D38_UnBias	205.506	141.126	64.380
100	HDR_L1_D39_UnBias	184.506	132.755	51.751
100	HDR_L2_D33_UnBias	172.595	130.883	41.712
100	HDR_L2_D34_UnBias	186.506	133.810	52.696
100	HDR_L2_D35_UnBias	178.250	134.589	43.661
100	HDR_L2_D36_UnBias	183.252	136.608	46.644
100	HDR_L2_D37_UnBias	181.993	134.289	47.704
100	HDR_L2_D38_UnBias	187.233	140.418	46.815
100	HDR_L2_D39_UnBias	202.068	143.485	58.583
100	HDR_L3_D32_UnBias	225.545	149.885	75.660
100	HDR_L3_D33_UnBias	162.430	128.516	33.914
100	HDR_L3_D34_UnBias	216.316	143.819	72.497
100	HDR_L3_D35_UnBias	209.609	150.820	58.789
100	HDR_L3_D36_UnBias	181.339	138.798	42.541
100	HDR_L3_D37_UnBias	226.409	146.827	79.582
100	HDR_L3_D38_UnBias	230.722	153.320	77.402
100	HDR_L3_D39_UnBias	212.778	145.572	67.206
	Max	230.722	180.638	86.418
	Average	197.150	145.022	52.128
	Min	162.430	128.516	17.669
	Std Dev	18.125	11.826	16.113



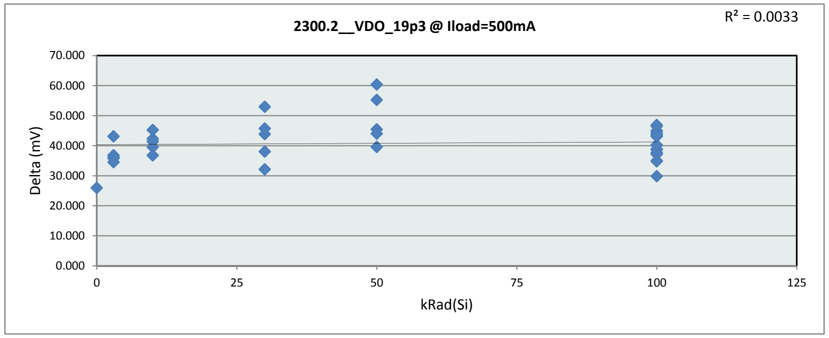
	2300.1__VDO_19p3 @					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	400	mV				
Min Limit	20	mV				
kRad(Si)	0	3	10	30	50	100
LL	20.000	20.000	20.000	20.000	20.000	20.000
Min	172.331	150.384	129.637	138.424	136.154	128.516
Average	172.331	161.582	149.891	142.448	144.369	139.643
Max	172.331	171.343	180.638	146.777	151.548	153.320
UL	400.000	400.000	400.000	400.000	400.000	400.000



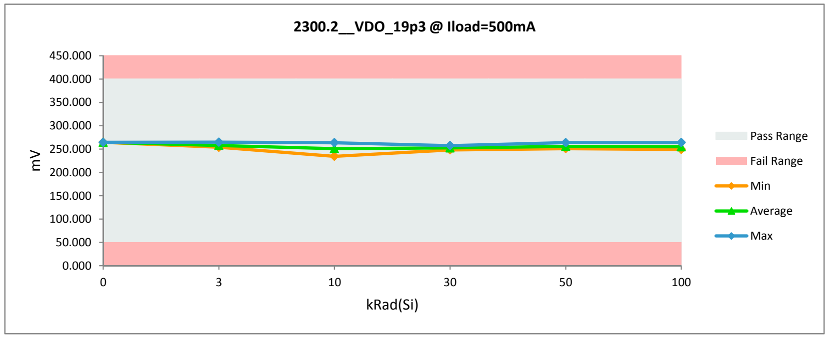
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.2__VDO_19p3 @ Iload=500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	50	50	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	290.391	264.431	25.960
3	HDR_L1_D26_UnBias	290.524	253.735	36.789
3	HDR_L1_D27_UnBias	297.980	254.879	43.101
3	HDR_L2_D26_UnBias	296.227	260.430	35.797
3	HDR_L2_D27_UnBias	300.941	264.757	36.184
3	HDR_L3_D26_UnBias	289.353	254.859	34.494
10	HDR_L1_D28_UnBias	279.608	234.411	45.197
10	HDR_L1_D29_UnBias	286.025	246.535	39.490
10	HDR_L2_D28_UnBias	305.761	263.498	42.263
10	HDR_L3_D27_UnBias	291.237	254.473	36.764
10	HDR_L3_D28_UnBias	296.384	255.005	41.379
30	HDR_L1_D30_UnBias	301.071	248.121	52.950
30	HDR_L2_D29_nUBias	286.772	248.748	38.024
30	HDR_L2_D30_UnBias	296.447	252.637	43.810
30	HDR_L3_D29_UnBias	303.051	257.370	45.681
30	HDR_L3_D30_UnBias	287.606	255.490	32.116
50	HDR_L1_D31_UnBias	311.151	255.920	55.231
50	HDR_L1_D32_UnBias	311.151	250.813	60.338
50	HDR_L2_D31_UnBias	290.920	251.345	39.575
50	HDR_L2_D32_UnBias	301.983	256.538	45.445
50	HDR_L3_D31_UnBias	307.757	263.745	44.012
100	HDR_L1_D33_UnBias	289.595	249.383	40.212
100	HDR_L1_D34_UnBias	298.038	253.766	44.272
100	HDR_L1_D35_UnBias	291.644	252.828	38.816
100	HDR_L1_D36_UnBias	294.215	251.016	43.199
100	HDR_L1_D37_UnBias	287.780	250.459	37.321
100	HDR_L1_D38_UnBias	300.633	255.703	44.930
100	HDR_L1_D39_UnBias	287.780	250.195	37.585
100	HDR_L2_D33_UnBias	284.150	249.136	35.014
100	HDR_L2_D34_UnBias	287.898	250.225	37.673
100	HDR_L2_D35_UnBias	287.405	250.282	37.123
100	HDR_L2_D36_UnBias	291.582	254.310	37.272
100	HDR_L2_D37_UnBias	289.344	250.691	38.653
100	HDR_L2_D38_UnBias	293.004	254.312	38.692
100	HDR_L2_D39_UnBias	296.632	256.490	40.142
100	HDR_L3_D32_UnBias	309.617	263.161	46.456
100	HDR_L3_D33_UnBias	279.253	249.419	29.834
100	HDR_L3_D34_UnBias	303.942	260.842	43.100
100	HDR_L3_D35_UnBias	304.655	261.028	43.627
100	HDR_L3_D36_UnBias	289.150	254.380	34.770
100	HDR_L3_D37_UnBias	307.798	262.902	44.896
100	HDR_L3_D38_UnBias	310.756	263.866	46.890
100	HDR_L3_D39_UnBias	305.074	261.383	43.691
	Max	311.151	264.757	60.338
	Average	295.635	254.733	40.902
	Min	279.253	234.411	25.960
	Std Dev	8.690	6.052	6.284



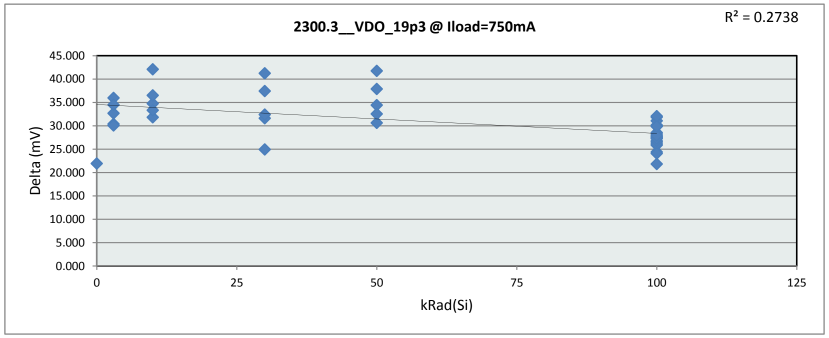
	2300.2__VDO_19p3 @					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	400	mV				
Min Limit	50	mV				
kRad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	264.431	253.735	234.411	248.121	250.813	249.136
Average	264.431	257.732	250.784	252.473	255.672	254.808
Max	264.431	264.757	263.498	257.370	263.745	263.866
UL	400.000	400.000	400.000	400.000	400.000	400.000



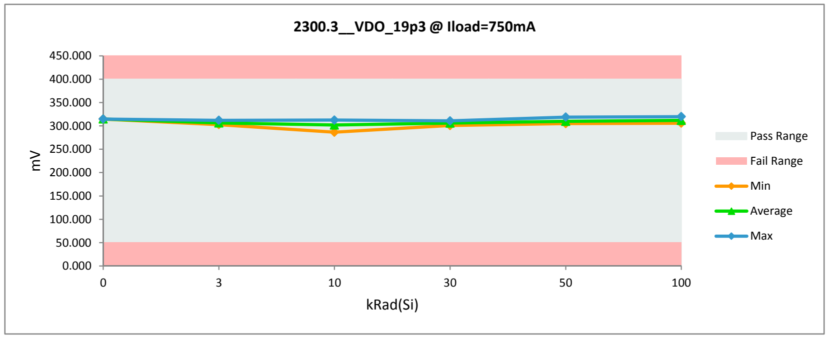
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.3__VDO_19p3 @ Iload=750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	50	50	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	336.527	314.633	21.894
3	HDR_L1_D26_UnBias	335.349	302.673	32.676
3	HDR_L1_D27_UnBias	340.181	304.221	35.960
3	HDR_L2_D26_UnBias	340.254	305.785	34.469
3	HDR_L2_D27_UnBias	342.320	311.941	30.379
3	HDR_L3_D26_UnBias	336.486	306.436	30.050
10	HDR_L1_D28_UnBias	328.571	286.499	42.072
10	HDR_L1_D29_UnBias	332.344	297.608	34.736
10	HDR_L2_D28_UnBias	344.289	312.471	31.818
10	HDR_L3_D27_UnBias	338.154	304.847	33.307
10	HDR_L3_D28_UnBias	343.839	307.337	36.502
30	HDR_L1_D30_UnBias	341.942	300.707	41.235
30	HDR_L2_D29_nUBias	333.691	302.082	31.609
30	HDR_L2_D30_UnBias	338.259	305.889	32.370
30	HDR_L3_D29_UnBias	347.259	309.823	37.436
30	HDR_L3_D30_UnBias	335.684	310.764	24.920
50	HDR_L1_D31_UnBias	346.610	308.759	37.851
50	HDR_L1_D32_UnBias	346.610	304.875	41.735
50	HDR_L2_D31_UnBias	337.410	306.802	30.608
50	HDR_L2_D32_UnBias	343.810	309.410	34.400
50	HDR_L3_D31_UnBias	351.338	318.822	32.516
100	HDR_L1_D33_UnBias	333.287	305.691	27.596
100	HDR_L1_D34_UnBias	339.593	309.629	29.964
100	HDR_L1_D35_UnBias	337.232	309.965	27.267
100	HDR_L1_D36_UnBias	336.721	308.186	28.535
100	HDR_L1_D37_UnBias	333.965	307.462	26.503
100	HDR_L1_D38_UnBias	339.808	309.681	30.127
100	HDR_L1_D39_UnBias	333.557	306.071	27.486
100	HDR_L2_D33_UnBias	332.108	306.273	25.835
100	HDR_L2_D34_UnBias	334.762	307.084	27.678
100	HDR_L2_D35_UnBias	332.678	308.314	24.364
100	HDR_L2_D36_UnBias	338.633	312.512	26.121
100	HDR_L2_D37_UnBias	335.135	308.407	26.728
100	HDR_L2_D38_UnBias	339.614	312.319	27.295
100	HDR_L2_D39_UnBias	342.683	314.471	28.212
100	HDR_L3_D32_UnBias	350.808	319.740	31.068
100	HDR_L3_D33_UnBias	329.294	307.478	21.816
100	HDR_L3_D34_UnBias	346.536	316.656	29.880
100	HDR_L3_D35_UnBias	346.193	318.297	27.896
100	HDR_L3_D36_UnBias	336.427	312.346	24.081
100	HDR_L3_D37_UnBias	351.468	319.635	31.833
100	HDR_L3_D38_UnBias	351.291	319.243	32.048
100	HDR_L3_D39_UnBias	347.996	318.143	29.853
	Max	351.468	319.740	42.072
	Average	339.784	309.069	30.715
	Min	328.571	286.499	21.816
	Std Dev	6.165	6.365	4.909



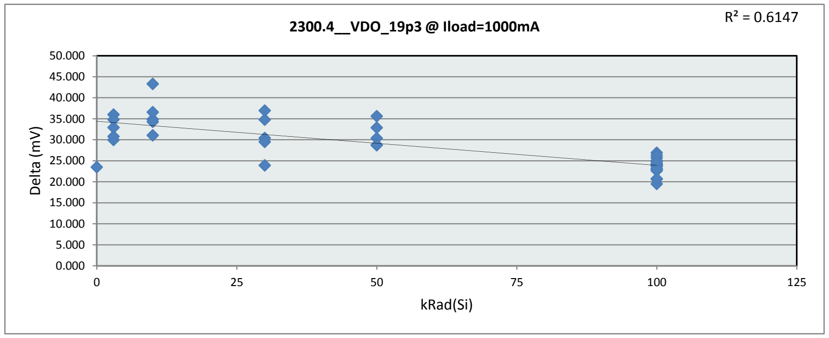
	2300.3__VDO_19p3 @					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	400	mV				
Min Limit	50	mV				
kRad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	314.633	302.673	286.499	300.707	304.875	305.691
Average	314.633	306.211	301.752	305.853	309.734	311.709
Max	314.633	311.941	312.471	310.764	318.822	319.740
UL	400.000	400.000	400.000	400.000	400.000	400.000



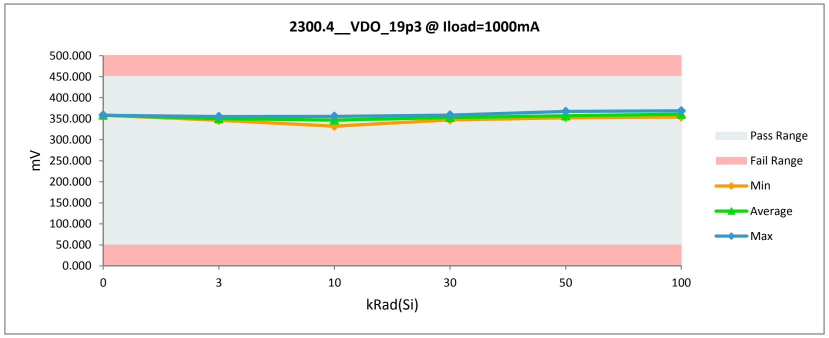
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.4__VDO_19p3 @ Iload=1000mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	450	450	
	Min Limit	50	50	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	381.699	358.221	23.478
3	HDR_L1_D26_UnBias	379.226	346.311	32.915
3	HDR_L1_D27_UnBias	382.945	346.970	35.975
3	HDR_L2_D26_UnBias	384.599	349.777	34.822
3	HDR_L2_D27_UnBias	385.095	355.153	29.942
3	HDR_L3_D26_UnBias	382.966	352.179	30.787
10	HDR_L1_D28_UnBias	375.423	332.146	43.277
10	HDR_L1_D29_UnBias	377.931	343.099	34.832
10	HDR_L2_D28_UnBias	386.693	355.643	31.050
10	HDR_L3_D27_UnBias	383.976	349.702	34.274
10	HDR_L3_D28_UnBias	389.915	353.377	36.538
30	HDR_L1_D30_UnBias	384.069	347.125	36.944
30	HDR_L2_D29_nUBias	379.156	348.774	30.382
30	HDR_L2_D30_UnBias	381.847	352.385	29.462
30	HDR_L3_D29_UnBias	391.184	356.431	34.753
30	HDR_L3_D30_UnBias	382.483	358.599	23.884
50	HDR_L1_D31_UnBias	387.804	354.935	32.869
50	HDR_L1_D32_UnBias	387.804	352.192	35.612
50	HDR_L2_D31_UnBias	383.405	354.731	28.674
50	HDR_L2_D32_UnBias	386.084	355.710	30.374
50	HDR_L3_D31_UnBias	395.984	367.228	28.756
100	HDR_L1_D33_UnBias	377.208	354.137	23.071
100	HDR_L1_D34_UnBias	383.020	358.002	25.018
100	HDR_L1_D35_UnBias	382.598	358.993	23.605
100	HDR_L1_D36_UnBias	381.055	357.001	24.054
100	HDR_L1_D37_UnBias	379.547	356.486	23.061
100	HDR_L1_D38_UnBias	382.347	357.339	25.008
100	HDR_L1_D39_UnBias	378.272	354.617	23.655
100	HDR_L2_D33_UnBias	378.521	355.469	23.052
100	HDR_L2_D34_UnBias	380.348	356.002	24.346
100	HDR_L2_D35_UnBias	378.070	357.377	20.693
100	HDR_L2_D36_UnBias	384.887	361.979	22.908
100	HDR_L2_D37_UnBias	380.079	357.447	22.632
100	HDR_L2_D38_UnBias	385.471	361.468	24.003
100	HDR_L2_D39_UnBias	387.853	363.722	24.131
100	HDR_L3_D32_UnBias	394.045	368.329	25.716
100	HDR_L3_D33_UnBias	376.814	357.337	19.477
100	HDR_L3_D34_UnBias	389.917	366.149	23.768
100	HDR_L3_D35_UnBias	390.482	367.458	23.024
100	HDR_L3_D36_UnBias	382.474	361.856	20.618
100	HDR_L3_D37_UnBias	395.657	368.757	26.900
100	HDR_L3_D38_UnBias	393.739	367.459	26.280
100	HDR_L3_D39_UnBias	392.053	367.236	24.817
	Max	395.984	368.757	43.277
	Average	384.296	356.403	27.894
	Min	375.423	332.146	19.477
	Std Dev	5.328	7.396	5.548



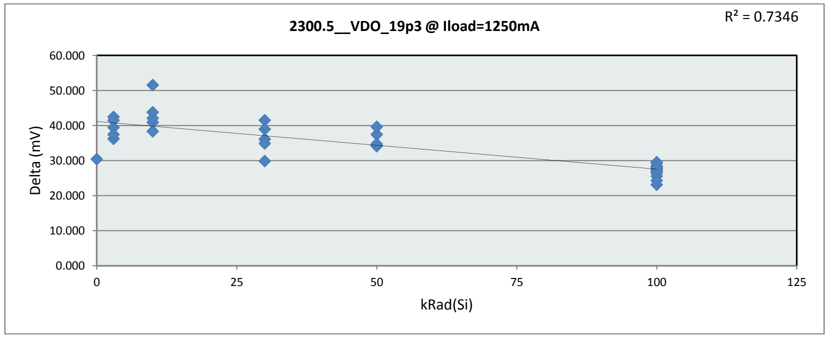
	2300.4__VDO_19p3 @					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	450	mV				
Min Limit	50	mV				
kRad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	358.221	346.311	332.146	347.125	352.192	354.137
Average	358.221	350.078	346.793	352.663	356.959	360.665
Max	358.221	355.153	355.643	358.599	367.228	368.757
UL	450.000	450.000	450.000	450.000	450.000	450.000



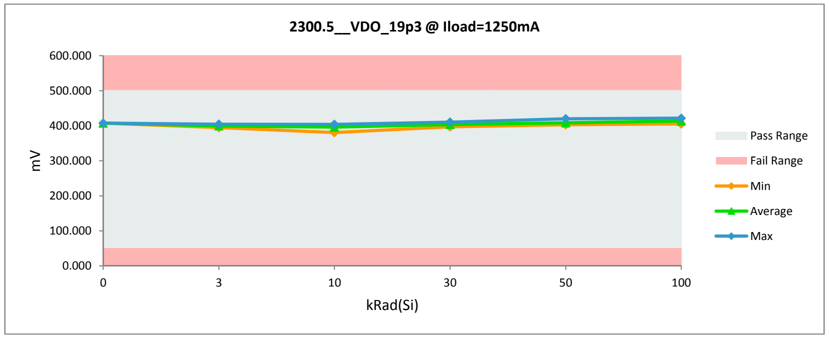
TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.5__VDO_19p3 @ Iload=1250mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	500	500	
	Min Limit	50	50	
kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	CORR_L2_D45	437.801	407.397	30.404
3	HDR_L1_D26_UnBias	435.135	395.677	39.458
3	HDR_L1_D27_UnBias	436.921	394.461	42.460
3	HDR_L2_D26_UnBias	441.249	399.773	41.476
3	HDR_L2_D27_UnBias	440.419	404.218	36.201
3	HDR_L3_D26_UnBias	439.930	402.510	37.420
10	HDR_L1_D28_UnBias	431.924	380.408	51.516
10	HDR_L1_D29_UnBias	433.942	393.021	40.921
10	HDR_L2_D28_UnBias	442.131	403.774	38.357
10	HDR_L3_D27_UnBias	440.948	398.866	42.082
10	HDR_L3_D28_UnBias	447.578	403.785	43.793
30	HDR_L1_D30_UnBias	438.257	396.785	41.472
30	HDR_L2_D29_nUBias	435.039	398.951	36.088
30	HDR_L2_D30_UnBias	438.323	403.432	34.891
30	HDR_L3_D29_UnBias	446.247	407.329	38.918
30	HDR_L3_D30_UnBias	440.123	410.262	29.861
50	HDR_L1_D31_UnBias	442.412	404.982	37.430
50	HDR_L1_D32_UnBias	442.412	402.790	39.622
50	HDR_L2_D31_UnBias	440.621	406.510	34.111
50	HDR_L2_D32_UnBias	440.961	406.605	34.356
50	HDR_L3_D31_UnBias	454.575	419.855	34.720
100	HDR_L1_D33_UnBias	432.099	405.096	27.003
100	HDR_L1_D34_UnBias	438.413	410.183	28.230
100	HDR_L1_D35_UnBias	439.244	411.653	27.591
100	HDR_L1_D36_UnBias	437.570	409.291	28.279
100	HDR_L1_D37_UnBias	435.821	408.891	26.930
100	HDR_L1_D38_UnBias	437.909	409.616	28.293
100	HDR_L1_D39_UnBias	433.790	406.901	26.889
100	HDR_L2_D33_UnBias	435.228	408.314	26.914
100	HDR_L2_D34_UnBias	436.350	408.560	27.790
100	HDR_L2_D35_UnBias	435.076	409.527	25.549
100	HDR_L2_D36_UnBias	442.557	415.359	27.198
100	HDR_L2_D37_UnBias	436.894	409.850	27.044
100	HDR_L2_D38_UnBias	442.609	414.202	28.407
100	HDR_L2_D39_UnBias	444.666	416.464	28.202
100	HDR_L3_D32_UnBias	449.982	420.695	29.287
100	HDR_L3_D33_UnBias	434.208	411.091	23.117
100	HDR_L3_D34_UnBias	445.288	418.856	26.432
100	HDR_L3_D35_UnBias	446.542	419.515	27.027
100	HDR_L3_D36_UnBias	438.919	414.650	24.269
100	HDR_L3_D37_UnBias	450.990	421.445	29.545
100	HDR_L3_D38_UnBias	448.566	419.229	29.337
100	HDR_L3_D39_UnBias	448.454	420.167	28.287
	Max	454.575	421.445	51.516
	Average	440.421	407.696	32.725
	Min	431.924	380.408	23.117
	Std Dev	5.344	8.573	6.587



	2300.5__VDO_19p3 @					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	500	mV				
Min Limit	50	mV				
kRad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	407.397	394.461	380.408	396.785	402.790	405.096
Average	407.397	399.328	395.971	403.352	408.148	413.162
Max	407.397	404.218	403.785	410.262	419.855	421.445
UL	500.000	500.000	500.000	500.000	500.000	500.000

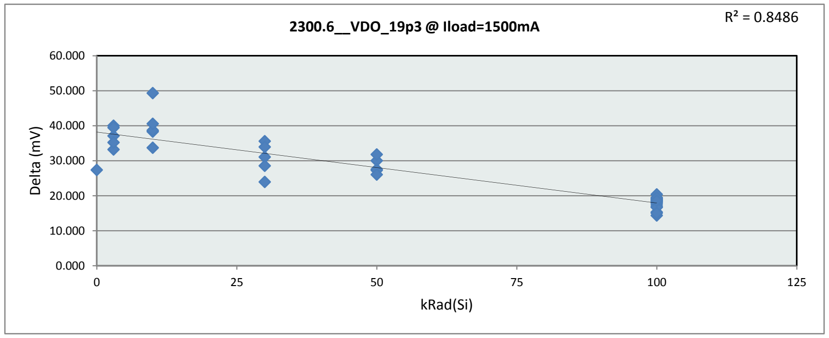


TPS7A4501-RHA
TID HDR Report (3KRad-100KRad Unbias)

All units passed SMD specification limits up to 100kRAD HDR.

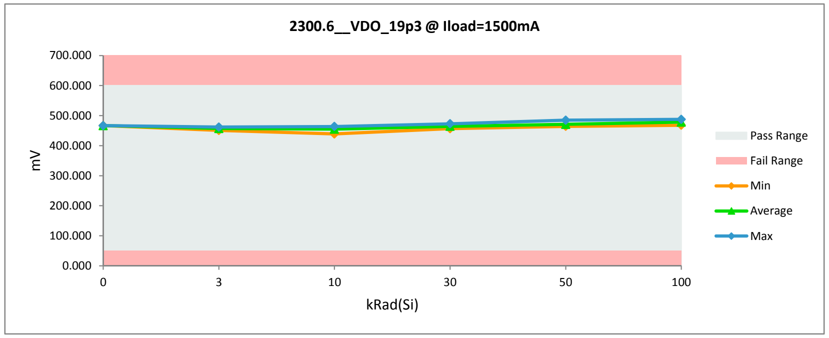
	2300.6__VDO_19p3 @ Iload=1500mA	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	mV	mV
Max Limit	600	600
Min Limit	50	50

kRad(Si)	Serial #	PreRad_HDR(3K-100K Unbias)	PostRad_HDR(3K-100K Unbias)	Delta
0	_CORR_L2_D45	494.141	466.776	27.365
3	HDR_L1_D26_UnBias	489.789	452.712	37.077
3	HDR_L1_D27_UnBias	490.780	450.803	39.977
3	HDR_L2_D26_UnBias	497.953	458.529	39.424
3	HDR_L2_D27_UnBias	494.991	461.806	33.185
3	HDR_L3_D26_UnBias	496.378	461.189	35.189
10	HDR_L1_D28_UnBias	488.237	438.916	49.321
10	HDR_L1_D29_UnBias	489.414	451.104	38.310
10	HDR_L2_D28_UnBias	496.068	462.374	33.694
10	HDR_L3_D27_UnBias	497.307	458.662	38.645
10	HDR_L3_D28_UnBias	504.268	463.736	40.532
30	HDR_L1_D30_UnBias	491.992	456.434	35.558
30	HDR_L2_D29_nUBias	490.724	459.692	31.032
30	HDR_L2_D30_UnBias	493.205	464.692	28.513
30	HDR_L3_D29_UnBias	502.221	468.286	33.935
30	HDR_L3_D30_UnBias	496.589	472.655	23.934
50	HDR_L1_D31_UnBias	496.050	466.072	29.978
50	HDR_L1_D32_UnBias	496.050	464.286	31.764
50	HDR_L2_D31_UnBias	498.420	470.897	27.523
50	HDR_L2_D32_UnBias	495.182	467.944	27.238
50	HDR_L3_D31_UnBias	510.893	484.859	26.034
100	HDR_L1_D33_UnBias	485.467	468.103	17.364
100	HDR_L1_D34_UnBias	492.580	473.953	18.627
100	HDR_L1_D35_UnBias	495.074	476.623	18.451
100	HDR_L1_D36_UnBias	492.678	474.323	18.355
100	HDR_L1_D37_UnBias	491.313	473.465	17.848
100	HDR_L1_D38_UnBias	491.652	472.639	19.013
100	HDR_L1_D39_UnBias	488.134	470.217	17.917
100	HDR_L2_D33_UnBias	491.867	473.572	18.295
100	HDR_L2_D34_UnBias	492.639	473.294	19.345
100	HDR_L2_D35_UnBias	490.607	475.330	15.277
100	HDR_L2_D36_UnBias	501.171	483.285	17.886
100	HDR_L2_D37_UnBias	492.549	475.683	16.866
100	HDR_L2_D38_UnBias	500.660	481.264	19.396
100	HDR_L2_D39_UnBias	502.576	483.838	18.738
100	HDR_L3_D32_UnBias	505.561	486.508	19.053
100	HDR_L3_D33_UnBias	491.413	477.066	14.347
100	HDR_L3_D34_UnBias	501.149	484.353	16.796
100	HDR_L3_D35_UnBias	502.421	485.770	16.651
100	HDR_L3_D36_UnBias	495.168	480.142	15.026
100	HDR_L3_D37_UnBias	507.741	487.364	20.377
100	HDR_L3_D38_UnBias	503.221	483.805	19.416
100	HDR_L3_D39_UnBias	504.515	485.934	18.581
	Max	510.893	487.364	49.321
	Average	496.065	470.441	25.624
	Min	485.467	438.916	14.347
	Std Dev	5.791	11.342	9.122



	2300.6__VDO_19p3 @	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	600	mV
Min Limit	50	mV

kRad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	466.776	450.803	438.916	456.434	464.286	468.103
Average	466.776	457.008	454.958	464.352	470.812	478.479
Max	466.776	461.806	463.736	472.655	484.859	487.364
UL	600.000	600.000	600.000	600.000	600.000	600.000



TPS7A4501-RHA

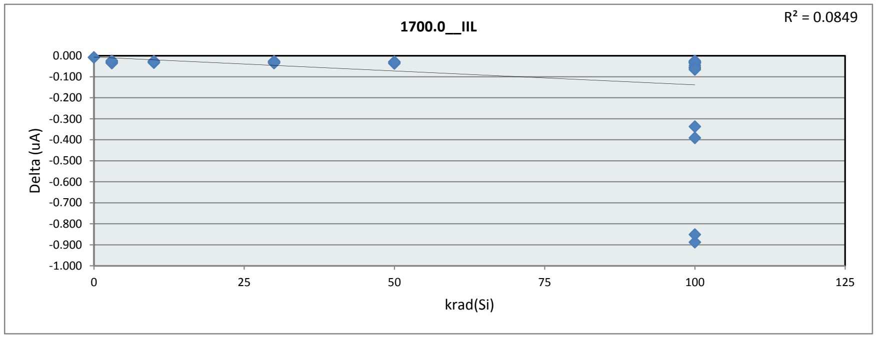
TID HDR Report 100 KRad (Biased)

All units passed SMD specification limits.

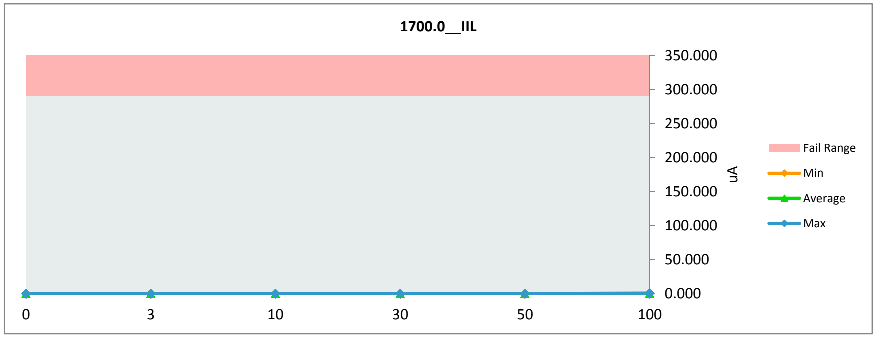
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		1700.0__IIL		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	290	290	
	Min Limit			
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	0.067	0.075	-0.008
3	HDR_L1_D1_Bias	0.001	0.035	-0.034
3	HDR_L1_D2_Bias	0.002	0.037	-0.035
3	HDR_L2_D1_Bias	0.003	0.031	-0.028
3	HDR_L2_D2_Bias	0.002	0.033	-0.031
3	HDR_L3_D1_Bias	0.009	0.033	-0.024
10	HDR_L1_D3_Bias	0.003	0.035	-0.032
10	HDR_L1_D4_Bias	0.000	0.033	-0.033
10	HDR_L2_D3_Bias	0.005	0.032	-0.027
10	HDR_L3_D2_Bias	0.004	0.030	-0.026
10	HDR_L3_D3_Bias	0.007	0.038	-0.031
30	HDR_L1_D5_Bias	0.001	0.036	-0.035
30	HDR_L2_D4_Bias	0.005	0.031	-0.026
30	HDR_L2_D5_Bias	0.005	0.037	-0.032
30	HDR_L3_D4_Bias	0.005	0.035	-0.030
30	HDR_L3_D5_Bias	0.006	0.035	-0.029
50	HDR_L1_D6_Bias	0.001	0.032	-0.031
50	HDR_L1_D7_Bias	0.000	0.037	-0.037
50	HDR_L2_D6_Bias	0.004	0.033	-0.029
50	HDR_L2_D7_Bias	0.001	0.037	-0.036
50	HDR_L3_D6_Bias	0.004	0.034	-0.030
100	HDR_L1_D8_Bias	0.002	0.037	-0.035
100	HDR_L1_D9_Bias	0.003	0.034	-0.031
100	HDR_L1_D10_Bias	0.002	0.057	-0.055
100	HDR_L1_D11_Bias	0.001	0.034	-0.033
100	HDR_L1_D12_Bias	0.003	0.032	-0.029
100	HDR_L1_D13_Bias	0.000	0.337	-0.337
100	HDR_L1_D14_Bias	0.001	0.067	-0.066
100	HDR_L2_D8_Bias	0.004	0.036	-0.032
100	HDR_L2_D9_Bias	0.002	0.036	-0.034
100	HDR_L2_D10_Bias	0.000	0.391	-0.391
100	HDR_L2_D11_Bias	0.000	0.031	-0.031
100	HDR_L2_D12_Bias	0.002	0.034	-0.032
100	HDR_L2_D13_Bias	0.001	0.889	-0.888
100	HDR_L2_D14_Bias	0.000	0.046	-0.046
100	HDR_L3_D7_Bias	0.006	0.031	-0.025
100	HDR_L3_D8_Bias	0.005	0.037	-0.032
100	HDR_L3_D9_Bias	0.004	0.035	-0.031
100	HDR_L3_D10_Bias	0.003	0.855	-0.852
100	HDR_L3_D11_Bias	0.004	0.033	-0.029
100	HDR_L3_D12_Bias	0.003	0.058	-0.055
100	HDR_L3_D13_Bias	0.004	0.034	-0.030
100	HDR_L3_D14_Bias	0.004	0.064	-0.060
	Max	0.067	0.889	-0.008
	Average	0.004	0.092	-0.088
	Min	0.000	0.030	-0.888
	Std Dev	0.010	0.188	0.189



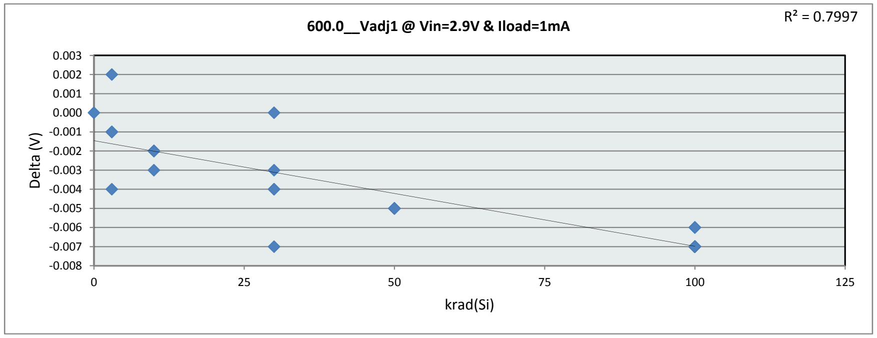
	1700.0__IIL					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	290	uA				
Min Limit		uA				
krad(Si)	0	3	10	30	50	100
LL						
Min	0.075	0.031	0.030	0.031	0.032	0.031
Average	0.075	0.034	0.034	0.035	0.035	0.146
Max	0.075	0.037	0.038	0.037	0.037	0.889
UL	290.000	290.000	290.000	290.000	290.000	290.000



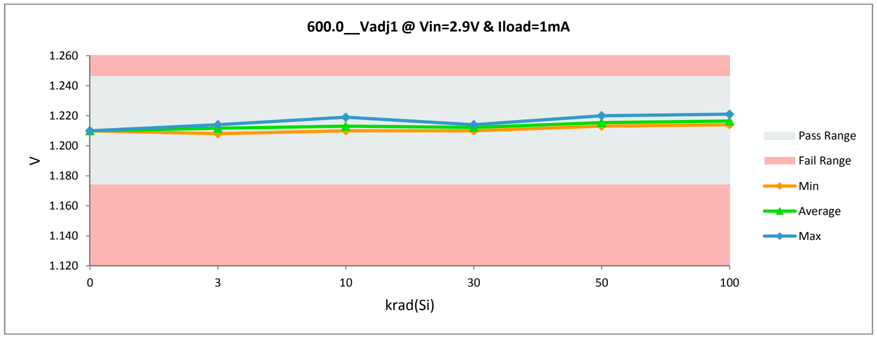
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		600.0__Vadj1 @ Vin=2.9V & Iload=1mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	1.246	1.246	
	Min Limit	1.174	1.174	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	1.210	1.210	0.000
3	HDR_L1_D1_Bias	1.207	1.208	-0.001
3	HDR_L1_D2_Bias	1.209	1.213	-0.004
3	HDR_L2_D1_Bias	1.212	1.210	0.002
3	HDR_L2_D2_Bias	1.213	1.214	-0.001
3	HDR_L3_D1_Bias	1.212	1.213	-0.001
10	HDR_L1_D3_Bias	1.208	1.210	-0.002
10	HDR_L1_D4_Bias	1.209	1.212	-0.003
10	HDR_L2_D3_Bias	1.210	1.212	-0.002
10	HDR_L3_D2_Bias	1.210	1.212	-0.002
10	HDR_L3_D3_Bias	1.217	1.219	-0.002
30	HDR_L1_D5_Bias	1.208	1.212	-0.004
30	HDR_L2_D4_Bias	1.209	1.213	-0.004
30	HDR_L2_D5_Bias	1.209	1.212	-0.003
30	HDR_L3_D4_Bias	1.210	1.210	0.000
30	HDR_L3_D5_Bias	1.207	1.214	-0.007
50	HDR_L1_D6_Bias	1.208	1.213	-0.005
50	HDR_L1_D7_Bias	1.211	1.216	-0.005
50	HDR_L2_D6_Bias	1.210	1.215	-0.005
50	HDR_L2_D7_Bias	1.215	1.220	-0.005
50	HDR_L3_D6_Bias	1.208	1.213	-0.005
100	HDR_L1_D8_Bias	1.209	1.216	-0.007
100	HDR_L1_D9_Bias	1.209	1.216	-0.007
100	HDR_L1_D10_Bias	1.210	1.217	-0.007
100	HDR_L1_D11_Bias	1.210	1.217	-0.007
100	HDR_L1_D12_Bias	1.209	1.216	-0.007
100	HDR_L1_D13_Bias	1.207	1.214	-0.007
100	HDR_L1_D14_Bias	1.210	1.217	-0.007
100	HDR_L2_D8_Bias	1.210	1.217	-0.007
100	HDR_L2_D9_Bias	1.211	1.218	-0.007
100	HDR_L2_D10_Bias	1.212	1.219	-0.007
100	HDR_L2_D11_Bias	1.210	1.217	-0.007
100	HDR_L2_D12_Bias	1.209	1.216	-0.007
100	HDR_L2_D13_Bias	1.215	1.221	-0.006
100	HDR_L2_D14_Bias	1.209	1.216	-0.007
100	HDR_L3_D7_Bias	1.208	1.215	-0.007
100	HDR_L3_D8_Bias	1.208	1.215	-0.007
100	HDR_L3_D9_Bias	1.211	1.218	-0.007
100	HDR_L3_D10_Bias	1.210	1.216	-0.006
100	HDR_L3_D11_Bias	1.210	1.217	-0.007
100	HDR_L3_D12_Bias	1.209	1.215	-0.006
100	HDR_L3_D13_Bias	1.207	1.214	-0.007
100	HDR_L3_D14_Bias	1.208	1.215	-0.007
	Max	1.217	1.221	0.002
	Average	1.210	1.215	-0.005
	Min	1.207	1.208	-0.007
	Std Dev	0.002	0.003	0.003



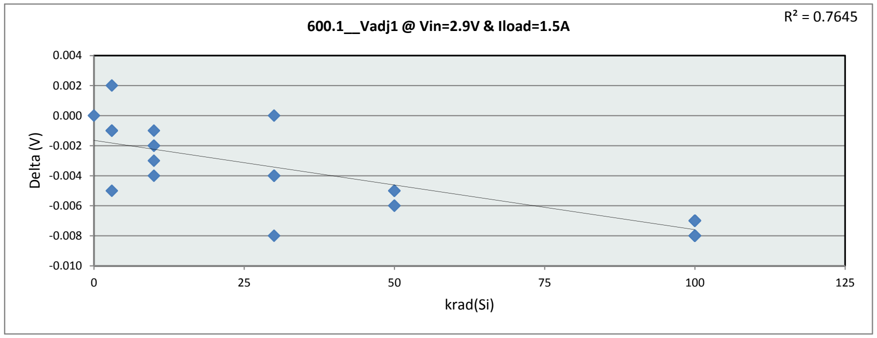
	600.0__Vadj1 @ Vin=2.9					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1.246	V				
Min Limit	1.174	V				
krad(Si)	0	3	10	30	50	100
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.210	1.208	1.210	1.210	1.213	1.214
Average	1.210	1.212	1.213	1.212	1.215	1.216
Max	1.210	1.214	1.219	1.214	1.220	1.221
UL	1.246	1.246	1.246	1.246	1.246	1.246



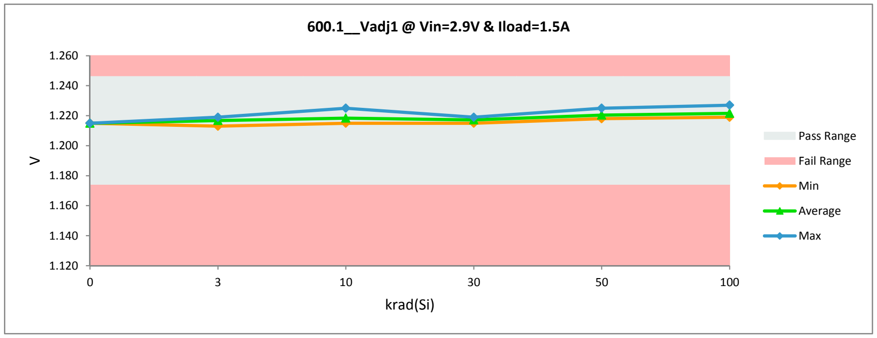
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		600.1__Vadj1 @ Vin=2.9V & Iload=1.5A		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	1.246	1.246	
	Min Limit	1.174	1.174	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	1.215	1.215	0.000
3	HDR_L1_D1_Bias	1.212	1.213	-0.001
3	HDR_L1_D2_Bias	1.214	1.219	-0.005
3	HDR_L2_D1_Bias	1.217	1.215	0.002
3	HDR_L2_D2_Bias	1.218	1.219	-0.001
3	HDR_L3_D1_Bias	1.217	1.218	-0.001
10	HDR_L1_D3_Bias	1.213	1.215	-0.002
10	HDR_L1_D4_Bias	1.214	1.217	-0.003
10	HDR_L2_D3_Bias	1.216	1.217	-0.001
10	HDR_L3_D2_Bias	1.214	1.218	-0.004
10	HDR_L3_D3_Bias	1.223	1.225	-0.002
30	HDR_L1_D5_Bias	1.213	1.217	-0.004
30	HDR_L2_D4_Bias	1.214	1.218	-0.004
30	HDR_L2_D5_Bias	1.213	1.217	-0.004
30	HDR_L3_D4_Bias	1.215	1.215	0.000
30	HDR_L3_D5_Bias	1.211	1.219	-0.008
50	HDR_L1_D6_Bias	1.212	1.218	-0.006
50	HDR_L1_D7_Bias	1.216	1.221	-0.005
50	HDR_L2_D6_Bias	1.215	1.220	-0.005
50	HDR_L2_D7_Bias	1.220	1.225	-0.005
50	HDR_L3_D6_Bias	1.212	1.218	-0.006
100	HDR_L1_D8_Bias	1.213	1.221	-0.008
100	HDR_L1_D9_Bias	1.214	1.221	-0.007
100	HDR_L1_D10_Bias	1.214	1.222	-0.008
100	HDR_L1_D11_Bias	1.214	1.222	-0.008
100	HDR_L1_D12_Bias	1.213	1.221	-0.008
100	HDR_L1_D13_Bias	1.212	1.219	-0.007
100	HDR_L1_D14_Bias	1.215	1.222	-0.007
100	HDR_L2_D8_Bias	1.215	1.223	-0.008
100	HDR_L2_D9_Bias	1.216	1.223	-0.007
100	HDR_L2_D10_Bias	1.217	1.225	-0.008
100	HDR_L2_D11_Bias	1.215	1.222	-0.007
100	HDR_L2_D12_Bias	1.214	1.221	-0.007
100	HDR_L2_D13_Bias	1.220	1.227	-0.007
100	HDR_L2_D14_Bias	1.214	1.221	-0.007
100	HDR_L3_D7_Bias	1.212	1.220	-0.008
100	HDR_L3_D8_Bias	1.212	1.220	-0.008
100	HDR_L3_D9_Bias	1.216	1.224	-0.008
100	HDR_L3_D10_Bias	1.214	1.221	-0.007
100	HDR_L3_D11_Bias	1.214	1.221	-0.007
100	HDR_L3_D12_Bias	1.213	1.220	-0.007
100	HDR_L3_D13_Bias	1.212	1.219	-0.007
100	HDR_L3_D14_Bias	1.212	1.220	-0.008
	Max	1.223	1.227	0.002
	Average	1.215	1.220	-0.005
	Min	1.211	1.213	-0.008
	Std Dev	0.002	0.003	0.003



	600.1__Vadj1 @ Vin=2.9					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1.246	V				
Min Limit	1.174	V				
krad(Si)	0	3	10	30	50	100
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.215	1.213	1.215	1.215	1.218	1.219
Average	1.215	1.217	1.218	1.217	1.220	1.222
Max	1.215	1.219	1.225	1.219	1.225	1.227
UL	1.246	1.246	1.246	1.246	1.246	1.246

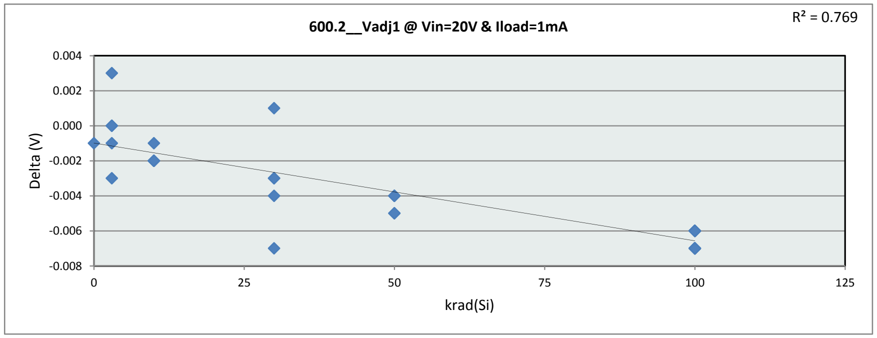


TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

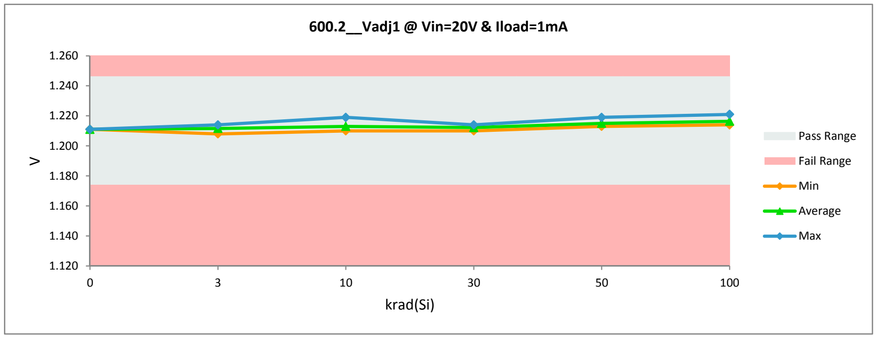
	600.2__Vadj1 @ Vin=20V & Iload=1mA	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	V	V
Max Limit	1.246	1.246
Min Limit	1.174	1.174

krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	1.210	1.211	-0.001
3	HDR_L1_D1_Bias	1.207	1.208	-0.001
3	HDR_L1_D2_Bias	1.210	1.213	-0.003
3	HDR_L2_D1_Bias	1.213	1.210	0.003
3	HDR_L2_D2_Bias	1.214	1.214	0.000
3	HDR_L3_D1_Bias	1.213	1.213	0.000
10	HDR_L1_D3_Bias	1.208	1.210	-0.002
10	HDR_L1_D4_Bias	1.210	1.212	-0.002
10	HDR_L2_D3_Bias	1.210	1.212	-0.002
10	HDR_L3_D2_Bias	1.210	1.212	-0.002
10	HDR_L3_D3_Bias	1.218	1.219	-0.001
30	HDR_L1_D5_Bias	1.209	1.212	-0.003
30	HDR_L2_D4_Bias	1.209	1.213	-0.004
30	HDR_L2_D5_Bias	1.209	1.212	-0.003
30	HDR_L3_D4_Bias	1.211	1.210	0.001
30	HDR_L3_D5_Bias	1.207	1.214	-0.007
50	HDR_L1_D6_Bias	1.208	1.213	-0.005
50	HDR_L1_D7_Bias	1.212	1.216	-0.004
50	HDR_L2_D6_Bias	1.210	1.214	-0.004
50	HDR_L2_D7_Bias	1.215	1.219	-0.004
50	HDR_L3_D6_Bias	1.208	1.213	-0.005
100	HDR_L1_D8_Bias	1.209	1.216	-0.007
100	HDR_L1_D9_Bias	1.210	1.216	-0.006
100	HDR_L1_D10_Bias	1.210	1.216	-0.006
100	HDR_L1_D11_Bias	1.210	1.217	-0.007
100	HDR_L1_D12_Bias	1.209	1.216	-0.007
100	HDR_L1_D13_Bias	1.207	1.214	-0.007
100	HDR_L1_D14_Bias	1.210	1.217	-0.007
100	HDR_L2_D8_Bias	1.211	1.217	-0.006
100	HDR_L2_D9_Bias	1.211	1.218	-0.007
100	HDR_L2_D10_Bias	1.213	1.219	-0.006
100	HDR_L2_D11_Bias	1.210	1.217	-0.007
100	HDR_L2_D12_Bias	1.210	1.216	-0.006
100	HDR_L2_D13_Bias	1.215	1.221	-0.006
100	HDR_L2_D14_Bias	1.210	1.216	-0.006
100	HDR_L3_D7_Bias	1.209	1.215	-0.006
100	HDR_L3_D8_Bias	1.208	1.215	-0.007
100	HDR_L3_D9_Bias	1.212	1.218	-0.006
100	HDR_L3_D10_Bias	1.210	1.216	-0.006
100	HDR_L3_D11_Bias	1.210	1.217	-0.007
100	HDR_L3_D12_Bias	1.209	1.215	-0.006
100	HDR_L3_D13_Bias	1.208	1.214	-0.006
100	HDR_L3_D14_Bias	1.208	1.215	-0.007
	Max	1.218	1.221	0.003
	Average	1.210	1.215	-0.004
	Min	1.207	1.208	-0.007
	Std Dev	0.002	0.003	0.003



	600.2__Vadj1 @ Vin=20	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.246	V
Min Limit	1.174	V

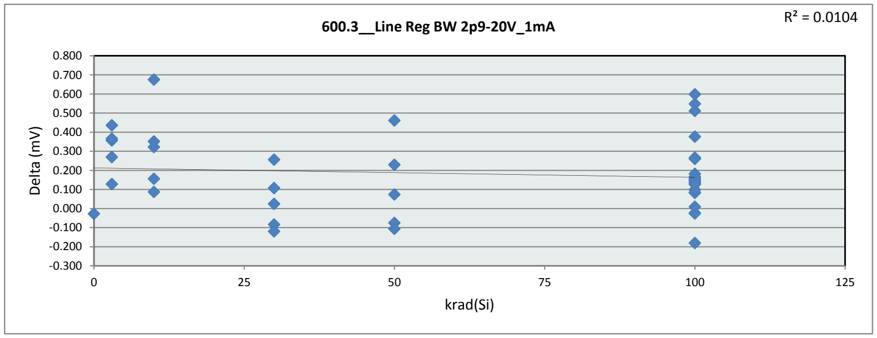
krad(Si)	0	3	10	30	50	100
LL	1.174	1.174	1.174	1.174	1.174	1.174
Min	1.211	1.208	1.210	1.210	1.213	1.214
Average	1.211	1.212	1.213	1.212	1.215	1.216
Max	1.211	1.214	1.219	1.214	1.219	1.221
UL	1.246	1.246	1.246	1.246	1.246	1.246



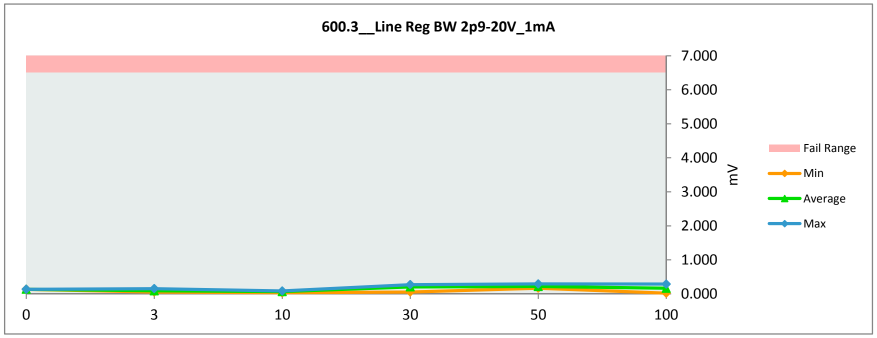
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		600.3__Line Reg BW 2p9-20V_1mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	6.5	6.5	
	Min Limit			
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	0.106	0.134	-0.028
3	HDR_L1_D1_Bias	0.210	0.082	0.128
3	HDR_L1_D2_Bias	0.412	0.056	0.356
3	HDR_L2_D1_Bias	0.351	0.082	0.269
3	HDR_L2_D2_Bias	0.590	0.154	0.436
3	HDR_L3_D1_Bias	0.440	0.075	0.365
10	HDR_L1_D3_Bias	0.171	0.084	0.087
10	HDR_L1_D4_Bias	0.372	0.050	0.322
10	HDR_L2_D3_Bias	0.188	0.033	0.155
10	HDR_L3_D2_Bias	0.434	0.083	0.351
10	HDR_L3_D3_Bias	0.761	0.086	0.675
30	HDR_L1_D5_Bias	0.188	0.272	-0.084
30	HDR_L2_D4_Bias	0.134	0.254	-0.120
30	HDR_L2_D5_Bias	0.216	0.192	0.024
30	HDR_L3_D4_Bias	0.514	0.258	0.256
30	HDR_L3_D5_Bias	0.163	0.056	0.107
50	HDR_L1_D6_Bias	0.245	0.172	0.073
50	HDR_L1_D7_Bias	0.397	0.168	0.229
50	HDR_L2_D6_Bias	0.216	0.292	-0.076
50	HDR_L2_D7_Bias	0.629	0.168	0.461
50	HDR_L3_D6_Bias	0.175	0.282	-0.107
100	HDR_L1_D8_Bias	0.279	0.148	0.131
100	HDR_L1_D9_Bias	0.286	0.202	0.084
100	HDR_L1_D10_Bias	0.346	0.195	0.151
100	HDR_L1_D11_Bias	0.353	0.197	0.156
100	HDR_L1_D12_Bias	0.354	0.173	0.181
100	HDR_L1_D13_Bias	0.300	0.153	0.147
100	HDR_L1_D14_Bias	0.409	0.143	0.266
100	HDR_L2_D8_Bias	0.199	0.223	-0.024
100	HDR_L2_D9_Bias	0.186	0.104	0.082
100	HDR_L2_D10_Bias	0.472	0.212	0.260
100	HDR_L2_D11_Bias	0.322	0.184	0.138
100	HDR_L2_D12_Bias	0.192	0.218	-0.026
100	HDR_L2_D13_Bias	0.710	0.112	0.598
100	HDR_L2_D14_Bias	0.247	0.238	0.009
100	HDR_L3_D7_Bias	0.269	0.171	0.098
100	HDR_L3_D8_Bias	0.350	0.184	0.166
100	HDR_L3_D9_Bias	0.615	0.067	0.548
100	HDR_L3_D10_Bias	0.419	0.043	0.376
100	HDR_L3_D11_Bias	0.534	0.023	0.511
100	HDR_L3_D12_Bias	0.314	0.170	0.144
100	HDR_L3_D13_Bias	0.106	0.287	-0.181
100	HDR_L3_D14_Bias	0.323	0.197	0.126
	Max	0.761	0.292	0.675
	Average	0.337	0.155	0.182
	Min	0.106	0.023	-0.181
	Std Dev	0.161	0.075	0.200



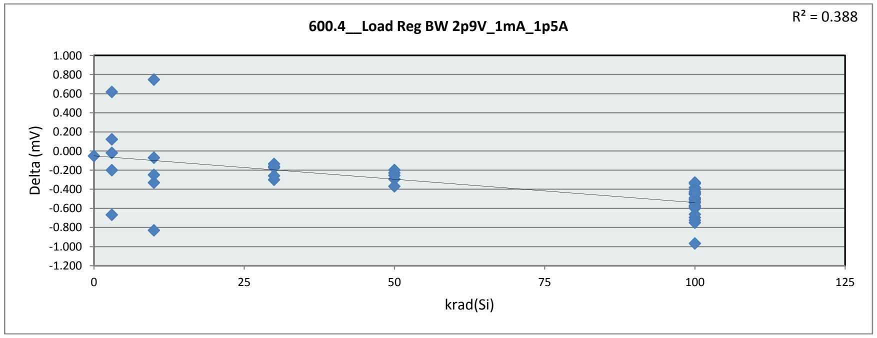
	600.3__Line Reg BW 2p9					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	6.5	mV				
Min Limit		mV				
krad(Si)	0	3	10	30	50	100
LL						
Min	0.134	0.056	0.033	0.056	0.168	0.023
Average	0.134	0.090	0.067	0.206	0.216	0.166
Max	0.134	0.154	0.086	0.272	0.292	0.287
UL	6.500	6.500	6.500	6.500	6.500	6.500



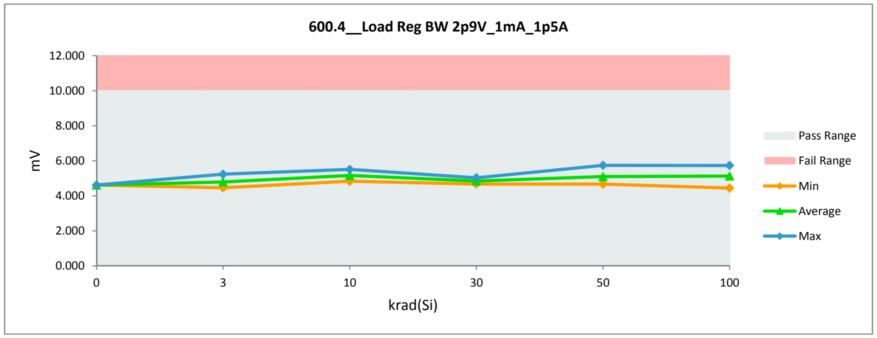
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		600.4__Load Reg BW 2p9V_1mA_1p5A		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	10	10	
	Min Limit	0	0	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	4.560	4.612	-0.052
3	HDR_L1_D1_Bias	4.620	4.640	-0.020
3	HDR_L1_D2_Bias	4.567	5.234	-0.667
3	HDR_L2_D1_Bias	5.073	4.456	0.617
3	HDR_L2_D2_Bias	4.978	4.856	0.122
3	HDR_L3_D1_Bias	4.563	4.764	-0.201
10	HDR_L1_D3_Bias	5.041	5.112	-0.071
10	HDR_L1_D4_Bias	4.580	4.912	-0.332
10	HDR_L2_D3_Bias	5.578	4.831	0.747
10	HDR_L3_D2_Bias	4.678	5.508	-0.830
10	HDR_L3_D3_Bias	5.198	5.448	-0.250
30	HDR_L1_D5_Bias	4.890	5.026	-0.136
30	HDR_L2_D4_Bias	4.855	5.029	-0.174
30	HDR_L2_D5_Bias	4.482	4.784	-0.302
30	HDR_L3_D4_Bias	4.465	4.724	-0.259
30	HDR_L3_D5_Bias	4.511	4.673	-0.162
50	HDR_L1_D6_Bias	4.628	4.827	-0.199
50	HDR_L1_D7_Bias	4.859	5.088	-0.229
50	HDR_L2_D6_Bias	4.913	5.169	-0.256
50	HDR_L2_D7_Bias	5.444	5.738	-0.294
50	HDR_L3_D6_Bias	4.297	4.666	-0.369
100	HDR_L1_D8_Bias	4.467	5.037	-0.570
100	HDR_L1_D9_Bias	4.271	4.770	-0.499
100	HDR_L1_D10_Bias	4.708	5.091	-0.383
100	HDR_L1_D11_Bias	4.572	5.539	-0.967
100	HDR_L1_D12_Bias	4.706	5.246	-0.540
100	HDR_L1_D13_Bias	4.474	4.815	-0.341
100	HDR_L1_D14_Bias	4.655	5.352	-0.697
100	HDR_L2_D8_Bias	5.070	5.733	-0.663
100	HDR_L2_D9_Bias	4.996	5.526	-0.530
100	HDR_L2_D10_Bias	4.915	5.514	-0.599
100	HDR_L2_D11_Bias	4.794	5.518	-0.724
100	HDR_L2_D12_Bias	4.520	5.105	-0.585
100	HDR_L2_D13_Bias	5.079	5.659	-0.580
100	HDR_L2_D14_Bias	4.791	5.121	-0.330
100	HDR_L3_D7_Bias	3.933	4.443	-0.510
100	HDR_L3_D8_Bias	4.470	4.872	-0.402
100	HDR_L3_D9_Bias	4.923	5.672	-0.749
100	HDR_L3_D10_Bias	4.116	4.554	-0.438
100	HDR_L3_D11_Bias	4.108	4.556	-0.448
100	HDR_L3_D12_Bias	4.318	4.771	-0.453
100	HDR_L3_D13_Bias	4.648	5.139	-0.491
100	HDR_L3_D14_Bias	4.342	4.769	-0.427
	Max	5.578	5.738	0.747
	Average	4.690	5.044	-0.354
	Min	3.933	4.443	-0.967
	Std Dev	0.340	0.370	0.326



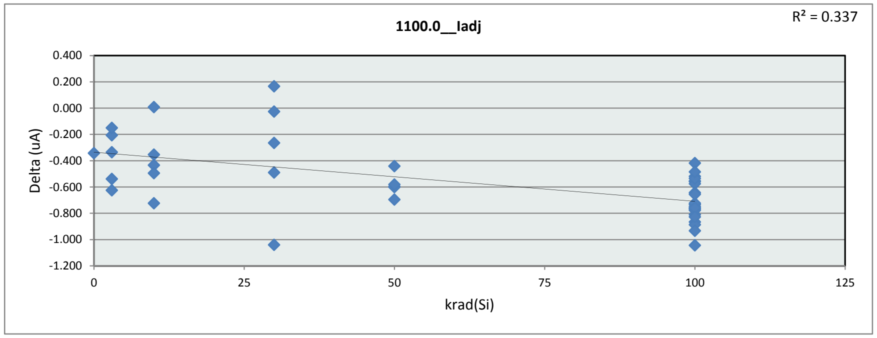
	600.4__Load Reg BW 2p					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	10	mV				
Min Limit	0	mV				
krad(Si)	0	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000	0.000
Min	4.612	4.456	4.831	4.673	4.666	4.443
Average	4.612	4.790	5.162	4.847	5.098	5.127
Max	4.612	5.234	5.508	5.029	5.738	5.733
UL	10.000	10.000	10.000	10.000	10.000	10.000



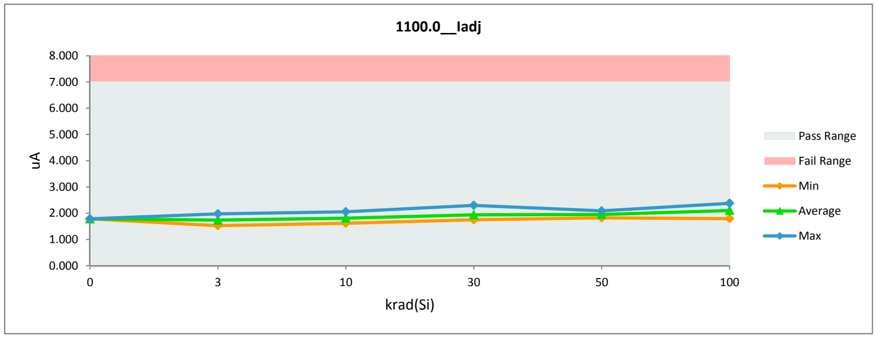
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		1100.0__Iadj		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	7	7	
	Min Limit	0	0	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	1.443	1.786	-0.343
3	HDR_L1_D1_Bias	1.480	1.816	-0.336
3	HDR_L1_D2_Bias	1.368	1.575	-0.207
3	HDR_L2_D1_Bias	1.376	1.527	-0.151
3	HDR_L2_D2_Bias	1.351	1.976	-0.625
3	HDR_L3_D1_Bias	1.251	1.790	-0.539
10	HDR_L1_D3_Bias	1.539	1.973	-0.434
10	HDR_L1_D4_Bias	1.332	2.056	-0.724
10	HDR_L2_D3_Bias	1.639	1.631	0.008
10	HDR_L3_D2_Bias	1.283	1.778	-0.495
10	HDR_L3_D3_Bias	1.265	1.619	-0.354
30	HDR_L1_D5_Bias	1.474	1.964	-0.490
30	HDR_L2_D4_Bias	1.637	1.902	-0.265
30	HDR_L2_D5_Bias	1.722	1.749	-0.027
30	HDR_L3_D4_Bias	1.260	2.300	-1.040
30	HDR_L3_D5_Bias	1.951	1.785	0.166
50	HDR_L1_D6_Bias	1.381	1.823	-0.442
50	HDR_L1_D7_Bias	1.336	1.934	-0.598
50	HDR_L2_D6_Bias	1.392	2.088	-0.696
50	HDR_L2_D7_Bias	1.354	1.955	-0.601
50	HDR_L3_D6_Bias	1.378	1.960	-0.582
100	HDR_L1_D8_Bias	1.431	2.165	-0.734
100	HDR_L1_D9_Bias	1.509	2.319	-0.810
100	HDR_L1_D10_Bias	1.418	2.168	-0.750
100	HDR_L1_D11_Bias	1.435	1.990	-0.555
100	HDR_L1_D12_Bias	1.373	2.142	-0.769
100	HDR_L1_D13_Bias	1.621	2.040	-0.419
100	HDR_L1_D14_Bias	1.333	2.377	-1.044
100	HDR_L2_D8_Bias	1.417	1.975	-0.558
100	HDR_L2_D9_Bias	1.382	2.248	-0.866
100	HDR_L2_D10_Bias	1.424	2.148	-0.724
100	HDR_L2_D11_Bias	1.367	1.886	-0.519
100	HDR_L2_D12_Bias	1.404	1.979	-0.575
100	HDR_L2_D13_Bias	1.353	2.240	-0.887
100	HDR_L2_D14_Bias	1.541	2.303	-0.762
100	HDR_L3_D7_Bias	1.556	2.200	-0.644
100	HDR_L3_D8_Bias	1.261	2.195	-0.934
100	HDR_L3_D9_Bias	1.258	1.793	-0.535
100	HDR_L3_D10_Bias	1.339	1.995	-0.656
100	HDR_L3_D11_Bias	1.245	2.022	-0.777
100	HDR_L3_D12_Bias	1.269	2.028	-0.759
100	HDR_L3_D13_Bias	1.519	2.004	-0.485
100	HDR_L3_D14_Bias	1.267	2.095	-0.828
	Max	1.951	2.377	0.166
	Average	1.417	1.984	-0.567
	Min	1.245	1.527	-1.044
	Std Dev	0.143	0.207	0.267



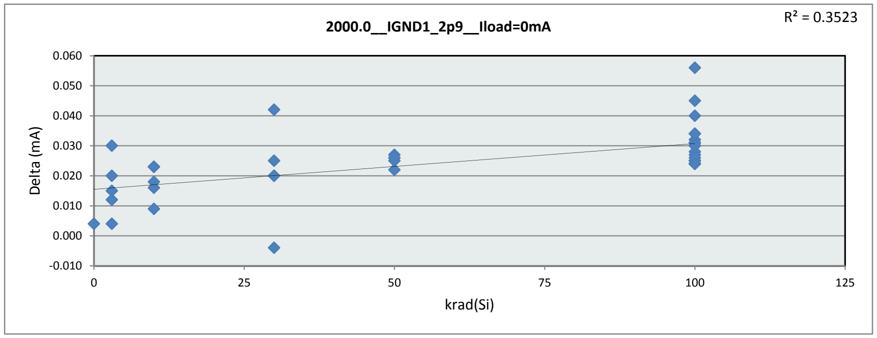
	1100.0__Iadj					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	7	uA				
Min Limit	0	uA				
krad(Si)	0	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000	0.000
Min	1.786	1.527	1.619	1.749	1.823	1.793
Average	1.786	1.737	1.811	1.940	1.952	2.105
Max	1.786	1.976	2.056	2.300	2.088	2.377
UL	7.000	7.000	7.000	7.000	7.000	7.000



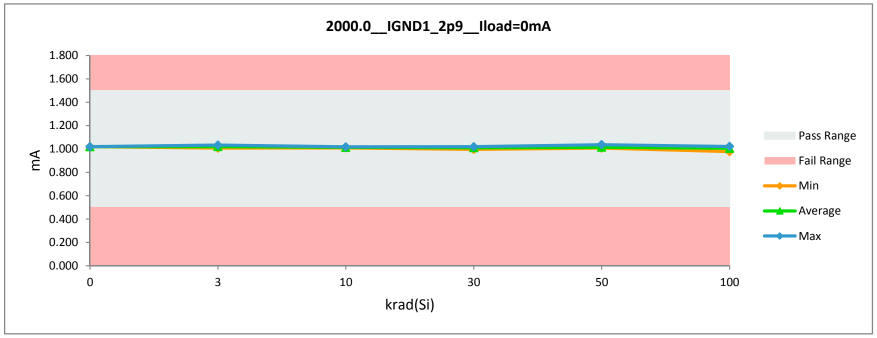
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2000.0__IGND1_2p9__Iload=0mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	1.5	1.5	
	Min Limit	0.5	0.5	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	1.023	1.019	0.004
3	HDR_L1_D1_Bias	1.027	1.007	0.020
3	HDR_L1_D2_Bias	1.047	1.017	0.030
3	HDR_L2_D1_Bias	1.037	1.033	0.004
3	HDR_L2_D2_Bias	1.044	1.029	0.015
3	HDR_L3_D1_Bias	1.025	1.013	0.012
10	HDR_L1_D3_Bias	1.031	1.013	0.018
10	HDR_L1_D4_Bias	1.036	1.013	0.023
10	HDR_L2_D3_Bias	1.032	1.009	0.023
10	HDR_L3_D2_Bias	1.027	1.018	0.009
10	HDR_L3_D3_Bias	1.033	1.017	0.016
30	HDR_L1_D5_Bias	1.025	1.005	0.020
30	HDR_L2_D4_Bias	1.036	1.016	0.020
30	HDR_L2_D5_Bias	1.040	1.015	0.025
30	HDR_L3_D4_Bias	1.038	0.996	0.042
30	HDR_L3_D5_Bias	1.015	1.019	-0.004
50	HDR_L1_D6_Bias	1.034	1.007	0.027
50	HDR_L1_D7_Bias	1.034	1.008	0.026
50	HDR_L2_D6_Bias	1.032	1.007	0.025
50	HDR_L2_D7_Bias	1.036	1.014	0.022
50	HDR_L3_D6_Bias	1.062	1.036	0.026
100	HDR_L1_D8_Bias	1.041	1.001	0.040
100	HDR_L1_D9_Bias	1.036	1.012	0.024
100	HDR_L1_D10_Bias	1.045	1.021	0.024
100	HDR_L1_D11_Bias	1.053	1.021	0.032
100	HDR_L1_D12_Bias	1.043	1.012	0.031
100	HDR_L1_D13_Bias	1.032	1.004	0.028
100	HDR_L1_D14_Bias	1.035	1.010	0.025
100	HDR_L2_D8_Bias	1.038	1.004	0.034
100	HDR_L2_D9_Bias	1.033	0.977	0.056
100	HDR_L2_D10_Bias	1.036	1.011	0.025
100	HDR_L2_D11_Bias	1.041	1.010	0.031
100	HDR_L2_D12_Bias	1.034	1.004	0.030
100	HDR_L2_D13_Bias	1.033	1.006	0.027
100	HDR_L2_D14_Bias	1.033	1.008	0.025
100	HDR_L3_D7_Bias	1.039	1.005	0.034
100	HDR_L3_D8_Bias	1.019	0.988	0.031
100	HDR_L3_D9_Bias	1.029	0.984	0.045
100	HDR_L3_D10_Bias	1.038	1.012	0.026
100	HDR_L3_D11_Bias	1.040	1.010	0.030
100	HDR_L3_D12_Bias	1.038	1.014	0.024
100	HDR_L3_D13_Bias	1.024	1.000	0.024
100	HDR_L3_D14_Bias	1.024	1.000	0.024
	Max	1.062	1.036	0.056
	Average	1.035	1.010	0.025
	Min	1.015	0.977	-0.004
	Std Dev	0.009	0.011	0.011



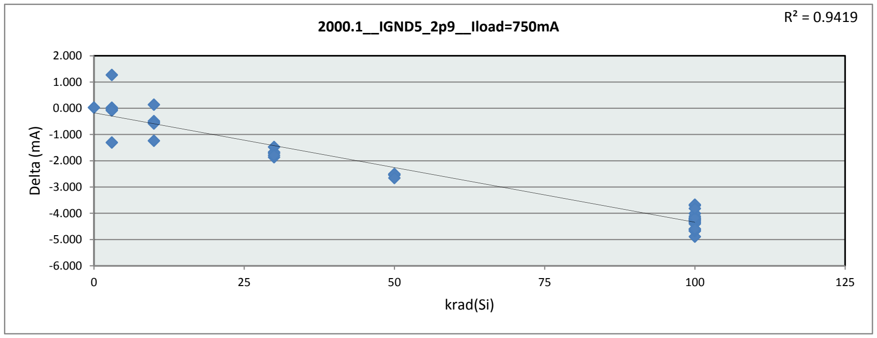
	2000.0__IGND1_2p9__I					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1.5	mA				
Min Limit	0.5	mA				
krad(Si)	0	3	10	30	50	100
LL	0.500	0.500	0.500	0.500	0.500	0.500
Min	1.019	1.007	1.009	0.996	1.007	0.977
Average	1.019	1.020	1.014	1.010	1.014	1.005
Max	1.019	1.033	1.018	1.019	1.036	1.021
UL	1.500	1.500	1.500	1.500	1.500	1.500



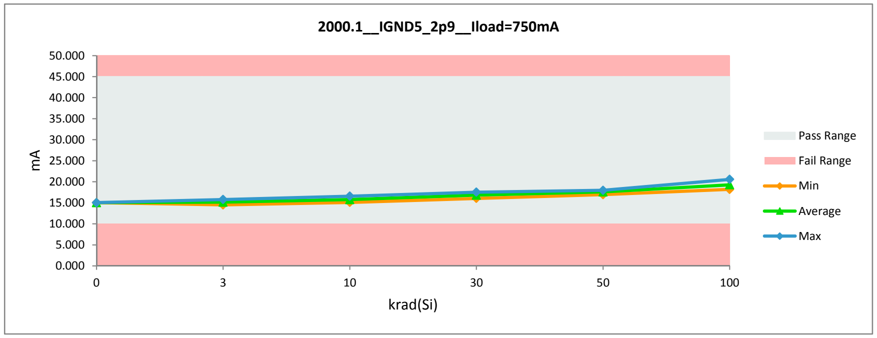
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2000.1__IGND5_2p9__Iload=750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	45	45	
	Min Limit	10	10	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	15.056	15.032	0.024
3	HDR_L1_D1_Bias	14.652	14.693	-0.041
3	HDR_L1_D2_Bias	14.462	15.770	-1.308
3	HDR_L2_D1_Bias	15.767	14.501	1.266
3	HDR_L2_D2_Bias	15.310	15.290	0.020
3	HDR_L3_D1_Bias	15.375	15.458	-0.083
10	HDR_L1_D3_Bias	14.561	15.100	-0.539
10	HDR_L1_D4_Bias	14.741	15.234	-0.493
10	HDR_L2_D3_Bias	16.049	15.917	0.132
10	HDR_L3_D2_Bias	15.340	16.582	-1.242
10	HDR_L3_D3_Bias	15.342	15.928	-0.586
30	HDR_L1_D5_Bias	14.747	16.461	-1.714
30	HDR_L2_D4_Bias	15.862	17.534	-1.672
30	HDR_L2_D5_Bias	14.571	16.047	-1.476
30	HDR_L3_D4_Bias	15.189	17.058	-1.869
30	HDR_L3_D5_Bias	15.200	16.992	-1.792
50	HDR_L1_D6_Bias	14.439	16.945	-2.506
50	HDR_L1_D7_Bias	14.832	17.382	-2.550
50	HDR_L2_D6_Bias	15.259	17.776	-2.517
50	HDR_L2_D7_Bias	15.442	17.969	-2.527
50	HDR_L3_D6_Bias	15.152	17.809	-2.657
100	HDR_L1_D8_Bias	14.537	18.820	-4.283
100	HDR_L1_D9_Bias	14.482	18.190	-3.708
100	HDR_L1_D10_Bias	14.581	18.255	-3.674
100	HDR_L1_D11_Bias	14.451	18.654	-4.203
100	HDR_L1_D12_Bias	14.521	18.810	-4.289
100	HDR_L1_D13_Bias	14.541	18.661	-4.120
100	HDR_L1_D14_Bias	14.851	19.084	-4.233
100	HDR_L2_D8_Bias	16.160	20.566	-4.406
100	HDR_L2_D9_Bias	15.421	19.778	-4.357
100	HDR_L2_D10_Bias	15.303	19.640	-4.337
100	HDR_L2_D11_Bias	15.373	19.608	-4.235
100	HDR_L2_D12_Bias	15.041	19.234	-4.193
100	HDR_L2_D13_Bias	15.285	19.527	-4.242
100	HDR_L2_D14_Bias	14.792	18.804	-4.012
100	HDR_L3_D7_Bias	15.001	19.605	-4.604
100	HDR_L3_D8_Bias	15.344	20.238	-4.894
100	HDR_L3_D9_Bias	15.237	19.919	-4.682
100	HDR_L3_D10_Bias	14.362	18.542	-4.180
100	HDR_L3_D11_Bias	15.003	19.621	-4.618
100	HDR_L3_D12_Bias	15.074	18.893	-3.819
100	HDR_L3_D13_Bias	15.359	20.035	-4.676
100	HDR_L3_D14_Bias	15.076	19.677	-4.601
	Max	16.160	20.566	1.266
	Average	15.050	17.806	-2.756
	Min	14.362	14.501	-4.894
	Std Dev	0.448	1.764	1.781



	2000.1__IGND5_2p9__I					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	45	mA				
Min Limit	10	mA				
krad(Si)	0	3	10	30	50	100
LL	10.000	10.000	10.000	10.000	10.000	10.000
Min	15.032	14.501	15.100	16.047	16.945	18.190
Average	15.032	15.142	15.752	16.818	17.576	19.280
Max	15.032	15.770	16.582	17.534	17.969	20.566
UL	45.000	45.000	45.000	45.000	45.000	45.000

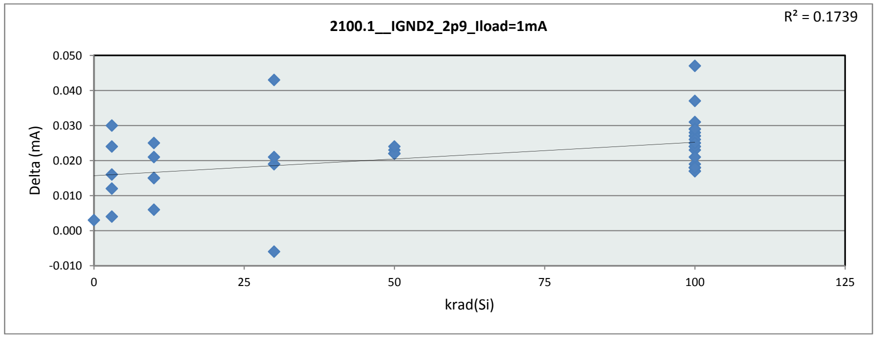


TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

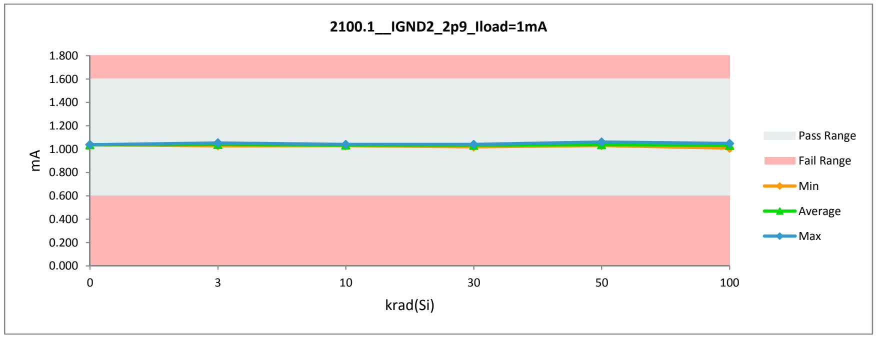
All units passed SMD specification limits up to 100kRAD HDR.

	2100.1__IGND2_2p9_Iload=1mA	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	mA	mA
Max Limit	1.6	1.6
Min Limit	0.6	0.6

krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	1.041	1.038	0.003
3	HDR_L1_D1_Bias	1.052	1.028	0.024
3	HDR_L1_D2_Bias	1.068	1.038	0.030
3	HDR_L2_D1_Bias	1.057	1.053	0.004
3	HDR_L2_D2_Bias	1.064	1.048	0.016
3	HDR_L3_D1_Bias	1.044	1.032	0.012
10	HDR_L1_D3_Bias	1.049	1.034	0.015
10	HDR_L1_D4_Bias	1.056	1.035	0.021
10	HDR_L2_D3_Bias	1.054	1.029	0.025
10	HDR_L3_D2_Bias	1.046	1.040	0.006
10	HDR_L3_D3_Bias	1.051	1.036	0.015
30	HDR_L1_D5_Bias	1.049	1.030	0.019
30	HDR_L2_D4_Bias	1.056	1.037	0.019
30	HDR_L2_D5_Bias	1.060	1.039	0.021
30	HDR_L3_D4_Bias	1.062	1.019	0.043
30	HDR_L3_D5_Bias	1.034	1.040	-0.006
50	HDR_L1_D6_Bias	1.054	1.031	0.023
50	HDR_L1_D7_Bias	1.054	1.032	0.022
50	HDR_L2_D6_Bias	1.053	1.031	0.022
50	HDR_L2_D7_Bias	1.059	1.037	0.022
50	HDR_L3_D6_Bias	1.084	1.060	0.024
100	HDR_L1_D8_Bias	1.060	1.029	0.031
100	HDR_L1_D9_Bias	1.062	1.037	0.025
100	HDR_L1_D10_Bias	1.066	1.048	0.018
100	HDR_L1_D11_Bias	1.074	1.047	0.027
100	HDR_L1_D12_Bias	1.067	1.039	0.028
100	HDR_L1_D13_Bias	1.054	1.030	0.024
100	HDR_L1_D14_Bias	1.055	1.038	0.017
100	HDR_L2_D8_Bias	1.058	1.031	0.027
100	HDR_L2_D9_Bias	1.055	1.008	0.047
100	HDR_L2_D10_Bias	1.059	1.036	0.023
100	HDR_L2_D11_Bias	1.060	1.036	0.024
100	HDR_L2_D12_Bias	1.057	1.031	0.026
100	HDR_L2_D13_Bias	1.052	1.035	0.017
100	HDR_L2_D14_Bias	1.052	1.033	0.019
100	HDR_L3_D7_Bias	1.061	1.032	0.029
100	HDR_L3_D8_Bias	1.040	1.015	0.025
100	HDR_L3_D9_Bias	1.049	1.012	0.037
100	HDR_L3_D10_Bias	1.058	1.037	0.021
100	HDR_L3_D11_Bias	1.065	1.036	0.029
100	HDR_L3_D12_Bias	1.057	1.039	0.018
100	HDR_L3_D13_Bias	1.043	1.025	0.018
100	HDR_L3_D14_Bias	1.043	1.025	0.018
	Max	1.084	1.060	0.047
	Average	1.056	1.034	0.022
	Min	1.034	1.008	-0.006
	Std Dev	0.009	0.010	0.009



	2100.1__IGND2_2p9_Ilo					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1.6	mA				
Min Limit	0.6	mA				
krad(Si)	0	3	10	30	50	100
LL	0.600	0.600	0.600	0.600	0.600	0.600
Min	1.038	1.028	1.029	1.019	1.031	1.008
Average	1.038	1.040	1.035	1.033	1.038	1.032
Max	1.038	1.053	1.040	1.040	1.060	1.048
UL	1.600	1.600	1.600	1.600	1.600	1.600

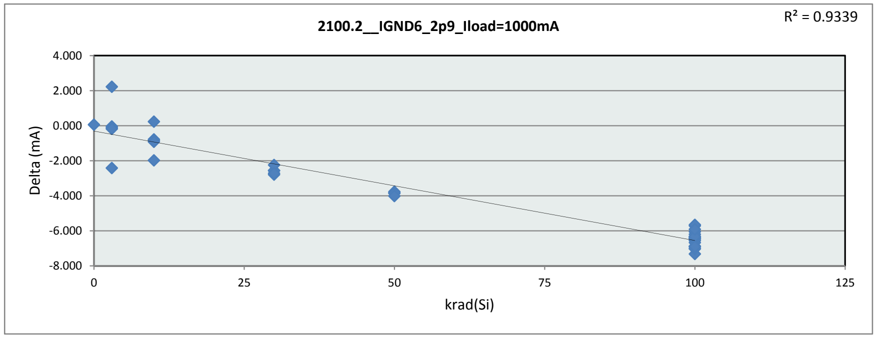


TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

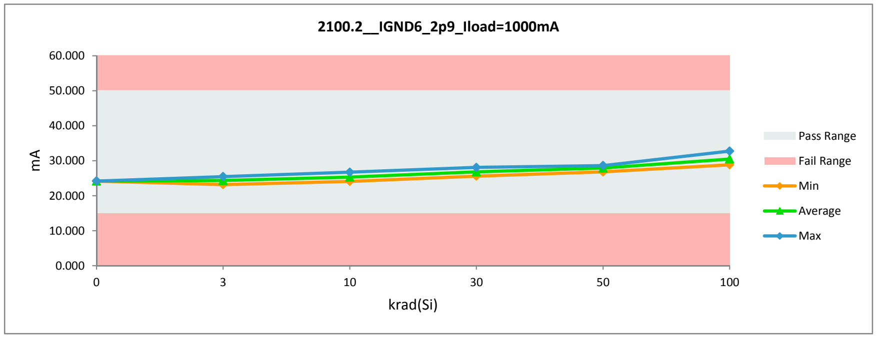
	2100.2__IGND6_2p9_Iload=1000mA	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	mA	mA
Max Limit	50	50
Min Limit	15	15

krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	24.242	24.188	0.054
3	HDR_L1_D1_Bias	23.411	23.534	-0.123
3	HDR_L1_D2_Bias	23.038	25.463	-2.425
3	HDR_L2_D1_Bias	25.392	23.178	2.214
3	HDR_L2_D2_Bias	24.523	24.575	-0.052
3	HDR_L3_D1_Bias	24.723	24.908	-0.185
10	HDR_L1_D3_Bias	23.237	24.088	-0.851
10	HDR_L1_D4_Bias	23.642	24.428	-0.786
10	HDR_L2_D3_Bias	25.856	25.627	0.229
10	HDR_L3_D2_Bias	24.727	26.715	-1.988
10	HDR_L3_D3_Bias	24.717	25.645	-0.928
30	HDR_L1_D5_Bias	23.550	26.129	-2.579
30	HDR_L2_D4_Bias	25.537	28.095	-2.558
30	HDR_L2_D5_Bias	23.335	25.587	-2.252
30	HDR_L3_D4_Bias	24.345	27.137	-2.792
30	HDR_L3_D5_Bias	24.337	27.060	-2.723
50	HDR_L1_D6_Bias	23.037	26.812	-3.775
50	HDR_L1_D7_Bias	23.744	27.607	-3.863
50	HDR_L2_D6_Bias	24.406	28.225	-3.819
50	HDR_L2_D7_Bias	24.762	28.616	-3.854
50	HDR_L3_D6_Bias	24.261	28.276	-4.015
100	HDR_L1_D8_Bias	23.183	29.613	-6.430
100	HDR_L1_D9_Bias	23.125	28.844	-5.719
100	HDR_L1_D10_Bias	23.218	28.879	-5.661
100	HDR_L1_D11_Bias	23.005	29.338	-6.333
100	HDR_L1_D12_Bias	23.151	29.602	-6.451
100	HDR_L1_D13_Bias	23.234	29.437	-6.203
100	HDR_L1_D14_Bias	23.784	30.185	-6.401
100	HDR_L2_D8_Bias	26.063	32.741	-6.678
100	HDR_L2_D9_Bias	24.685	31.217	-6.532
100	HDR_L2_D10_Bias	24.483	31.040	-6.557
100	HDR_L2_D11_Bias	24.703	31.111	-6.408
100	HDR_L2_D12_Bias	24.158	30.497	-6.339
100	HDR_L2_D13_Bias	24.486	30.912	-6.426
100	HDR_L2_D14_Bias	23.662	29.716	-6.054
100	HDR_L3_D7_Bias	24.044	30.922	-6.878
100	HDR_L3_D8_Bias	24.622	31.949	-7.327
100	HDR_L3_D9_Bias	24.398	31.410	-7.012
100	HDR_L3_D10_Bias	23.201	29.528	-6.327
100	HDR_L3_D11_Bias	24.035	30.961	-6.926
100	HDR_L3_D12_Bias	24.136	30.058	-5.922
100	HDR_L3_D13_Bias	24.660	31.688	-7.028
100	HDR_L3_D14_Bias	24.195	31.101	-6.906
	Max	26.063	32.741	2.214
	Average	24.118	28.294	-4.176
	Min	23.005	23.178	-7.327
	Std Dev	0.781	2.649	2.683



	2100.2__IGND6_2p9_Il	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	50	mA
Min Limit	15	mA

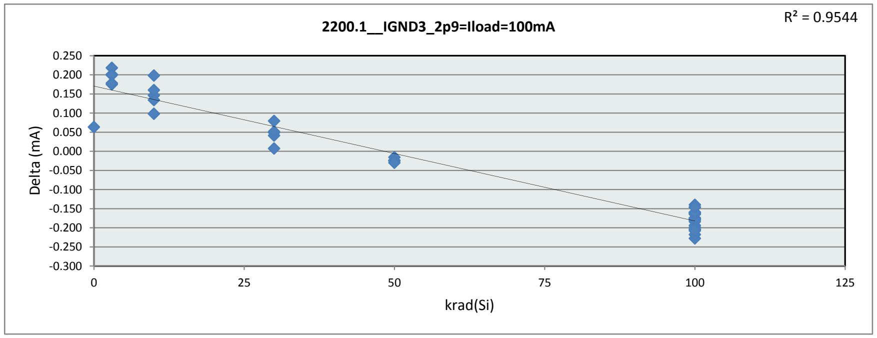
krad(Si)	0	3	10	30	50	100
LL	15.000	15.000	15.000	15.000	15.000	15.000
Min	24.188	23.178	24.088	25.587	26.812	28.844
Average	24.188	24.332	25.301	26.802	27.907	30.489
Max	24.188	25.463	26.715	28.095	28.616	32.741
UL	50.000	50.000	50.000	50.000	50.000	50.000



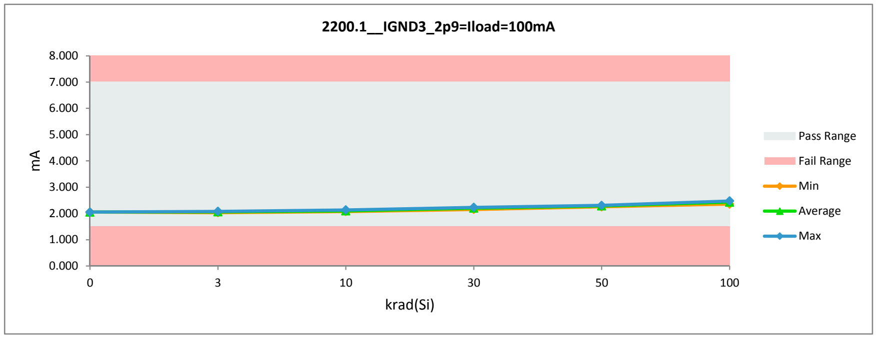
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2200.1__IGND3_2p9=Iload=100mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	7	7	
	Min Limit	1.5	1.5	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	2.113	2.050	0.063
3	HDR_L1_D1_Bias	2.231	2.030	0.201
3	HDR_L1_D2_Bias	2.250	2.075	0.175
3	HDR_L2_D1_Bias	2.275	2.057	0.218
3	HDR_L2_D2_Bias	2.279	2.080	0.199
3	HDR_L3_D1_Bias	2.233	2.055	0.178
10	HDR_L1_D3_Bias	2.230	2.084	0.146
10	HDR_L1_D4_Bias	2.231	2.071	0.160
10	HDR_L2_D3_Bias	2.284	2.086	0.198
10	HDR_L3_D2_Bias	2.231	2.133	0.098
10	HDR_L3_D3_Bias	2.237	2.103	0.134
30	HDR_L1_D5_Bias	2.236	2.195	0.041
30	HDR_L2_D4_Bias	2.281	2.232	0.049
30	HDR_L2_D5_Bias	2.232	2.153	0.079
30	HDR_L3_D4_Bias	2.249	2.198	0.051
30	HDR_L3_D5_Bias	2.227	2.220	0.007
50	HDR_L1_D6_Bias	2.226	2.251	-0.025
50	HDR_L1_D7_Bias	2.251	2.275	-0.024
50	HDR_L2_D6_Bias	2.272	2.288	-0.016
50	HDR_L2_D7_Bias	2.277	2.302	-0.025
50	HDR_L3_D6_Bias	2.278	2.308	-0.030
100	HDR_L1_D8_Bias	2.242	2.422	-0.180
100	HDR_L1_D9_Bias	2.235	2.375	-0.140
100	HDR_L1_D10_Bias	2.253	2.399	-0.146
100	HDR_L1_D11_Bias	2.261	2.438	-0.177
100	HDR_L1_D12_Bias	2.254	2.433	-0.179
100	HDR_L1_D13_Bias	2.229	2.404	-0.175
100	HDR_L1_D14_Bias	2.245	2.429	-0.184
100	HDR_L2_D8_Bias	2.298	2.473	-0.175
100	HDR_L2_D9_Bias	2.277	2.442	-0.165
100	HDR_L2_D10_Bias	2.272	2.466	-0.194
100	HDR_L2_D11_Bias	2.264	2.426	-0.162
100	HDR_L2_D12_Bias	2.242	2.402	-0.160
100	HDR_L2_D13_Bias	2.267	2.444	-0.177
100	HDR_L2_D14_Bias	2.240	2.404	-0.164
100	HDR_L3_D7_Bias	2.242	2.446	-0.204
100	HDR_L3_D8_Bias	2.240	2.468	-0.228
100	HDR_L3_D9_Bias	2.250	2.449	-0.199
100	HDR_L3_D10_Bias	2.194	2.354	-0.160
100	HDR_L3_D11_Bias	2.250	2.454	-0.204
100	HDR_L3_D12_Bias	2.253	2.400	-0.147
100	HDR_L3_D13_Bias	2.243	2.461	-0.218
100	HDR_L3_D14_Bias	2.228	2.436	-0.208
	Max	2.298	2.473	0.218
	Average	2.247	2.295	-0.048
	Min	2.113	2.030	-0.228
	Std Dev	0.029	0.155	0.150



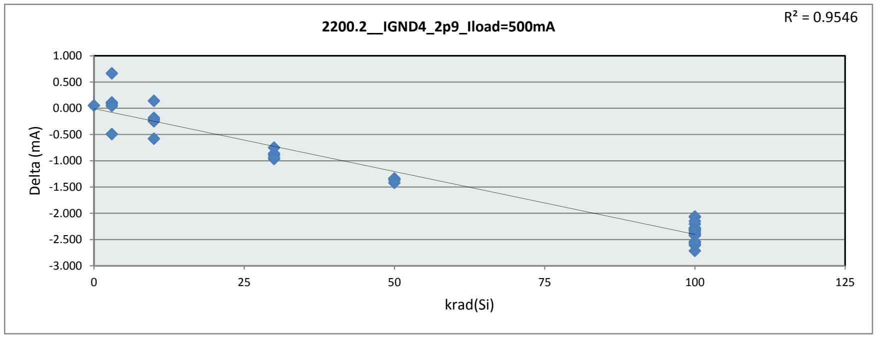
	2200.1__IGND3_2p9=Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	7	mA				
Min Limit	1.5	mA				
krad(Si)	0	3	10	30	50	100
LL	1.500	1.500	1.500	1.500	1.500	1.500
Min	2.050	2.030	2.071	2.153	2.251	2.354
Average	2.050	2.059	2.095	2.200	2.285	2.428
Max	2.050	2.080	2.133	2.232	2.308	2.473
UL	7.000	7.000	7.000	7.000	7.000	7.000



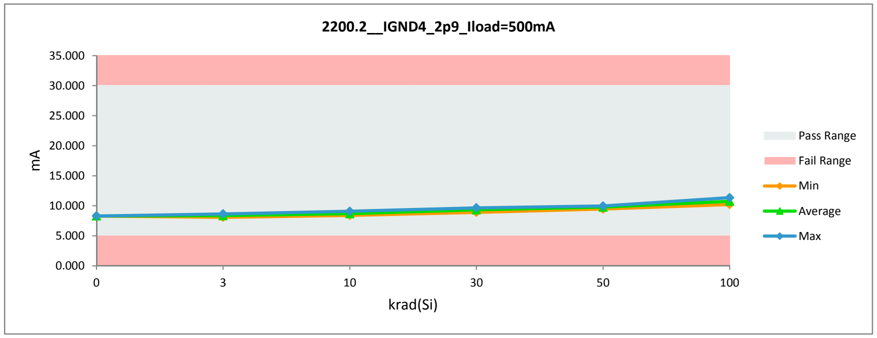
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2200.2__IGND4_2p9_Iload=500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	5	5	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	8.347	8.296	0.051
3	HDR_L1_D1_Bias	8.227	8.144	0.083
3	HDR_L1_D2_Bias	8.160	8.651	-0.491
3	HDR_L2_D1_Bias	8.746	8.083	0.663
3	HDR_L2_D2_Bias	8.555	8.445	0.110
3	HDR_L3_D1_Bias	8.541	8.499	0.042
10	HDR_L1_D3_Bias	8.187	8.403	-0.216
10	HDR_L1_D4_Bias	8.238	8.423	-0.185
10	HDR_L2_D3_Bias	8.885	8.744	0.141
10	HDR_L3_D2_Bias	8.506	9.088	-0.582
10	HDR_L3_D3_Bias	8.523	8.771	-0.248
30	HDR_L1_D5_Bias	8.284	9.178	-0.894
30	HDR_L2_D4_Bias	8.792	9.657	-0.865
30	HDR_L2_D5_Bias	8.165	8.915	-0.750
30	HDR_L3_D4_Bias	8.482	9.448	-0.966
30	HDR_L3_D5_Bias	8.479	9.422	-0.943
50	HDR_L1_D6_Bias	8.119	9.459	-1.340
50	HDR_L1_D7_Bias	8.310	9.680	-1.370
50	HDR_L2_D6_Bias	8.538	9.877	-1.339
50	HDR_L2_D7_Bias	8.619	9.963	-1.344
50	HDR_L3_D6_Bias	8.475	9.896	-1.421
100	HDR_L1_D8_Bias	8.180	10.567	-2.387
100	HDR_L1_D9_Bias	8.147	10.218	-2.071
100	HDR_L1_D10_Bias	8.220	10.284	-2.064
100	HDR_L1_D11_Bias	8.164	10.493	-2.329
100	HDR_L1_D12_Bias	8.188	10.565	-2.377
100	HDR_L1_D13_Bias	8.161	10.439	-2.278
100	HDR_L1_D14_Bias	8.311	10.651	-2.340
100	HDR_L2_D8_Bias	8.929	11.353	-2.424
100	HDR_L2_D9_Bias	8.613	11.035	-2.422
100	HDR_L2_D10_Bias	8.563	10.955	-2.392
100	HDR_L2_D11_Bias	8.544	10.866	-2.322
100	HDR_L2_D12_Bias	8.382	10.684	-2.302
100	HDR_L2_D13_Bias	8.540	10.870	-2.330
100	HDR_L2_D14_Bias	8.292	10.499	-2.207
100	HDR_L3_D7_Bias	8.382	10.927	-2.545
100	HDR_L3_D8_Bias	8.546	11.262	-2.716
100	HDR_L3_D9_Bias	8.504	11.113	-2.609
100	HDR_L3_D10_Bias	7.999	10.283	-2.284
100	HDR_L3_D11_Bias	8.390	10.944	-2.554
100	HDR_L3_D12_Bias	8.426	10.578	-2.152
100	HDR_L3_D13_Bias	8.542	11.124	-2.582
100	HDR_L3_D14_Bias	8.399	10.939	-2.540
	Max	8.929	11.353	0.663
	Average	8.409	9.900	-1.490
	Min	7.999	8.083	-2.716
	Std Dev	0.213	1.010	1.018



	2200.2__IGND4_2p9_Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	30	mA				
Min Limit	5	mA				
krad(Si)	0	3	10	30	50	100
LL	5.000	5.000	5.000	5.000	5.000	5.000
Min	8.296	8.083	8.403	8.915	9.459	10.218
Average	8.296	8.364	8.686	9.324	9.775	10.757
Max	8.296	8.651	9.088	9.657	9.963	11.353
UL	30.000	30.000	30.000	30.000	30.000	30.000

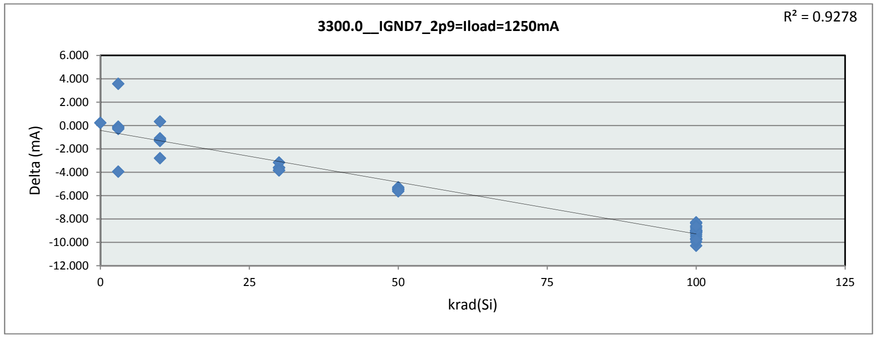


TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

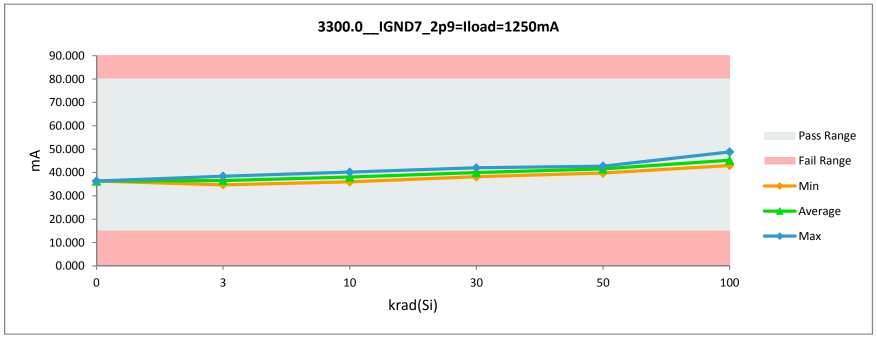
	3300.0__IGND7_2p9=Iload=1250mA	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	mA	mA
Max Limit	80	80
Min Limit	15	15

krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	36.541	36.314	0.227
3	HDR_L1_D1_Bias	35.014	35.192	-0.178
3	HDR_L1_D2_Bias	34.431	38.384	-3.953
3	HDR_L2_D1_Bias	38.261	34.686	3.575
3	HDR_L2_D2_Bias	36.821	36.925	-0.104
3	HDR_L3_D1_Bias	37.276	37.571	-0.295
10	HDR_L1_D3_Bias	34.733	35.960	-1.227
10	HDR_L1_D4_Bias	35.507	36.605	-1.098
10	HDR_L2_D3_Bias	38.934	38.597	0.337
10	HDR_L3_D2_Bias	37.364	40.155	-2.791
10	HDR_L3_D3_Bias	37.380	38.698	-1.318
30	HDR_L1_D5_Bias	35.215	38.842	-3.627
30	HDR_L2_D4_Bias	38.398	41.987	-3.589
30	HDR_L2_D5_Bias	34.998	38.162	-3.164
30	HDR_L3_D4_Bias	36.572	40.407	-3.835
30	HDR_L3_D5_Bias	36.497	40.332	-3.835
50	HDR_L1_D6_Bias	34.448	39.734	-5.286
50	HDR_L1_D7_Bias	35.620	41.090	-5.470
50	HDR_L2_D6_Bias	36.539	41.940	-5.401
50	HDR_L2_D7_Bias	37.200	42.703	-5.503
50	HDR_L3_D6_Bias	36.391	42.028	-5.637
100	HDR_L1_D8_Bias	34.666	43.640	-8.974
100	HDR_L1_D9_Bias	34.601	42.975	-8.374
100	HDR_L1_D10_Bias	34.687	42.970	-8.283
100	HDR_L1_D11_Bias	34.356	43.300	-8.944
100	HDR_L1_D12_Bias	34.606	43.669	-9.063
100	HDR_L1_D13_Bias	34.763	43.526	-8.763
100	HDR_L1_D14_Bias	35.666	44.783	-9.117
100	HDR_L2_D8_Bias	39.294	48.776	-9.482
100	HDR_L2_D9_Bias	36.972	46.057	-9.085
100	HDR_L2_D10_Bias	36.679	46.008	-9.329
100	HDR_L2_D11_Bias	37.169	46.290	-9.121
100	HDR_L2_D12_Bias	36.320	45.312	-8.992
100	HDR_L2_D13_Bias	36.779	45.965	-9.186
100	HDR_L2_D14_Bias	35.393	44.000	-8.607
100	HDR_L3_D7_Bias	36.096	45.752	-9.656
100	HDR_L3_D8_Bias	36.952	47.243	-10.291
100	HDR_L3_D9_Bias	36.652	46.367	-9.715
100	HDR_L3_D10_Bias	35.245	44.261	-9.016
100	HDR_L3_D11_Bias	36.072	45.806	-9.734
100	HDR_L3_D12_Bias	36.212	44.848	-8.636
100	HDR_L3_D13_Bias	37.031	46.991	-9.960
100	HDR_L3_D14_Bias	36.351	46.116	-9.765
	Max	39.294	48.776	3.575
	Average	36.202	42.116	-5.913
	Min	34.356	34.686	-10.291
	Std Dev	1.250	3.763	3.823



	3300.0__IGND7_2p9=Il	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	80	mA
Min Limit	15	mA

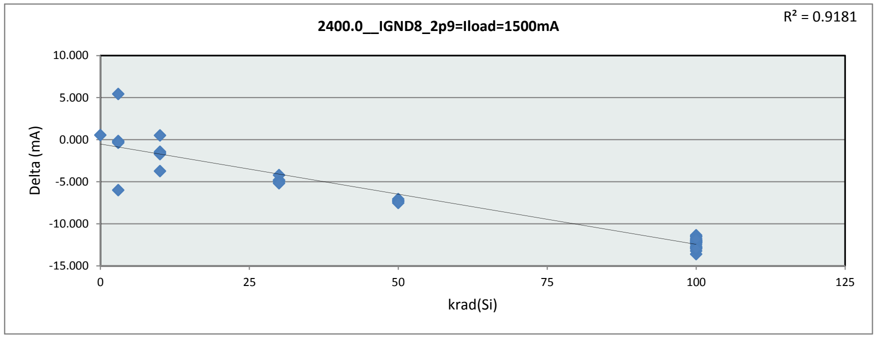
krad(Si)	0	3	10	30	50	100
LL	15.000	15.000	15.000	15.000	15.000	15.000
Min	36.314	34.686	35.960	38.162	39.734	42.970
Average	36.314	36.552	38.003	39.946	41.499	45.212
Max	36.314	38.384	40.155	41.987	42.703	48.776
UL	80.000	80.000	80.000	80.000	80.000	80.000



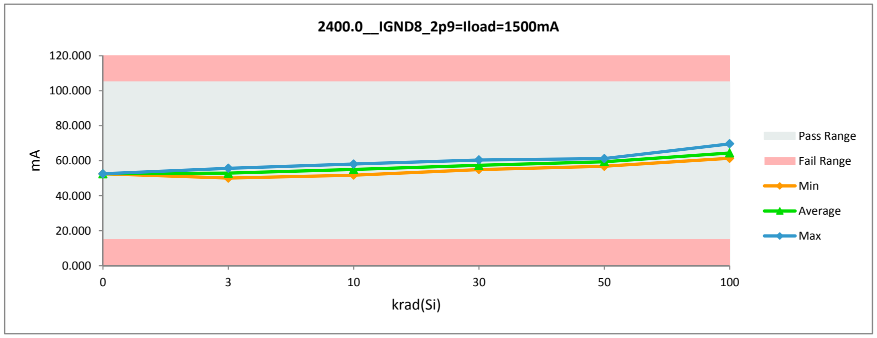
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2400.0__IGND8_2p9=Iload=1500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	105	105	
	Min Limit	15	15	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	53.038	52.500	0.538
3	HDR_L1_D1_Bias	50.538	50.775	-0.237
3	HDR_L1_D2_Bias	49.686	55.690	-6.004
3	HDR_L2_D1_Bias	55.495	50.062	5.433
3	HDR_L2_D2_Bias	53.275	53.435	-0.160
3	HDR_L3_D1_Bias	54.090	54.471	-0.381
10	HDR_L1_D3_Bias	50.164	51.763	-1.599
10	HDR_L1_D4_Bias	51.515	52.952	-1.437
10	HDR_L2_D3_Bias	56.440	55.930	0.510
10	HDR_L3_D2_Bias	54.328	58.071	-3.743
10	HDR_L3_D3_Bias	54.361	56.086	-1.725
30	HDR_L1_D5_Bias	50.823	55.694	-4.871
30	HDR_L2_D4_Bias	55.603	60.405	-4.802
30	HDR_L2_D5_Bias	50.700	54.919	-4.219
30	HDR_L3_D4_Bias	52.926	57.923	-4.997
30	HDR_L3_D5_Bias	52.717	57.903	-5.186
50	HDR_L1_D6_Bias	49.760	56.820	-7.060
50	HDR_L1_D7_Bias	51.590	58.887	-7.297
50	HDR_L2_D6_Bias	52.776	60.030	-7.254
50	HDR_L2_D7_Bias	53.873	61.213	-7.340
50	HDR_L3_D6_Bias	52.634	60.156	-7.522
100	HDR_L1_D8_Bias	50.056	62.024	-11.968
100	HDR_L1_D9_Bias	49.975	61.497	-11.522
100	HDR_L1_D10_Bias	50.011	61.387	-11.376
100	HDR_L1_D11_Bias	49.585	61.573	-11.988
100	HDR_L1_D12_Bias	49.924	62.068	-12.144
100	HDR_L1_D13_Bias	50.208	62.001	-11.793
100	HDR_L1_D14_Bias	51.651	63.903	-12.252
100	HDR_L2_D8_Bias	56.974	69.648	-12.674
100	HDR_L2_D9_Bias	53.413	65.454	-12.041
100	HDR_L2_D10_Bias	52.975	65.430	-12.455
100	HDR_L2_D11_Bias	53.863	66.099	-12.236
100	HDR_L2_D12_Bias	52.635	64.719	-12.084
100	HDR_L2_D13_Bias	53.235	65.471	-12.236
100	HDR_L2_D14_Bias	51.146	62.697	-11.551
100	HDR_L3_D7_Bias	52.206	65.030	-12.824
100	HDR_L3_D8_Bias	53.444	67.062	-13.618
100	HDR_L3_D9_Bias	53.047	65.868	-12.821
100	HDR_L3_D10_Bias	51.693	63.738	-12.045
100	HDR_L3_D11_Bias	52.164	65.078	-12.914
100	HDR_L3_D12_Bias	52.364	64.181	-11.817
100	HDR_L3_D13_Bias	53.635	66.869	-13.234
100	HDR_L3_D14_Bias	52.665	65.642	-12.977
	Max	56.974	69.648	5.433
	Average	52.400	60.305	-7.905
	Min	49.585	50.062	-13.618
	Std Dev	1.871	5.063	5.160



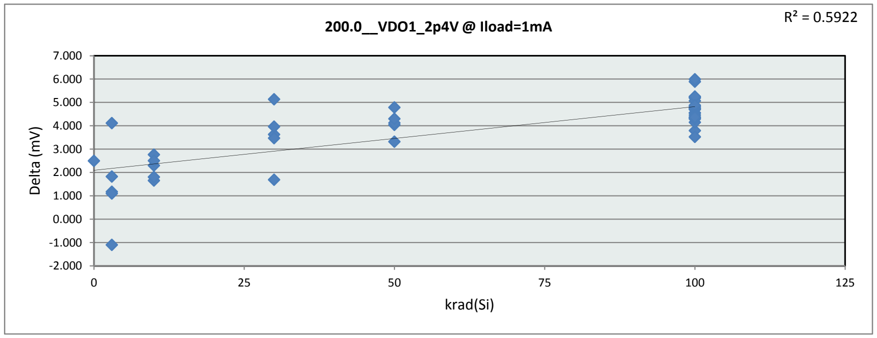
	2400.0__IGND8_2p9=Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	105	mA				
Min Limit	15	mA				
krad(Si)	0	3	10	30	50	100
LL	15.000	15.000	15.000	15.000	15.000	15.000
Min	52.500	50.062	51.763	54.919	56.820	61.387
Average	52.500	52.887	54.960	57.369	59.421	64.429
Max	52.500	55.690	58.071	60.405	61.213	69.648
UL	105.000	105.000	105.000	105.000	105.000	105.000



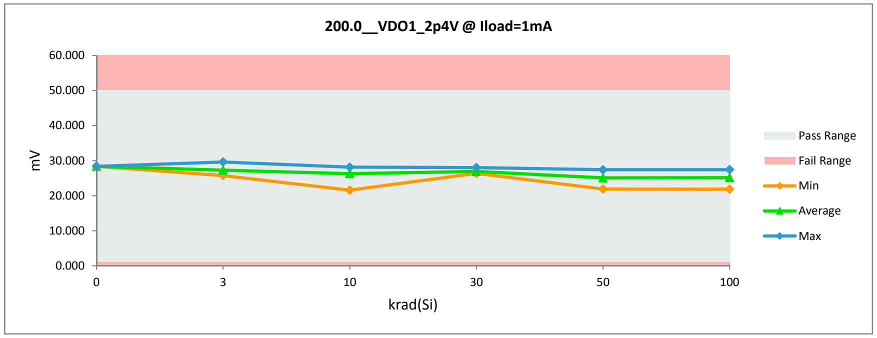
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.0__VDO1_2p4V @ Iload=1mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	50	50	
	Min Limit	1	1	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	30.871	28.376	2.495
3	HDR_L1_D1_Bias	31.440	29.617	1.823
3	HDR_L1_D2_Bias	29.893	25.779	4.114
3	HDR_L2_D1_Bias	27.503	28.606	-1.103
3	HDR_L2_D2_Bias	26.908	25.732	1.176
3	HDR_L3_D1_Bias	27.849	26.753	1.096
10	HDR_L1_D3_Bias	30.426	28.132	2.294
10	HDR_L1_D4_Bias	29.693	26.930	2.763
10	HDR_L2_D3_Bias	29.198	27.546	1.652
10	HDR_L3_D2_Bias	29.758	27.257	2.501
10	HDR_L3_D3_Bias	23.358	21.556	1.802
30	HDR_L1_D5_Bias	30.390	26.763	3.627
30	HDR_L2_D4_Bias	30.176	26.707	3.469
30	HDR_L2_D5_Bias	30.570	26.611	3.959
30	HDR_L3_D4_Bias	29.710	28.020	1.690
30	HDR_L3_D5_Bias	31.486	26.351	5.135
50	HDR_L1_D6_Bias	31.074	26.293	4.781
50	HDR_L1_D7_Bias	28.336	24.301	4.035
50	HDR_L2_D6_Bias	29.555	25.439	4.116
50	HDR_L2_D7_Bias	25.188	21.873	3.315
50	HDR_L3_D6_Bias	31.703	27.406	4.297
100	HDR_L1_D8_Bias	30.056	24.172	5.884
100	HDR_L1_D9_Bias	29.853	25.161	4.692
100	HDR_L1_D10_Bias	29.597	24.835	4.762
100	HDR_L1_D11_Bias	29.336	24.121	5.215
100	HDR_L1_D12_Bias	30.128	24.942	5.186
100	HDR_L1_D13_Bias	31.588	26.521	5.067
100	HDR_L1_D14_Bias	29.187	24.819	4.368
100	HDR_L2_D8_Bias	29.171	24.621	4.550
100	HDR_L2_D9_Bias	28.760	22.769	5.991
100	HDR_L2_D10_Bias	27.233	23.442	3.791
100	HDR_L2_D11_Bias	29.628	24.907	4.721
100	HDR_L2_D12_Bias	30.295	25.554	4.741
100	HDR_L2_D13_Bias	25.361	21.840	3.521
100	HDR_L2_D14_Bias	30.409	25.864	4.545
100	HDR_L3_D7_Bias	31.505	26.253	5.252
100	HDR_L3_D8_Bias	31.426	26.601	4.825
100	HDR_L3_D9_Bias	28.279	23.404	4.875
100	HDR_L3_D10_Bias	30.292	25.972	4.320
100	HDR_L3_D11_Bias	30.031	25.578	4.453
100	HDR_L3_D12_Bias	31.038	26.890	4.148
100	HDR_L3_D13_Bias	31.724	27.433	4.291
100	HDR_L3_D14_Bias	31.533	27.168	4.365
	Max	31.724	29.617	5.991
	Average	29.570	25.789	3.781
	Min	23.358	21.556	-1.103
	Std Dev	1.844	1.840	1.471



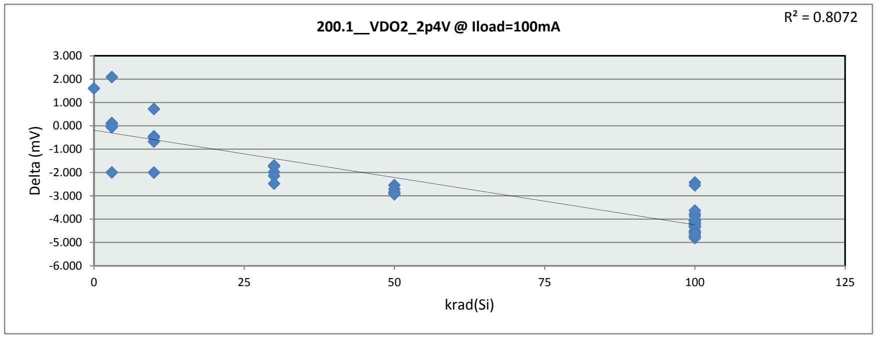
	200.0__VDO1_2p4V @ Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	50	mV				
Min Limit	1	mV				
krad(Si)	0	3	10	30	50	100
LL	1.000	1.000	1.000	1.000	1.000	1.000
Min	28.376	25.732	21.556	26.351	21.873	21.840
Average	28.376	27.297	26.284	26.890	25.062	25.130
Max	28.376	29.617	28.132	28.020	27.406	27.433
UL	50.000	50.000	50.000	50.000	50.000	50.000



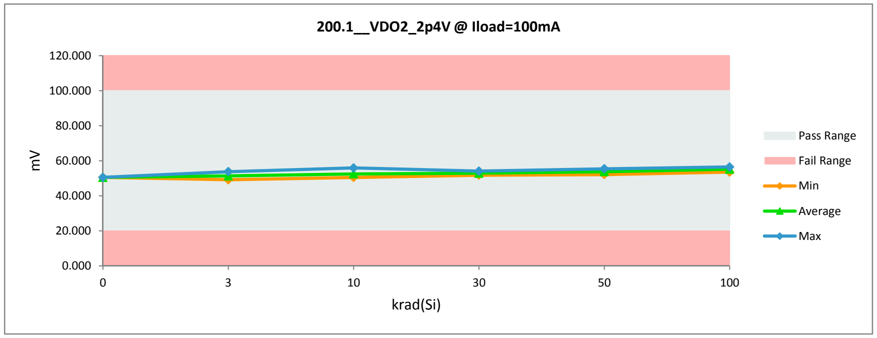
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.1__VDO2_2p4V @ Iload=100mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	100	100	
	Min Limit	20	20	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	52.097	50.494	1.603
3	HDR_L1_D1_Bias	49.252	49.135	0.117
3	HDR_L1_D2_Bias	49.798	51.796	-1.998
3	HDR_L2_D1_Bias	52.026	49.937	2.089
3	HDR_L2_D2_Bias	52.218	52.142	0.076
3	HDR_L3_D1_Bias	53.666	53.733	-0.067
10	HDR_L1_D3_Bias	49.809	50.486	-0.677
10	HDR_L1_D4_Bias	50.144	50.599	-0.455
10	HDR_L2_D3_Bias	51.310	53.316	-2.006
10	HDR_L3_D2_Bias	52.795	52.076	0.719
10	HDR_L3_D3_Bias	55.387	55.899	-0.512
30	HDR_L1_D5_Bias	49.894	52.044	-2.150
30	HDR_L2_D4_Bias	50.694	52.682	-1.988
30	HDR_L2_D5_Bias	50.014	51.759	-1.745
30	HDR_L3_D4_Bias	52.131	53.837	-1.706
30	HDR_L3_D5_Bias	51.574	54.057	-2.483
50	HDR_L1_D6_Bias	49.244	52.096	-2.852
50	HDR_L1_D7_Bias	51.163	53.878	-2.715
50	HDR_L2_D6_Bias	50.823	53.677	-2.854
50	HDR_L2_D7_Bias	52.863	55.409	-2.546
50	HDR_L3_D6_Bias	50.776	53.718	-2.942
100	HDR_L1_D8_Bias	49.947	53.726	-3.779
100	HDR_L1_D9_Bias	49.788	54.517	-4.729
100	HDR_L1_D10_Bias	50.151	54.968	-4.817
100	HDR_L1_D11_Bias	50.046	54.359	-4.313
100	HDR_L1_D12_Bias	49.887	54.424	-4.537
100	HDR_L1_D13_Bias	48.959	53.705	-4.746
100	HDR_L1_D14_Bias	50.567	55.076	-4.509
100	HDR_L2_D8_Bias	51.235	55.106	-3.871
100	HDR_L2_D9_Bias	51.081	53.514	-2.433
100	HDR_L2_D10_Bias	51.911	56.003	-4.092
100	HDR_L2_D11_Bias	50.959	55.022	-4.063
100	HDR_L2_D12_Bias	50.642	54.821	-4.179
100	HDR_L2_D13_Bias	52.783	56.422	-3.639
100	HDR_L2_D14_Bias	50.256	54.603	-4.347
100	HDR_L3_D7_Bias	51.426	55.452	-4.026
100	HDR_L3_D8_Bias	51.754	56.023	-4.269
100	HDR_L3_D9_Bias	52.581	55.134	-2.553
100	HDR_L3_D10_Bias	52.204	56.388	-4.184
100	HDR_L3_D11_Bias	51.887	55.934	-4.047
100	HDR_L3_D12_Bias	51.550	56.147	-4.597
100	HDR_L3_D13_Bias	51.570	56.299	-4.729
100	HDR_L3_D14_Bias	51.579	56.202	-4.623
	Max	55.387	56.422	2.089
	Average	51.173	53.875	-2.702
	Min	48.959	49.135	-4.817
	Std Dev	1.294	1.929	1.873



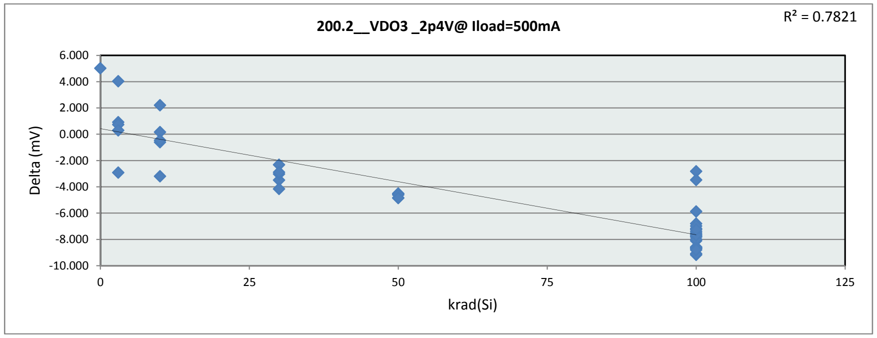
	200.1__VDO2_2p4V @ Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	100	mV				
Min Limit	20	mV				
krad(Si)	0	3	10	30	50	100
LL	20.000	20.000	20.000	20.000	20.000	20.000
Min	50.494	49.135	50.486	51.759	52.096	53.514
Average	50.494	51.349	52.475	52.876	53.756	55.175
Max	50.494	53.733	55.899	54.057	55.409	56.422
UL	100.000	100.000	100.000	100.000	100.000	100.000



TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

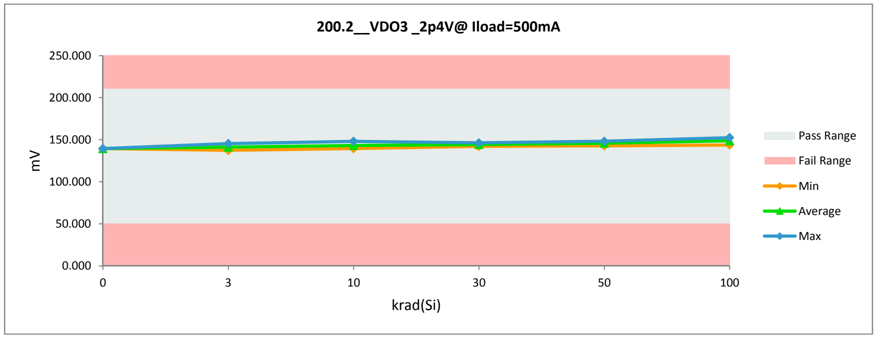
All units passed SMD specification limits up to 100kRAD HDR.

		200.2__VDO3 _2p4V@ Iload=500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	210	210	
	Min Limit	50	50	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	144.443	139.427	5.016
3	HDR_L1_D1_Bias	138.317	137.401	0.916
3	HDR_L1_D2_Bias	139.025	141.940	-2.915
3	HDR_L2_D1_Bias	143.130	139.098	4.032
3	HDR_L2_D2_Bias	142.603	141.871	0.732
3	HDR_L3_D1_Bias	145.792	145.498	0.294
10	HDR_L1_D3_Bias	138.992	139.600	-0.608
10	HDR_L1_D4_Bias	140.369	140.204	0.165
10	HDR_L2_D3_Bias	141.964	145.155	-3.191
10	HDR_L3_D2_Bias	145.142	142.935	2.207
10	HDR_L3_D3_Bias	147.669	148.126	-0.457
30	HDR_L1_D5_Bias	139.097	142.588	-3.491
30	HDR_L2_D4_Bias	141.124	144.151	-3.027
30	HDR_L2_D5_Bias	139.836	142.160	-2.324
30	HDR_L3_D4_Bias	143.291	146.188	-2.897
30	HDR_L3_D5_Bias	142.170	146.321	-4.151
50	HDR_L1_D6_Bias	138.301	142.834	-4.533
50	HDR_L1_D7_Bias	141.436	145.944	-4.508
50	HDR_L2_D6_Bias	140.748	145.583	-4.835
50	HDR_L2_D7_Bias	143.572	148.178	-4.606
50	HDR_L3_D6_Bias	141.742	146.589	-4.847
100	HDR_L1_D8_Bias	139.348	145.227	-5.879
100	HDR_L1_D9_Bias	139.178	147.857	-8.679
100	HDR_L1_D10_Bias	139.332	148.503	-9.171
100	HDR_L1_D11_Bias	139.262	147.050	-7.788
100	HDR_L1_D12_Bias	139.045	147.147	-8.102
100	HDR_L1_D13_Bias	137.992	146.672	-8.680
100	HDR_L1_D14_Bias	140.386	148.963	-8.577
100	HDR_L2_D8_Bias	142.174	148.969	-6.795
100	HDR_L2_D9_Bias	140.921	143.744	-2.823
100	HDR_L2_D10_Bias	142.185	149.995	-7.810
100	HDR_L2_D11_Bias	141.475	148.882	-7.407
100	HDR_L2_D12_Bias	140.848	148.372	-7.524
100	HDR_L2_D13_Bias	143.125	150.296	-7.171
100	HDR_L2_D14_Bias	139.644	147.636	-7.992
100	HDR_L3_D7_Bias	142.281	149.263	-6.982
100	HDR_L3_D8_Bias	142.689	150.334	-7.645
100	HDR_L3_D9_Bias	143.802	147.279	-3.477
100	HDR_L3_D10_Bias	144.856	152.534	-7.678
100	HDR_L3_D11_Bias	142.664	149.923	-7.259
100	HDR_L3_D12_Bias	142.377	151.015	-8.638
100	HDR_L3_D13_Bias	142.674	151.762	-9.088
100	HDR_L3_D14_Bias	142.621	151.411	-8.790
	Max	147.669	152.534	5.016
	Average	141.573	146.154	-4.581
	Min	137.992	137.401	-9.171
	Std Dev	2.204	3.766	3.787



	200.2__VDO3 _2p4V@ Il	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	210	mV
Min Limit	50	mV

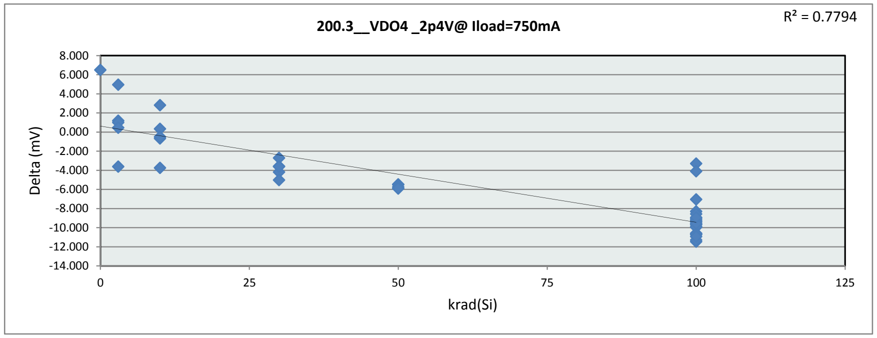
krad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	139.427	137.401	139.600	142.160	142.834	143.744
Average	139.427	141.162	143.204	144.282	145.826	148.765
Max	139.427	145.498	148.126	146.321	148.178	152.534
UL	210.000	210.000	210.000	210.000	210.000	210.000



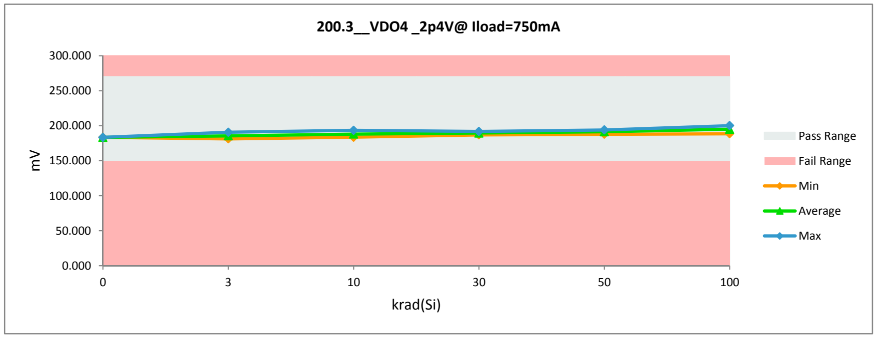
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.3__VDO4 _2p4V@ Iload=750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	270	270	
	Min Limit	150	150	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	189.804	183.319	6.485
3	HDR_L1_D1_Bias	182.311	181.131	1.180
3	HDR_L1_D2_Bias	183.024	186.644	-3.620
3	HDR_L2_D1_Bias	188.166	183.215	4.951
3	HDR_L2_D2_Bias	187.060	186.060	1.000
3	HDR_L3_D1_Bias	191.114	190.678	0.436
10	HDR_L1_D3_Bias	182.930	183.603	-0.673
10	HDR_L1_D4_Bias	185.026	184.693	0.333
10	HDR_L2_D3_Bias	186.789	190.543	-3.754
10	HDR_L3_D2_Bias	190.711	187.899	2.812
10	HDR_L3_D3_Bias	192.892	193.404	-0.512
30	HDR_L1_D5_Bias	183.112	187.312	-4.200
30	HDR_L2_D4_Bias	185.822	189.416	-3.594
30	HDR_L2_D5_Bias	184.168	186.888	-2.720
30	HDR_L3_D4_Bias	188.192	191.814	-3.622
30	HDR_L3_D5_Bias	186.774	191.795	-5.021
50	HDR_L1_D6_Bias	182.325	187.805	-5.480
50	HDR_L1_D7_Bias	185.935	191.456	-5.521
50	HDR_L2_D6_Bias	185.141	191.065	-5.924
50	HDR_L2_D7_Bias	188.191	193.944	-5.753
50	HDR_L3_D6_Bias	186.689	192.582	-5.893
100	HDR_L1_D8_Bias	183.466	190.518	-7.052
100	HDR_L1_D9_Bias	183.354	193.964	-10.610
100	HDR_L1_D10_Bias	183.224	194.689	-11.465
100	HDR_L1_D11_Bias	183.216	192.871	-9.655
100	HDR_L1_D12_Bias	182.966	192.925	-9.959
100	HDR_L1_D13_Bias	182.023	192.693	-10.670
100	HDR_L1_D14_Bias	184.652	195.363	-10.711
100	HDR_L2_D8_Bias	187.209	195.525	-8.316
100	HDR_L2_D9_Bias	185.207	188.506	-3.299
100	HDR_L2_D10_Bias	186.629	196.326	-9.697
100	HDR_L2_D11_Bias	186.162	195.338	-9.176
100	HDR_L2_D12_Bias	185.324	194.645	-9.321
100	HDR_L2_D13_Bias	187.500	196.535	-9.035
100	HDR_L2_D14_Bias	183.576	193.482	-9.906
100	HDR_L3_D7_Bias	187.051	195.635	-8.584
100	HDR_L3_D8_Bias	187.482	196.903	-9.421
100	HDR_L3_D9_Bias	188.712	192.821	-4.109
100	HDR_L3_D10_Bias	190.544	200.108	-9.564
100	HDR_L3_D11_Bias	187.326	196.272	-8.946
100	HDR_L3_D12_Bias	187.115	197.814	-10.699
100	HDR_L3_D13_Bias	187.619	198.922	-11.303
100	HDR_L3_D14_Bias	187.523	198.463	-10.940
	Max	192.892	200.108	6.485
	Average	186.141	191.758	-5.617
	Min	182.023	181.131	-11.465
	Std Dev	2.634	4.662	4.732



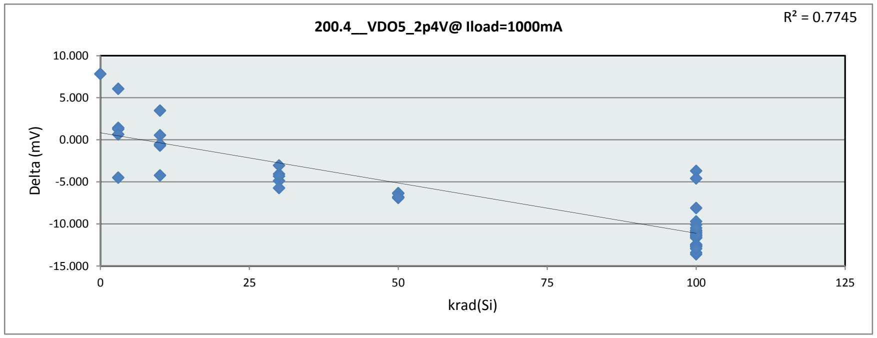
	200.3__VDO4 _2p4V@ Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	270	mV				
Min Limit	150	mV				
krad(Si)	0	3	10	30	50	100
LL	150.000	150.000	150.000	150.000	150.000	150.000
Min	183.319	181.131	183.603	186.888	187.805	188.506
Average	183.319	185.546	188.028	189.445	191.370	195.014
Max	183.319	190.678	193.404	191.814	193.944	200.108
UL	270.000	270.000	270.000	270.000	270.000	270.000



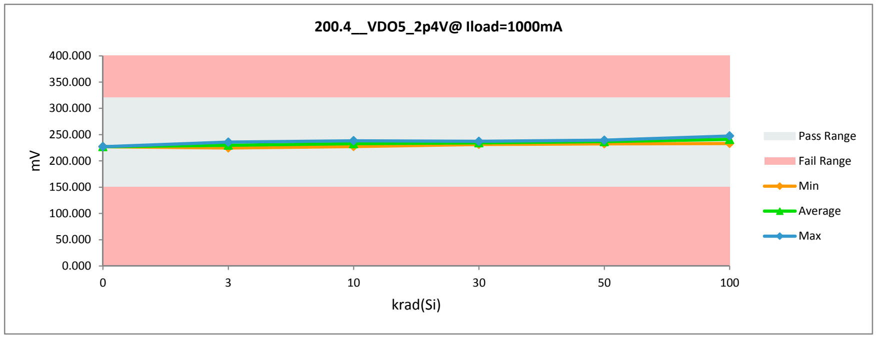
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.4__VDO5_2p4V@ Iload=1000mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	320	320	
	Min Limit	150	150	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	234.947	227.115	7.832
3	HDR_L1_D1_Bias	226.082	224.660	1.422
3	HDR_L1_D2_Bias	226.792	231.286	-4.494
3	HDR_L2_D1_Bias	233.138	227.076	6.062
3	HDR_L2_D2_Bias	231.335	230.071	1.264
3	HDR_L3_D1_Bias	236.294	235.669	0.625
10	HDR_L1_D3_Bias	226.629	227.321	-0.692
10	HDR_L1_D4_Bias	229.632	229.101	0.531
10	HDR_L2_D3_Bias	231.577	235.816	-4.239
10	HDR_L3_D2_Bias	236.240	232.780	3.460
10	HDR_L3_D3_Bias	237.850	238.370	-0.520
30	HDR_L1_D5_Bias	226.865	231.742	-4.877
30	HDR_L2_D4_Bias	230.469	234.543	-4.074
30	HDR_L2_D5_Bias	228.351	231.398	-3.047
30	HDR_L3_D4_Bias	232.899	237.220	-4.321
30	HDR_L3_D5_Bias	231.266	237.006	-5.740
50	HDR_L1_D6_Bias	226.181	232.527	-6.346
50	HDR_L1_D7_Bias	230.194	236.580	-6.386
50	HDR_L2_D6_Bias	229.432	236.355	-6.923
50	HDR_L2_D7_Bias	232.561	239.356	-6.795
50	HDR_L3_D6_Bias	231.519	238.347	-6.828
100	HDR_L1_D8_Bias	227.351	235.465	-8.114
100	HDR_L1_D9_Bias	227.390	239.846	-12.456
100	HDR_L1_D10_Bias	226.886	240.497	-13.611
100	HDR_L1_D11_Bias	226.931	238.297	-11.366
100	HDR_L1_D12_Bias	226.645	238.301	-11.656
100	HDR_L1_D13_Bias	225.896	238.448	-12.552
100	HDR_L1_D14_Bias	228.693	241.402	-12.709
100	HDR_L2_D8_Bias	232.253	241.956	-9.703
100	HDR_L2_D9_Bias	229.381	233.091	-3.710
100	HDR_L2_D10_Bias	230.878	242.338	-11.460
100	HDR_L2_D11_Bias	230.770	241.598	-10.828
100	HDR_L2_D12_Bias	229.703	240.717	-11.014
100	HDR_L2_D13_Bias	231.672	242.431	-10.759
100	HDR_L2_D14_Bias	227.310	238.966	-11.656
100	HDR_L3_D7_Bias	231.676	241.767	-10.091
100	HDR_L3_D8_Bias	232.088	243.212	-11.124
100	HDR_L3_D9_Bias	233.369	237.960	-4.591
100	HDR_L3_D10_Bias	236.170	247.484	-11.314
100	HDR_L3_D11_Bias	231.826	242.312	-10.486
100	HDR_L3_D12_Bias	231.679	244.315	-12.636
100	HDR_L3_D13_Bias	232.373	245.785	-13.412
100	HDR_L3_D14_Bias	232.335	245.286	-12.951
	Max	237.850	247.484	7.832
	Average	230.547	237.112	-6.565
	Min	225.896	224.660	-13.611
	Std Dev	3.098	5.530	5.638



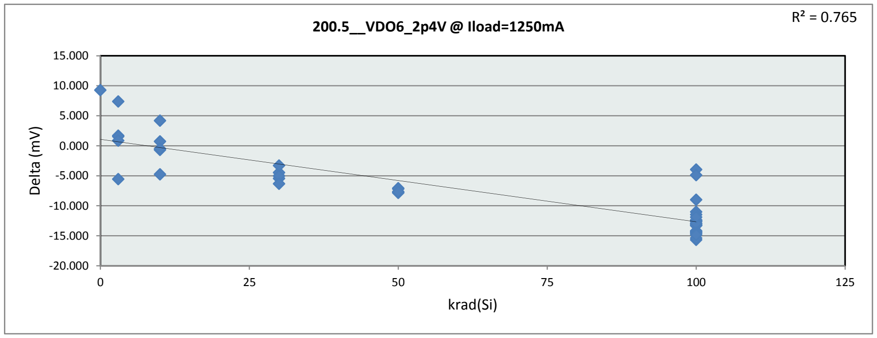
	200.4__VDO5_2p4V@ Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	320	mV				
Min Limit	150	mV				
krad(Si)	0	3	10	30	50	100
LL	150.000	150.000	150.000	150.000	150.000	150.000
Min	227.115	224.660	227.321	231.398	232.527	233.091
Average	227.115	229.752	232.678	234.382	236.633	240.976
Max	227.115	235.669	238.370	237.220	239.356	247.484
UL	320.000	320.000	320.000	320.000	320.000	320.000



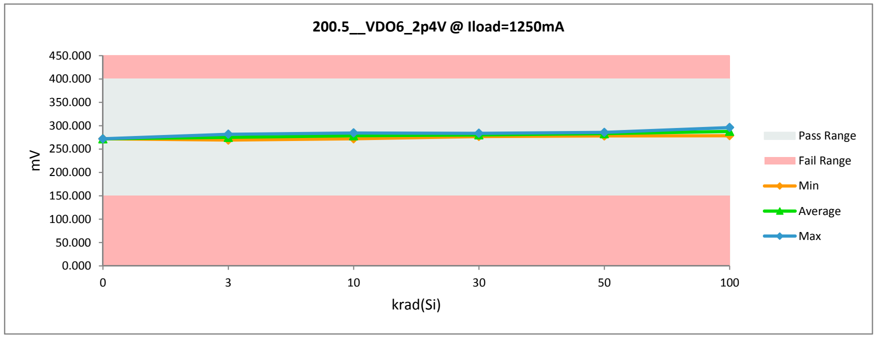
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		200.5__VDO6_2p4V @ Iload=1250mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	150	150	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	281.185	271.932	9.253
3	HDR_L1_D1_Bias	270.852	269.177	1.675
3	HDR_L1_D2_Bias	271.484	277.040	-5.556
3	HDR_L2_D1_Bias	279.240	271.879	7.361
3	HDR_L2_D2_Bias	276.644	275.098	1.546
3	HDR_L3_D1_Bias	282.587	281.740	0.847
10	HDR_L1_D3_Bias	271.254	271.949	-0.695
10	HDR_L1_D4_Bias	275.327	274.599	0.728
10	HDR_L2_D3_Bias	277.483	282.243	-4.760
10	HDR_L3_D2_Bias	282.975	278.794	4.181
10	HDR_L3_D3_Bias	283.840	284.341	-0.501
30	HDR_L1_D5_Bias	271.595	277.053	-5.458
30	HDR_L2_D4_Bias	276.235	280.720	-4.485
30	HDR_L2_D5_Bias	273.596	276.896	-3.300
30	HDR_L3_D4_Bias	278.633	283.666	-5.033
30	HDR_L3_D5_Bias	276.833	283.181	-6.348
50	HDR_L1_D6_Bias	271.048	278.140	-7.092
50	HDR_L1_D7_Bias	275.433	282.626	-7.193
50	HDR_L2_D6_Bias	274.772	282.625	-7.853
50	HDR_L2_D7_Bias	277.912	285.676	-7.764
50	HDR_L3_D6_Bias	277.463	285.121	-7.658
100	HDR_L1_D8_Bias	272.192	281.200	-9.008
100	HDR_L1_D9_Bias	272.479	286.665	-14.186
100	HDR_L1_D10_Bias	271.461	287.147	-15.686
100	HDR_L1_D11_Bias	271.563	284.534	-12.971
100	HDR_L1_D12_Bias	271.244	284.509	-13.265
100	HDR_L1_D13_Bias	270.815	285.143	-14.328
100	HDR_L1_D14_Bias	273.727	288.336	-14.609
100	HDR_L2_D8_Bias	278.450	289.464	-11.014
100	HDR_L2_D9_Bias	274.606	278.574	-3.968
100	HDR_L2_D10_Bias	276.137	289.284	-13.147
100	HDR_L2_D11_Bias	276.486	288.871	-12.385
100	HDR_L2_D12_Bias	275.202	287.810	-12.608
100	HDR_L2_D13_Bias	276.817	289.222	-12.405
100	HDR_L2_D14_Bias	272.011	285.334	-13.323
100	HDR_L3_D7_Bias	277.401	288.881	-11.480
100	HDR_L3_D8_Bias	277.817	290.474	-12.657
100	HDR_L3_D9_Bias	279.021	283.918	-4.897
100	HDR_L3_D10_Bias	283.102	296.033	-12.931
100	HDR_L3_D11_Bias	277.396	289.313	-11.917
100	HDR_L3_D12_Bias	277.321	291.797	-14.476
100	HDR_L3_D13_Bias	278.243	293.627	-15.384
100	HDR_L3_D14_Bias	278.307	293.154	-14.847
	Max	283.840	296.033	9.253
	Average	276.004	283.437	-7.432
	Min	270.815	269.177	-15.686
	Std Dev	3.634	6.407	6.526



	200.5__VDO6_2p4V @ Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	400	mV				
Min Limit	150	mV				
krad(Si)	0	3	10	30	50	100
LL	150.000	150.000	150.000	150.000	150.000	150.000
Min	271.932	269.177	271.949	276.896	278.140	278.574
Average	271.932	274.987	278.385	280.303	282.838	287.877
Max	271.932	281.740	284.341	283.666	285.676	296.033
UL	400.000	400.000	400.000	400.000	400.000	400.000

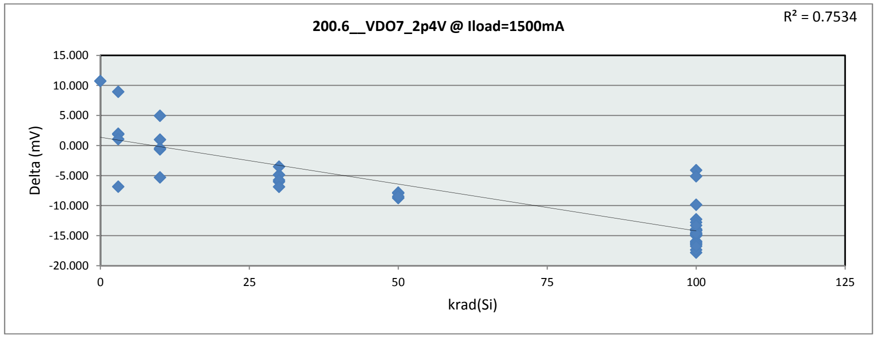


TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

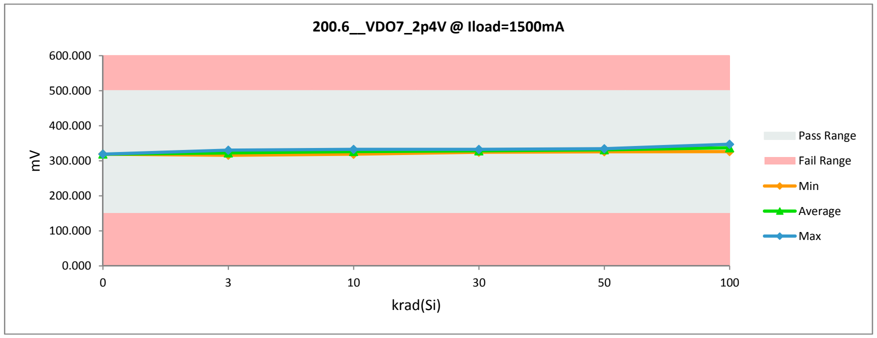
	200.6__VDO7_2p4V @ Iload=1500mA	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	mV	mV
Max Limit	500	500
Min Limit	150	150

krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	329.684	318.955	10.729
3	HDR_L1_D1_Bias	317.741	315.777	1.964
3	HDR_L1_D2_Bias	318.265	325.101	-6.836
3	HDR_L2_D1_Bias	327.675	318.738	8.937
3	HDR_L2_D2_Bias	324.163	322.302	1.861
3	HDR_L3_D1_Bias	331.188	330.116	1.072
10	HDR_L1_D3_Bias	317.974	318.621	-0.647
10	HDR_L1_D4_Bias	323.332	322.337	0.995
10	HDR_L2_D3_Bias	325.752	331.063	-5.311
10	HDR_L3_D2_Bias	332.097	327.140	4.957
10	HDR_L3_D3_Bias	332.085	332.535	-0.450
30	HDR_L1_D5_Bias	318.414	324.435	-6.021
30	HDR_L2_D4_Bias	324.318	329.193	-4.875
30	HDR_L2_D5_Bias	321.073	324.598	-3.525
30	HDR_L3_D4_Bias	326.610	332.362	-5.752
30	HDR_L3_D5_Bias	324.681	331.542	-6.861
50	HDR_L1_D6_Bias	318.047	325.880	-7.833
50	HDR_L1_D7_Bias	322.810	330.742	-7.932
50	HDR_L2_D6_Bias	322.379	331.127	-8.748
50	HDR_L2_D7_Bias	325.445	334.148	-8.703
50	HDR_L3_D6_Bias	325.660	334.142	-8.482
100	HDR_L1_D8_Bias	319.123	328.990	-9.867
100	HDR_L1_D9_Bias	319.781	335.722	-15.941
100	HDR_L1_D10_Bias	318.071	335.894	-17.823
100	HDR_L1_D11_Bias	318.267	332.815	-14.548
100	HDR_L1_D12_Bias	317.900	332.752	-14.852
100	HDR_L1_D13_Bias	317.917	334.027	-16.110
100	HDR_L1_D14_Bias	320.928	337.421	-16.493
100	HDR_L2_D8_Bias	327.037	339.315	-12.278
100	HDR_L2_D9_Bias	322.105	326.221	-4.116
100	HDR_L2_D10_Bias	323.595	338.425	-14.830
100	HDR_L2_D11_Bias	324.498	338.417	-13.919
100	HDR_L2_D12_Bias	323.009	337.182	-14.173
100	HDR_L2_D13_Bias	324.133	338.208	-14.075
100	HDR_L2_D14_Bias	318.849	333.832	-14.983
100	HDR_L3_D7_Bias	325.448	338.229	-12.781
100	HDR_L3_D8_Bias	325.836	339.952	-14.116
100	HDR_L3_D9_Bias	326.826	331.945	-5.119
100	HDR_L3_D10_Bias	332.464	347.142	-14.678
100	HDR_L3_D11_Bias	325.220	338.502	-13.282
100	HDR_L3_D12_Bias	325.197	341.532	-16.335
100	HDR_L3_D13_Bias	326.364	343.720	-17.356
100	HDR_L3_D14_Bias	326.597	343.350	-16.753
	Max	332.464	347.142	10.729
	Average	323.687	331.964	-8.276
	Min	317.741	315.777	-17.823
	Std Dev	4.259	7.339	7.444



	200.6__VDO7_2p4V @ I	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	500	mV
Min Limit	150	mV

krad(Si)	0	3	10	30	50	100
LL	150.000	150.000	150.000	150.000	150.000	150.000
Min	318.955	315.777	318.621	324.435	325.880	326.221
Average	318.955	322.407	326.339	328.426	331.208	336.982
Max	318.955	330.116	332.535	332.362	334.148	347.142
UL	500.000	500.000	500.000	500.000	500.000	500.000

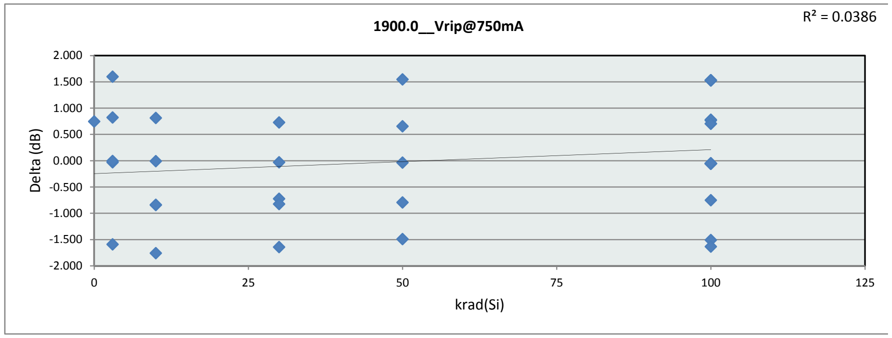


TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

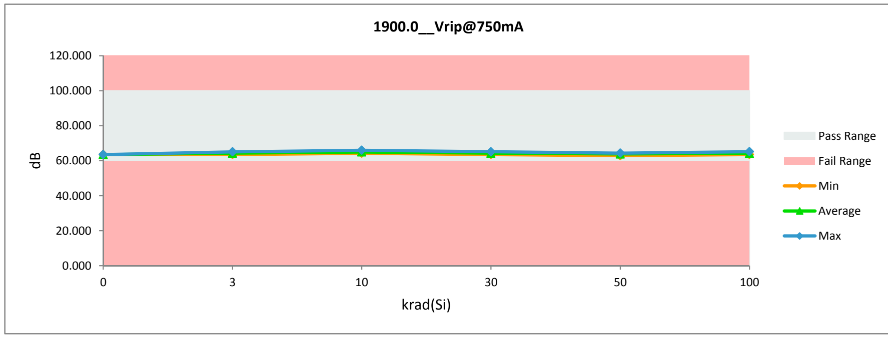
	1900.0__Vrip@750mA	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	dB	dB
Max Limit	100	100
Min Limit	60	60

krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	64.244	63.500	0.744
3	HDR_L1_D1_Bias	63.473	65.065	-1.592
3	HDR_L1_D2_Bias	64.248	64.280	-0.032
3	HDR_L2_D1_Bias	65.099	63.501	1.598
3	HDR_L2_D2_Bias	64.281	64.287	-0.006
3	HDR_L3_D1_Bias	65.099	64.277	0.822
10	HDR_L1_D3_Bias	64.237	65.997	-1.760
10	HDR_L1_D4_Bias	64.249	65.092	-0.843
10	HDR_L2_D3_Bias	64.255	64.266	-0.011
10	HDR_L3_D2_Bias	65.080	64.269	0.811
10	HDR_L3_D3_Bias	64.317	65.158	-0.841
30	HDR_L1_D5_Bias	64.240	64.271	-0.031
30	HDR_L2_D4_Bias	64.244	63.518	0.726
30	HDR_L2_D5_Bias	62.789	63.515	-0.726
30	HDR_L3_D4_Bias	64.255	65.081	-0.826
30	HDR_L3_D5_Bias	63.468	65.113	-1.645
50	HDR_L1_D6_Bias	63.478	62.824	0.654
50	HDR_L1_D7_Bias	65.092	63.547	1.545
50	HDR_L2_D6_Bias	63.494	64.289	-0.795
50	HDR_L2_D7_Bias	62.844	64.335	-1.491
50	HDR_L3_D6_Bias	64.237	64.275	-0.038
100	HDR_L1_D8_Bias	65.071	64.306	0.765
100	HDR_L1_D9_Bias	65.073	63.545	1.528
100	HDR_L1_D10_Bias	62.799	63.550	-0.751
100	HDR_L1_D11_Bias	65.079	63.555	1.524
100	HDR_L1_D12_Bias	64.244	64.303	-0.059
100	HDR_L1_D13_Bias	65.057	65.111	-0.054
100	HDR_L1_D14_Bias	65.082	65.135	-0.053
100	HDR_L2_D8_Bias	63.500	63.553	-0.053
100	HDR_L2_D9_Bias	65.085	64.317	0.768
100	HDR_L2_D10_Bias	64.274	64.329	-0.055
100	HDR_L2_D11_Bias	65.080	65.135	-0.055
100	HDR_L2_D12_Bias	65.071	63.542	1.529
100	HDR_L2_D13_Bias	65.120	65.176	-0.056
100	HDR_L2_D14_Bias	65.074	64.297	0.777
100	HDR_L3_D7_Bias	64.236	64.293	-0.057
100	HDR_L3_D8_Bias	64.235	64.294	-0.059
100	HDR_L3_D9_Bias	62.816	64.325	-1.509
100	HDR_L3_D10_Bias	63.492	63.542	-0.050
100	HDR_L3_D11_Bias	64.251	63.550	0.701
100	HDR_L3_D12_Bias	63.485	65.121	-1.636
100	HDR_L3_D13_Bias	65.059	63.529	1.530
100	HDR_L3_D14_Bias	64.234	63.532	0.702
	Max	65.120	65.997	1.598
	Average	64.282	64.244	0.038
	Min	62.789	62.824	-1.760
	Std Dev	0.735	0.688	0.966



	1900.0__Vrip@750mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	100	dB
Min Limit	60	dB

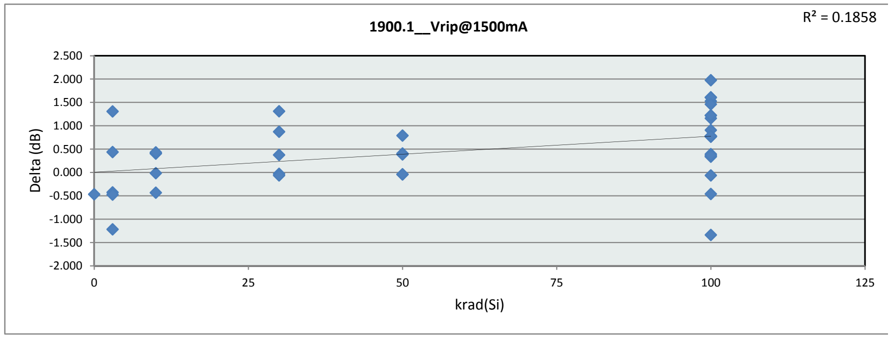
krad(Si)	0	3	10	30	50	100
LL	60.000	60.000	60.000	60.000	60.000	60.000
Min	63.500	63.501	64.266	63.515	62.824	63.529
Average	63.500	64.282	64.956	64.300	63.854	64.184
Max	63.500	65.065	65.997	65.113	64.335	65.176
UL	100.000	100.000	100.000	100.000	100.000	100.000



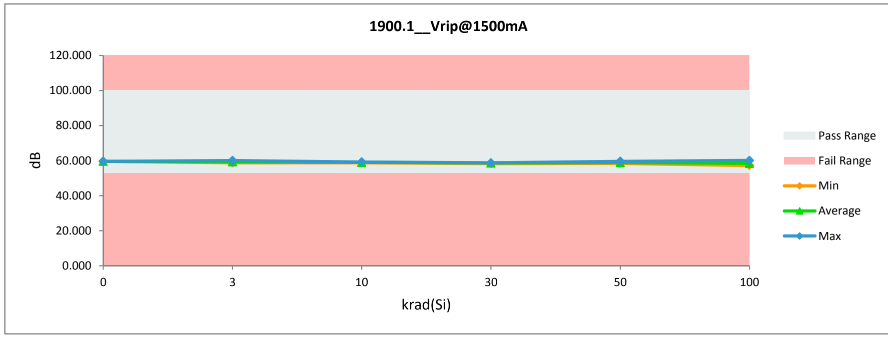
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		1900.1__Vrip@1500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	dB	dB	
	Max Limit	100	100	
	Min Limit	53	53	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	59.111	59.580	-0.469
3	HDR_L1_D1_Bias	59.553	59.117	0.436
3	HDR_L1_D2_Bias	60.044	58.737	1.307
3	HDR_L2_D1_Bias	59.152	59.580	-0.428
3	HDR_L2_D2_Bias	57.948	59.167	-1.219
3	HDR_L3_D1_Bias	59.596	60.072	-0.476
10	HDR_L1_D3_Bias	59.120	59.135	-0.015
10	HDR_L1_D4_Bias	59.127	58.721	0.406
10	HDR_L2_D3_Bias	58.714	59.147	-0.433
10	HDR_L3_D2_Bias	59.131	58.727	0.404
10	HDR_L3_D3_Bias	59.647	59.218	0.429
30	HDR_L1_D5_Bias	58.695	58.322	0.373
30	HDR_L2_D4_Bias	60.040	58.730	1.310
30	HDR_L2_D5_Bias	58.695	58.726	-0.031
30	HDR_L3_D4_Bias	59.580	58.708	0.872
30	HDR_L3_D5_Bias	58.677	58.742	-0.065
50	HDR_L1_D6_Bias	59.558	59.600	-0.042
50	HDR_L1_D7_Bias	59.590	59.185	0.405
50	HDR_L2_D6_Bias	59.129	58.746	0.383
50	HDR_L2_D7_Bias	59.180	58.391	0.789
50	HDR_L3_D6_Bias	58.689	58.730	-0.041
100	HDR_L1_D8_Bias	60.037	60.102	-0.065
100	HDR_L1_D9_Bias	58.292	58.752	-0.460
100	HDR_L1_D10_Bias	59.576	59.186	0.390
100	HDR_L1_D11_Bias	59.133	58.367	0.766
100	HDR_L1_D12_Bias	59.125	58.356	0.769
100	HDR_L1_D13_Bias	59.551	57.576	1.975
100	HDR_L1_D14_Bias	59.579	57.973	1.606
100	HDR_L2_D8_Bias	58.711	58.363	0.348
100	HDR_L2_D9_Bias	58.308	59.647	-1.339
100	HDR_L2_D10_Bias	59.601	58.382	1.219
100	HDR_L2_D11_Bias	59.131	58.360	0.771
100	HDR_L2_D12_Bias	59.121	57.961	1.160
100	HDR_L2_D13_Bias	59.177	58.403	0.774
100	HDR_L2_D14_Bias	58.298	57.963	0.335
100	HDR_L3_D7_Bias	59.111	57.585	1.526
100	HDR_L3_D8_Bias	59.114	58.746	0.368
100	HDR_L3_D9_Bias	60.561	59.657	0.904
100	HDR_L3_D10_Bias	59.124	58.344	0.780
100	HDR_L3_D11_Bias	59.573	57.969	1.604
100	HDR_L3_D12_Bias	59.119	58.342	0.777
100	HDR_L3_D13_Bias	58.686	57.224	1.462
100	HDR_L3_D14_Bias	59.557	58.335	1.222
	Max	60.561	60.102	1.975
	Average	59.197	58.713	0.483
	Min	57.948	57.224	-1.339
	Std Dev	0.525	0.648	0.740



	1900.1__Vrip@1500mA					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	100	dB				
Min Limit	53	dB				
krad(Si)	0	3	10	30	50	100
LL	53.000	53.000	53.000	53.000	53.000	53.000
Min	59.580	58.737	58.721	58.322	58.391	57.224
Average	59.580	59.335	58.990	58.646	58.930	58.436
Max	59.580	60.072	59.218	58.742	59.600	60.102
UL	100.000	100.000	100.000	100.000	100.000	100.000



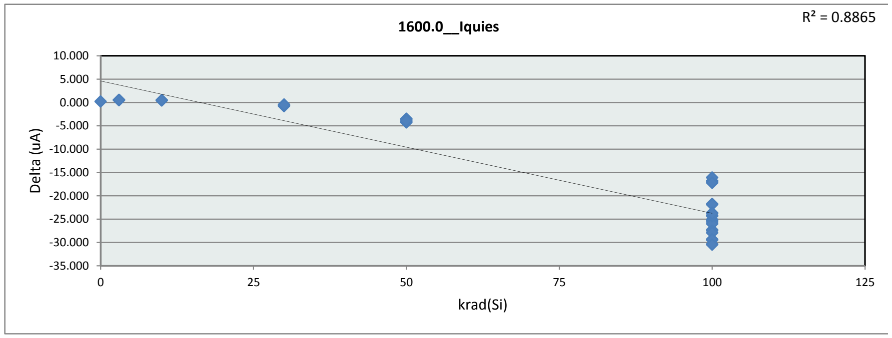
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

1600.0__Iquies

Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	uA	uA
Max Limit	50	50
Min Limit		

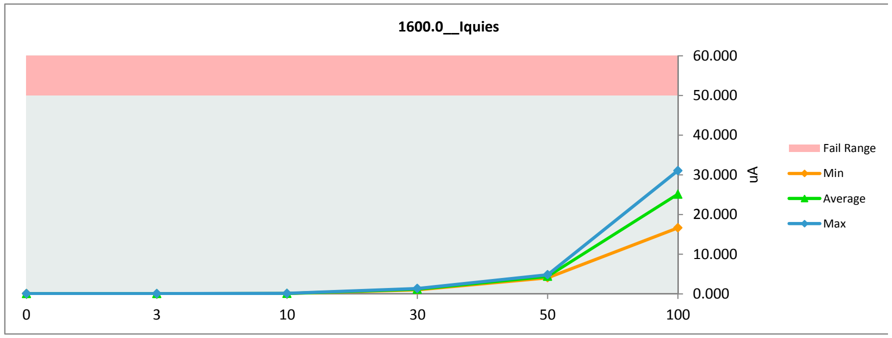
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	0.269	0.061	0.208
3	HDR_L1_D1_Bias	0.582	0.054	0.528
3	HDR_L1_D2_Bias	0.561	0.063	0.498
3	HDR_L2_D1_Bias	0.575	0.067	0.508
3	HDR_L2_D2_Bias	0.568	0.071	0.497
3	HDR_L3_D1_Bias	0.571	0.066	0.505
10	HDR_L1_D3_Bias	0.550	0.099	0.451
10	HDR_L1_D4_Bias	0.549	0.102	0.447
10	HDR_L2_D3_Bias	0.563	0.091	0.472
10	HDR_L3_D2_Bias	0.558	0.132	0.426
10	HDR_L3_D3_Bias	0.559	0.090	0.469
30	HDR_L1_D5_Bias	0.554	1.174	-0.620
30	HDR_L2_D4_Bias	0.556	1.219	-0.663
30	HDR_L2_D5_Bias	0.553	1.022	-0.469
30	HDR_L3_D4_Bias	0.568	1.365	-0.797
30	HDR_L3_D5_Bias	0.559	1.110	-0.551
50	HDR_L1_D6_Bias	0.553	4.161	-3.608
50	HDR_L1_D7_Bias	0.551	4.064	-3.513
50	HDR_L2_D6_Bias	0.552	4.832	-4.280
50	HDR_L2_D7_Bias	0.550	4.560	-4.010
50	HDR_L3_D6_Bias	0.560	4.542	-3.982
100	HDR_L1_D8_Bias	0.544	17.392	-16.848
100	HDR_L1_D9_Bias	0.550	29.894	-29.344
100	HDR_L1_D10_Bias	0.543	22.287	-21.744
100	HDR_L1_D11_Bias	0.550	17.357	-16.807
100	HDR_L1_D12_Bias	0.545	22.430	-21.885
100	HDR_L1_D13_Bias	0.556	25.672	-25.116
100	HDR_L1_D14_Bias	0.563	24.223	-23.660
100	HDR_L2_D8_Bias	0.548	25.899	-25.351
100	HDR_L2_D9_Bias	0.546	16.647	-16.101
100	HDR_L2_D10_Bias	0.581	30.919	-30.338
100	HDR_L2_D11_Bias	0.566	24.795	-24.229
100	HDR_L2_D12_Bias	0.554	27.846	-27.292
100	HDR_L2_D13_Bias	0.549	26.168	-25.619
100	HDR_L2_D14_Bias	0.557	26.584	-26.027
100	HDR_L3_D7_Bias	0.565	24.930	-24.365
100	HDR_L3_D8_Bias	0.566	30.046	-29.480
100	HDR_L3_D9_Bias	0.561	17.797	-17.236
100	HDR_L3_D10_Bias	0.558	24.352	-23.794
100	HDR_L3_D11_Bias	0.607	28.062	-27.455
100	HDR_L3_D12_Bias	0.552	28.487	-27.935
100	HDR_L3_D13_Bias	0.553	29.911	-29.358
100	HDR_L3_D14_Bias	0.558	31.054	-30.496
	Max	0.607	31.054	0.528
	Average	0.552	13.528	-12.976
	Min	0.269	0.054	-30.496
	Std Dev	0.046	12.495	12.488



1600.0__Iquies

Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	50	uA
Min Limit		uA

krad(Si)	0	3	10	30	50	100
LL						
Min	0.061	0.054	0.090	1.022	4.064	16.647
Average	0.061	0.064	0.103	1.178	4.432	25.125
Max	0.061	0.071	0.132	1.365	4.832	31.054
UL	50.000	50.000	50.000	50.000	50.000	50.000

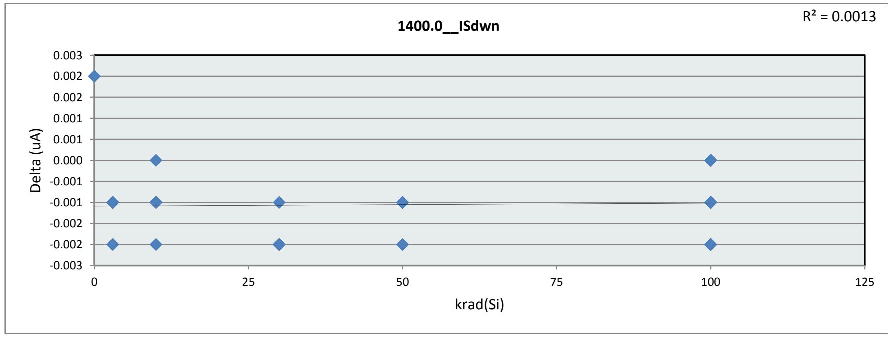


TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

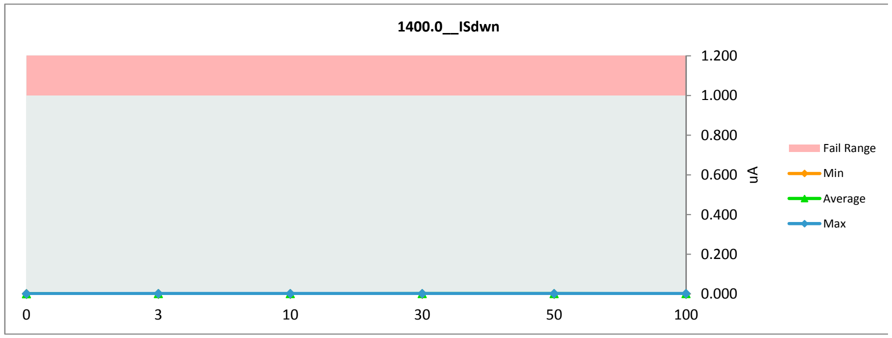
All units passed SMD specification limits up to 100kRAD HDR.

	1400.0__ISdwn	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	uA	uA
Max Limit	1	1
Min Limit		

krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	0.003	0.001	0.002
3	HDR_L1_D1_Bias	0.000	0.001	-0.001
3	HDR_L1_D2_Bias	0.000	0.001	-0.001
3	HDR_L2_D1_Bias	0.000	0.001	-0.001
3	HDR_L2_D2_Bias	0.000	0.002	-0.002
3	HDR_L3_D1_Bias	0.000	0.001	-0.001
10	HDR_L1_D3_Bias	0.000	0.002	-0.002
10	HDR_L1_D4_Bias	0.001	0.001	0.000
10	HDR_L2_D3_Bias	0.000	0.001	-0.001
10	HDR_L3_D2_Bias	0.000	0.001	-0.001
10	HDR_L3_D3_Bias	0.000	0.001	-0.001
30	HDR_L1_D5_Bias	0.000	0.002	-0.002
30	HDR_L2_D4_Bias	0.000	0.002	-0.002
30	HDR_L2_D5_Bias	0.000	0.001	-0.001
30	HDR_L3_D4_Bias	0.000	0.002	-0.002
30	HDR_L3_D5_Bias	0.000	0.002	-0.002
50	HDR_L1_D6_Bias	0.001	0.002	-0.001
50	HDR_L1_D7_Bias	0.000	0.001	-0.001
50	HDR_L2_D6_Bias	0.000	0.001	-0.001
50	HDR_L2_D7_Bias	0.001	0.002	-0.001
50	HDR_L3_D6_Bias	0.000	0.002	-0.002
100	HDR_L1_D8_Bias	0.001	0.001	0.000
100	HDR_L1_D9_Bias	0.000	0.002	-0.002
100	HDR_L1_D10_Bias	0.001	0.001	0.000
100	HDR_L1_D11_Bias	0.000	0.001	-0.001
100	HDR_L1_D12_Bias	0.001	0.001	0.000
100	HDR_L1_D13_Bias	0.001	0.001	0.000
100	HDR_L1_D14_Bias	0.000	0.002	-0.002
100	HDR_L2_D8_Bias	0.001	0.001	0.000
100	HDR_L2_D9_Bias	0.001	0.001	0.000
100	HDR_L2_D10_Bias	0.000	0.001	-0.001
100	HDR_L2_D11_Bias	0.000	0.002	-0.002
100	HDR_L2_D12_Bias	0.000	0.001	-0.001
100	HDR_L2_D13_Bias	0.000	0.001	-0.001
100	HDR_L2_D14_Bias	0.000	0.002	-0.002
100	HDR_L3_D7_Bias	0.000	0.001	-0.001
100	HDR_L3_D8_Bias	0.001	0.002	-0.001
100	HDR_L3_D9_Bias	0.000	0.001	-0.001
100	HDR_L3_D10_Bias	0.000	0.001	-0.001
100	HDR_L3_D11_Bias	0.000	0.001	-0.001
100	HDR_L3_D12_Bias	0.000	0.001	-0.001
100	HDR_L3_D13_Bias	0.000	0.001	-0.001
100	HDR_L3_D14_Bias	0.000	0.002	-0.002
	Max	0.003	0.002	0.002
	Average	0.000	0.001	-0.001
	Min	0.000	0.001	-0.002
	Std Dev	0.001	0.000	0.001



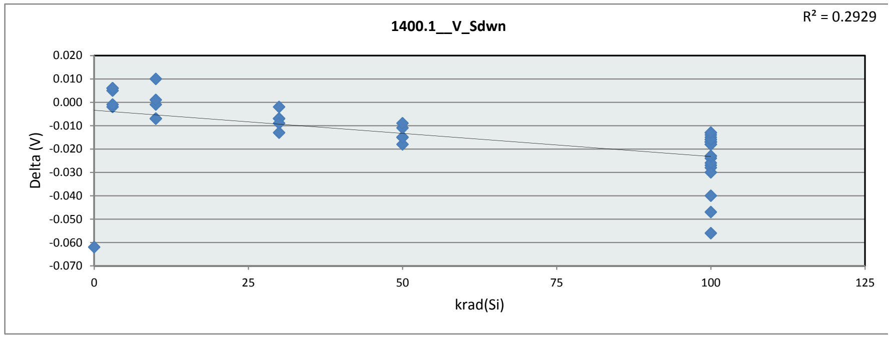
	1400.0__ISdwn					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	1	uA				
Min Limit		uA				
krad(Si)	0	3	10	30	50	100
LL						
Min	0.001	0.001	0.001	0.001	0.001	0.001
Average	0.001	0.001	0.001	0.002	0.002	0.001
Max	0.001	0.002	0.002	0.002	0.002	0.002
UL	1.000	1.000	1.000	1.000	1.000	1.000



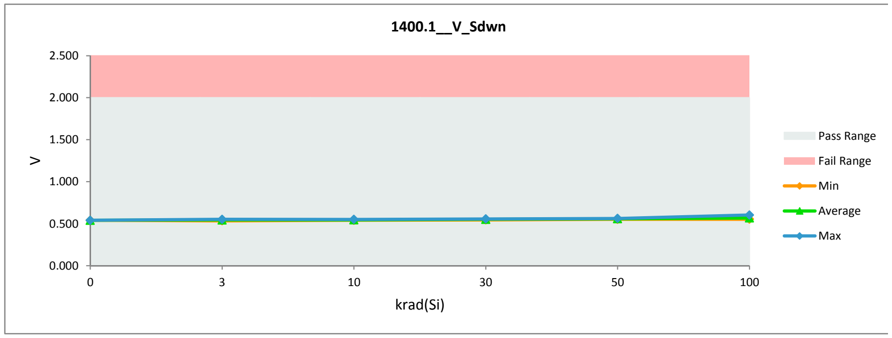
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		1400.1__V_Sdwn		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	2	2	
	Min Limit	0	0	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	0.479	0.541	-0.062
3	HDR_L1_D1_Bias	0.546	0.548	-0.002
3	HDR_L1_D2_Bias	0.551	0.552	-0.001
3	HDR_L2_D1_Bias	0.551	0.545	0.006
3	HDR_L2_D2_Bias	0.549	0.544	0.005
3	HDR_L3_D1_Bias	0.540	0.534	0.006
10	HDR_L1_D3_Bias	0.545	0.546	-0.001
10	HDR_L1_D4_Bias	0.544	0.551	-0.007
10	HDR_L2_D3_Bias	0.551	0.541	0.010
10	HDR_L3_D2_Bias	0.538	0.545	-0.007
10	HDR_L3_D3_Bias	0.544	0.543	0.001
30	HDR_L1_D5_Bias	0.546	0.553	-0.007
30	HDR_L2_D4_Bias	0.549	0.556	-0.007
30	HDR_L2_D5_Bias	0.544	0.557	-0.013
30	HDR_L3_D4_Bias	0.543	0.545	-0.002
30	HDR_L3_D5_Bias	0.542	0.551	-0.009
50	HDR_L1_D6_Bias	0.545	0.563	-0.018
50	HDR_L1_D7_Bias	0.545	0.560	-0.015
50	HDR_L2_D6_Bias	0.549	0.560	-0.011
50	HDR_L2_D7_Bias	0.551	0.560	-0.009
50	HDR_L3_D6_Bias	0.537	0.552	-0.015
100	HDR_L1_D8_Bias	0.545	0.585	-0.040
100	HDR_L1_D9_Bias	0.544	0.561	-0.017
100	HDR_L1_D10_Bias	0.548	0.564	-0.016
100	HDR_L1_D11_Bias	0.547	0.574	-0.027
100	HDR_L1_D12_Bias	0.545	0.568	-0.023
100	HDR_L1_D13_Bias	0.544	0.561	-0.017
100	HDR_L1_D14_Bias	0.544	0.561	-0.017
100	HDR_L2_D8_Bias	0.551	0.579	-0.028
100	HDR_L2_D9_Bias	0.547	0.603	-0.056
100	HDR_L2_D10_Bias	0.547	0.561	-0.014
100	HDR_L2_D11_Bias	0.544	0.568	-0.024
100	HDR_L2_D12_Bias	0.544	0.562	-0.018
100	HDR_L2_D13_Bias	0.549	0.566	-0.017
100	HDR_L2_D14_Bias	0.542	0.557	-0.015
100	HDR_L3_D7_Bias	0.542	0.572	-0.030
100	HDR_L3_D8_Bias	0.542	0.568	-0.026
100	HDR_L3_D9_Bias	0.544	0.591	-0.047
100	HDR_L3_D10_Bias	0.540	0.558	-0.018
100	HDR_L3_D11_Bias	0.543	0.566	-0.023
100	HDR_L3_D12_Bias	0.544	0.557	-0.013
100	HDR_L3_D13_Bias	0.544	0.560	-0.016
100	HDR_L3_D14_Bias	0.540	0.553	-0.013
	Max	0.551	0.603	0.010
	Average	0.543	0.559	-0.016
	Min	0.479	0.534	-0.062
	Std Dev	0.011	0.014	0.015



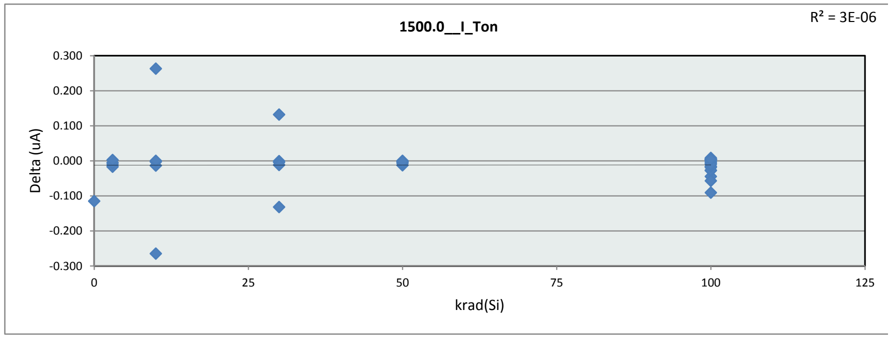
	1400.1__V_Sdwn					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	2	V				
Min Limit	0	V				
krad(Si)	0	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000	0.000
Min	0.541	0.534	0.541	0.545	0.552	0.553
Average	0.541	0.545	0.545	0.552	0.559	0.568
Max	0.541	0.552	0.551	0.557	0.563	0.603
UL	2.000	2.000	2.000	2.000	2.000	2.000



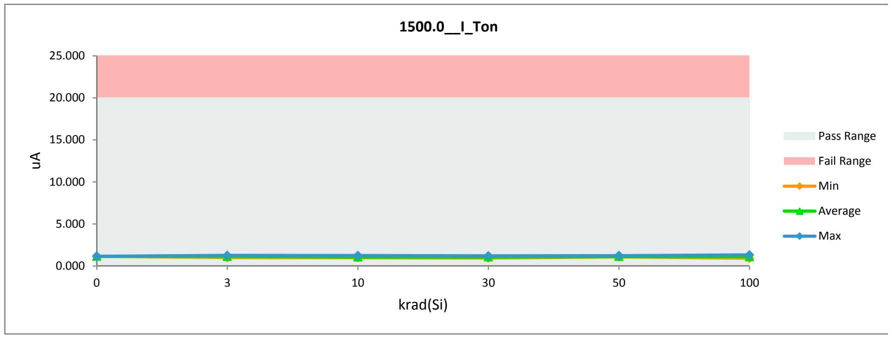
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		1500.0__I_Ton		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	20	20	
	Min Limit	0	0	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	1.040	1.155	-0.115
3	HDR_L1_D1_Bias	1.049	1.061	-0.012
3	HDR_L1_D2_Bias	1.242	1.259	-0.017
3	HDR_L2_D1_Bias	1.240	1.246	-0.006
3	HDR_L2_D2_Bias	1.158	1.164	-0.006
3	HDR_L3_D1_Bias	1.000	0.998	0.002
10	HDR_L1_D3_Bias	1.092	1.095	-0.003
10	HDR_L1_D4_Bias	1.051	1.065	-0.014
10	HDR_L2_D3_Bias	1.247	0.984	0.263
10	HDR_L3_D2_Bias	0.978	1.243	-0.265
10	HDR_L3_D3_Bias	1.009	1.009	0.000
30	HDR_L1_D5_Bias	1.109	1.110	-0.001
30	HDR_L2_D4_Bias	1.201	1.205	-0.004
30	HDR_L2_D5_Bias	1.072	1.084	-0.012
30	HDR_L3_D4_Bias	1.064	0.932	0.132
30	HDR_L3_D5_Bias	0.935	1.067	-0.132
50	HDR_L1_D6_Bias	1.062	1.075	-0.013
50	HDR_L1_D7_Bias	1.118	1.125	-0.007
50	HDR_L2_D6_Bias	1.201	1.204	-0.003
50	HDR_L2_D7_Bias	1.228	1.228	0.000
50	HDR_L3_D6_Bias	1.067	1.070	-0.003
100	HDR_L1_D8_Bias	1.117	1.162	-0.045
100	HDR_L1_D9_Bias	1.046	1.047	-0.001
100	HDR_L1_D10_Bias	1.251	1.245	0.006
100	HDR_L1_D11_Bias	1.290	1.309	-0.019
100	HDR_L1_D12_Bias	1.169	1.177	-0.008
100	HDR_L1_D13_Bias	1.031	1.031	0.000
100	HDR_L1_D14_Bias	1.071	1.066	0.005
100	HDR_L2_D8_Bias	1.217	1.245	-0.028
100	HDR_L2_D9_Bias	1.223	1.314	-0.091
100	HDR_L2_D10_Bias	1.215	1.212	0.003
100	HDR_L2_D11_Bias	1.093	1.110	-0.017
100	HDR_L2_D12_Bias	1.036	1.041	-0.005
100	HDR_L2_D13_Bias	1.129	1.131	-0.002
100	HDR_L2_D14_Bias	1.060	1.058	0.002
100	HDR_L3_D7_Bias	1.040	1.067	-0.027
100	HDR_L3_D8_Bias	0.950	0.966	-0.016
100	HDR_L3_D9_Bias	1.044	1.101	-0.057
100	HDR_L3_D10_Bias	1.012	1.009	0.003
100	HDR_L3_D11_Bias	1.037	1.047	-0.010
100	HDR_L3_D12_Bias	1.073	1.065	0.008
100	HDR_L3_D13_Bias	1.045	1.041	0.004
100	HDR_L3_D14_Bias	0.921	0.917	0.004
	Max	1.290	1.314	0.263
	Average	1.098	1.110	-0.012
	Min	0.921	0.917	-0.265
	Std Dev	0.094	0.099	0.069



	1500.0__I_Ton					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	20	uA				
Min Limit	0	uA				
krad(Si)	0	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000	0.000
Min	1.155	0.998	0.984	0.932	1.070	0.917
Average	1.155	1.146	1.079	1.080	1.140	1.107
Max	1.155	1.259	1.243	1.205	1.228	1.314
UL	20.000	20.000	20.000	20.000	20.000	20.000

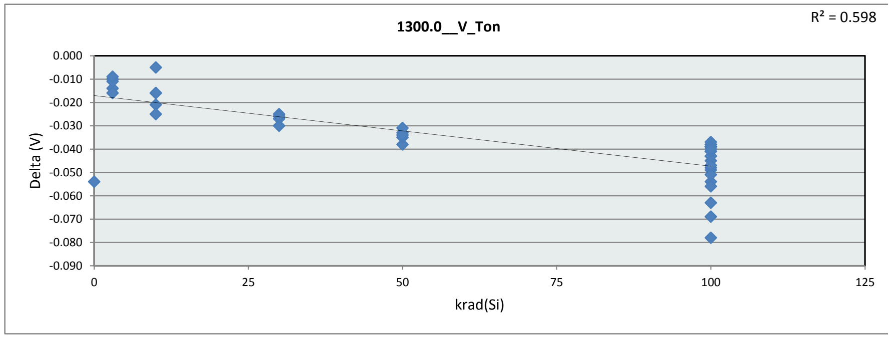


TPS7A4501-RHA

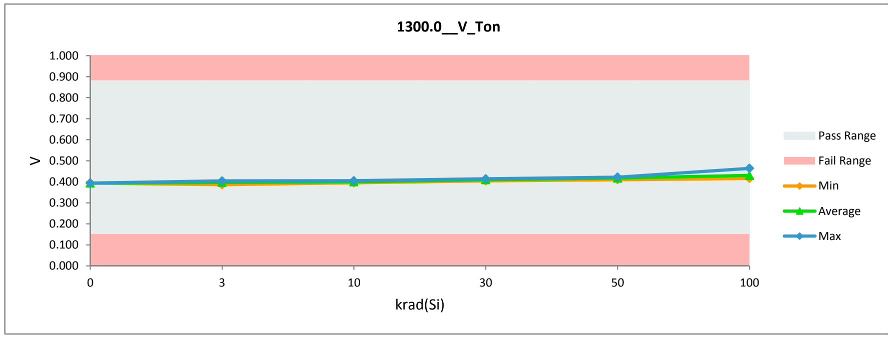
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		1300.0__V_Ton		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	0.88	0.88	
	Min Limit	0.15	0.15	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	0.340	0.394	-0.054
3	HDR_L1_D1_Bias	0.386	0.400	-0.014
3	HDR_L1_D2_Bias	0.388	0.404	-0.016
3	HDR_L2_D1_Bias	0.388	0.398	-0.010
3	HDR_L2_D2_Bias	0.386	0.397	-0.011
3	HDR_L3_D1_Bias	0.377	0.386	-0.009
10	HDR_L1_D3_Bias	0.386	0.402	-0.016
10	HDR_L1_D4_Bias	0.384	0.405	-0.021
10	HDR_L2_D3_Bias	0.390	0.395	-0.005
10	HDR_L3_D2_Bias	0.377	0.402	-0.025
10	HDR_L3_D3_Bias	0.380	0.396	-0.016
30	HDR_L1_D5_Bias	0.385	0.411	-0.026
30	HDR_L2_D4_Bias	0.387	0.414	-0.027
30	HDR_L2_D5_Bias	0.384	0.414	-0.030
30	HDR_L3_D4_Bias	0.379	0.404	-0.025
30	HDR_L3_D5_Bias	0.380	0.406	-0.026
50	HDR_L1_D6_Bias	0.384	0.422	-0.038
50	HDR_L1_D7_Bias	0.384	0.419	-0.035
50	HDR_L2_D6_Bias	0.387	0.420	-0.033
50	HDR_L2_D7_Bias	0.387	0.418	-0.031
50	HDR_L3_D6_Bias	0.376	0.410	-0.034
100	HDR_L1_D8_Bias	0.384	0.447	-0.063
100	HDR_L1_D9_Bias	0.383	0.426	-0.043
100	HDR_L1_D10_Bias	0.386	0.425	-0.039
100	HDR_L1_D11_Bias	0.387	0.436	-0.049
100	HDR_L1_D12_Bias	0.385	0.430	-0.045
100	HDR_L1_D13_Bias	0.384	0.425	-0.041
100	HDR_L1_D14_Bias	0.384	0.422	-0.038
100	HDR_L2_D8_Bias	0.388	0.442	-0.054
100	HDR_L2_D9_Bias	0.386	0.464	-0.078
100	HDR_L2_D10_Bias	0.386	0.425	-0.039
100	HDR_L2_D11_Bias	0.383	0.431	-0.048
100	HDR_L2_D12_Bias	0.383	0.426	-0.043
100	HDR_L2_D13_Bias	0.386	0.427	-0.041
100	HDR_L2_D14_Bias	0.382	0.420	-0.038
100	HDR_L3_D7_Bias	0.379	0.435	-0.056
100	HDR_L3_D8_Bias	0.379	0.430	-0.051
100	HDR_L3_D9_Bias	0.381	0.450	-0.069
100	HDR_L3_D10_Bias	0.377	0.416	-0.039
100	HDR_L3_D11_Bias	0.381	0.428	-0.047
100	HDR_L3_D12_Bias	0.381	0.418	-0.037
100	HDR_L3_D13_Bias	0.380	0.419	-0.039
100	HDR_L3_D14_Bias	0.377	0.417	-0.040
	Max	0.390	0.464	-0.005
	Average	0.382	0.418	-0.036
	Min	0.340	0.386	-0.078
	Std Dev	0.008	0.016	0.016



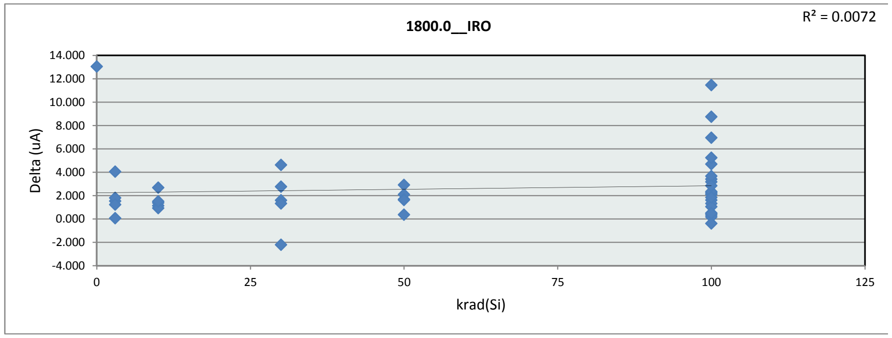
	1300.0__V_Ton					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	0.88	V				
Min Limit	0.15	V				
krad(Si)	0	3	10	30	50	100
LL	0.150	0.150	0.150	0.150	0.150	0.150
Min	0.394	0.386	0.395	0.404	0.410	0.416
Average	0.394	0.397	0.400	0.410	0.418	0.430
Max	0.394	0.404	0.405	0.414	0.422	0.464
UL	0.880	0.880	0.880	0.880	0.880	0.880



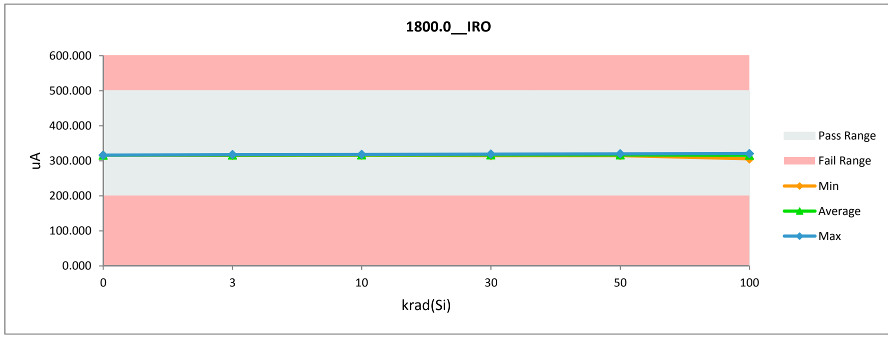
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		1800.0__IRO		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	500	500	
	Min Limit	200	200	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	329.122	316.067	13.055
3	HDR_L1_D1_Bias	316.824	315.286	1.538
3	HDR_L1_D2_Bias	319.151	315.103	4.048
3	HDR_L2_D1_Bias	317.652	317.585	0.067
3	HDR_L2_D2_Bias	319.445	317.632	1.813
3	HDR_L3_D1_Bias	316.574	315.347	1.227
10	HDR_L1_D3_Bias	317.780	316.651	1.129
10	HDR_L1_D4_Bias	320.728	318.043	2.685
10	HDR_L2_D3_Bias	317.439	316.060	1.379
10	HDR_L3_D2_Bias	317.927	316.997	0.930
10	HDR_L3_D3_Bias	317.228	315.718	1.510
30	HDR_L1_D5_Bias	316.987	315.384	1.603
30	HDR_L2_D4_Bias	318.343	317.016	1.327
30	HDR_L2_D5_Bias	321.843	319.074	2.769
30	HDR_L3_D4_Bias	319.322	314.692	4.630
30	HDR_L3_D5_Bias	315.531	317.739	-2.208
50	HDR_L1_D6_Bias	320.240	317.324	2.916
50	HDR_L1_D7_Bias	317.500	315.404	2.096
50	HDR_L2_D6_Bias	316.631	314.941	1.690
50	HDR_L2_D7_Bias	315.774	315.403	0.371
50	HDR_L3_D6_Bias	321.476	319.848	1.628
100	HDR_L1_D8_Bias	320.066	313.106	6.960
100	HDR_L1_D9_Bias	319.846	318.234	1.612
100	HDR_L1_D10_Bias	318.907	318.572	0.335
100	HDR_L1_D11_Bias	319.187	316.005	3.182
100	HDR_L1_D12_Bias	319.869	317.743	2.126
100	HDR_L1_D13_Bias	319.045	316.927	2.118
100	HDR_L1_D14_Bias	319.343	319.161	0.182
100	HDR_L2_D8_Bias	318.839	314.141	4.698
100	HDR_L2_D9_Bias	316.920	305.461	11.459
100	HDR_L2_D10_Bias	317.309	315.985	1.324
100	HDR_L2_D11_Bias	319.825	316.422	3.403
100	HDR_L2_D12_Bias	320.216	317.951	2.265
100	HDR_L2_D13_Bias	316.685	314.348	2.337
100	HDR_L2_D14_Bias	319.788	318.736	1.052
100	HDR_L3_D7_Bias	321.334	316.094	5.240
100	HDR_L3_D8_Bias	315.905	312.240	3.665
100	HDR_L3_D9_Bias	316.555	307.807	8.748
100	HDR_L3_D10_Bias	320.011	318.161	1.850
100	HDR_L3_D11_Bias	320.053	317.200	2.853
100	HDR_L3_D12_Bias	320.156	320.540	-0.384
100	HDR_L3_D13_Bias	316.973	316.463	0.510
100	HDR_L3_D14_Bias	316.294	315.824	0.470
	Max	329.122	320.540	13.055
	Average	318.759	316.150	2.609
	Min	315.531	305.461	-2.208
	Std Dev	2.332	2.745	2.886



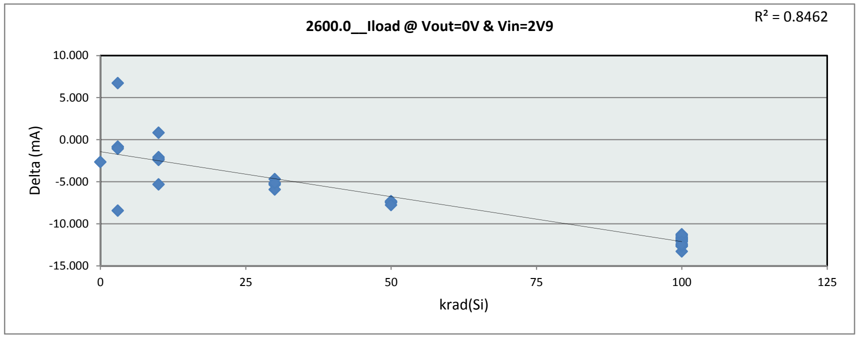
	1800.0__IRO					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	500	uA				
Min Limit	200	uA				
krad(Si)	0	3	10	30	50	100
LL	200.000	200.000	200.000	200.000	200.000	200.000
Min	316.067	315.103	315.718	314.692	314.941	305.461
Average	316.067	316.191	316.694	316.781	316.584	315.778
Max	316.067	317.632	318.043	319.074	319.848	320.540
UL	500.000	500.000	500.000	500.000	500.000	500.000



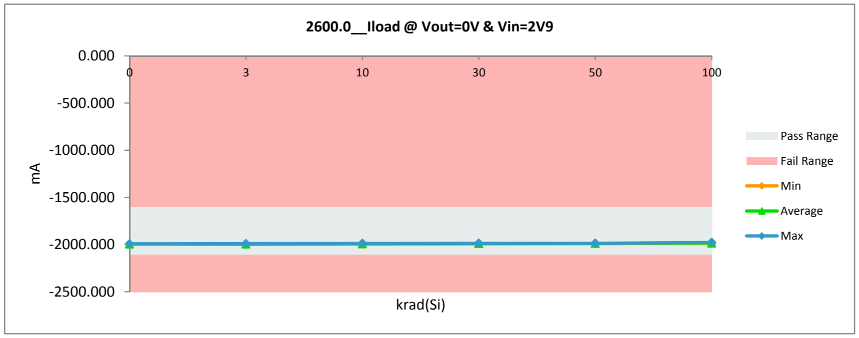
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2600.0__Iload @ Vout=0V & Vin=2V9		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	-1600	-1600	
	Min Limit	-2100	-2100	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	-1995.722	-1993.072	-2.650
3	HDR_L1_D1_Bias	-1996.431	-1995.521	-0.910
3	HDR_L1_D2_Bias	-1997.913	-1989.467	-8.446
3	HDR_L2_D1_Bias	-1990.295	-1997.011	6.716
3	HDR_L2_D2_Bias	-1993.349	-1992.521	-0.828
3	HDR_L3_D1_Bias	-1992.139	-1991.058	-1.081
10	HDR_L1_D3_Bias	-1997.007	-1994.724	-2.283
10	HDR_L1_D4_Bias	-1995.705	-1993.625	-2.080
10	HDR_L2_D3_Bias	-1988.724	-1989.549	0.825
10	HDR_L3_D2_Bias	-1991.852	-1986.542	-5.310
10	HDR_L3_D3_Bias	-1992.458	-1990.052	-2.406
30	HDR_L1_D5_Bias	-1996.118	-1990.764	-5.354
30	HDR_L2_D4_Bias	-1989.861	-1984.660	-5.201
30	HDR_L2_D5_Bias	-1996.694	-1992.009	-4.685
30	HDR_L3_D4_Bias	-1993.539	-1987.609	-5.930
30	HDR_L3_D5_Bias	-1993.188	-1988.035	-5.153
50	HDR_L1_D6_Bias	-1997.558	-1990.237	-7.321
50	HDR_L1_D7_Bias	-1995.574	-1988.082	-7.492
50	HDR_L2_D6_Bias	-1993.496	-1986.042	-7.454
50	HDR_L2_D7_Bias	-1992.664	-1985.310	-7.354
50	HDR_L3_D6_Bias	-1993.883	-1986.103	-7.780
100	HDR_L1_D8_Bias	-1997.301	-1985.461	-11.840
100	HDR_L1_D9_Bias	-1997.397	-1985.661	-11.736
100	HDR_L1_D10_Bias	-1997.396	-1985.453	-11.943
100	HDR_L1_D11_Bias	-1998.231	-1986.330	-11.901
100	HDR_L1_D12_Bias	-1997.440	-1985.378	-12.062
100	HDR_L1_D13_Bias	-1996.861	-1985.424	-11.437
100	HDR_L1_D14_Bias	-1995.211	-1983.533	-11.678
100	HDR_L2_D8_Bias	-1988.238	-1976.429	-11.809
100	HDR_L2_D9_Bias	-1992.703	-1980.903	-11.800
100	HDR_L2_D10_Bias	-1993.521	-1981.510	-12.011
100	HDR_L2_D11_Bias	-1992.485	-1980.818	-11.667
100	HDR_L2_D12_Bias	-1994.009	-1982.418	-11.591
100	HDR_L2_D13_Bias	-1993.607	-1981.847	-11.760
100	HDR_L2_D14_Bias	-1995.807	-1984.554	-11.253
100	HDR_L3_D7_Bias	-1994.381	-1981.988	-12.393
100	HDR_L3_D8_Bias	-1992.500	-1979.218	-13.282
100	HDR_L3_D9_Bias	-1993.399	-1980.745	-12.654
100	HDR_L3_D10_Bias	-1996.896	-1985.558	-11.338
100	HDR_L3_D11_Bias	-1994.454	-1981.898	-12.556
100	HDR_L3_D12_Bias	-1994.148	-1981.995	-12.153
100	HDR_L3_D13_Bias	-1992.098	-1979.419	-12.679
100	HDR_L3_D14_Bias	-1993.561	-1981.097	-12.464
	Max	-1988.238	-1976.429	6.716
	Average	-1994.321	-1986.270	-8.051
	Min	-1998.231	-1997.011	-13.282
	Std Dev	2.490	4.848	4.820



	2600.0__Iload @ Vout=					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	-1600	mA				
Min Limit	-2100	mA				
krad(Si)	0	3	10	30	50	100
LL	-2100.000	-2100.000	-2100.000	-2100.000	-2100.000	-2100.000
Min	-1993.072	-1997.011	-1994.724	-1992.009	-1990.237	-1986.330
Average	-1993.072	-1993.116	-1990.898	-1988.615	-1987.155	-1982.620
Max	-1993.072	-1989.467	-1986.542	-1984.660	-1985.310	-1976.429
UL	-1600.000	-1600.000	-1600.000	-1600.000	-1600.000	-1600.000

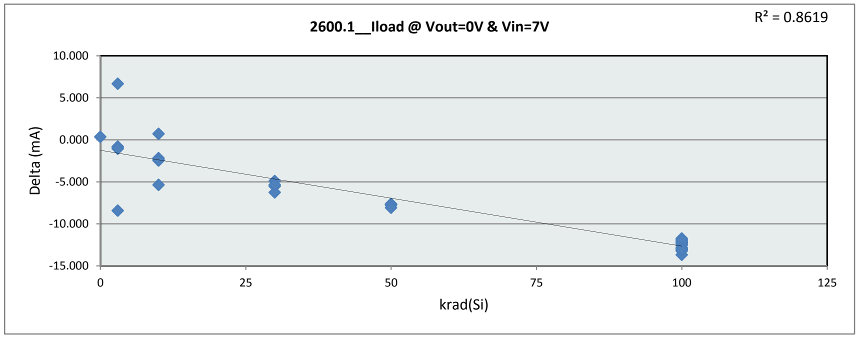


TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

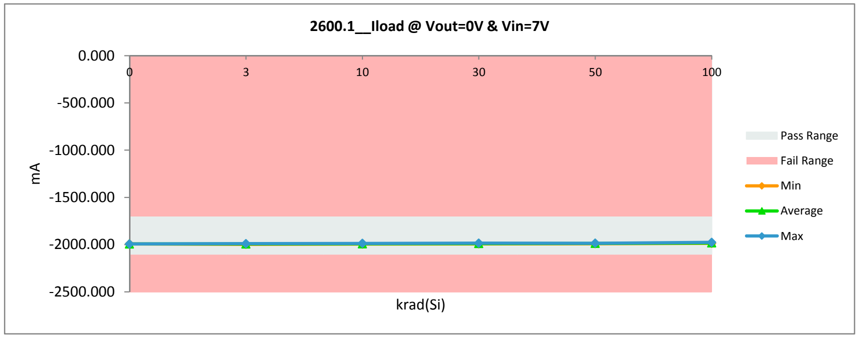
2600.1__Iload @ Vout=0V & Vin=7V

	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	-1700	-1700	
	Min Limit	-2100	-2100	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	-1992.674	-1993.017	0.343
3	HDR_L1_D1_Bias	-1996.343	-1995.449	-0.894
3	HDR_L1_D2_Bias	-1997.803	-1989.370	-8.433
3	HDR_L2_D1_Bias	-1990.188	-1996.852	6.664
3	HDR_L2_D2_Bias	-1993.211	-1992.394	-0.817
3	HDR_L3_D1_Bias	-1992.019	-1990.952	-1.067
10	HDR_L1_D3_Bias	-1996.901	-1994.524	-2.377
10	HDR_L1_D4_Bias	-1995.513	-1993.314	-2.199
10	HDR_L2_D3_Bias	-1988.645	-1989.344	0.699
10	HDR_L3_D2_Bias	-1991.715	-1986.340	-5.375
10	HDR_L3_D3_Bias	-1992.333	-1989.867	-2.466
30	HDR_L1_D5_Bias	-1996.028	-1990.488	-5.540
30	HDR_L2_D4_Bias	-1989.787	-1984.398	-5.389
30	HDR_L2_D5_Bias	-1996.519	-1991.602	-4.917
30	HDR_L3_D4_Bias	-1993.467	-1987.195	-6.272
30	HDR_L3_D5_Bias	-1993.089	-1987.720	-5.369
50	HDR_L1_D6_Bias	-1997.381	-1989.743	-7.638
50	HDR_L1_D7_Bias	-1995.453	-1987.693	-7.760
50	HDR_L2_D6_Bias	-1993.367	-1985.613	-7.754
50	HDR_L2_D7_Bias	-1992.564	-1984.836	-7.728
50	HDR_L3_D6_Bias	-1993.761	-1985.670	-8.091
100	HDR_L1_D8_Bias	-1997.192	-1984.919	-12.273
100	HDR_L1_D9_Bias	-1997.221	-1984.903	-12.318
100	HDR_L1_D10_Bias	-1997.301	-1984.801	-12.500
100	HDR_L1_D11_Bias	-1997.988	-1985.719	-12.269
100	HDR_L1_D12_Bias	-1997.330	-1984.821	-12.509
100	HDR_L1_D13_Bias	-1996.746	-1984.769	-11.977
100	HDR_L1_D14_Bias	-1995.178	-1982.939	-12.239
100	HDR_L2_D8_Bias	-1988.136	-1975.831	-12.305
100	HDR_L2_D9_Bias	-1992.536	-1980.368	-12.168
100	HDR_L2_D10_Bias	-1993.355	-1980.835	-12.520
100	HDR_L2_D11_Bias	-1992.304	-1980.172	-12.132
100	HDR_L2_D12_Bias	-1993.827	-1981.667	-12.160
100	HDR_L2_D13_Bias	-1993.469	-1981.258	-12.211
100	HDR_L2_D14_Bias	-1995.656	-1983.902	-11.754
100	HDR_L3_D7_Bias	-1994.259	-1981.334	-12.925
100	HDR_L3_D8_Bias	-1992.253	-1978.575	-13.678
100	HDR_L3_D9_Bias	-1993.320	-1980.292	-13.028
100	HDR_L3_D10_Bias	-1996.754	-1984.873	-11.881
100	HDR_L3_D11_Bias	-1994.330	-1981.231	-13.099
100	HDR_L3_D12_Bias	-1994.035	-1981.205	-12.830
100	HDR_L3_D13_Bias	-1992.023	-1978.797	-13.226
100	HDR_L3_D14_Bias	-1993.405	-1980.369	-13.036
	Max	-1988.136	-1975.831	6.664
	Average	-1994.125	-1985.813	-8.312
	Min	-1997.988	-1996.852	-13.678
	Std Dev	2.482	5.020	5.101



2600.1__Iload @ Vout=0

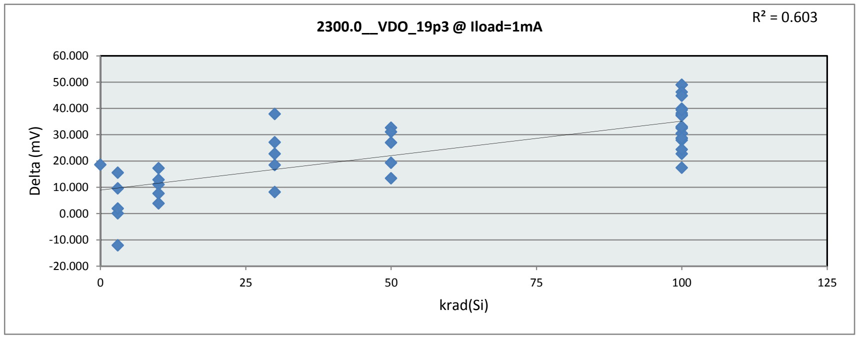
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	-1700 mA					
Min Limit	-2100 mA					
krad(Si)	0	3	10	30	50	100
LL	-2100.000	-2100.000	-2100.000	-2100.000	-2100.000	-2100.000
Min	-1993.017	-1996.852	-1994.524	-1991.602	-1989.743	-1985.719
Average	-1993.017	-1993.003	-1990.678	-1988.281	-1986.711	-1981.981
Max	-1993.017	-1989.370	-1986.340	-1984.398	-1984.836	-1975.831
UL	-1700.000	-1700.000	-1700.000	-1700.000	-1700.000	-1700.000



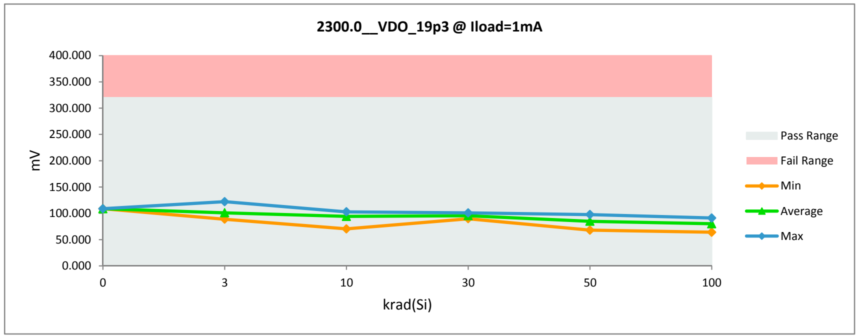
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.0__VDO_19p3 @ Iload=1mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	320	320	
	Min Limit	1	1	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	127.313	108.729	18.584
3	HDR_L1_D1_Bias	131.726	122.122	9.604
3	HDR_L1_D2_Bias	107.918	92.348	15.570
3	HDR_L2_D1_Bias	95.132	107.228	-12.096
3	HDR_L2_D2_Bias	88.898	88.834	0.064
3	HDR_L3_D1_Bias	96.103	94.199	1.904
10	HDR_L1_D3_Bias	113.907	102.839	11.068
10	HDR_L1_D4_Bias	118.275	101.042	17.233
10	HDR_L2_D3_Bias	110.729	97.888	12.841
10	HDR_L3_D2_Bias	106.012	98.384	7.628
10	HDR_L3_D3_Bias	74.257	70.410	3.847
30	HDR_L1_D5_Bias	121.786	94.672	27.114
30	HDR_L2_D4_Bias	113.382	94.945	18.437
30	HDR_L2_D5_Bias	120.323	97.576	22.747
30	HDR_L3_D4_Bias	108.978	100.827	8.151
30	HDR_L3_D5_Bias	127.589	89.711	37.878
50	HDR_L1_D6_Bias	125.919	93.286	32.633
50	HDR_L1_D7_Bias	98.606	79.287	19.319
50	HDR_L2_D6_Bias	112.677	85.696	26.981
50	HDR_L2_D7_Bias	81.272	67.885	13.387
50	HDR_L3_D6_Bias	128.759	97.690	31.069
100	HDR_L1_D8_Bias	115.460	77.248	38.212
100	HDR_L1_D9_Bias	119.871	80.001	39.870
100	HDR_L1_D10_Bias	106.050	78.180	27.870
100	HDR_L1_D11_Bias	103.980	73.510	30.470
100	HDR_L1_D12_Bias	115.465	77.798	37.667
100	HDR_L1_D13_Bias	135.797	86.818	48.979
100	HDR_L1_D14_Bias	107.031	84.292	22.739
100	HDR_L2_D8_Bias	108.302	75.702	32.600
100	HDR_L2_D9_Bias	107.731	70.465	37.266
100	HDR_L2_D10_Bias	94.187	69.810	24.377
100	HDR_L2_D11_Bias	111.670	79.200	32.470
100	HDR_L2_D12_Bias	122.657	85.261	37.396
100	HDR_L2_D13_Bias	81.450	64.047	17.403
100	HDR_L2_D14_Bias	115.035	86.444	28.591
100	HDR_L3_D7_Bias	132.068	83.137	48.931
100	HDR_L3_D8_Bias	130.267	84.075	46.192
100	HDR_L3_D9_Bias	97.793	67.340	30.453
100	HDR_L3_D10_Bias	117.682	85.010	32.672
100	HDR_L3_D11_Bias	114.646	81.599	33.047
100	HDR_L3_D12_Bias	119.233	90.495	28.738
100	HDR_L3_D13_Bias	130.255	90.832	39.423
100	HDR_L3_D14_Bias	135.848	91.036	44.812
	Max	135.848	122.122	48.979
	Average	112.373	87.160	25.213
	Min	74.257	64.047	-12.096
	Std Dev	14.914	12.394	14.032



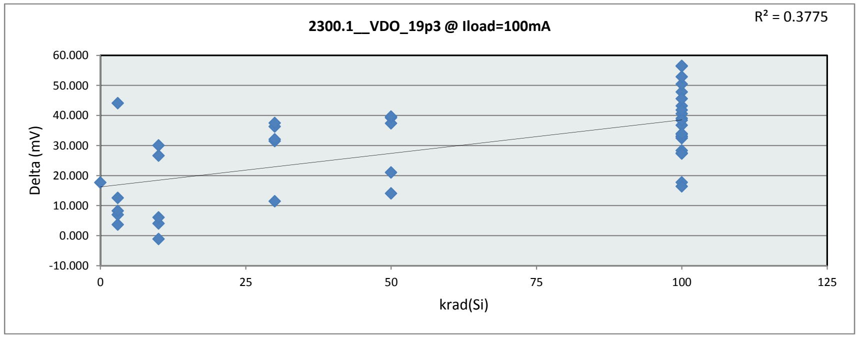
	2300.0__VDO_19p3 @ Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	320	mV				
Min Limit	1	mV				
krad(Si)	0	3	10	30	50	100
LL	1.000	1.000	1.000	1.000	1.000	1.000
Min	108.729	88.834	70.410	89.711	67.885	64.047
Average	108.729	100.946	94.113	95.546	84.769	80.105
Max	108.729	122.122	102.839	100.827	97.690	91.036
UL	320.000	320.000	320.000	320.000	320.000	320.000



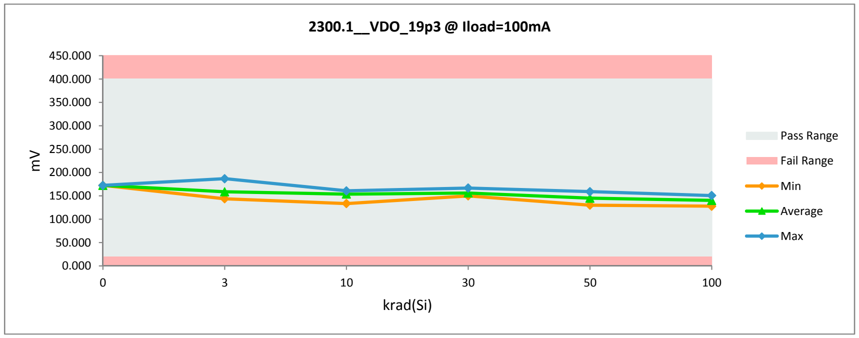
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.1__VDO_19p3 @ Iload=100mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	20	20	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	190.000	172.331	17.669
3	HDR_L1_D1_Bias	199.238	186.660	12.578
3	HDR_L1_D2_Bias	187.859	143.756	44.103
3	HDR_L2_D1_Bias	156.683	152.973	3.710
3	HDR_L2_D2_Bias	160.722	153.757	6.965
3	HDR_L3_D1_Bias	164.525	156.283	8.242
10	HDR_L1_D3_Bias	187.228	160.582	26.646
10	HDR_L1_D4_Bias	161.903	157.858	4.045
10	HDR_L2_D3_Bias	158.483	159.577	-1.094
10	HDR_L3_D2_Bias	186.474	156.400	30.074
10	HDR_L3_D3_Bias	139.499	133.411	6.088
30	HDR_L1_D5_Bias	183.621	152.126	31.495
30	HDR_L2_D4_Bias	182.013	149.945	32.068
30	HDR_L2_D5_Bias	196.817	160.502	36.315
30	HDR_L3_D4_Bias	178.066	166.599	11.467
30	HDR_L3_D5_Bias	188.405	150.880	37.525
50	HDR_L1_D6_Bias	191.717	152.461	39.256
50	HDR_L1_D7_Bias	175.940	138.528	37.412
50	HDR_L2_D6_Bias	165.246	144.193	21.053
50	HDR_L2_D7_Bias	144.140	130.056	14.084
50	HDR_L3_D6_Bias	198.660	159.011	39.649
100	HDR_L1_D8_Bias	178.075	137.471	40.604
100	HDR_L1_D9_Bias	185.070	137.259	47.811
100	HDR_L1_D10_Bias	179.261	136.045	43.216
100	HDR_L1_D11_Bias	178.439	132.843	45.596
100	HDR_L1_D12_Bias	175.356	138.589	36.767
100	HDR_L1_D13_Bias	179.148	146.707	32.441
100	HDR_L1_D14_Bias	169.449	141.963	27.486
100	HDR_L2_D8_Bias	169.375	136.291	33.084
100	HDR_L2_D9_Bias	158.787	130.462	28.325
100	HDR_L2_D10_Bias	150.797	133.044	17.753
100	HDR_L2_D11_Bias	173.387	140.463	32.924
100	HDR_L2_D12_Bias	183.851	144.815	39.036
100	HDR_L2_D13_Bias	144.202	127.794	16.408
100	HDR_L2_D14_Bias	192.412	141.969	50.443
100	HDR_L3_D7_Bias	198.193	141.766	56.427
100	HDR_L3_D8_Bias	187.986	146.148	41.838
100	HDR_L3_D9_Bias	162.782	129.001	33.781
100	HDR_L3_D10_Bias	176.323	148.972	27.351
100	HDR_L3_D11_Bias	183.406	144.995	38.411
100	HDR_L3_D12_Bias	201.876	148.959	52.917
100	HDR_L3_D13_Bias	207.127	150.634	56.493
100	HDR_L3_D14_Bias	181.827	147.915	33.912
	Max	207.127	186.660	56.493
	Average	177.078	147.023	30.055
	Min	139.499	127.794	-1.094
	Std Dev	16.355	12.236	15.056



	2300.1__VDO_19p3 @ Il				
Test Site	CLAB				
Tester	ETS#3				
Test Number	EF556000				
Max Limit	400 mV				
Min Limit	20 mV				
krad(Si)	0	3	10	30	50	100
LL	20.000	20.000	20.000	20.000	20.000	20.000
Min	172.331	143.756	133.411	149.945	130.056	127.794
Average	172.331	158.686	153.566	156.010	144.850	140.187
Max	172.331	186.660	160.582	166.599	159.011	150.634
UL	400.000	400.000	400.000	400.000	400.000	400.000

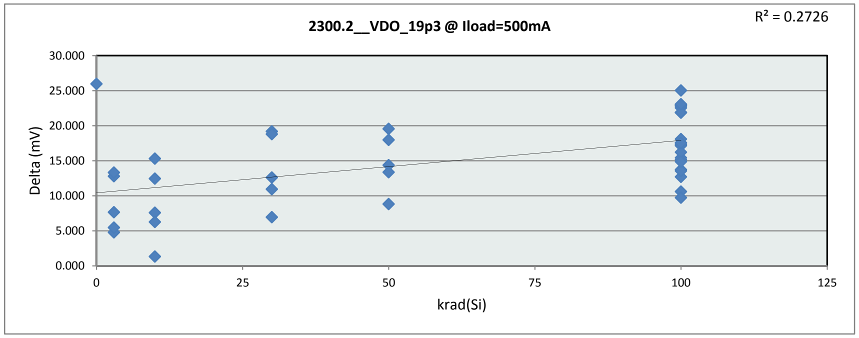


TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

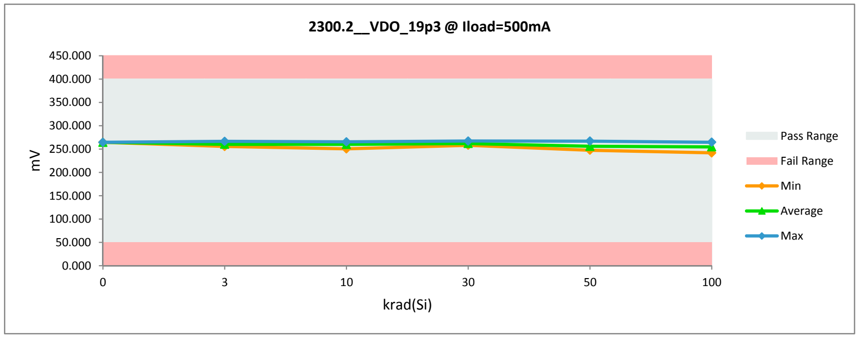
	2300.2__VDO_19p3 @ Iload=500mA	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	mV	mV
Max Limit	400	400
Min Limit	50	50

krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	290.391	264.431	25.960
3	HDR_L1_D1_Bias	279.208	266.433	12.775
3	HDR_L1_D2_Bias	268.747	255.431	13.316
3	HDR_L2_D1_Bias	264.264	259.496	4.768
3	HDR_L2_D2_Bias	261.541	256.085	5.456
3	HDR_L3_D1_Bias	270.825	263.174	7.651
10	HDR_L1_D3_Bias	275.457	260.174	15.283
10	HDR_L1_D4_Bias	268.558	260.990	7.568
10	HDR_L2_D3_Bias	266.773	265.444	1.329
10	HDR_L3_D2_Bias	275.248	262.799	12.449
10	HDR_L3_D3_Bias	256.608	250.354	6.254
30	HDR_L1_D5_Bias	269.006	258.071	10.935
30	HDR_L2_D4_Bias	272.499	259.889	12.610
30	HDR_L2_D5_Bias	281.911	262.737	19.174
30	HDR_L3_D4_Bias	274.024	267.094	6.930
30	HDR_L3_D5_Bias	279.716	260.937	18.779
50	HDR_L1_D6_Bias	275.728	256.185	19.543
50	HDR_L1_D7_Bias	266.553	252.189	14.364
50	HDR_L2_D6_Bias	269.785	256.434	13.351
50	HDR_L2_D7_Bias	256.278	247.459	8.819
50	HDR_L3_D6_Bias	284.837	266.872	17.965
100	HDR_L1_D8_Bias	269.895	247.367	22.528
100	HDR_L1_D9_Bias	271.377	253.823	17.554
100	HDR_L1_D10_Bias	266.770	253.058	13.712
100	HDR_L1_D11_Bias	271.405	248.441	22.964
100	HDR_L1_D12_Bias	269.561	252.273	17.288
100	HDR_L1_D13_Bias	272.083	256.672	15.411
100	HDR_L1_D14_Bias	268.194	255.497	12.697
100	HDR_L2_D8_Bias	270.164	252.087	18.077
100	HDR_L2_D9_Bias	266.844	241.828	25.016
100	HDR_L2_D10_Bias	261.335	250.749	10.586
100	HDR_L2_D11_Bias	271.530	254.389	17.141
100	HDR_L2_D12_Bias	272.284	258.750	13.534
100	HDR_L2_D13_Bias	256.014	246.294	9.720
100	HDR_L2_D14_Bias	279.386	256.618	22.768
100	HDR_L3_D7_Bias	279.869	257.030	22.839
100	HDR_L3_D8_Bias	281.372	259.521	21.851
100	HDR_L3_D9_Bias	266.962	245.081	21.881
100	HDR_L3_D10_Bias	278.763	263.629	15.134
100	HDR_L3_D11_Bias	273.410	257.209	16.201
100	HDR_L3_D12_Bias	278.372	263.519	14.853
100	HDR_L3_D13_Bias	286.923	263.873	23.050
100	HDR_L3_D14_Bias	282.001	264.484	17.517
	Max	290.391	267.094	25.960
	Average	272.150	257.090	15.060
	Min	256.014	241.828	1.329
	Std Dev	7.859	6.384	5.944



	2300.2__VDO_19p3 @ Il	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	400	mV
Min Limit	50	mV

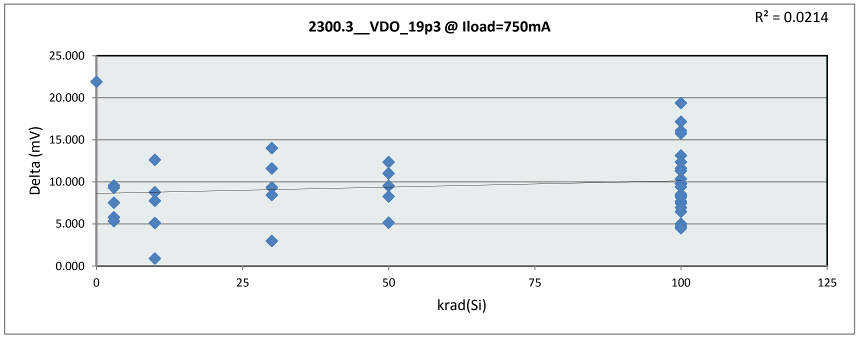
krad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	264.431	255.431	250.354	258.071	247.459	241.828
Average	264.431	260.124	259.952	261.746	255.828	254.645
Max	264.431	266.433	265.444	267.094	266.872	264.484
UL	400.000	400.000	400.000	400.000	400.000	400.000



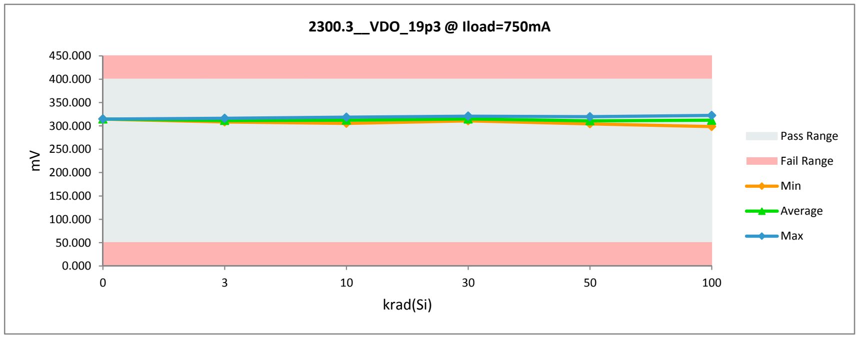
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.3__VDO_19p3 @ Iload=750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	50	50	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	336.527	314.633	21.894
3	HDR_L1_D1_Bias	324.376	314.835	9.541
3	HDR_L1_D2_Bias	318.012	308.714	9.298
3	HDR_L2_D1_Bias	317.459	309.947	7.512
3	HDR_L2_D2_Bias	314.228	308.441	5.787
3	HDR_L3_D1_Bias	321.452	316.119	5.333
10	HDR_L1_D3_Bias	319.617	310.869	8.748
10	HDR_L1_D4_Bias	319.726	311.982	7.744
10	HDR_L2_D3_Bias	319.410	318.533	0.877
10	HDR_L3_D2_Bias	327.409	314.798	12.611
10	HDR_L3_D3_Bias	310.498	305.401	5.097
30	HDR_L1_D5_Bias	319.288	310.864	8.424
30	HDR_L2_D4_Bias	323.187	313.868	9.319
30	HDR_L2_D5_Bias	325.155	313.572	11.583
30	HDR_L3_D4_Bias	323.785	320.820	2.965
30	HDR_L3_D5_Bias	328.602	314.596	14.006
50	HDR_L1_D6_Bias	323.335	310.995	12.340
50	HDR_L1_D7_Bias	317.006	307.502	9.504
50	HDR_L2_D6_Bias	320.008	311.757	8.251
50	HDR_L2_D7_Bias	309.456	304.313	5.143
50	HDR_L3_D6_Bias	330.640	319.649	10.991
100	HDR_L1_D8_Bias	319.256	303.190	16.066
100	HDR_L1_D9_Bias	321.278	310.932	10.346
100	HDR_L1_D10_Bias	316.777	310.322	6.455
100	HDR_L1_D11_Bias	318.089	304.956	13.133
100	HDR_L1_D12_Bias	318.404	308.648	9.756
100	HDR_L1_D13_Bias	321.645	313.983	7.662
100	HDR_L1_D14_Bias	318.021	313.011	5.010
100	HDR_L2_D8_Bias	321.998	310.403	11.595
100	HDR_L2_D9_Bias	317.889	298.520	19.369
100	HDR_L2_D10_Bias	313.749	309.030	4.719
100	HDR_L2_D11_Bias	322.356	312.556	9.800
100	HDR_L2_D12_Bias	323.645	315.482	8.163
100	HDR_L2_D13_Bias	309.250	304.768	4.482
100	HDR_L2_D14_Bias	324.424	313.122	11.302
100	HDR_L3_D7_Bias	330.039	314.288	15.751
100	HDR_L3_D8_Bias	329.660	317.324	12.336
100	HDR_L3_D9_Bias	318.745	301.614	17.131
100	HDR_L3_D10_Bias	329.345	321.887	7.458
100	HDR_L3_D11_Bias	324.257	314.860	9.397
100	HDR_L3_D12_Bias	327.851	320.926	6.925
100	HDR_L3_D13_Bias	330.880	322.372	8.508
100	HDR_L3_D14_Bias	330.464	322.100	8.364
	Max	336.527	322.372	21.894
	Average	321.795	312.244	9.551
	Min	309.250	298.520	0.877
	Std Dev	6.041	5.619	4.249



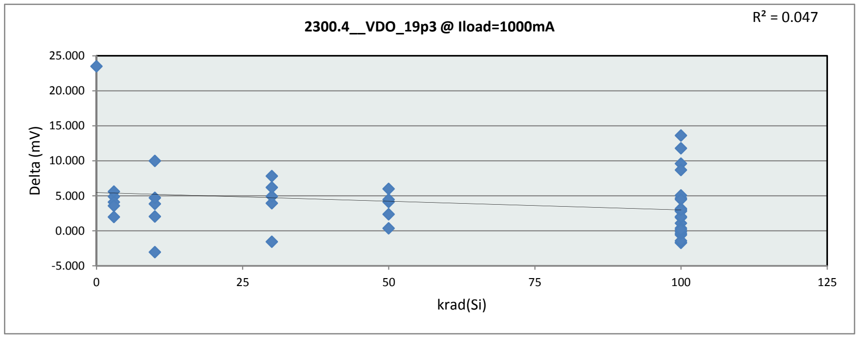
	2300.3__VDO_19p3 @ Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	400	mV				
Min Limit	50	mV				
krad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	314.633	308.441	305.401	310.864	304.313	298.520
Average	314.633	311.611	312.317	314.744	310.843	312.013
Max	314.633	316.119	318.533	320.820	319.649	322.372
UL	400.000	400.000	400.000	400.000	400.000	400.000



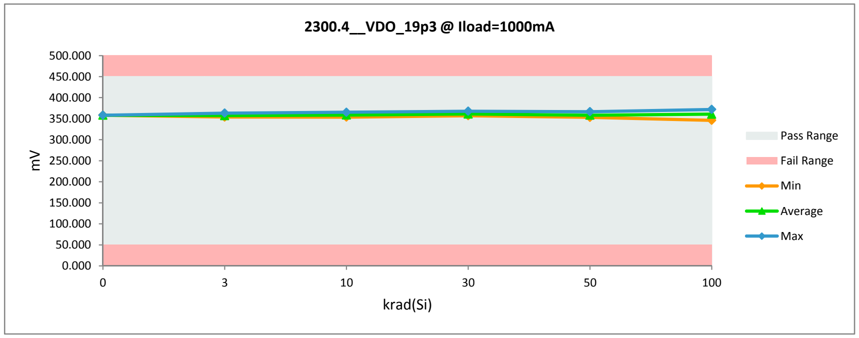
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.4__VDO_19p3 @ Iload=1000mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	450	450	
	Min Limit	50	50	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	381.699	358.221	23.478
3	HDR_L1_D1_Bias	363.592	358.711	4.881
3	HDR_L1_D2_Bias	359.674	355.597	4.077
3	HDR_L2_D1_Bias	360.934	355.354	5.580
3	HDR_L2_D2_Bias	357.374	353.812	3.562
3	HDR_L3_D1_Bias	365.112	363.153	1.959
10	HDR_L1_D3_Bias	359.694	355.859	3.835
10	HDR_L1_D4_Bias	362.168	357.465	4.703
10	HDR_L2_D3_Bias	362.297	365.355	-3.058
10	HDR_L3_D2_Bias	370.855	360.874	9.981
10	HDR_L3_D3_Bias	355.677	353.654	2.023
30	HDR_L1_D5_Bias	361.061	357.128	3.933
30	HDR_L2_D4_Bias	365.493	360.580	4.913
30	HDR_L2_D5_Bias	364.643	358.469	6.174
30	HDR_L3_D4_Bias	366.143	367.714	-1.571
30	HDR_L3_D5_Bias	369.797	361.989	7.808
50	HDR_L1_D6_Bias	363.298	357.320	5.978
50	HDR_L1_D7_Bias	359.471	355.360	4.111
50	HDR_L2_D6_Bias	361.503	359.147	2.356
50	HDR_L2_D7_Bias	353.489	353.144	0.345
50	HDR_L3_D6_Bias	371.003	366.544	4.459
100	HDR_L1_D8_Bias	360.560	350.965	9.595
100	HDR_L1_D9_Bias	362.481	359.330	3.151
100	HDR_L1_D10_Bias	358.809	359.414	-0.605
100	HDR_L1_D11_Bias	358.227	353.566	4.661
100	HDR_L1_D12_Bias	359.833	357.055	2.778
100	HDR_L1_D13_Bias	362.956	361.893	1.063
100	HDR_L1_D14_Bias	359.981	361.640	-1.659
100	HDR_L2_D8_Bias	364.527	359.473	5.054
100	HDR_L2_D9_Bias	359.749	346.148	13.601
100	HDR_L2_D10_Bias	356.598	358.330	-1.732
100	HDR_L2_D11_Bias	364.505	361.642	2.863
100	HDR_L2_D12_Bias	365.525	363.635	1.890
100	HDR_L2_D13_Bias	353.113	354.548	-1.435
100	HDR_L2_D14_Bias	362.897	360.894	2.003
100	HDR_L3_D7_Bias	371.782	363.110	8.672
100	HDR_L3_D8_Bias	371.009	366.527	4.482
100	HDR_L3_D9_Bias	362.268	350.483	11.785
100	HDR_L3_D10_Bias	371.977	371.611	0.366
100	HDR_L3_D11_Bias	366.728	363.721	3.007
100	HDR_L3_D12_Bias	369.813	370.214	-0.401
100	HDR_L3_D13_Bias	371.833	371.973	-0.140
100	HDR_L3_D14_Bias	371.530	371.404	0.126
	Max	381.699	371.973	23.478
	Average	363.760	359.838	3.922
	Min	353.113	346.148	-3.058
	Std Dev	5.777	5.833	4.775



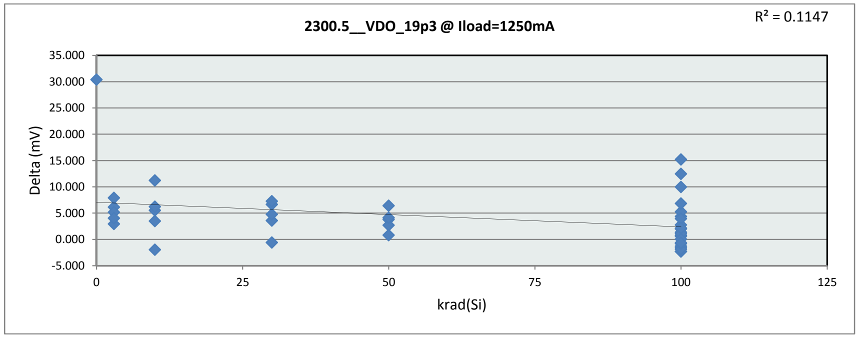
	2300.4__VDO_19p3 @ Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	450	mV				
Min Limit	50	mV				
krad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	358.221	353.812	353.654	357.128	353.144	346.148
Average	358.221	357.325	358.641	361.176	358.303	360.799
Max	358.221	363.153	365.355	367.714	366.544	371.973
UL	450.000	450.000	450.000	450.000	450.000	450.000



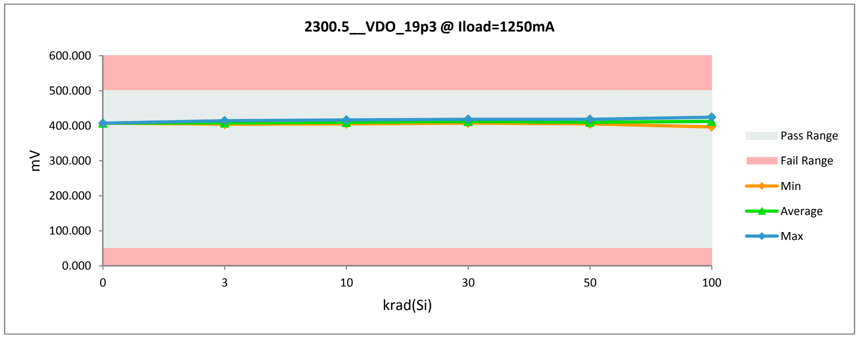
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.5__VDO_19p3 @ Iload=1250mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	500	500	
	Min Limit	50	50	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	CORR_L2_D45	437.801	407.397	30.404
3	HDR_L1_D1_Bias	413.198	407.050	6.148
3	HDR_L1_D2_Bias	409.919	406.979	2.940
3	HDR_L2_D1_Bias	413.723	405.828	7.895
3	HDR_L2_D2_Bias	409.223	404.058	5.165
3	HDR_L3_D1_Bias	418.297	414.261	4.036
10	HDR_L1_D3_Bias	410.619	405.085	5.534
10	HDR_L1_D4_Bias	414.393	408.154	6.239
10	HDR_L2_D3_Bias	414.676	416.637	-1.961
10	HDR_L3_D2_Bias	423.146	411.919	11.227
10	HDR_L3_D3_Bias	409.023	405.534	3.489
30	HDR_L1_D5_Bias	410.896	407.319	3.577
30	HDR_L2_D4_Bias	416.607	411.849	4.758
30	HDR_L2_D5_Bias	416.037	409.386	6.651
30	HDR_L3_D4_Bias	417.926	418.519	-0.593
30	HDR_L3_D5_Bias	420.661	413.409	7.252
50	HDR_L1_D6_Bias	414.016	407.592	6.424
50	HDR_L1_D7_Bias	410.691	406.886	3.805
50	HDR_L2_D6_Bias	413.394	410.699	2.695
50	HDR_L2_D7_Bias	405.897	405.087	0.810
50	HDR_L3_D6_Bias	422.511	418.383	4.128
100	HDR_L1_D8_Bias	411.470	401.491	9.979
100	HDR_L1_D9_Bias	413.015	411.642	1.373
100	HDR_L1_D10_Bias	409.288	411.591	-2.303
100	HDR_L1_D11_Bias	409.289	404.912	4.377
100	HDR_L1_D12_Bias	410.239	408.245	1.994
100	HDR_L1_D13_Bias	413.713	413.115	0.598
100	HDR_L1_D14_Bias	411.090	413.384	-2.294
100	HDR_L2_D8_Bias	416.922	411.681	5.241
100	HDR_L2_D9_Bias	411.869	396.656	15.213
100	HDR_L2_D10_Bias	408.984	410.560	-1.576
100	HDR_L2_D11_Bias	416.102	413.352	2.750
100	HDR_L2_D12_Bias	416.368	415.604	0.764
100	HDR_L2_D13_Bias	405.271	406.562	-1.291
100	HDR_L2_D14_Bias	413.416	412.320	1.096
100	HDR_L3_D7_Bias	422.008	415.183	6.825
100	HDR_L3_D8_Bias	421.775	417.837	3.938
100	HDR_L3_D9_Bias	414.151	401.670	12.481
100	HDR_L3_D10_Bias	424.427	424.366	0.061
100	HDR_L3_D11_Bias	417.498	415.360	2.138
100	HDR_L3_D12_Bias	420.323	422.193	-1.870
100	HDR_L3_D13_Bias	423.093	423.884	-0.791
100	HDR_L3_D14_Bias	423.303	423.943	-0.640
	Max	437.801	424.366	30.404
	Average	415.262	411.107	4.155
	Min	405.271	396.656	-2.303
	Std Dev	6.096	6.251	5.760



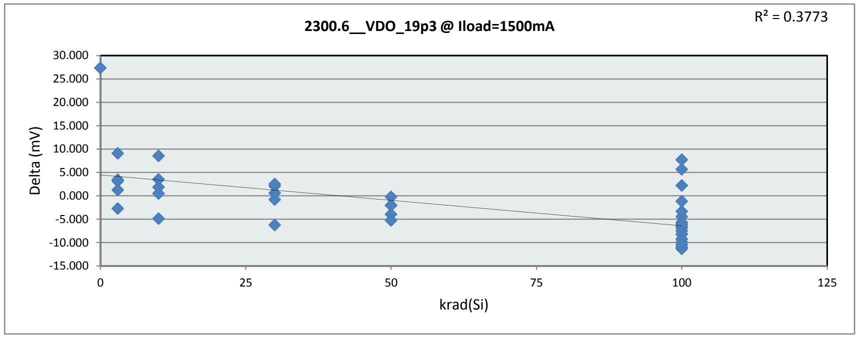
2300.5__VDO_19p3 @ Il						
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	500	mV				
Min Limit	50	mV				
krad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	407.397	404.058	405.085	407.319	405.087	396.656
Average	407.397	407.635	409.466	412.096	409.729	412.525
Max	407.397	414.261	416.637	418.519	418.383	424.366
UL	500.000	500.000	500.000	500.000	500.000	500.000



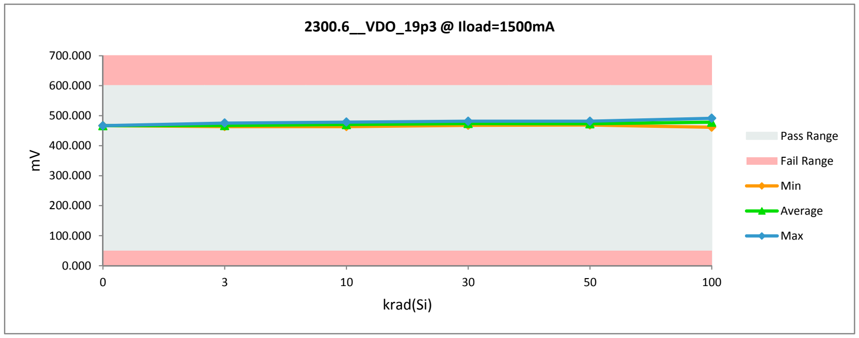
TPS7A4501-RHA
TID HDR Report (3KRad - 100KRad Bias)

All units passed SMD specification limits up to 100kRAD HDR.

		2300.6__VDO_19p3 @ Iload=1500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	600	600	
	Min Limit	50	50	
krad(Si)	Serial #	PreRad HDR(3K-100K Bias)	PostRad_HDR(3K-100K Bias)	Delta
0	_CORR_L2_D45	494.141	466.776	27.365
3	HDR_L1_D1_Bias	468.463	465.034	3.429
3	HDR_L1_D2_Bias	465.616	468.353	-2.737
3	HDR_L2_D1_Bias	472.767	463.687	9.080
3	HDR_L2_D2_Bias	466.926	463.811	3.115
3	HDR_L3_D1_Bias	476.726	475.482	1.244
10	HDR_L1_D3_Bias	465.446	463.597	1.849
10	HDR_L1_D4_Bias	471.940	468.440	3.500
10	HDR_L2_D3_Bias	473.595	478.510	-4.915
10	HDR_L3_D2_Bias	482.299	473.776	8.523
10	HDR_L3_D3_Bias	467.832	467.350	0.482
30	HDR_L1_D5_Bias	467.212	468.021	-0.809
30	HDR_L2_D4_Bias	475.222	474.631	0.591
30	HDR_L2_D5_Bias	472.089	470.028	2.061
30	HDR_L3_D4_Bias	475.174	481.439	-6.265
30	HDR_L3_D5_Bias	477.898	475.420	2.478
50	HDR_L1_D6_Bias	469.604	469.831	-0.227
50	HDR_L1_D7_Bias	467.328	469.369	-2.041
50	HDR_L2_D6_Bias	470.772	474.756	-3.984
50	HDR_L2_D7_Bias	463.857	469.124	-5.267
50	HDR_L3_D6_Bias	479.590	481.672	-2.082
100	HDR_L1_D8_Bias	466.955	464.782	2.173
100	HDR_L1_D9_Bias	470.007	476.920	-6.913
100	HDR_L1_D10_Bias	465.173	476.531	-11.358
100	HDR_L1_D11_Bias	464.262	468.734	-4.472
100	HDR_L1_D12_Bias	465.764	472.341	-6.577
100	HDR_L1_D13_Bias	469.928	478.188	-8.260
100	HDR_L1_D14_Bias	467.562	478.705	-11.143
100	HDR_L2_D8_Bias	476.154	479.505	-3.351
100	HDR_L2_D9_Bias	469.363	461.671	7.692
100	HDR_L2_D10_Bias	466.526	476.964	-10.438
100	HDR_L2_D11_Bias	474.345	480.471	-6.126
100	HDR_L2_D12_Bias	474.501	482.025	-7.524
100	HDR_L2_D13_Bias	462.880	472.775	-9.895
100	HDR_L2_D14_Bias	468.686	476.876	-8.190
100	HDR_L3_D7_Bias	479.777	480.990	-1.213
100	HDR_L3_D8_Bias	479.021	484.749	-5.728
100	HDR_L3_D9_Bias	471.501	465.856	5.645
100	HDR_L3_D10_Bias	482.220	491.476	-9.256
100	HDR_L3_D11_Bias	475.205	481.321	-6.116
100	HDR_L3_D12_Bias	477.641	488.721	-11.080
100	HDR_L3_D13_Bias	480.125	491.136	-11.011
100	HDR_L3_D14_Bias	480.394	490.878	-10.484
	Max	494.141	491.476	27.365
	Average	472.383	474.668	-2.285
	Min	462.880	461.671	-11.358
	Std Dev	6.433	7.951	7.354



	2300.6__VDO_19p3 @ Il					
Test Site	CLAB					
Tester	ETS#3					
Test Number	EF556000					
Max Limit	600	mV				
Min Limit	50	mV				
krad(Si)	0	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000	50.000
Min	466.776	463.687	463.597	468.021	469.124	461.671
Average	466.776	467.273	470.335	473.908	472.950	478.255
Max	466.776	475.482	478.510	481.439	481.672	491.476
UL	600.000	600.000	600.000	600.000	600.000	600.000



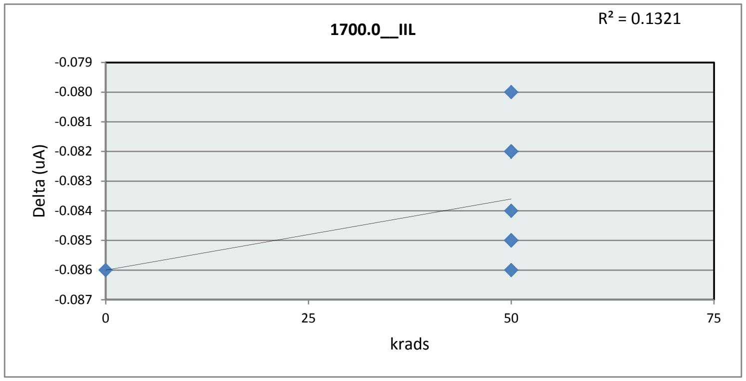
TPS7A4501-RHA

TID LDR Report 50 KRad (Bias and Unbias)

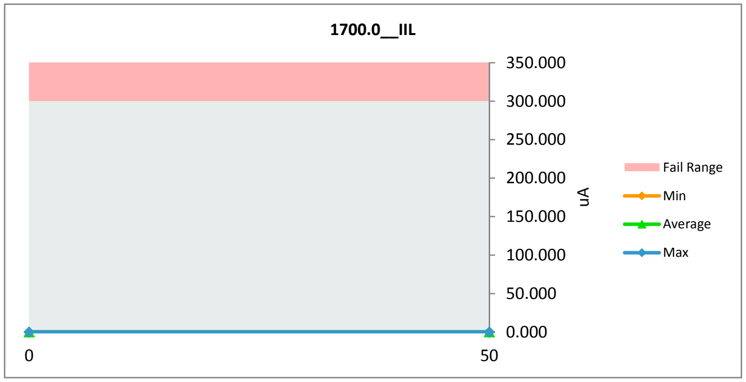
All units passed SMD specification limits.

TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		1700.0__IIL		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		uA	uA	
Max Limit		300	300	
Min Limit				
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	0.000	0.086	-0.086
50	LDR_L1_D22_Unbias	0.002	0.084	-0.082
50	LDR_L1_D23_Unbias	0.000	0.084	-0.084
50	LDR_L2_D23_Unbias	0.001	0.086	-0.085
50	LDR_L2_D24_Unbias	0.000	0.085	-0.085
50	LDR_L3_D22_Unbias	0.001	0.086	-0.085
50	LDR_L1_D16_bias	0.002	0.082	-0.080
50	LDR_L1_D17_bias	0.002	0.084	-0.082
50	LDR_L2_D17_bias	0.000	0.086	-0.086
50	LDR_L2_D18_bias	0.001	0.083	-0.082
50	LDR_L2_D19_bias	0.000	0.085	-0.085
	Max	0.002	0.086	-0.080
	Average	0.001	0.085	-0.084
	Min	0.000	0.082	-0.086
	Std Dev	0.001	0.001	0.002



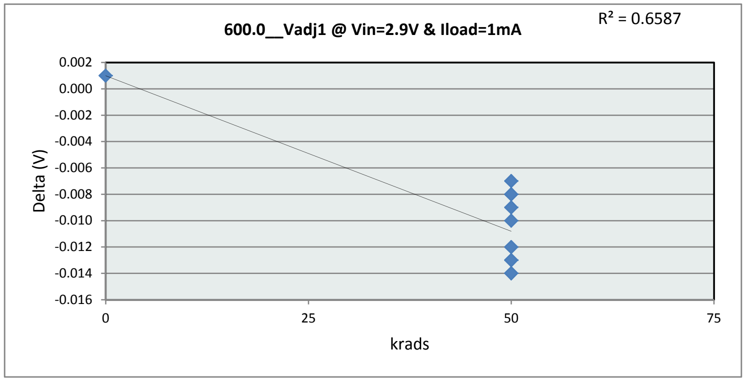
	1700.0__IIL	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	300	uA
Min Limit		uA
krads	0	50
LL		
Min	0.086	0.082
Average	0.086	0.085
Max	0.086	0.086
UL	300.000	300.000



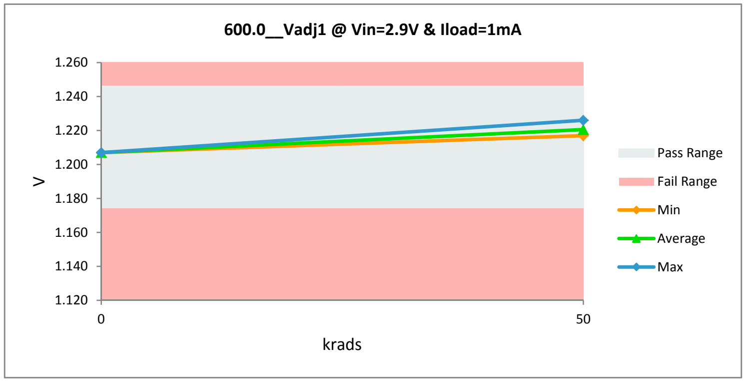
TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA

All units passed SMD specification limits up to 50kRAD LDR.

		600.0__Vadj1 @ Vin=2.9V & Iloa		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	1.246	1.246	
	Min Limit	1.174	1.174	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	1.208	1.207	0.001
50	LDR_L1_D22_Unbias	1.208	1.217	-0.009
50	LDR_L1_D23_Unbias	1.209	1.217	-0.008
50	LDR_L2_D23_Unbias	1.211	1.218	-0.007
50	LDR_L2_D24_Unbias	1.209	1.217	-0.008
50	LDR_L3_D22_Unbias	1.207	1.217	-0.010
50	LDR_L1_D16_bias	1.212	1.226	-0.014
50	LDR_L1_D17_bias	1.209	1.223	-0.014
50	LDR_L2_D17_bias	1.211	1.223	-0.012
50	LDR_L2_D18_bias	1.208	1.221	-0.013
50	LDR_L2_D19_bias	1.213	1.226	-0.013
	Max	1.213	1.226	0.001
	Average	1.210	1.219	-0.010
	Min	1.207	1.207	-0.014
	Std Dev	0.002	0.005	0.004

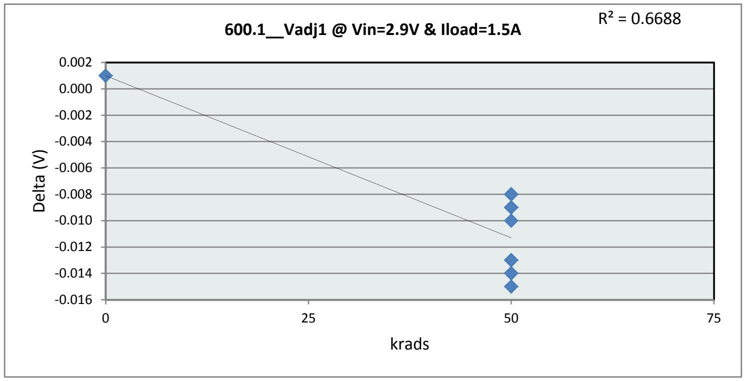


	600.0__Vadj1 @ Vin=2.9V & Iload=1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.246	V
Min Limit	1.174	V
krads	0	50
LL	1.174	1.174
Min	1.207	1.217
Average	1.207	1.221
Max	1.207	1.226
UL	1.246	1.246

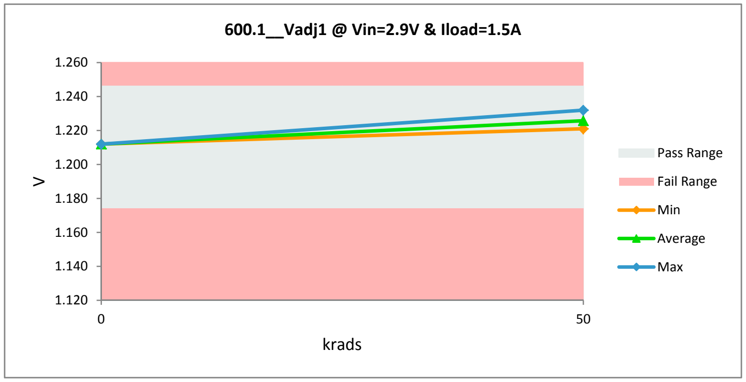


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		600.1__Vadj1 @ Vin=2.9V & Iloa		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		V	V	
Max Limit		1.246	1.246	
Min Limit		1.174	1.174	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	1.213	1.212	0.001
50	LDR_L1_D22_Unbias	1.213	1.222	-0.009
50	LDR_L1_D23_Unbias	1.213	1.222	-0.009
50	LDR_L2_D23_Unbias	1.215	1.223	-0.008
50	LDR_L2_D24_Unbias	1.214	1.222	-0.008
50	LDR_L3_D22_Unbias	1.211	1.221	-0.010
50	LDR_L1_D16_bias	1.217	1.231	-0.014
50	LDR_L1_D17_bias	1.214	1.229	-0.015
50	LDR_L2_D17_bias	1.216	1.229	-0.013
50	LDR_L2_D18_bias	1.213	1.226	-0.013
50	LDR_L2_D19_bias	1.218	1.232	-0.014
	Max	1.218	1.232	0.001
	Average	1.214	1.224	-0.010
	Min	1.211	1.212	-0.015
	Std Dev	0.002	0.006	0.005

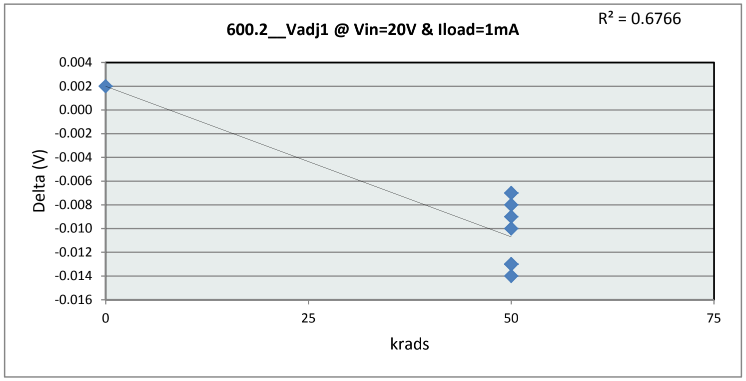


	600.1__Vadj1 @ Vin=2.9V & Iload=1.5A	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.246	V
Min Limit	1.174	V
krads	0	50
LL	1.174	1.174
Min	1.212	1.221
Average	1.212	1.226
Max	1.212	1.232
UL	1.246	1.246

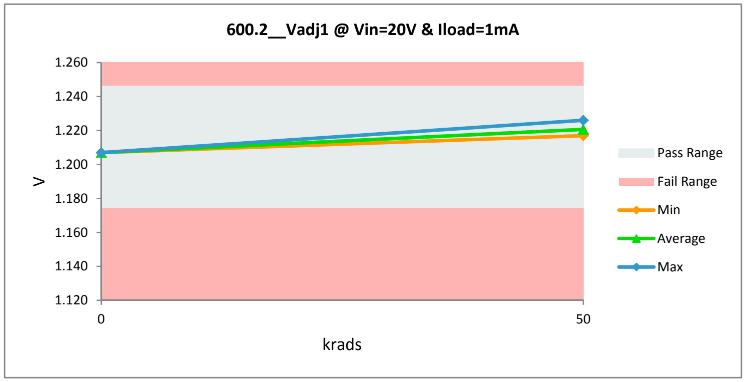


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		600.2__Vadj1 @ Vin=20V & Iloa		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	1.246	1.246	
	Min Limit	1.174	1.174	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	1.209	1.207	0.002
50	LDR_L1_D22_Unbias	1.208	1.217	-0.009
50	LDR_L1_D23_Unbias	1.209	1.217	-0.008
50	LDR_L2_D23_Unbias	1.211	1.218	-0.007
50	LDR_L2_D24_Unbias	1.210	1.217	-0.007
50	LDR_L3_D22_Unbias	1.207	1.217	-0.010
50	LDR_L1_D16_bias	1.212	1.226	-0.014
50	LDR_L1_D17_bias	1.210	1.223	-0.013
50	LDR_L2_D17_bias	1.211	1.224	-0.013
50	LDR_L2_D18_bias	1.208	1.221	-0.013
50	LDR_L2_D19_bias	1.213	1.226	-0.013
	Max	1.213	1.226	0.002
	Average	1.210	1.219	-0.010
	Min	1.207	1.207	-0.014
	Std Dev	0.002	0.006	0.005

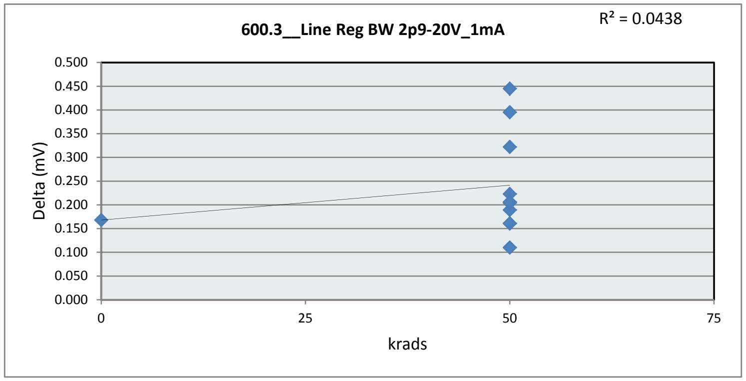


	600.2__Vadj1 @ Vin=20V & Iload=1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.246	V
Min Limit	1.174	V
krads	0	50
LL	1.174	1.174
Min	1.207	1.217
Average	1.207	1.221
Max	1.207	1.226
UL	1.246	1.246

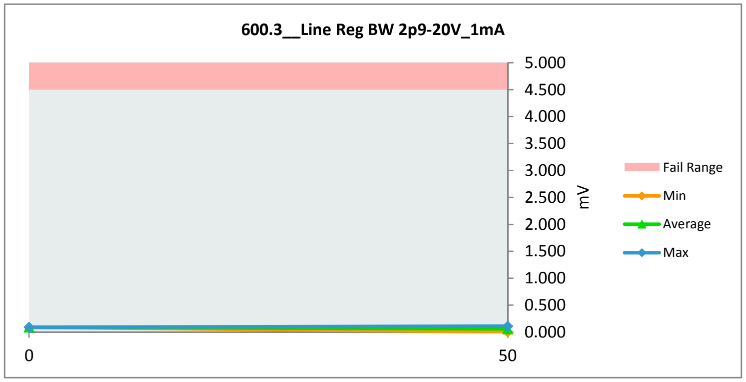


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

			600.3__Line Reg BW 2p9-20V_1	
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	4.5	4.5	
	Min Limit			
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	0.258	0.090	0.168
50	LDR_L1_D22_Unbias	0.219	0.109	0.110
50	LDR_L1_D23_Unbias	0.240	0.079	0.161
50	LDR_L2_D23_Unbias	0.386	0.064	0.322
50	LDR_L2_D24_Unbias	0.173	0.012	0.161
50	LDR_L3_D22_Unbias	0.299	0.110	0.189
50	LDR_L1_D16_bias	0.476	0.081	0.395
50	LDR_L1_D17_bias	0.318	0.095	0.223
50	LDR_L2_D17_bias	0.243	0.039	0.204
50	LDR_L2_D18_bias	0.209	0.003	0.206
50	LDR_L2_D19_bias	0.452	0.007	0.445
	Max	0.476	0.110	0.445
	Average	0.298	0.063	0.235
	Min	0.173	0.003	0.110
	Std Dev	0.101	0.041	0.106

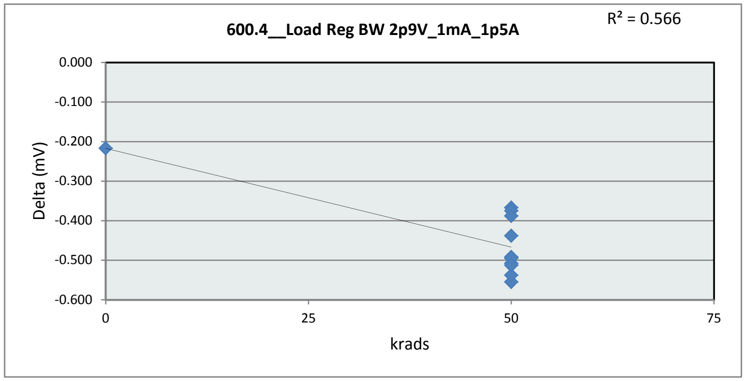


	600.3__Line Reg BW 2p9-20V_1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	4.5	mV
Min Limit		mV
krads	0	50
LL		
Min	0.090	0.003
Average	0.090	0.060
Max	0.090	0.110
UL	4.500	4.500

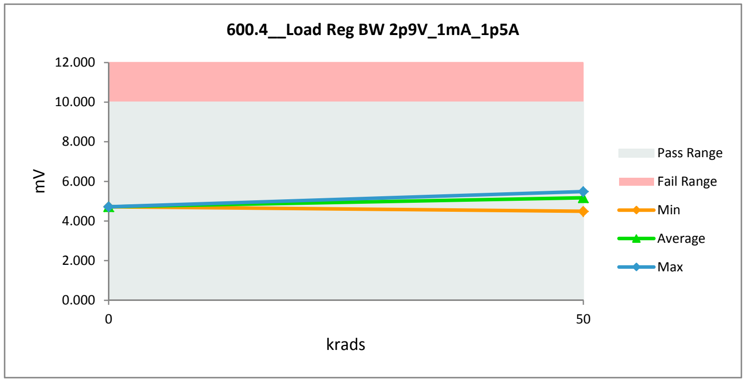


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		600.4__Load Reg BW 2p9V_1mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		10	10	
Min Limit		0	0	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	4.506	4.723	-0.217
50	LDR_L1_D22_Unbias	4.844	5.352	-0.508
50	LDR_L1_D23_Unbias	4.702	5.069	-0.367
50	LDR_L2_D23_Unbias	4.556	5.048	-0.492
50	LDR_L2_D24_Unbias	5.016	5.454	-0.438
50	LDR_L3_D22_Unbias	4.115	4.490	-0.375
50	LDR_L1_D16_bias	4.824	5.379	-0.555
50	LDR_L1_D17_bias	4.518	5.056	-0.538
50	LDR_L2_D17_bias	4.959	5.454	-0.495
50	LDR_L2_D18_bias	4.582	4.970	-0.388
50	LDR_L2_D19_bias	4.975	5.488	-0.513
	Max	5.016	5.488	-0.217
	Average	4.691	5.135	-0.444
	Min	4.115	4.490	-0.555
	Std Dev	0.269	0.326	0.100



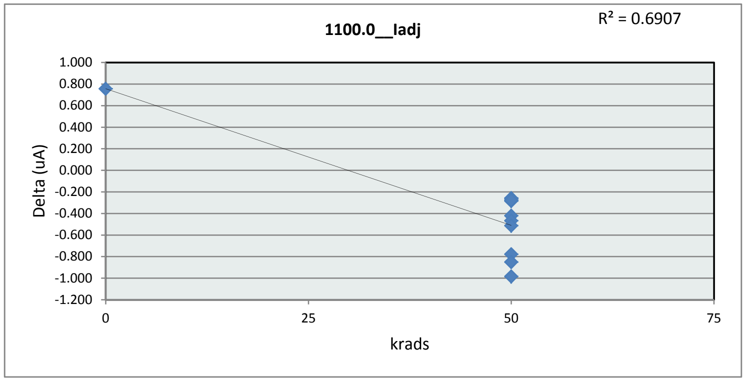
	600.4__Load Reg BW 2p9V_1mA_1p5A	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	10	mV
Min Limit	0	mV
krads	0	50
LL	0.000	0.000
Min	4.723	4.490
Average	4.723	5.176
Max	4.723	5.488
UL	10.000	10.000



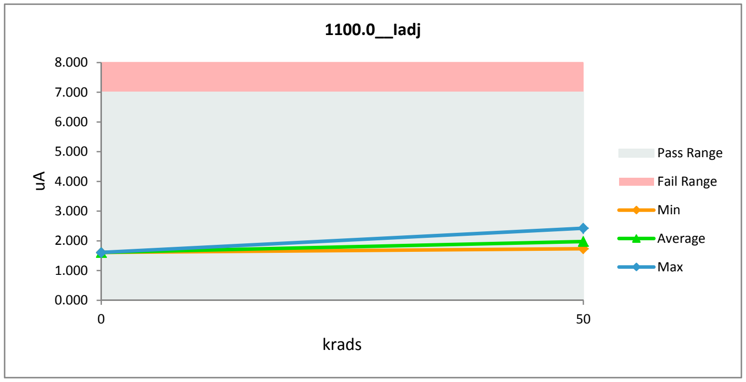
TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

	1100.0__Iadj	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	uA	uA
Max Limit	7	7
Min Limit	0	0

krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	2.367	1.610	0.757
50	LDR_L1_D22_Unbias	1.353	1.774	-0.421
50	LDR_L1_D23_Unbias	1.501	1.763	-0.262
50	LDR_L2_D23_Unbias	1.452	1.736	-0.284
50	LDR_L2_D24_Unbias	1.497	1.755	-0.258
50	LDR_L3_D22_Unbias	1.512	1.789	-0.277
50	LDR_L1_D16_bias	1.458	1.925	-0.467
50	LDR_L1_D17_bias	1.426	1.939	-0.513
50	LDR_L2_D17_bias	1.366	2.350	-0.984
50	LDR_L2_D18_bias	1.535	2.313	-0.778
50	LDR_L2_D19_bias	1.575	2.426	-0.851
	Max	2.367	2.426	0.757
	Average	1.549	1.944	-0.394
	Min	1.353	1.610	-0.984
	Std Dev	0.279	0.285	0.459

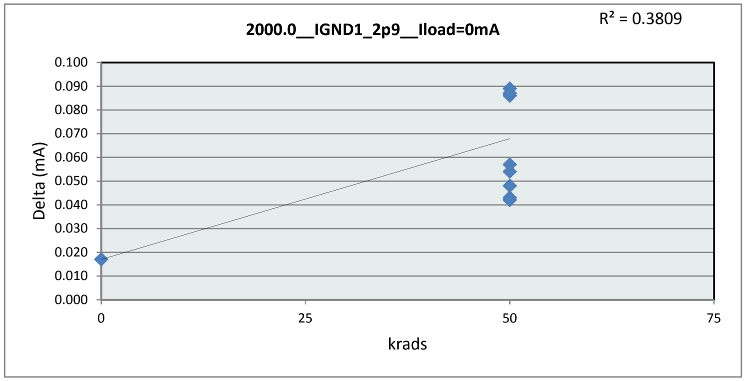


	1100.0__Iadj	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	7	uA
Min Limit	0	uA
krads	0	50
LL	0.000	0.000
Min	1.610	1.736
Average	1.610	1.977
Max	1.610	2.426
UL	7.000	7.000

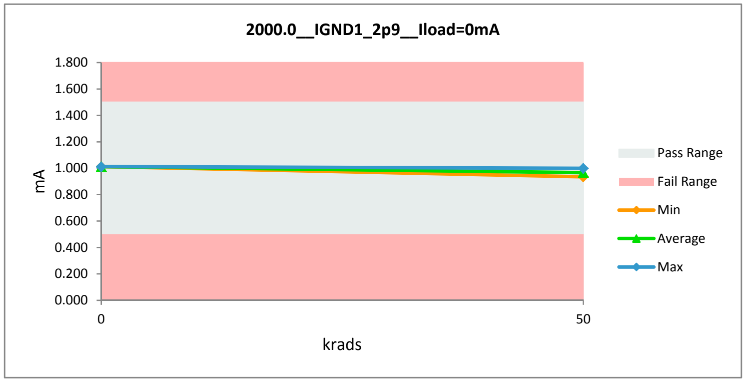


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2000.0__IGND1_2p9__Iload=0		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	1.5	1.5	
	Min Limit	0.5	0.5	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	1.029	1.012	0.017
50	LDR_L1_D22_Unbias	1.023	0.969	0.054
50	LDR_L1_D23_Unbias	1.033	0.985	0.048
50	LDR_L2_D23_Unbias	1.028	0.985	0.043
50	LDR_L2_D24_Unbias	1.041	0.999	0.042
50	LDR_L3_D22_Unbias	1.038	0.981	0.057
50	LDR_L1_D16_bias	1.040	0.954	0.086
50	LDR_L1_D17_bias	1.024	0.935	0.089
50	LDR_L2_D17_bias	1.034	0.947	0.087
50	LDR_L2_D18_bias	1.044	0.958	0.086
50	LDR_L2_D19_bias	1.044	0.957	0.087
	Max	1.044	1.012	0.089
	Average	1.034	0.971	0.063
	Min	1.023	0.935	0.017
	Std Dev	0.008	0.023	0.025

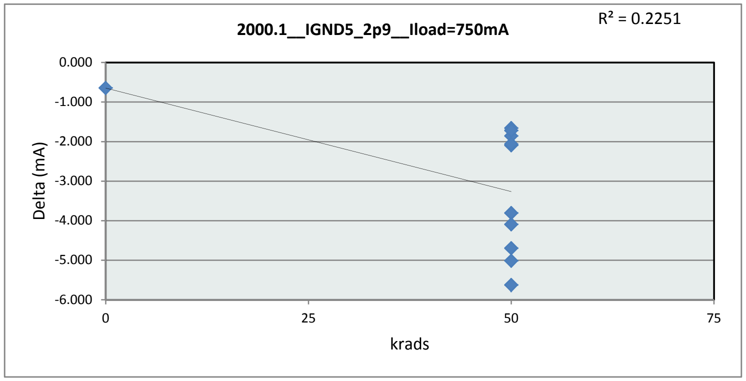


	2000.0__IGND1_2p9__Iload=0mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.5	mA
Min Limit	0.5	mA
krads	0	50
LL	0.500	0.500
Min	1.012	0.935
Average	1.012	0.967
Max	1.012	0.999
UL	1.500	1.500

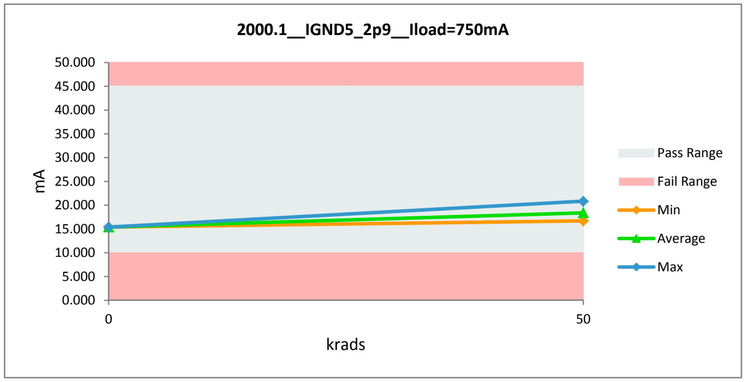


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2000.1__IGND5_2p9__Iload=75		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	45	45	
	Min Limit	10	10	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	14.745	15.391	-0.646
50	LDR_L1_D22_Unbias	14.704	16.800	-2.096
50	LDR_L1_D23_Unbias	14.857	16.713	-1.856
50	LDR_L2_D23_Unbias	15.059	16.717	-1.658
50	LDR_L2_D24_Unbias	16.058	17.777	-1.719
50	LDR_L3_D22_Unbias	15.014	17.077	-2.063
50	LDR_L1_D16_bias	15.134	19.829	-4.695
50	LDR_L1_D17_bias	14.786	20.413	-5.627
50	LDR_L2_D17_bias	15.423	19.230	-3.807
50	LDR_L2_D18_bias	14.516	18.610	-4.094
50	LDR_L2_D19_bias	15.820	20.835	-5.015
	Max	16.058	20.835	-0.646
	Average	15.101	18.127	-3.025
	Min	14.516	15.391	-5.627
	Std Dev	0.483	1.771	1.663

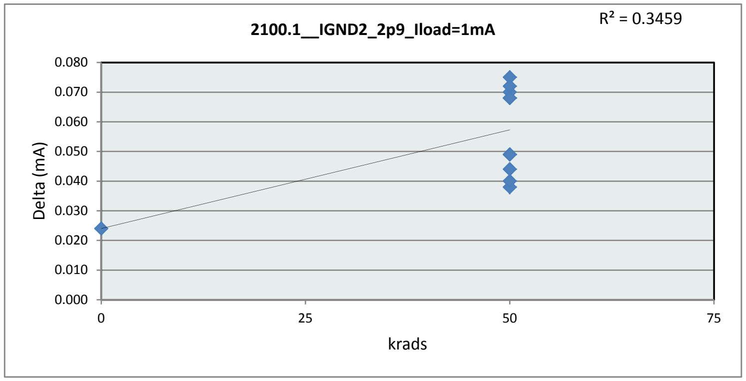


	2000.1__IGND5_2p9__Iload=750mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	45	mA
Min Limit	10	mA
krads	0	50
LL	10.000	10.000
Min	15.391	16.713
Average	15.391	18.400
Max	15.391	20.835
UL	45.000	45.000

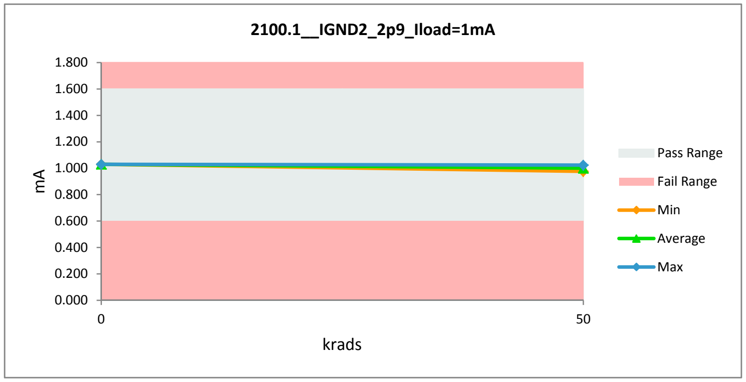


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2100.1__IGND2_2p9_Iload=1m		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	1.6	1.6	
	Min Limit	0.6	0.6	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	1.054	1.030	0.024
50	LDR_L1_D22_Unbias	1.047	0.998	0.049
50	LDR_L1_D23_Unbias	1.057	1.013	0.044
50	LDR_L2_D23_Unbias	1.050	1.012	0.038
50	LDR_L2_D24_Unbias	1.064	1.024	0.040
50	LDR_L3_D22_Unbias	1.059	1.010	0.049
50	LDR_L1_D16_bias	1.062	0.992	0.070
50	LDR_L1_D17_bias	1.044	0.976	0.068
50	LDR_L2_D17_bias	1.059	0.984	0.075
50	LDR_L2_D18_bias	1.063	0.995	0.068
50	LDR_L2_D19_bias	1.067	0.995	0.072
	Max	1.067	1.030	0.075
	Average	1.057	1.003	0.054
	Min	1.044	0.976	0.024
	Std Dev	0.007	0.017	0.017

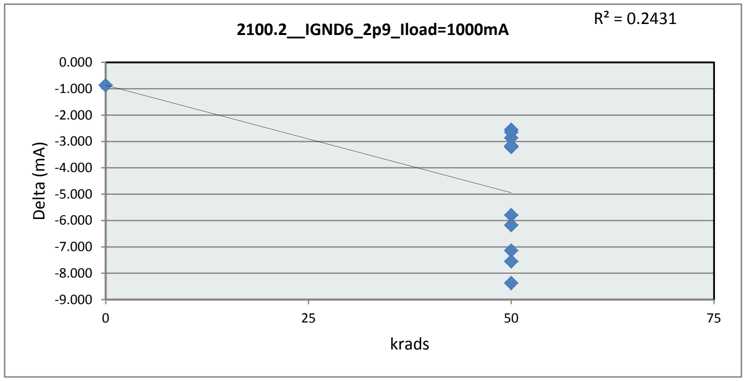


	2100.1__IGND2_2p9_Iload=1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.6	mA
Min Limit	0.6	mA
krads	0	50
LL	0.600	0.600
Min	1.030	0.976
Average	1.030	1.000
Max	1.030	1.024
UL	1.600	1.600

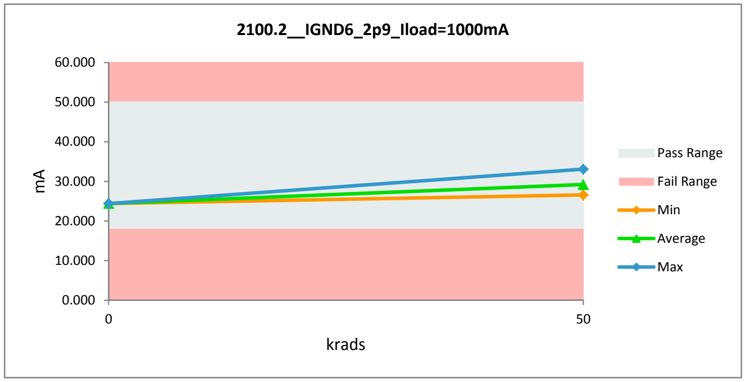


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2100.2__IGND6_2p9_Iload=100		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	50	50	
	Min Limit	18	18	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	23.564	24.429	-0.865
50	LDR_L1_D22_Unbias	23.502	26.711	-3.209
50	LDR_L1_D23_Unbias	23.733	26.593	-2.860
50	LDR_L2_D23_Unbias	24.090	26.639	-2.549
50	LDR_L2_D24_Unbias	25.881	28.523	-2.642
50	LDR_L3_D22_Unbias	24.046	27.211	-3.165
50	LDR_L1_D16_bias	24.263	31.402	-7.139
50	LDR_L1_D17_bias	23.620	31.986	-8.366
50	LDR_L2_D17_bias	24.710	30.501	-5.791
50	LDR_L2_D18_bias	23.222	29.395	-6.173
50	LDR_L2_D19_bias	25.554	33.101	-7.547
	Max	25.881	33.101	-0.865
	Average	24.199	28.772	-4.573
	Min	23.222	24.429	-8.366
	Std Dev	0.858	2.725	2.494

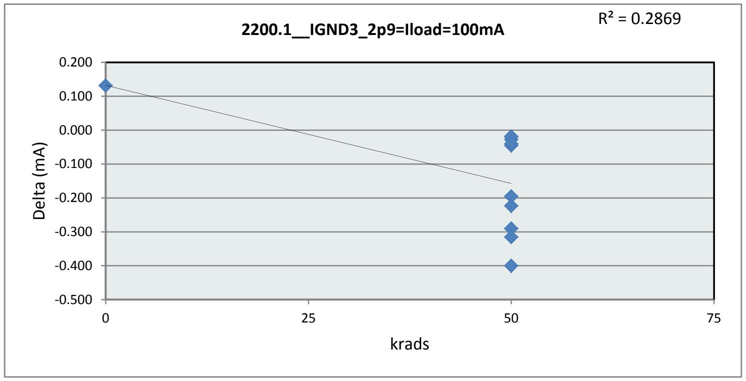


	2100.2__IGND6_2p9_Iload=1000mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	50	mA
Min Limit	18	mA
krads	0	50
LL	18.000	18.000
Min	24.429	26.593
Average	24.429	29.206
Max	24.429	33.101
UL	50.000	50.000

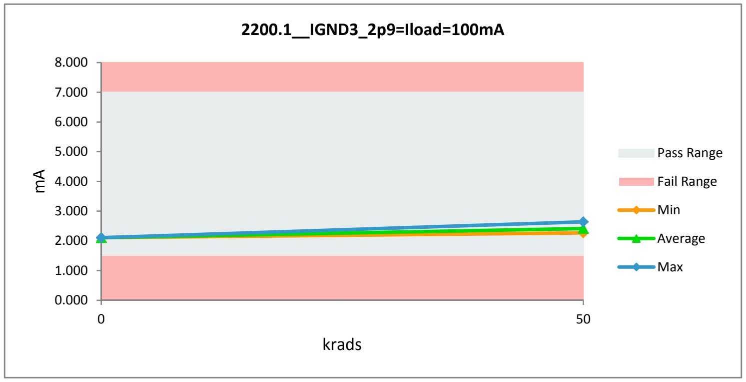


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2200.1__IGND3_2p9=Iload=10		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	7	7	
	Min Limit	1.5	1.5	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	2.240	2.108	0.132
50	LDR_L1_D22_Unbias	2.233	2.278	-0.045
50	LDR_L1_D23_Unbias	2.256	2.283	-0.027
50	LDR_L2_D23_Unbias	2.251	2.270	-0.019
50	LDR_L2_D24_Unbias	2.293	2.311	-0.018
50	LDR_L3_D22_Unbias	2.259	2.299	-0.040
50	LDR_L1_D16_bias	2.266	2.556	-0.290
50	LDR_L1_D17_bias	2.243	2.643	-0.400
50	LDR_L2_D17_bias	2.275	2.470	-0.195
50	LDR_L2_D18_bias	2.235	2.458	-0.223
50	LDR_L2_D19_bias	2.283	2.598	-0.315
	Max	2.293	2.643	0.132
	Average	2.258	2.389	-0.131
	Min	2.233	2.108	-0.400
	Std Dev	0.020	0.167	0.163

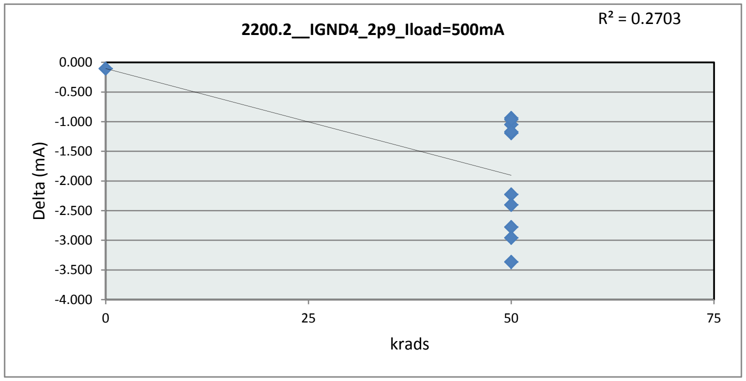


	2200.1__IGND3_2p9=Iload=100mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	7	mA
Min Limit	1.5	mA
krads	0	50
LL	1.500	1.500
Min	2.108	2.270
Average	2.108	2.417
Max	2.108	2.643
UL	7.000	7.000

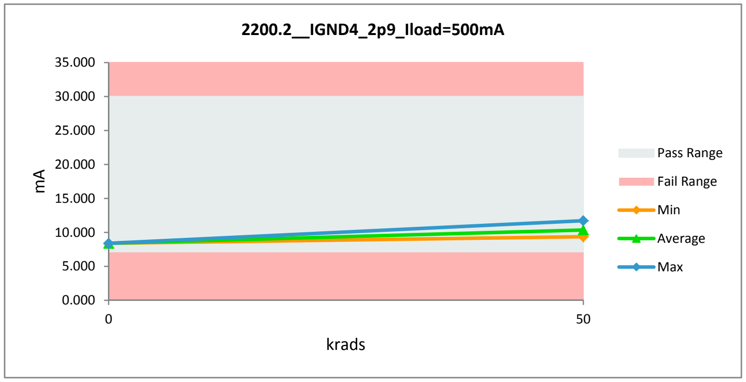


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2200.2__IGND4_2p9_Iload=500		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	30	30	
	Min Limit	7	7	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	8.281	8.384	-0.103
50	LDR_L1_D22_Unbias	8.253	9.446	-1.193
50	LDR_L1_D23_Unbias	8.335	9.382	-1.047
50	LDR_L2_D23_Unbias	8.428	9.364	-0.936
50	LDR_L2_D24_Unbias	8.892	9.856	-0.964
50	LDR_L3_D22_Unbias	8.402	9.570	-1.168
50	LDR_L1_D16_bias	8.450	11.225	-2.775
50	LDR_L1_D17_bias	8.297	11.661	-3.364
50	LDR_L2_D17_bias	8.609	10.835	-2.226
50	LDR_L2_D18_bias	8.143	10.543	-2.400
50	LDR_L2_D19_bias	8.758	11.714	-2.956
	Max	8.892	11.714	-0.103
	Average	8.441	10.180	-1.739
	Min	8.143	8.384	-3.364
	Std Dev	0.227	1.084	1.044

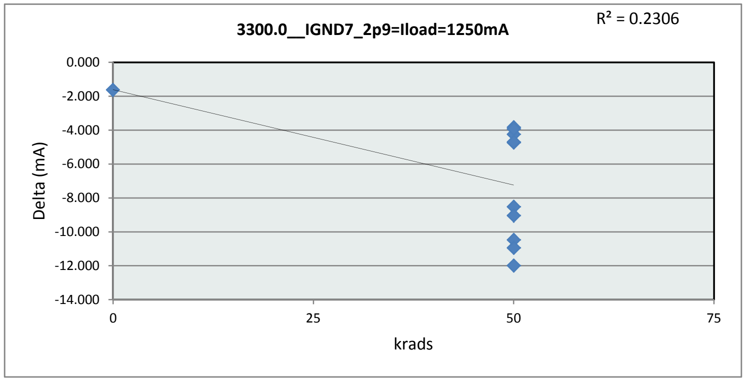


	2200.2__IGND4_2p9_Iload=500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	30	mA
Min Limit	7	mA
krads	0	50
LL	7.000	7.000
Min	8.384	9.364
Average	8.384	10.360
Max	8.384	11.714
UL	30.000	30.000

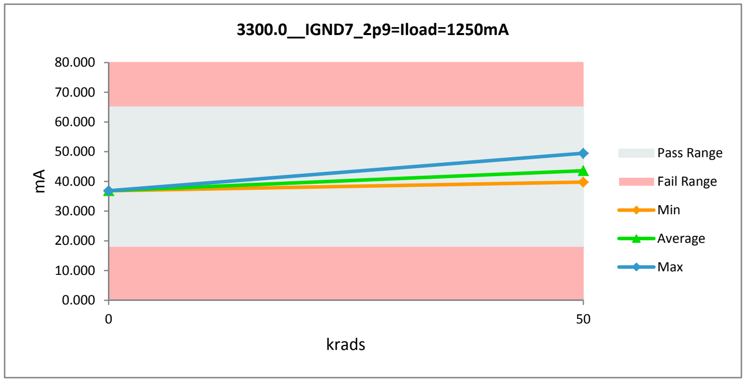


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		3300.0__IGND7_2p9=Iload=125		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	65	65	
	Min Limit	18	18	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	35.255	36.869	-1.614
50	LDR_L1_D22_Unbias	35.178	39.912	-4.734
50	LDR_L1_D23_Unbias	35.518	39.758	-4.240
50	LDR_L2_D23_Unbias	36.066	39.893	-3.827
50	LDR_L2_D24_Unbias	38.958	42.875	-3.917
50	LDR_L3_D22_Unbias	36.039	40.736	-4.697
50	LDR_L1_D16_bias	36.492	46.960	-10.468
50	LDR_L1_D17_bias	35.330	47.313	-11.983
50	LDR_L2_D17_bias	37.041	45.556	-8.515
50	LDR_L2_D18_bias	34.787	43.820	-9.033
50	LDR_L2_D19_bias	38.572	49.508	-10.936
	Max	38.958	49.508	-1.614
	Average	36.294	43.018	-6.724
	Min	34.787	36.869	-11.983
	Std Dev	1.383	3.953	3.530

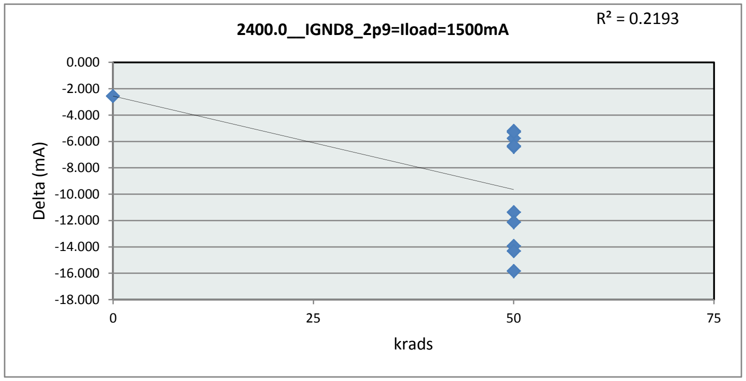


	3300.0__IGND7_2p9=Iload=1250mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	65	mA
Min Limit	18	mA
krads	0	50
LL	18.000	18.000
Min	36.869	39.758
Average	36.869	43.633
Max	36.869	49.508
UL	65.000	65.000

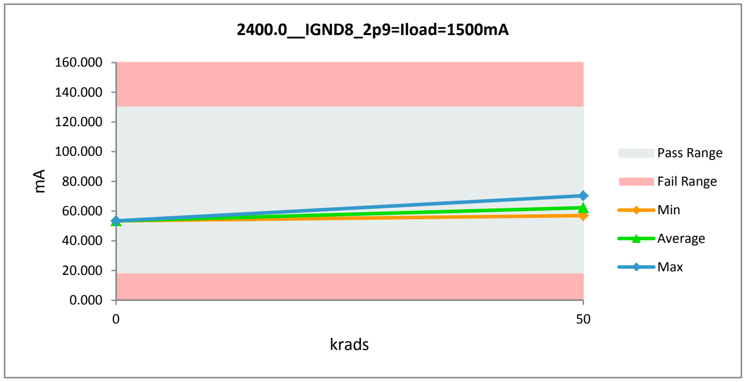


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2400.0__IGND8_2p9=Iload=150		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	130	130	
	Min Limit	18	18	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	50.928	53.484	-2.556
50	LDR_L1_D22_Unbias	50.823	57.226	-6.403
50	LDR_L1_D23_Unbias	51.305	57.054	-5.749
50	LDR_L2_D23_Unbias	52.089	57.287	-5.198
50	LDR_L2_D24_Unbias	56.436	61.721	-5.285
50	LDR_L3_D22_Unbias	52.112	58.431	-6.319
50	LDR_L1_D16_bias	52.901	66.819	-13.918
50	LDR_L1_D17_bias	51.038	66.858	-15.820
50	LDR_L2_D17_bias	53.534	64.894	-11.360
50	LDR_L2_D18_bias	50.335	62.443	-12.108
50	LDR_L2_D19_bias	56.048	70.360	-14.312
	Max	56.436	70.360	-2.556
	Average	52.504	61.507	-9.003
	Min	50.335	53.484	-15.820
	Std Dev	2.078	5.267	4.565

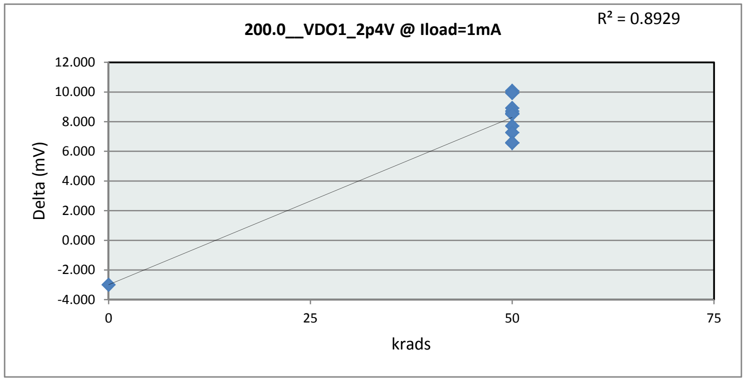


	2400.0__IGND8_2p9=Iload=1500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	130	mA
Min Limit	18	mA
krads	0	50
LL	18.000	18.000
Min	53.484	57.054
Average	53.484	62.309
Max	53.484	70.360
UL	130.000	130.000

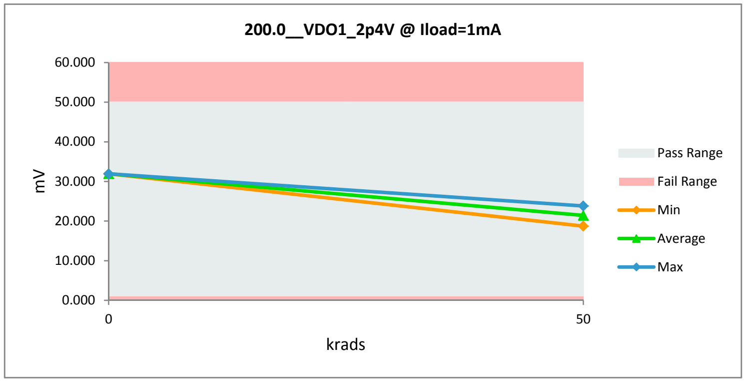


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		200.0__VDO1_2p4V @ Iload=1m		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	50	50	
	Min Limit	1	1	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	28.929	31.924	-2.995
50	LDR_L1_D22_Unbias	30.688	22.968	7.720
50	LDR_L1_D23_Unbias	30.619	23.341	7.278
50	LDR_L2_D23_Unbias	29.018	22.449	6.569
50	LDR_L2_D24_Unbias	30.065	23.476	6.589
50	LDR_L3_D22_Unbias	32.391	23.812	8.579
50	LDR_L1_D16_bias	27.883	18.957	8.926
50	LDR_L1_D17_bias	29.665	19.573	10.092
50	LDR_L2_D17_bias	28.789	20.070	8.719
50	LDR_L2_D18_bias	31.020	21.082	9.938
50	LDR_L2_D19_bias	27.229	18.716	8.513
	Max	32.391	31.924	10.092
	Average	29.663	22.397	7.266
	Min	27.229	18.716	-2.995
	Std Dev	1.491	3.683	3.602

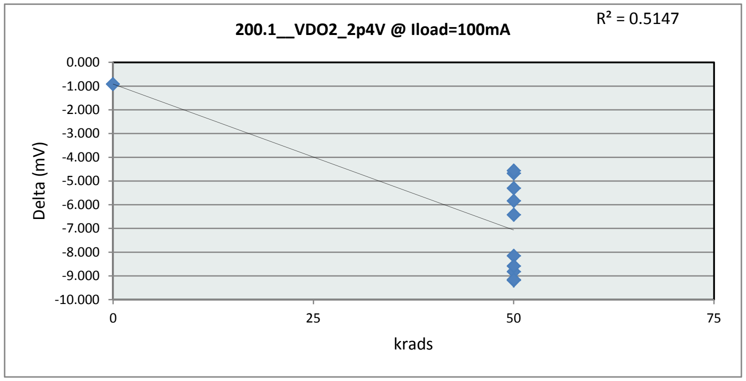


	200.0__VDO1_2p4V @ Iload=1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	50	mV
Min Limit	1	mV
krads	0	50
LL	1.000	1.000
Min	31.924	18.716
Average	31.924	21.444
Max	31.924	23.812
UL	50.000	50.000

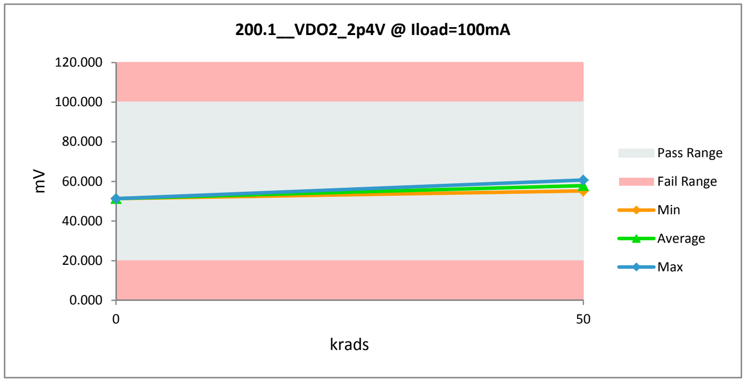


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		200.1__VDO2_2p4V @ Iload=10		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		100	100	
Min Limit		20	20	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	50.448	51.359	-0.911
50	LDR_L1_D22_Unbias	50.029	55.860	-5.831
50	LDR_L1_D23_Unbias	49.992	55.290	-5.298
50	LDR_L2_D23_Unbias	51.114	55.787	-4.673
50	LDR_L2_D24_Unbias	50.690	55.251	-4.561
50	LDR_L3_D22_Unbias	51.303	57.719	-6.416
50	LDR_L1_D16_bias	51.462	60.282	-8.820
50	LDR_L1_D17_bias	50.589	59.770	-9.181
50	LDR_L2_D17_bias	51.269	59.422	-8.153
50	LDR_L2_D18_bias	49.692	58.848	-9.156
50	LDR_L2_D19_bias	52.100	60.686	-8.586
	Max	52.100	60.686	-0.911
	Average	50.790	57.298	-6.508
	Min	49.692	51.359	-9.181
	Std Dev	0.732	2.854	2.587

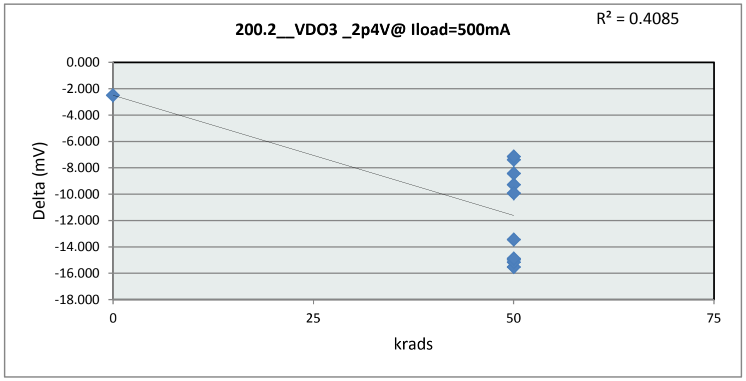


	200.1__VDO2_2p4V @ Iload=100mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	100	mV
Min Limit	20	mV
krads	0	50
LL	20.000	20.000
Min	51.359	55.251
Average	51.359	57.892
Max	51.359	60.686
UL	100.000	100.000

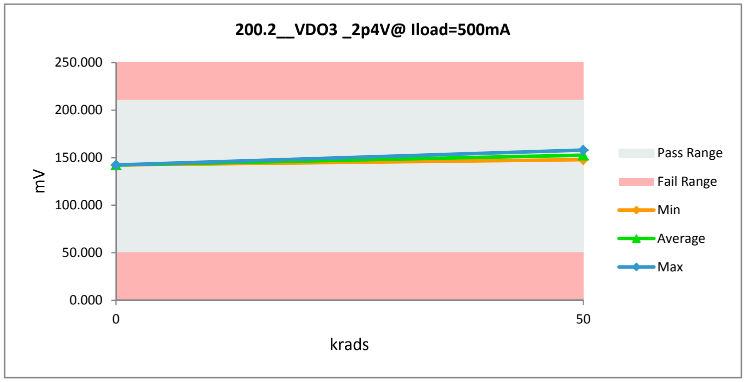


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		200.2__VDO3 _2p4V@ Iload=50		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	210	210	
	Min Limit	50	50	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	139.905	142.397	-2.492
50	LDR_L1_D22_Unbias	139.713	148.987	-9.274
50	LDR_L1_D23_Unbias	139.523	147.950	-8.427
50	LDR_L2_D23_Unbias	141.085	148.471	-7.386
50	LDR_L2_D24_Unbias	141.101	148.243	-7.142
50	LDR_L3_D22_Unbias	142.309	152.221	-9.912
50	LDR_L1_D16_bias	142.039	157.003	-14.964
50	LDR_L1_D17_bias	140.284	155.810	-15.526
50	LDR_L2_D17_bias	141.382	154.820	-13.438
50	LDR_L2_D18_bias	139.294	154.449	-15.155
50	LDR_L2_D19_bias	143.080	157.959	-14.879
	Max	143.080	157.959	-2.492
	Average	140.883	151.665	-10.781
	Min	139.294	142.397	-15.526
	Std Dev	1.249	4.818	4.302

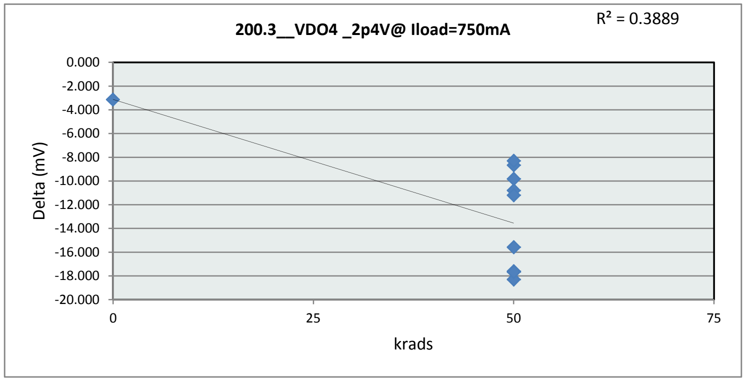


	200.2__VDO3 _2p4V@ Iload=500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	210	mV
Min Limit	50	mV
krads	0	50
LL	50.000	50.000
Min	142.397	147.950
Average	142.397	152.591
Max	142.397	157.959
UL	210.000	210.000

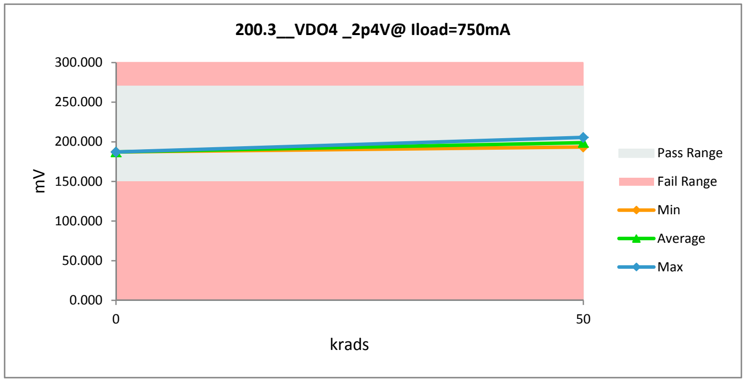


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		200.3__VDO4 _2p4V@ Iload=75		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	270	270	
	Min Limit	150	150	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	183.985	187.112	-3.127
50	LDR_L1_D22_Unbias	184.008	194.796	-10.788
50	LDR_L1_D23_Unbias	183.683	193.500	-9.817
50	LDR_L2_D23_Unbias	185.390	194.051	-8.661
50	LDR_L2_D24_Unbias	185.840	194.132	-8.292
50	LDR_L3_D22_Unbias	187.168	198.362	-11.194
50	LDR_L1_D16_bias	186.739	204.350	-17.611
50	LDR_L1_D17_bias	184.518	202.820	-18.302
50	LDR_L2_D17_bias	185.801	201.381	-15.580
50	LDR_L2_D18_bias	183.510	201.114	-17.604
50	LDR_L2_D19_bias	187.957	205.622	-17.665
	Max	187.957	205.622	-3.127
	Average	185.327	197.931	-12.604
	Min	183.510	187.112	-18.302
	Std Dev	1.516	5.679	5.040

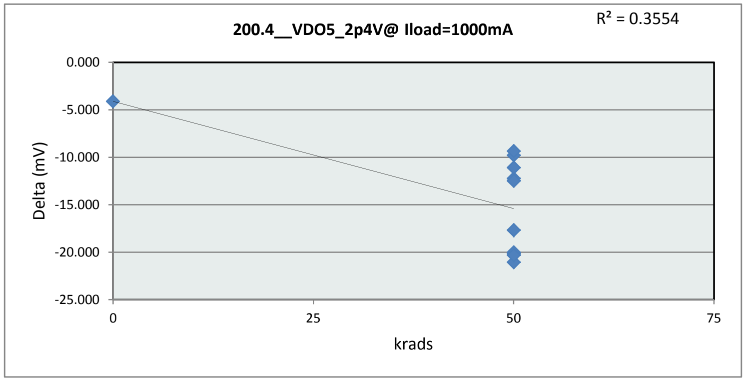


	200.3__VDO4 _2p4V@ Iload=750mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	270	mV
Min Limit	150	mV
krads	0	50
LL	150.000	150.000
Min	187.112	193.500
Average	187.112	199.013
Max	187.112	205.622
UL	270.000	270.000

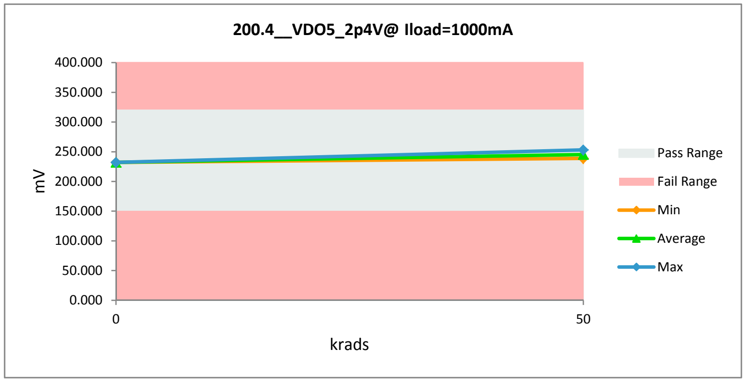


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		200.4__VDO5_2p4V@ Iload=100		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		320	320	
Min Limit		150	150	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	227.847	231.950	-4.103
50	LDR_L1_D22_Unbias	228.076	240.299	-12.223
50	LDR_L1_D23_Unbias	227.618	238.701	-11.083
50	LDR_L2_D23_Unbias	229.551	239.325	-9.774
50	LDR_L2_D24_Unbias	230.564	239.903	-9.339
50	LDR_L3_D22_Unbias	231.864	244.341	-12.477
50	LDR_L1_D16_bias	231.247	251.392	-20.145
50	LDR_L1_D17_bias	228.516	249.568	-21.052
50	LDR_L2_D17_bias	230.007	247.664	-17.657
50	LDR_L2_D18_bias	227.554	247.569	-20.015
50	LDR_L2_D19_bias	232.761	253.079	-20.318
	Max	232.761	253.079	-4.103
	Average	229.600	243.981	-14.381
	Min	227.554	231.950	-21.052
	Std Dev	1.833	6.480	5.717

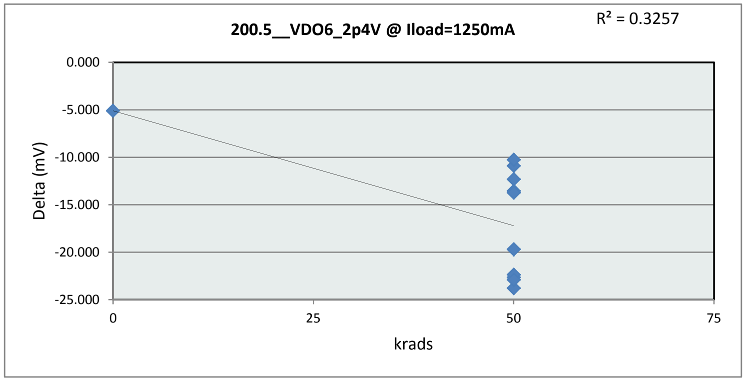


	200.4__VDO5_2p4V@ Iload=1000mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	320	mV
Min Limit	150	mV
krads	0	50
LL	150.000	150.000
Min	231.950	238.701
Average	231.950	245.184
Max	231.950	253.079
UL	320.000	320.000

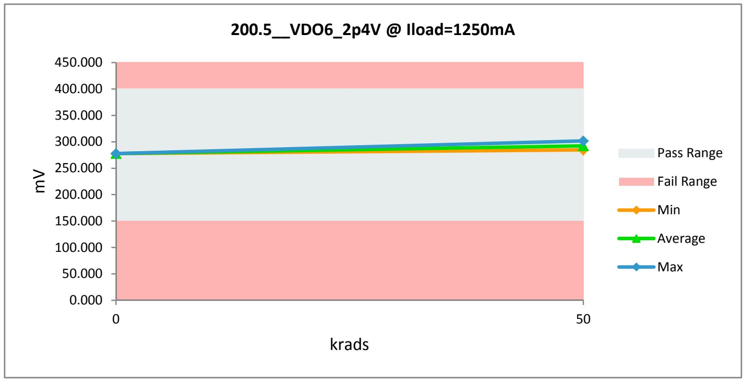


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		200.5__VDO6_2p4V @ Iload=12		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	150	150	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	272.676	277.776	-5.100
50	LDR_L1_D22_Unbias	273.133	286.664	-13.531
50	LDR_L1_D23_Unbias	272.538	284.841	-12.303
50	LDR_L2_D23_Unbias	274.726	285.624	-10.898
50	LDR_L2_D24_Unbias	276.436	286.690	-10.254
50	LDR_L3_D22_Unbias	277.662	291.384	-13.722
50	LDR_L1_D16_bias	276.802	299.452	-22.650
50	LDR_L1_D17_bias	273.496	297.276	-23.780
50	LDR_L2_D17_bias	275.224	294.904	-19.680
50	LDR_L2_D18_bias	272.625	294.998	-22.373
50	LDR_L2_D19_bias	278.704	301.616	-22.912
	Max	278.704	301.616	-5.100
	Average	274.911	291.020	-16.109
	Min	272.538	277.776	-23.780
	Std Dev	2.214	7.307	6.398

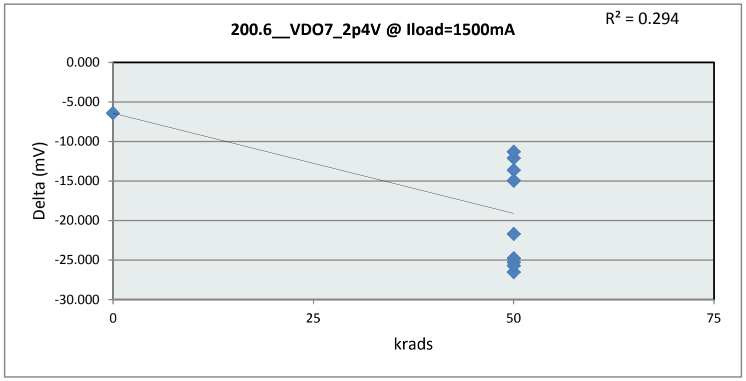


	200.5__VDO6_2p4V @ Iload=1250mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	400	mV
Min Limit	150	mV
krads	0	50
LL	150.000	150.000
Min	277.776	284.841
Average	277.776	292.345
Max	277.776	301.616
UL	400.000	400.000

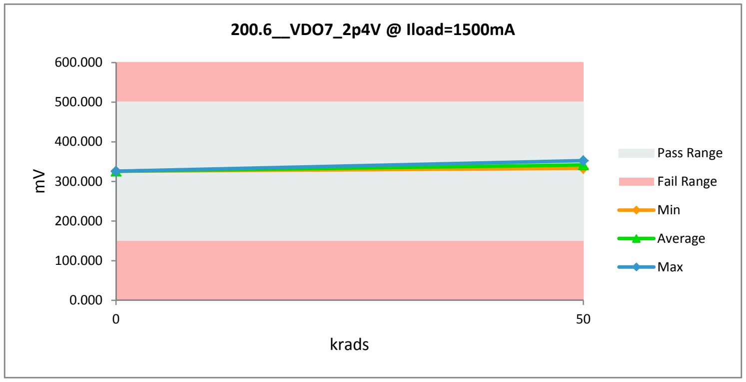


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		200.6__VDO7_2p4V @ Iload=15		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		500	500	
Min Limit		150	150	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	319.606	326.028	-6.422
50	LDR_L1_D22_Unbias	320.341	335.292	-14.951
50	LDR_L1_D23_Unbias	319.597	333.219	-13.622
50	LDR_L2_D23_Unbias	322.133	334.230	-12.097
50	LDR_L2_D24_Unbias	324.678	335.964	-11.286
50	LDR_L3_D22_Unbias	325.720	340.674	-14.954
50	LDR_L1_D16_bias	324.581	349.874	-25.293
50	LDR_L1_D17_bias	320.651	347.175	-26.524
50	LDR_L2_D17_bias	322.634	344.308	-21.674
50	LDR_L2_D18_bias	319.875	344.627	-24.752
50	LDR_L2_D19_bias	326.987	352.692	-25.705
	Max	326.987	352.692	-6.422
	Average	322.437	340.371	-17.935
	Min	319.597	326.028	-26.524
	Std Dev	2.673	8.136	7.042

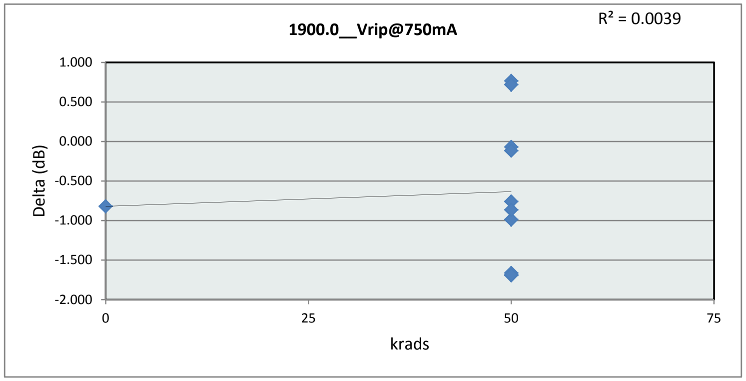


	200.6__VDO7_2p4V @ Iload=1500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	500	mV
Min Limit	150	mV
krads	0	50
LL	150.000	150.000
Min	326.028	333.219
Average	326.028	341.806
Max	326.028	352.692
UL	500.000	500.000

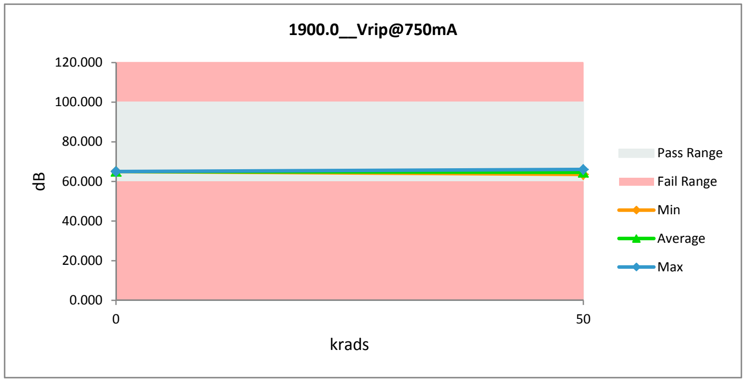


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		1900.0__Vrip@750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	dB	dB	
	Max Limit	100	100	
	Min Limit	60	60	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	64.239	65.058	-0.819
50	LDR_L1_D22_Unbias	65.067	66.053	-0.986
50	LDR_L1_D23_Unbias	64.241	64.309	-0.068
50	LDR_L2_D23_Unbias	62.807	63.565	-0.758
50	LDR_L2_D24_Unbias	65.075	64.308	0.767
50	LDR_L3_D22_Unbias	63.472	65.134	-1.662
50	LDR_L1_D16_bias	63.514	65.207	-1.693
50	LDR_L1_D17_bias	63.492	63.606	-0.114
50	LDR_L2_D17_bias	63.503	65.190	-1.687
50	LDR_L2_D18_bias	63.480	64.343	-0.863
50	LDR_L2_D19_bias	65.104	64.383	0.721
	Max	65.104	66.053	0.767
	Average	63.999	64.651	-0.651
	Min	62.807	63.565	-1.693
	Std Dev	0.796	0.751	0.889

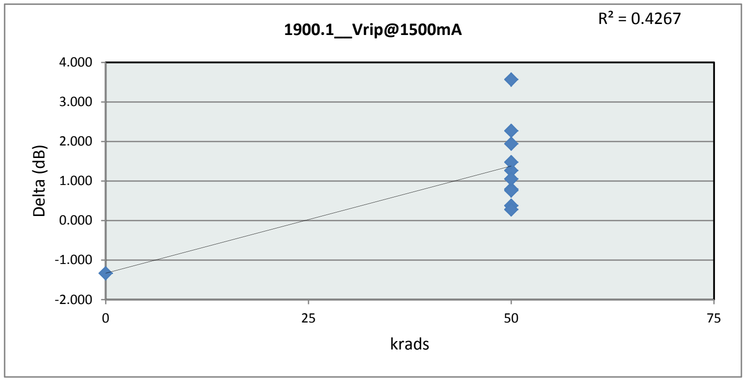


	1900.0__Vrip@750mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	100	dB
Min Limit	60	dB
krads	0	50
LL	60.000	60.000
Min	65.058	63.565
Average	65.058	64.610
Max	65.058	66.053
UL	100.000	100.000

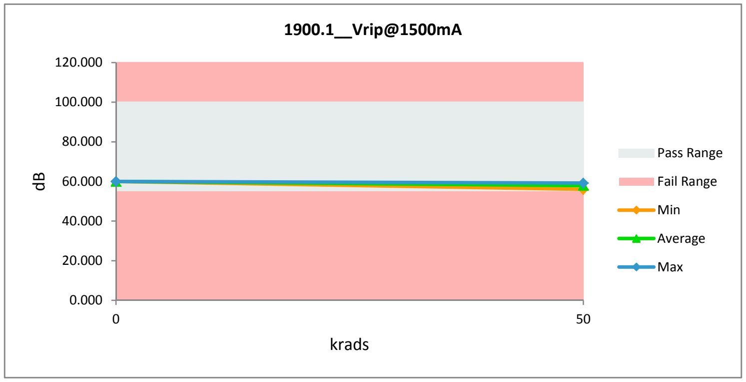


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		1900.1__Vrip@1500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	dB	dB	
	Max Limit	100	100	
	Min Limit	55	55	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	58.695	60.026	-1.331
50	LDR_L1_D22_Unbias	59.565	58.771	0.794
50	LDR_L1_D23_Unbias	60.037	58.770	1.267
50	LDR_L2_D23_Unbias	59.581	59.203	0.378
50	LDR_L2_D24_Unbias	59.126	58.363	0.763
50	LDR_L3_D22_Unbias	59.549	57.603	1.946
50	LDR_L1_D16_bias	58.726	57.673	1.053
50	LDR_L1_D17_bias	59.572	57.302	2.270
50	LDR_L2_D17_bias	58.312	58.030	0.282
50	LDR_L2_D18_bias	59.115	57.637	1.478
50	LDR_L2_D19_bias	59.603	56.031	3.572
	Max	60.037	60.026	3.572
	Average	59.262	58.128	1.134
	Min	58.312	56.031	-1.331
	Std Dev	0.514	1.070	1.252



	1900.1__Vrip@1500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	100	dB
Min Limit	55	dB
krads	0	50
LL	55.000	55.000
Min	60.026	56.031
Average	60.026	57.938
Max	60.026	59.203
UL	100.000	100.000

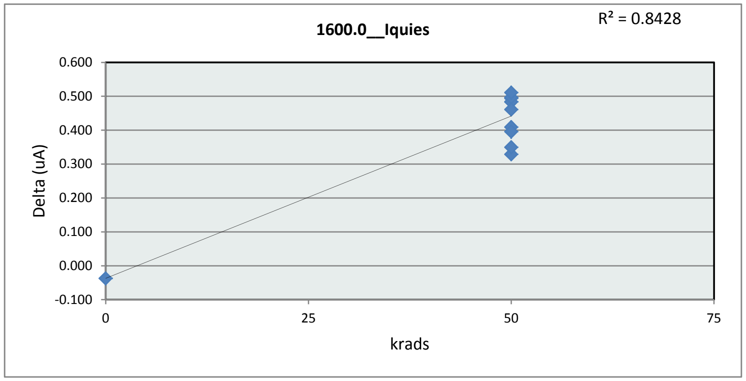


TID LDR Report (50KRad Bias and Unbias)

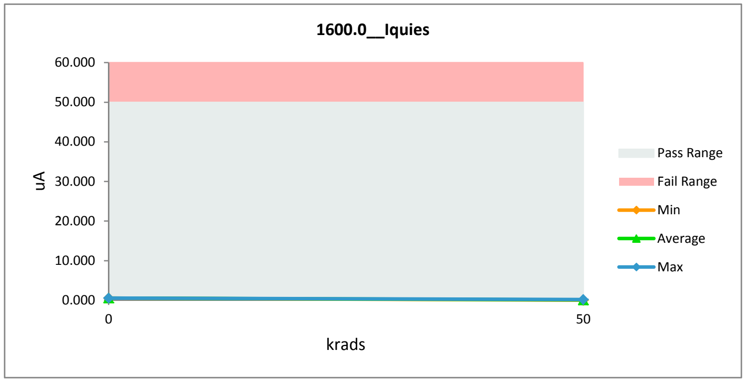
TPS7A4501-RHA

All units passed SMD specification limits up to 50kRAD LDR.

		1600.0__Iquies		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	50	50	
	Min Limit	0	0	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	0.549	0.586	-0.037
50	LDR_L1_D22_Unbias	0.552	0.068	0.484
50	LDR_L1_D23_Unbias	0.560	0.066	0.494
50	LDR_L2_D23_Unbias	0.546	0.062	0.484
50	LDR_L2_D24_Unbias	0.558	0.061	0.497
50	LDR_L3_D22_Unbias	0.562	0.051	0.511
50	LDR_L1_D16_bias	0.543	0.082	0.461
50	LDR_L1_D17_bias	0.559	0.150	0.409
50	LDR_L2_D17_bias	0.545	0.216	0.329
50	LDR_L2_D18_bias	0.540	0.190	0.350
50	LDR_L2_D19_bias	0.559	0.163	0.396
	Max	0.562	0.586	0.511
	Average	0.552	0.154	0.398
	Min	0.540	0.051	-0.037
	Std Dev	0.008	0.155	0.157

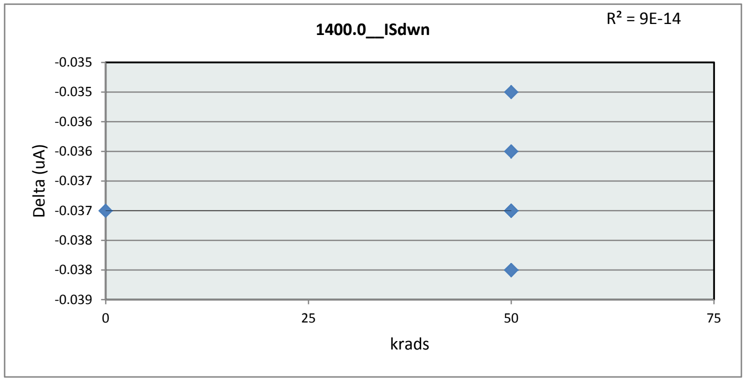


	1600.0__Iquies	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	50	uA
Min Limit	0	uA
krads	0	50
LL	0.000	0.000
Min	0.586	0.051
Average	0.586	0.111
Max	0.586	0.216
UL	50.000	50.000

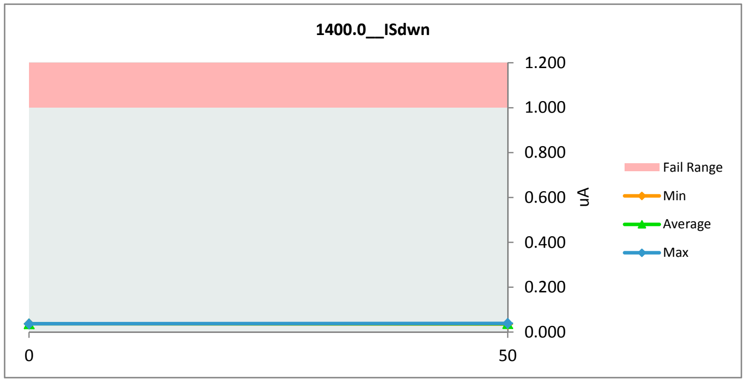


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		1400.0__ISdwn		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	1	1	
	Min Limit			
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	0.000	0.037	-0.037
50	LDR_L1_D22_Unbias	0.001	0.039	-0.038
50	LDR_L1_D23_Unbias	0.001	0.037	-0.036
50	LDR_L2_D23_Unbias	0.001	0.038	-0.037
50	LDR_L2_D24_Unbias	0.001	0.038	-0.037
50	LDR_L3_D22_Unbias	0.000	0.037	-0.037
50	LDR_L1_D16_bias	0.001	0.036	-0.035
50	LDR_L1_D17_bias	0.000	0.037	-0.037
50	LDR_L2_D17_bias	0.000	0.038	-0.038
50	LDR_L2_D18_bias	0.000	0.037	-0.037
50	LDR_L2_D19_bias	0.000	0.038	-0.038
	Max	0.001	0.039	-0.035
	Average	0.000	0.037	-0.037
	Min	0.000	0.036	-0.038
	Std Dev	0.001	0.001	0.001

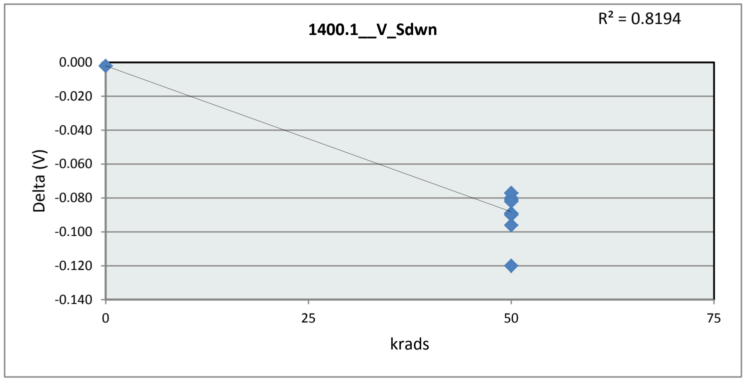


	1400.0__ISdwn	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1	uA
Min Limit		uA
krads	0	50
LL		
Min	0.037	0.036
Average	0.037	0.038
Max	0.037	0.039
UL	1.000	1.000

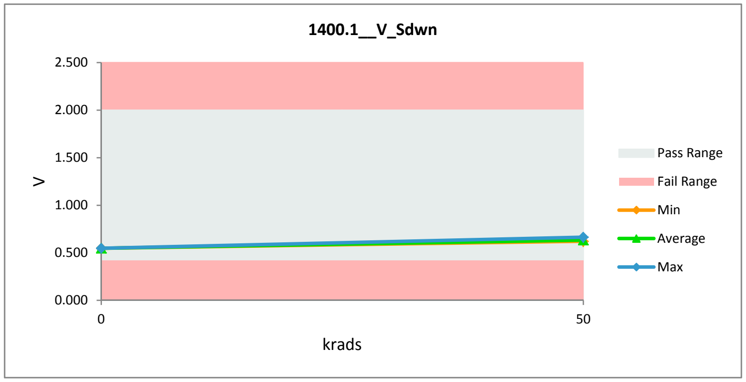


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		1400.1__V_Sdwn		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		V	V	
Max Limit		2	2	
Min Limit		0.42	0.42	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	0.545	0.547	-0.002
50	LDR_L1_D22_Unbias	0.546	0.627	-0.081
50	LDR_L1_D23_Unbias	0.545	0.625	-0.080
50	LDR_L2_D23_Unbias	0.544	0.621	-0.077
50	LDR_L2_D24_Unbias	0.547	0.624	-0.077
50	LDR_L3_D22_Unbias	0.539	0.621	-0.082
50	LDR_L1_D16_bias	0.544	0.664	-0.120
50	LDR_L1_D17_bias	0.546	0.642	-0.096
50	LDR_L2_D17_bias	0.546	0.635	-0.089
50	LDR_L2_D18_bias	0.544	0.633	-0.089
50	LDR_L2_D19_bias	0.546	0.636	-0.090
	Max	0.547	0.664	-0.002
	Average	0.545	0.625	-0.080
	Min	0.539	0.547	-0.120
	Std Dev	0.002	0.029	0.029

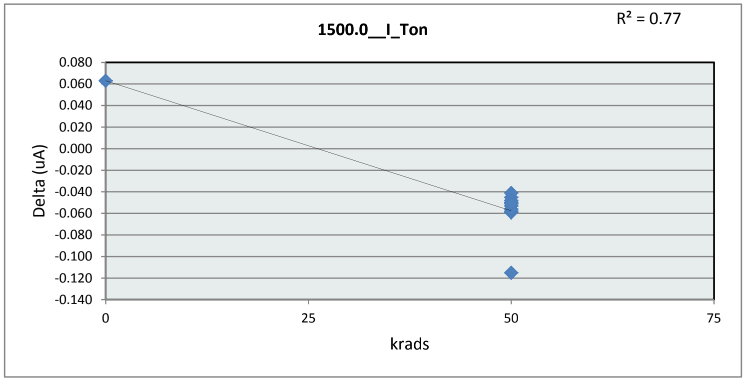


	1400.1__V_Sdwn	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	2	V
Min Limit	0.42	V
krads	0	50
LL	0.420	0.420
Min	0.547	0.621
Average	0.547	0.633
Max	0.547	0.664
UL	2.000	2.000

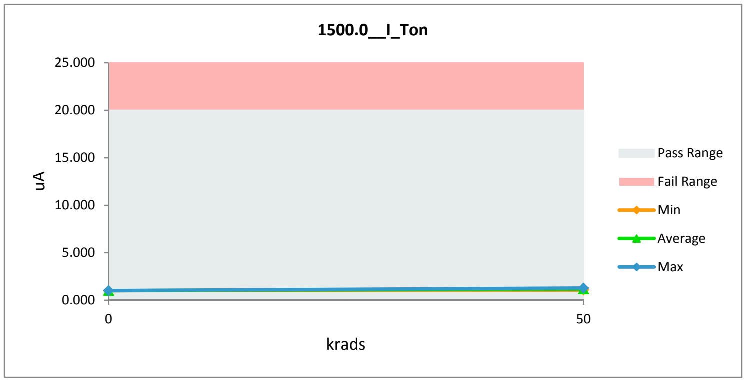


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		1500.0__I_Ton		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		uA	uA	
Max Limit		20	20	
Min Limit		0	0	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	1.076	1.013	0.063
50	LDR_L1_D22_Unbias	1.081	1.126	-0.045
50	LDR_L1_D23_Unbias	1.167	1.220	-0.053
50	LDR_L2_D23_Unbias	1.115	1.165	-0.050
50	LDR_L2_D24_Unbias	1.231	1.290	-0.059
50	LDR_L3_D22_Unbias	1.034	1.075	-0.041
50	LDR_L1_D16_bias	1.090	1.205	-0.115
50	LDR_L1_D17_bias	1.117	1.175	-0.058
50	LDR_L2_D17_bias	1.156	1.212	-0.056
50	LDR_L2_D18_bias	1.124	1.172	-0.048
50	LDR_L2_D19_bias	1.177	1.228	-0.051
	Max	1.231	1.290	0.063
	Average	1.124	1.171	-0.047
	Min	1.034	1.013	-0.115
	Std Dev	0.055	0.077	0.041



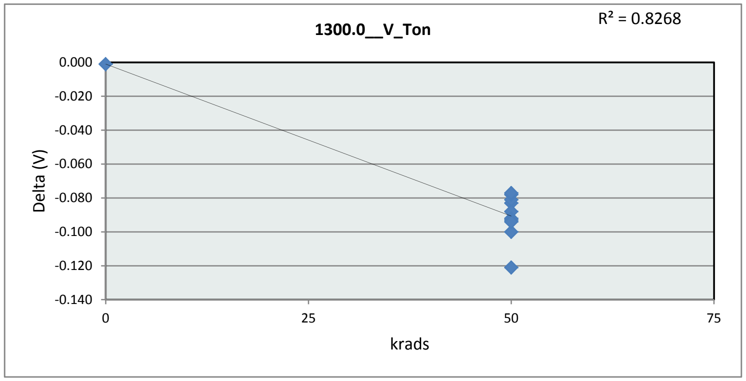
	1500.0__I_Ton	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	20	uA
Min Limit	0	uA
krads	0	50
LL	0.000	0.000
Min	1.013	1.075
Average	1.013	1.187
Max	1.013	1.290
UL	20.000	20.000



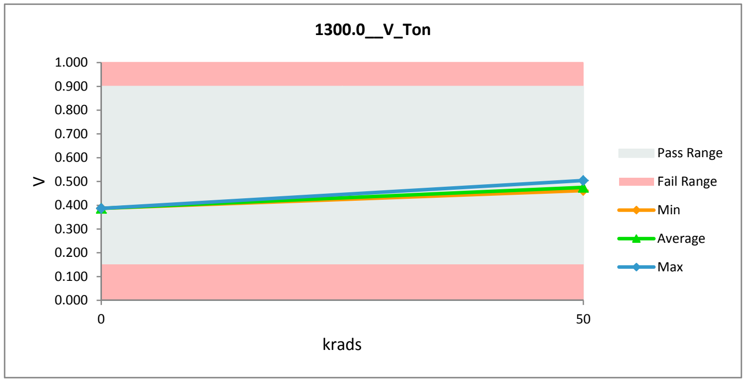
TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

	1300.0__V_Ton	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	V	V
Max Limit	0.9	0.9
Min Limit	0.15	0.15

krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	0.386	0.387	-0.001
50	LDR_L1_D22_Unbias	0.386	0.469	-0.083
50	LDR_L1_D23_Unbias	0.385	0.466	-0.081
50	LDR_L2_D23_Unbias	0.384	0.462	-0.078
50	LDR_L2_D24_Unbias	0.387	0.464	-0.077
50	LDR_L3_D22_Unbias	0.378	0.466	-0.088
50	LDR_L1_D16_bias	0.383	0.504	-0.121
50	LDR_L1_D17_bias	0.386	0.486	-0.100
50	LDR_L2_D17_bias	0.386	0.478	-0.092
50	LDR_L2_D18_bias	0.382	0.475	-0.093
50	LDR_L2_D19_bias	0.386	0.480	-0.094
	Max	0.387	0.504	-0.001
	Average	0.384	0.467	-0.083
	Min	0.378	0.387	-0.121
	Std Dev	0.003	0.029	0.030

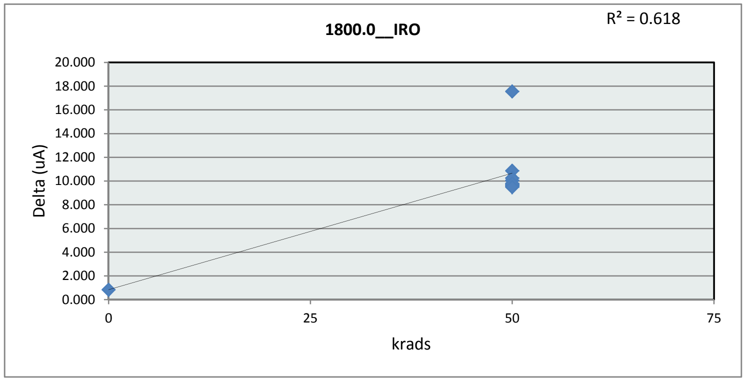


	1300.0__V_Ton	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	0.9	V
Min Limit	0.15	V
krads	0	50
LL	0.150	0.150
Min	0.387	0.462
Average	0.387	0.475
Max	0.387	0.504
UL	0.900	0.900

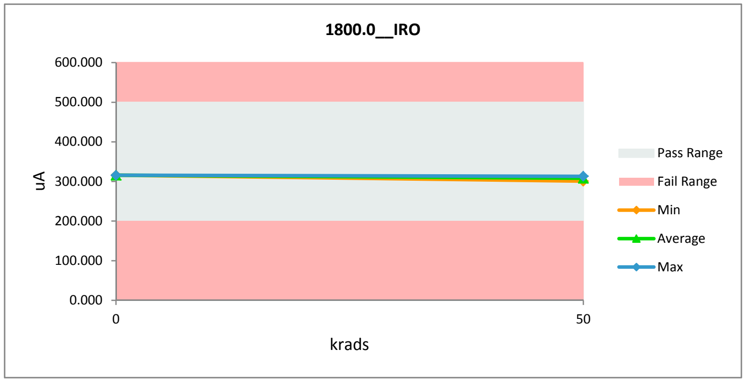


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		1800.0__IRO		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	500	500	
	Min Limit	200	200	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	316.503	315.660	0.843
50	LDR_L1_D22_Unbias	317.562	307.519	10.043
50	LDR_L1_D23_Unbias	316.830	307.256	9.574
50	LDR_L2_D23_Unbias	317.706	308.037	9.669
50	LDR_L2_D24_Unbias	319.007	309.354	9.653
50	LDR_L3_D22_Unbias	322.884	313.131	9.753
50	LDR_L1_D16_bias	318.513	300.962	17.551
50	LDR_L1_D17_bias	315.748	304.882	10.866
50	LDR_L2_D17_bias	317.547	307.301	10.246
50	LDR_L2_D18_bias	322.192	312.398	9.794
50	LDR_L2_D19_bias	319.661	310.168	9.493
	Max	322.884	315.660	17.551
	Average	318.559	308.788	9.771
	Min	315.748	300.962	0.843
	Std Dev	2.262	4.057	3.767

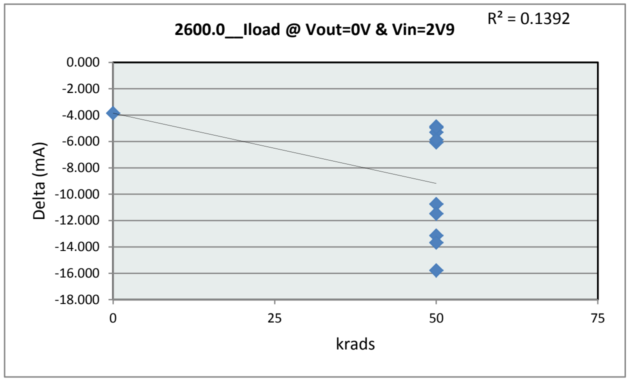


	1800.0__IRO	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	500	uA
Min Limit	200	uA
krads	0	50
LL	200.000	200.000
Min	315.660	300.962
Average	315.660	308.101
Max	315.660	313.131
UL	500.000	500.000

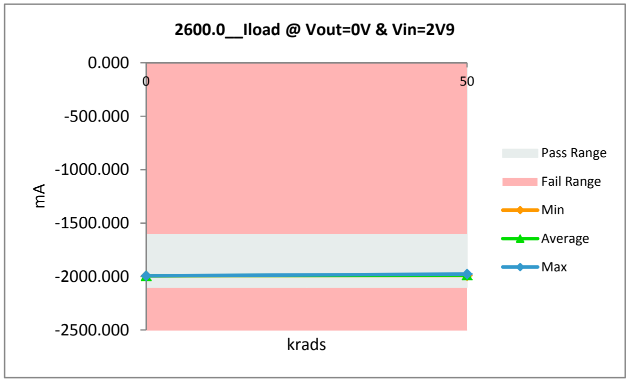


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2600.0__Iload @ Vout=0V & Vin		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	-1600	-1600	
	Min Limit	-2100	-2100	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	-1996.161	-1992.305	-3.856
50	LDR_L1_D22_Unbias	-1996.158	-1990.089	-6.069
50	LDR_L1_D23_Unbias	-1995.607	-1990.316	-5.291
50	LDR_L2_D23_Unbias	-1994.645	-1989.789	-4.856
50	LDR_L2_D24_Unbias	-1988.686	-1983.748	-4.938
50	LDR_L3_D22_Unbias	-1994.541	-1988.674	-5.867
50	LDR_L1_D16_bias	-1993.971	-1980.845	-13.126
50	LDR_L1_D17_bias	-1995.906	-1980.126	-15.780
50	LDR_L2_D17_bias	-1992.668	-1981.930	-10.738
50	LDR_L2_D18_bias	-1997.072	-1985.606	-11.466
50	LDR_L2_D19_bias	-1989.885	-1976.218	-13.667
	Max	-1988.686	-1976.218	-3.856
	Average	-1994.118	-1985.422	-8.696
	Min	-1997.072	-1992.305	-15.780
	Std Dev	2.692	5.211	4.303

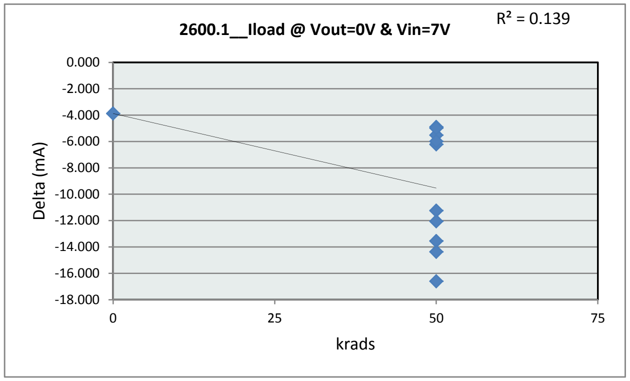


	2600.0__Iload @ Vout=0V & Vin=2V9	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	-1600	mA
Min Limit	-2100	mA
krads	0	50
LL	-2100.000	-2100.000
Min	-1992.305	-1990.316
Average	-1992.305	-1984.734
Max	-1992.305	-1976.218
UL	-1600.000	-1600.000

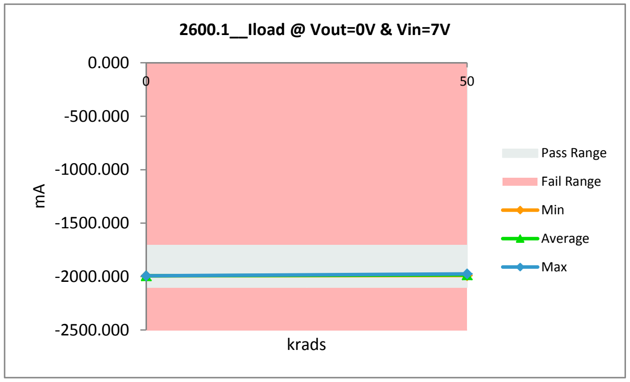


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2600.1__Iload @ Vout=0V & Vin		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mA	mA	
Max Limit		-1700	-1700	
Min Limit		-2100	-2100	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	-1996.079	-1992.206	-3.873
50	LDR_L1_D22_Unbias	-1996.088	-1989.874	-6.214
50	LDR_L1_D23_Unbias	-1995.483	-1989.965	-5.518
50	LDR_L2_D23_Unbias	-1994.452	-1989.563	-4.889
50	LDR_L2_D24_Unbias	-1988.592	-1983.612	-4.980
50	LDR_L3_D22_Unbias	-1994.393	-1988.410	-5.983
50	LDR_L1_D16_bias	-1993.895	-1980.346	-13.549
50	LDR_L1_D17_bias	-1995.839	-1979.241	-16.598
50	LDR_L2_D17_bias	-1992.575	-1981.339	-11.236
50	LDR_L2_D18_bias	-1996.842	-1984.794	-12.048
50	LDR_L2_D19_bias	-1989.762	-1975.391	-14.371
	Max	-1988.592	-1975.391	-3.873
	Average	-1994.000	-1984.976	-9.024
	Min	-1996.842	-1992.206	-16.598
	Std Dev	2.682	5.434	4.581

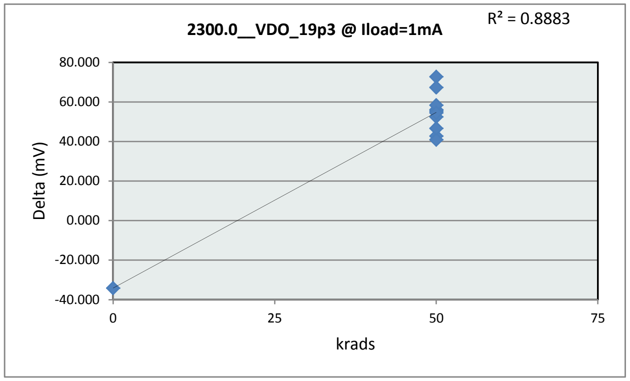


	2600.1__Iload @ Vout=0V & Vin=7V	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	-1700	mA
Min Limit	-2100	mA
krads	0	50
LL	-2100.000	-2100.000
Min	-1992.206	-1989.965
Average	-1992.206	-1984.254
Max	-1992.206	-1975.391
UL	-1700.000	-1700.000

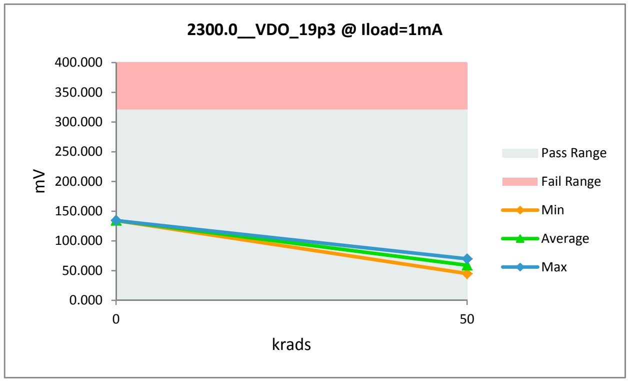


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
		2300.0__VDO_19p3 @ Iload=1m		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	320	320	
	Min Limit	1	1	
0	_CORR_L1_D21_Unbias	100.276	134.419	-34.143
50	LDR_L1_D22_Unbias	122.788	66.700	56.088
50	LDR_L1_D23_Unbias	119.798	67.301	52.497
50	LDR_L2_D23_Unbias	107.991	65.187	42.804
50	LDR_L2_D24_Unbias	110.715	69.773	40.942
50	LDR_L3_D22_Unbias	142.160	69.373	72.787
50	LDR_L1_D16_bias	100.298	44.931	55.367
50	LDR_L1_D17_bias	108.135	49.732	58.403
50	LDR_L2_D17_bias	106.315	51.852	54.463
50	LDR_L2_D18_bias	125.096	57.770	67.326
50	LDR_L2_D19_bias	94.434	47.781	46.653
	Max	142.160	134.419	72.787
	Average	112.546	65.893	46.653
	Min	94.434	44.931	-34.143
	Std Dev	13.795	24.531	28.432

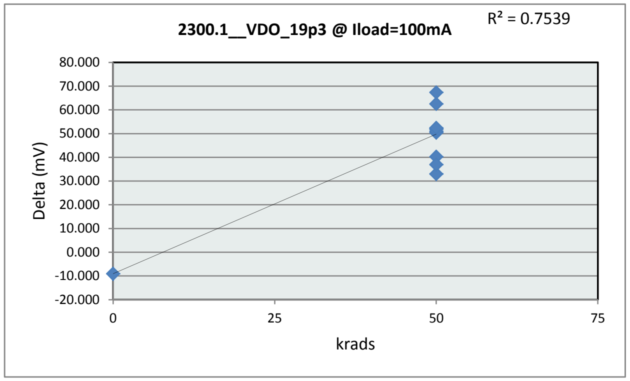


	2300.0__VDO_19p3 @ Iload=1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	320	mV
Min Limit	1	mV
krads	0	50
LL	1.000	1.000
Min	134.419	44.931
Average	134.419	59.040
Max	134.419	69.773
UL	320.000	320.000

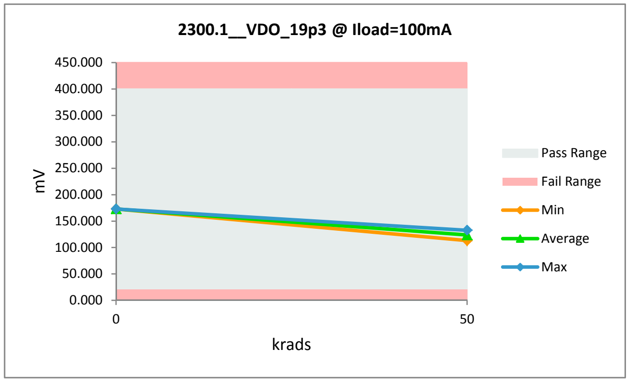


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2300.1__VDO_19p3 @ Iload=10		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	20	20	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	164.017	173.055	-9.038
50	LDR_L1_D22_Unbias	179.080	127.239	51.841
50	LDR_L1_D23_Unbias	177.745	127.374	50.371
50	LDR_L2_D23_Unbias	159.230	126.207	33.023
50	LDR_L2_D24_Unbias	191.656	129.112	62.544
50	LDR_L3_D22_Unbias	184.829	132.710	52.119
50	LDR_L1_D16_bias	153.479	113.233	40.246
50	LDR_L1_D17_bias	170.212	119.215	50.997
50	LDR_L2_D17_bias	172.649	120.237	52.412
50	LDR_L2_D18_bias	191.004	123.651	67.353
50	LDR_L2_D19_bias	155.401	118.459	36.942
	Max	191.656	173.055	67.353
	Average	172.664	128.227	44.437
	Min	153.479	113.233	-9.038
	Std Dev	13.562	15.882	20.426

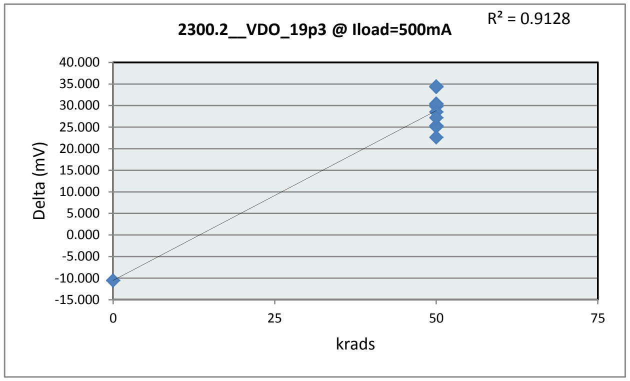


	2300.1__VDO_19p3 @ Iload=100mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	400	mV
Min Limit	20	mV
krads	0	50
LL	20.000	20.000
Min	173.055	113.233
Average	173.055	123.744
Max	173.055	132.710
UL	400.000	400.000

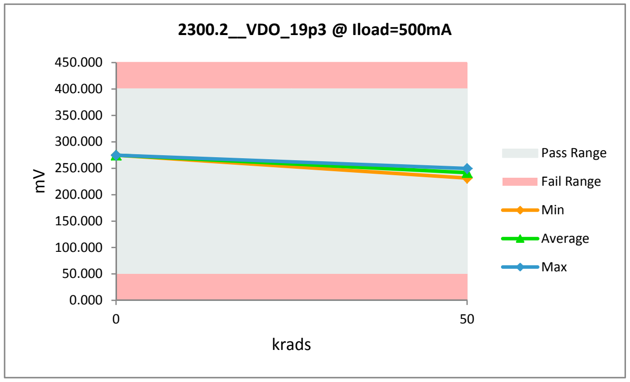


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2300.2__VDO_19p3 @ Iload=50		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	50	50	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	264.224	274.764	-10.540
50	LDR_L1_D22_Unbias	273.380	242.934	30.446
50	LDR_L1_D23_Unbias	267.953	242.596	25.357
50	LDR_L2_D23_Unbias	267.427	242.346	25.081
50	LDR_L2_D24_Unbias	274.808	245.025	29.783
50	LDR_L3_D22_Unbias	283.963	249.650	34.313
50	LDR_L1_D16_bias	261.798	231.455	30.343
50	LDR_L1_D17_bias	268.265	239.743	28.522
50	LDR_L2_D17_bias	267.442	240.249	27.193
50	LDR_L2_D18_bias	277.690	243.237	34.453
50	LDR_L2_D19_bias	263.434	240.785	22.649
	Max	283.963	274.764	34.453
	Average	270.035	244.799	25.236
	Min	261.798	231.455	-10.540
	Std Dev	6.729	10.857	12.420

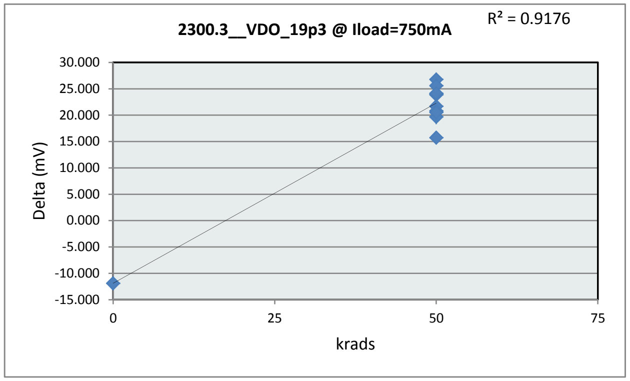


	2300.2__VDO_19p3 @ Iload=500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	400	mV
Min Limit	50	mV
krads	0	50
LL	50.000	50.000
Min	274.764	231.455
Average	274.764	241.802
Max	274.764	249.650
UL	400.000	400.000

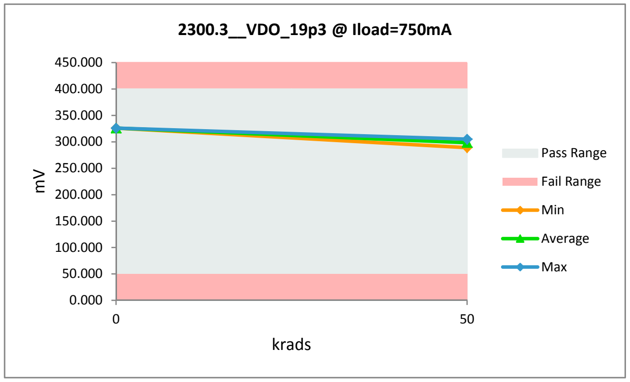


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2300.3__VDO_19p3 @ Iload=75		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	50	50	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	314.042	325.940	-11.898
50	LDR_L1_D22_Unbias	321.876	297.854	24.022
50	LDR_L1_D23_Unbias	319.012	297.342	21.670
50	LDR_L2_D23_Unbias	318.546	297.748	20.798
50	LDR_L2_D24_Unbias	324.543	300.675	23.868
50	LDR_L3_D22_Unbias	331.917	305.148	26.769
50	LDR_L1_D16_bias	314.793	289.215	25.578
50	LDR_L1_D17_bias	318.261	298.586	19.675
50	LDR_L2_D17_bias	318.742	298.204	20.538
50	LDR_L2_D18_bias	324.934	300.809	24.125
50	LDR_L2_D19_bias	316.384	300.658	15.726
	Max	331.917	325.940	26.769
	Average	320.277	301.107	19.170
	Min	314.042	289.215	-11.898
	Std Dev	5.225	9.087	10.757

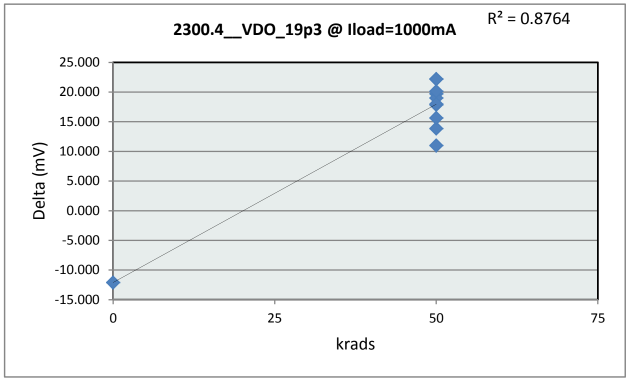


	2300.3__VDO_19p3 @ Iload=750mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	400	mV
Min Limit	50	mV
krads	0	50
LL	50.000	50.000
Min	325.940	289.215
Average	325.940	298.624
Max	325.940	305.148
UL	400.000	400.000

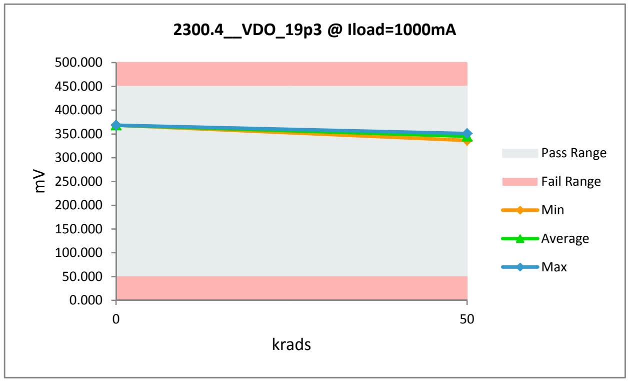


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

		2300.4__VDO_19p3 @ Iload=10		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	450	450	
	Min Limit	50	50	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	356.350	368.445	-12.095
50	LDR_L1_D22_Unbias	363.031	343.323	19.708
50	LDR_L1_D23_Unbias	361.665	342.657	19.008
50	LDR_L2_D23_Unbias	360.732	342.897	17.835
50	LDR_L2_D24_Unbias	365.947	345.814	20.133
50	LDR_L3_D22_Unbias	373.121	350.920	22.201
50	LDR_L1_D16_bias	358.618	336.431	22.187
50	LDR_L1_D17_bias	360.457	346.600	13.857
50	LDR_L2_D17_bias	360.921	345.298	15.623
50	LDR_L2_D18_bias	365.406	347.434	17.972
50	LDR_L2_D19_bias	359.944	348.959	10.985
	Max	373.121	368.445	22.201
	Average	362.381	347.162	15.219
	Min	356.350	336.431	-12.095
	Std Dev	4.507	8.027	9.677



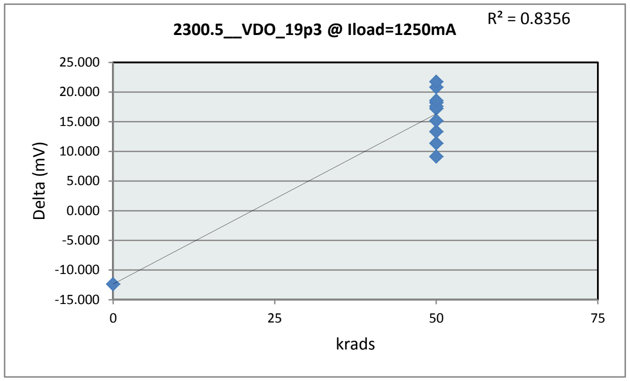
	2300.4__VDO_19p3 @ Iload=1000mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	450	mV
Min Limit	50	mV
krads	0	50
LL	50.000	50.000
Min	368.445	336.431
Average	368.445	345.033
Max	368.445	350.920
UL	450.000	450.000



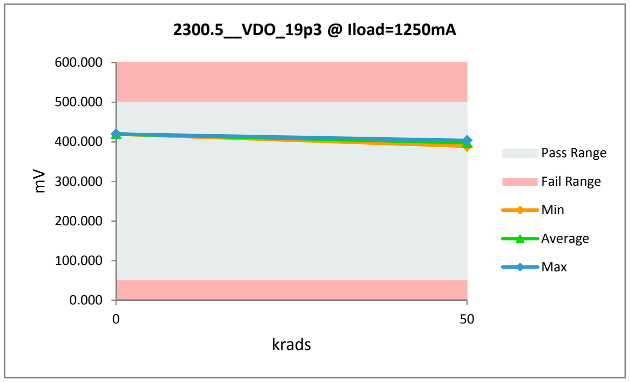
TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA

All units passed SMD specification limits up to 50kRAD LDR.

		2300.5__VDO_19p3 @ Iload=12		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	500	500	
	Min Limit	50	50	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	407.552	419.927	-12.375
50	LDR_L1_D22_Unbias	413.782	395.551	18.231
50	LDR_L1_D23_Unbias	411.904	394.675	17.229
50	LDR_L2_D23_Unbias	412.788	395.197	17.591
50	LDR_L2_D24_Unbias	417.024	398.455	18.569
50	LDR_L3_D22_Unbias	424.587	403.751	20.836
50	LDR_L1_D16_bias	410.718	388.955	21.763
50	LDR_L1_D17_bias	411.580	400.196	11.384
50	LDR_L2_D17_bias	411.903	398.571	13.332
50	LDR_L2_D18_bias	415.931	400.761	15.170
50	LDR_L2_D19_bias	412.582	403.439	9.143
	Max	424.587	419.927	21.763
	Average	413.668	399.953	13.716
	Min	407.552	388.955	-12.375
	Std Dev	4.408	7.882	9.466

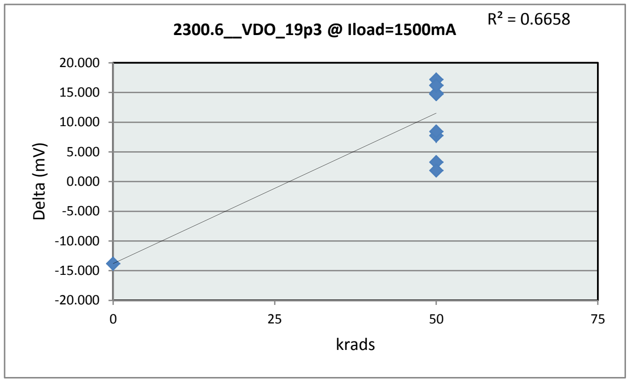


	2300.5__VDO_19p3 @ Iload=1250mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	500	mV
Min Limit	50	mV
krads	0	50
LL	50.000	50.000
Min	419.927	388.955
Average	419.927	397.955
Max	419.927	403.751
UL	500.000	500.000

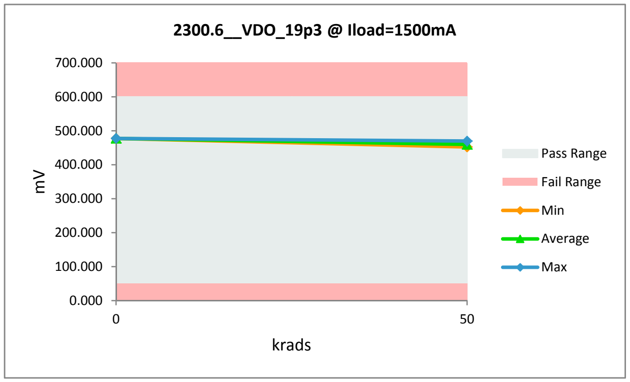


TID LDR Report (50KRad Bias and Unbias)
TPS7A4501-RHA
All units passed SMD specification limits up to 50kRAD LDR.

krads	Serial #	2300.6__VDO_19p3 @ Iload=15		Delta
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		600	600	
Min Limit		50	50	
krads	Serial #	PreRad_LDR_50K	PostRad_LDR_50K	Delta
0	_CORR_L1_D21_Unbias	463.801	477.617	-13.816
50	LDR_L1_D22_Unbias	469.779	455.048	14.731
50	LDR_L1_D23_Unbias	468.659	453.760	14.899
50	LDR_L2_D23_Unbias	470.097	455.364	14.733
50	LDR_L2_D24_Unbias	475.910	459.716	16.194
50	LDR_L3_D22_Unbias	481.349	464.172	17.177
50	LDR_L1_D16_bias	468.677	452.464	16.213
50	LDR_L1_D17_bias	468.047	464.768	3.279
50	LDR_L2_D17_bias	469.492	461.753	7.739
50	LDR_L2_D18_bias	472.123	463.705	8.418
50	LDR_L2_D19_bias	471.631	469.771	1.860
	Max	481.349	477.617	17.177
	Average	470.870	461.649	9.221
	Min	463.801	452.464	-13.816
	Std Dev	4.568	7.581	9.364



2300.6__VDO_19p3 @ Iload=1500mA		
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	600	mV
Min Limit	50	mV
krads	0	50
LL	50.000	50.000
Min	477.617	452.464
Average	477.617	460.052
Max	477.617	469.771
UL	600.000	600.000



TPS7A4501-RHA

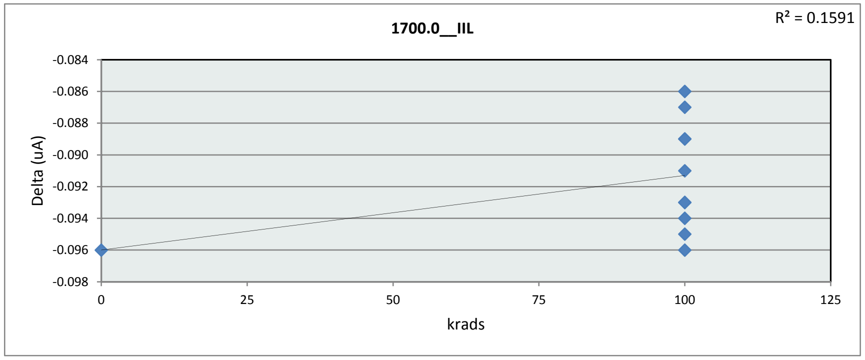
TID LDR Report 100 KRad (Bias and Unbias)

All units passed SMD specification limits up to 100KRAD LDR.

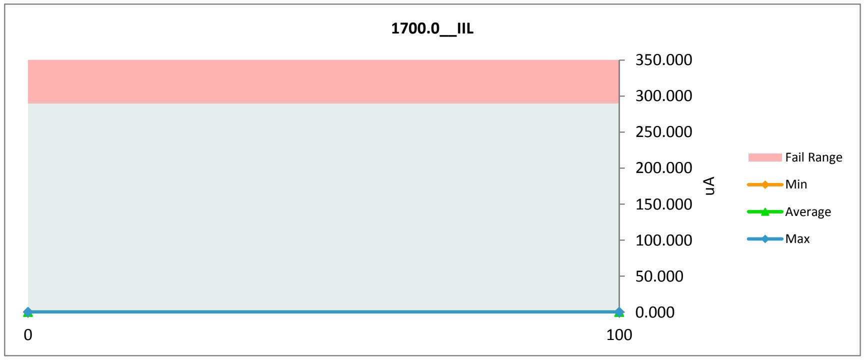
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		1700.0__IIL		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	290	290	
	Min Limit			
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	0.001	0.097	-0.096
100	LDR_L1_D18_Bias	0.001	0.090	-0.089
100	LDR_L1_D19_Bias	0.001	0.087	-0.086
100	LDR_L1_D20_Bias	0.001	0.094	-0.093
100	LDR_L2_D20_Bias	0.001	0.097	-0.096
100	LDR_L2_D21_Bias	0.001	0.095	-0.094
100	LDR_L1_D24_Unbias	0.002	0.095	-0.093
100	LDR_L2_D25_Unbias	0.002	0.097	-0.095
100	LDR_L3_D23_Unbias	0.000	0.091	-0.091
100	LDR_L3_D24_Unbias	0.003	0.090	-0.087
100	LDR_L3_D25_Unbias	0.004	0.093	-0.089
	Max	0.004	0.097	-0.086
	Average	0.002	0.093	-0.092
	Min	0.000	0.087	-0.096
	Std Dev	0.001	0.003	0.004



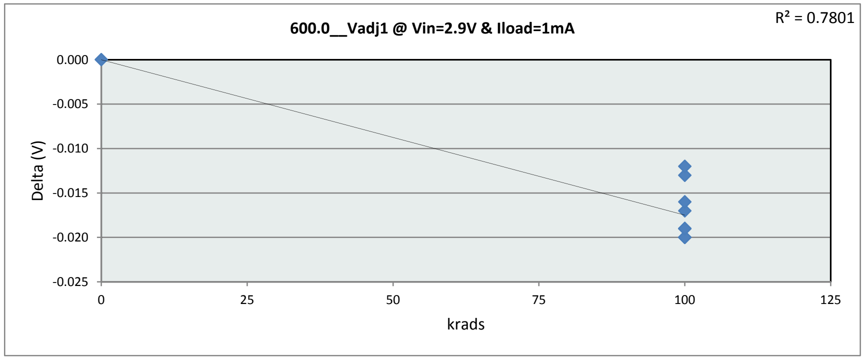
	1700.0__IIL	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	290	uA
Min Limit		uA
krads	0	100
LL		
Min	0.097	0.087
Average	0.097	0.093
Max	0.097	0.097
UL	290.000	290.000



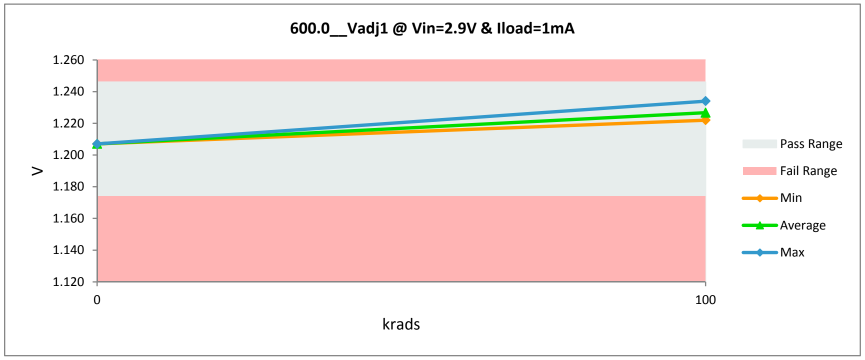
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		600.0__Vadj1 @ Vin=2.9V & Iload=1m		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		V	V	
Max Limit		1.246	1.246	
Min Limit		1.174	1.174	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	1.207	1.207	0.000
100	LDR_L1_D18_Bias	1.207	1.227	-0.020
100	LDR_L1_D19_Bias	1.208	1.228	-0.020
100	LDR_L1_D20_Bias	1.208	1.228	-0.020
100	LDR_L2_D20_Bias	1.215	1.234	-0.019
100	LDR_L2_D21_Bias	1.208	1.227	-0.019
100	LDR_L1_D24_Unbias	1.209	1.222	-0.013
100	LDR_L2_D25_Unbias	1.210	1.222	-0.012
100	LDR_L3_D23_Unbias	1.208	1.225	-0.017
100	LDR_L3_D24_Unbias	1.210	1.229	-0.019
100	LDR_L3_D25_Unbias	1.209	1.225	-0.016
	Max	1.215	1.234	0.000
	Average	1.209	1.225	-0.016
	Min	1.207	1.207	-0.020
	Std Dev	0.002	0.007	0.006



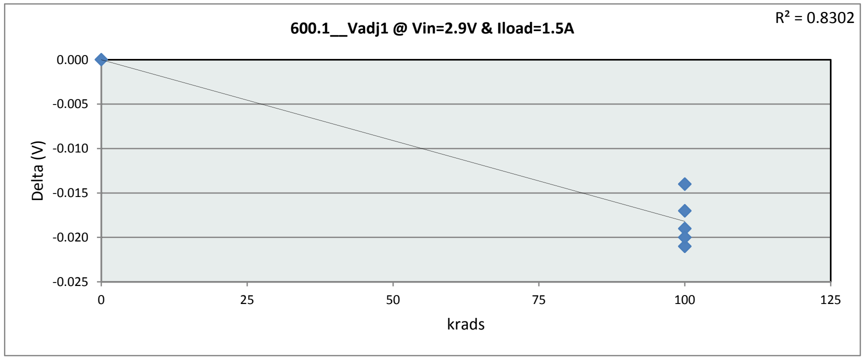
	600.0__Vadj1 @ Vin=2.9V & Iload=1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.246	V
Min Limit	1.174	V
krads	0	100
LL	1.174	1.174
Min	1.207	1.222
Average	1.207	1.227
Max	1.207	1.234
UL	1.246	1.246



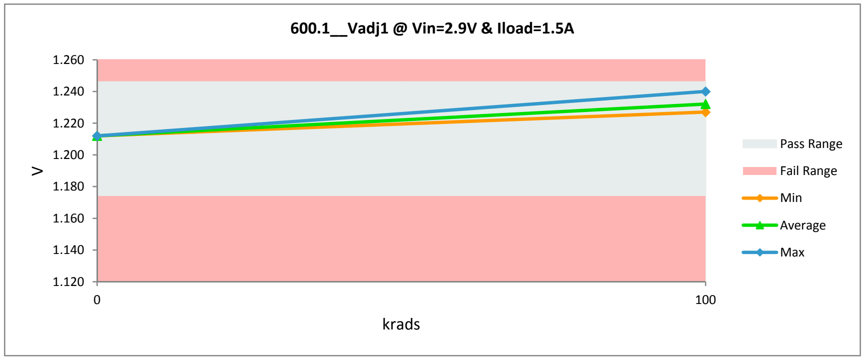
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		600.1__Vadj1 @ Vin=2.9V & Iload=1.		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	1.246	1.246	
	Min Limit	1.174	1.174	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	1.212	1.212	0.000
100	LDR_L1_D18_Bias	1.212	1.233	-0.021
100	LDR_L1_D19_Bias	1.213	1.233	-0.020
100	LDR_L1_D20_Bias	1.213	1.232	-0.019
100	LDR_L2_D20_Bias	1.221	1.240	-0.019
100	LDR_L2_D21_Bias	1.212	1.233	-0.021
100	LDR_L1_D24_Unbias	1.213	1.227	-0.014
100	LDR_L2_D25_Unbias	1.215	1.229	-0.014
100	LDR_L3_D23_Unbias	1.212	1.229	-0.017
100	LDR_L3_D24_Unbias	1.214	1.234	-0.020
100	LDR_L3_D25_Unbias	1.214	1.231	-0.017
	Max	1.221	1.240	0.000
	Average	1.214	1.230	-0.017
	Min	1.212	1.212	-0.021
	Std Dev	0.003	0.007	0.006



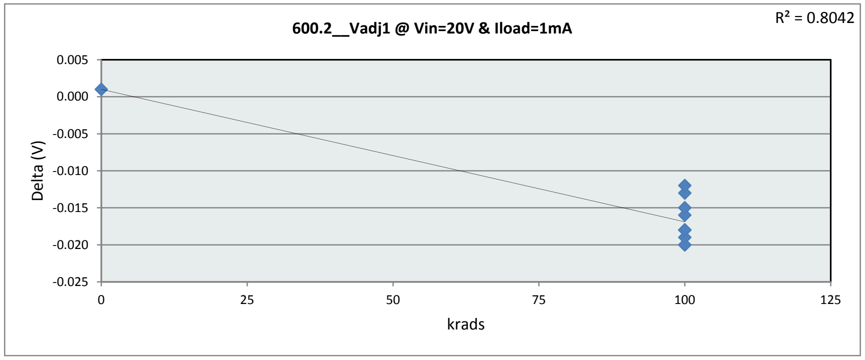
	600.1__Vadj1 @ Vin=2.9V & Iload=1.5A	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.246	V
Min Limit	1.174	V
krads	0	100
LL	1.174	1.174
Min	1.212	1.227
Average	1.212	1.232
Max	1.212	1.240
UL	1.246	1.246



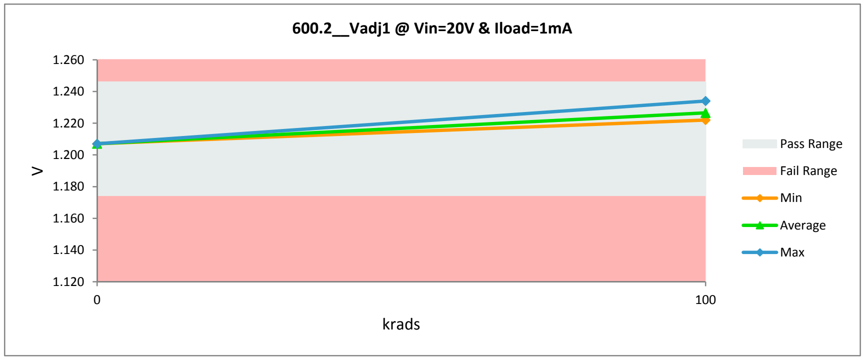
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		600.2__Vadj1 @ Vin=20V & Iload=1m		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	1.246	1.246	
	Min Limit	1.174	1.174	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	1.208	1.207	0.001
100	LDR_L1_D18_Bias	1.207	1.227	-0.020
100	LDR_L1_D19_Bias	1.208	1.228	-0.020
100	LDR_L1_D20_Bias	1.209	1.227	-0.018
100	LDR_L2_D20_Bias	1.216	1.234	-0.018
100	LDR_L2_D21_Bias	1.208	1.227	-0.019
100	LDR_L1_D24_Unbias	1.209	1.222	-0.013
100	LDR_L2_D25_Unbias	1.210	1.222	-0.012
100	LDR_L3_D23_Unbias	1.209	1.225	-0.016
100	LDR_L3_D24_Unbias	1.210	1.228	-0.018
100	LDR_L3_D25_Unbias	1.210	1.225	-0.015
	Max	1.216	1.234	0.001
	Average	1.209	1.225	-0.015
	Min	1.207	1.207	-0.020
	Std Dev	0.002	0.007	0.006

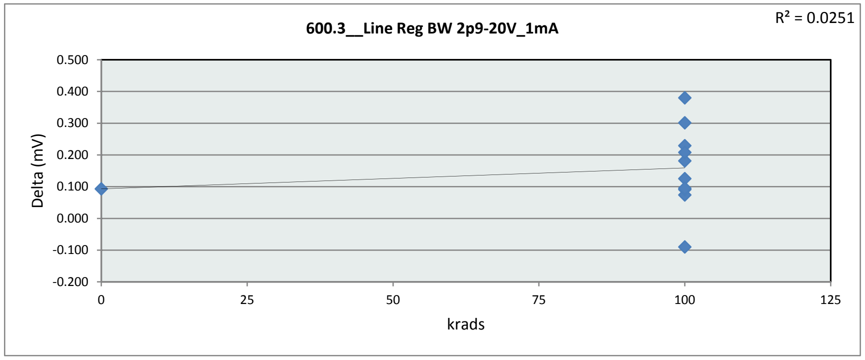


	600.2__Vadj1 @ Vin=20V & Iload=1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.246	V
Min Limit	1.174	V
krads	0	100
LL	1.174	1.174
Min	1.207	1.222
Average	1.207	1.227
Max	1.207	1.234
UL	1.246	1.246

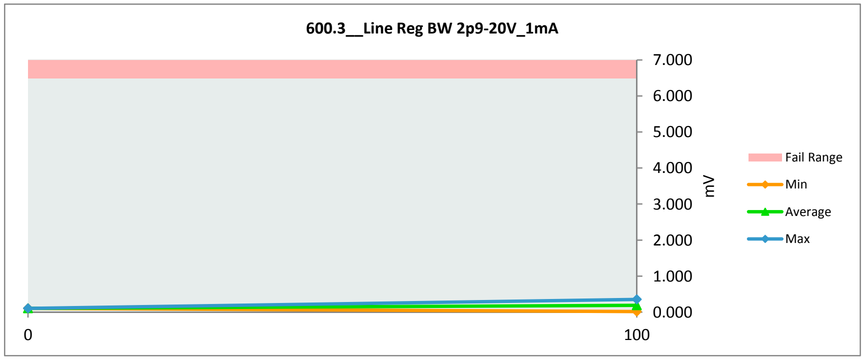


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		600.3__Line Reg BW 2p9-20V_1mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		6.5	6.5	
Min Limit				
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	0.198	0.105	0.093
100	LDR_L1_D18_Bias	0.210	0.085	0.125
100	LDR_L1_D19_Bias	0.315	0.014	0.301
100	LDR_L1_D20_Bias	0.212	0.302	-0.090
100	LDR_L2_D20_Bias	0.534	0.154	0.380
100	LDR_L2_D21_Bias	0.247	0.173	0.074
100	LDR_L1_D24_Unbias	0.408	0.179	0.229
100	LDR_L2_D25_Unbias	0.330	0.239	0.091
100	LDR_L3_D23_Unbias	0.350	0.169	0.181
100	LDR_L3_D24_Unbias	0.447	0.352	0.095
100	LDR_L3_D25_Unbias	0.419	0.211	0.208
	Max	0.534	0.352	0.380
	Average	0.334	0.180	0.153
	Min	0.198	0.014	-0.090
	Std Dev	0.111	0.096	0.126

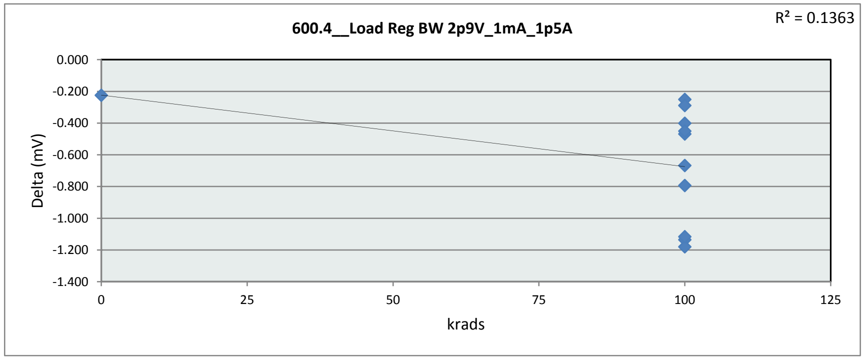


	600.3__Line Reg BW 2p9-20V_1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	6.5	mV
Min Limit		mV
krads	0	100
LL		
Min	0.105	0.014
Average	0.105	0.188
Max	0.105	0.352
UL	6.500	6.500

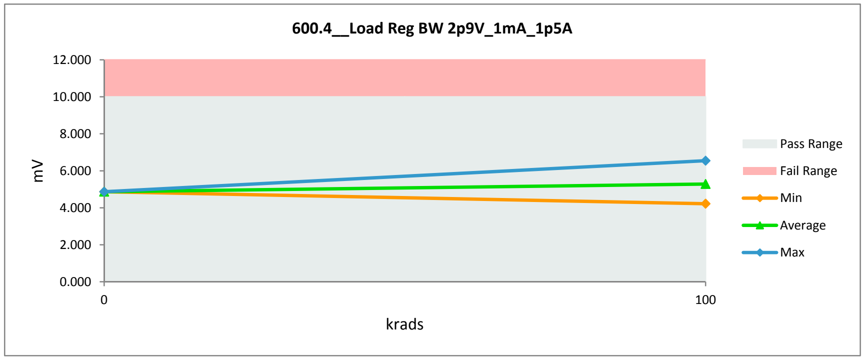


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		600.4__Load Reg BW 2p9V_1mA_1p5		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	10	10	
	Min Limit	0	0	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	4.643	4.867	-0.224
100	LDR_L1_D18_Bias	4.511	5.178	-0.667
100	LDR_L1_D19_Bias	4.436	5.229	-0.793
100	LDR_L1_D20_Bias	4.380	4.631	-0.251
100	LDR_L2_D20_Bias	5.203	5.671	-0.468
100	LDR_L2_D21_Bias	4.522	5.657	-1.135
100	LDR_L1_D24_Unbias	4.297	4.698	-0.401
100	LDR_L2_D25_Unbias	5.364	6.543	-1.179
100	LDR_L3_D23_Unbias	3.932	4.221	-0.289
100	LDR_L3_D24_Unbias	4.492	4.942	-0.450
100	LDR_L3_D25_Unbias	4.937	6.053	-1.116
	Max	5.364	6.543	-0.224
	Average	4.611	5.245	-0.634
	Min	3.932	4.221	-1.179
	Std Dev	0.412	0.682	0.368

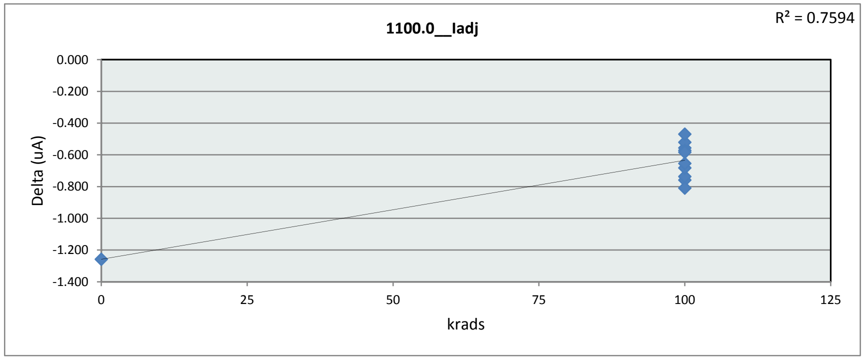


	600.4__Load Reg BW 2p9V_1mA_1p5A	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	10	mV
Min Limit	0	mV
krads	0	100
LL	0.000	0.000
Min	4.867	4.221
Average	4.867	5.282
Max	4.867	6.543
UL	10.000	10.000

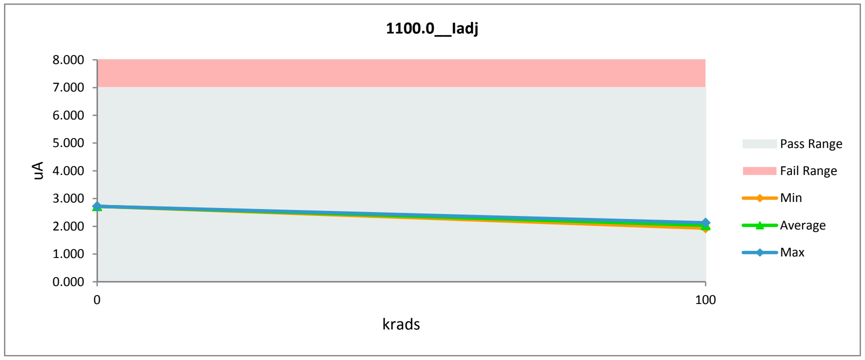


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
		1100.0__Iadj		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	7	7	
	Min Limit	0	0	
0	_CORR_L1_D25	1.461	2.719	-1.258
100	LDR_L1_D18_Bias	1.369	2.128	-0.759
100	LDR_L1_D19_Bias	1.383	2.120	-0.737
100	LDR_L1_D20_Bias	1.477	2.033	-0.556
100	LDR_L2_D20_Bias	1.402	2.084	-0.682
100	LDR_L2_D21_Bias	1.497	2.018	-0.521
100	LDR_L1_D24_Unbias	1.359	1.931	-0.572
100	LDR_L2_D25_Unbias	1.373	1.956	-0.583
100	LDR_L3_D23_Unbias	1.544	2.013	-0.469
100	LDR_L3_D24_Unbias	1.311	2.120	-0.809
100	LDR_L3_D25_Unbias	1.286	1.940	-0.654
	Max	1.544	2.719	-0.469
	Average	1.406	2.097	-0.691
	Min	1.286	1.931	-1.258
	Std Dev	0.080	0.219	0.216

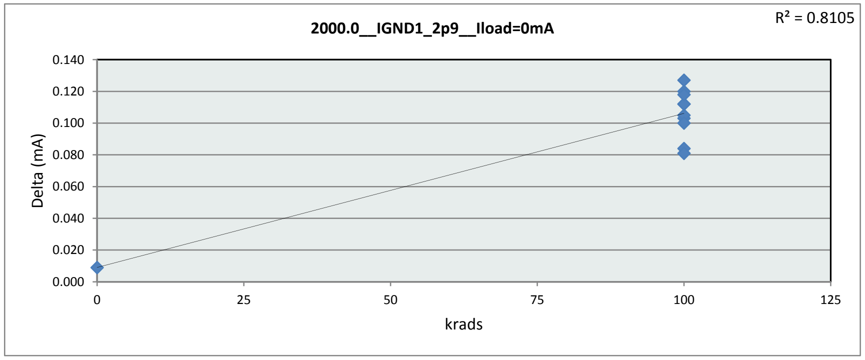


	1100.0__Iadj	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	7	uA
Min Limit	0	uA
krads	0	100
LL	0.000	0.000
Min	2.719	1.931
Average	2.719	2.034
Max	2.719	2.128
UL	7.000	7.000

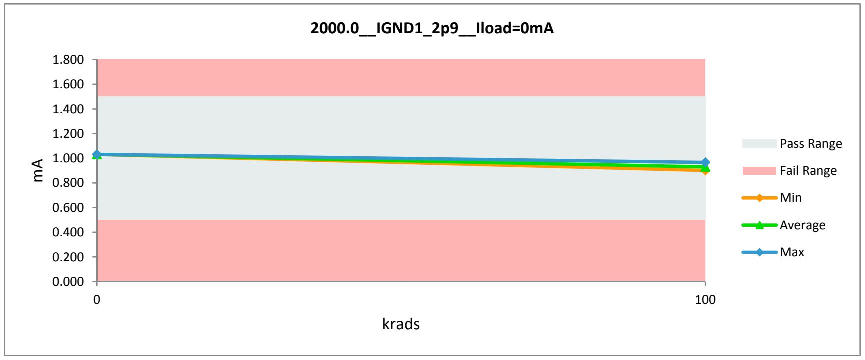


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		2000.0__IGND1_2p9__Iload=0mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	1.5	1.5	
	Min Limit	0.5	0.5	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	1.040	1.031	0.009
100	LDR_L1_D18_Bias	1.029	0.902	0.127
100	LDR_L1_D19_Bias	1.041	0.921	0.120
100	LDR_L1_D20_Bias	1.045	0.942	0.103
100	LDR_L2_D20_Bias	1.043	0.938	0.105
100	LDR_L2_D21_Bias	1.036	0.924	0.112
100	LDR_L1_D24_Unbias	1.051	0.967	0.084
100	LDR_L2_D25_Unbias	1.034	0.953	0.081
100	LDR_L3_D23_Unbias	1.042	0.930	0.112
100	LDR_L3_D24_Unbias	1.028	0.910	0.118
100	LDR_L3_D25_Unbias	1.020	0.920	0.100
	Max	1.051	1.031	0.127
	Average	1.037	0.940	0.097
	Min	1.020	0.902	0.009
	Std Dev	0.009	0.036	0.033



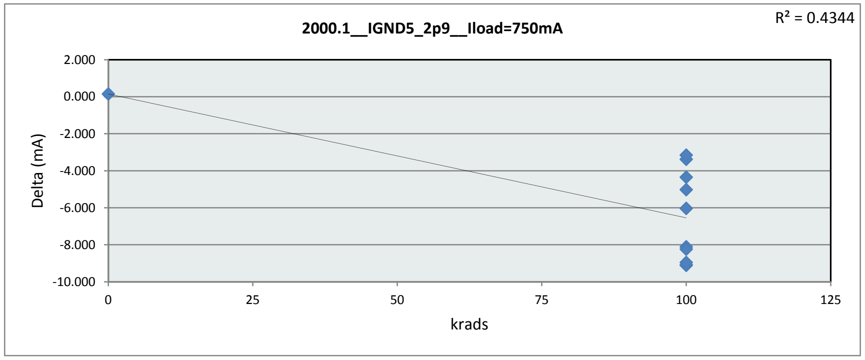
	2000.0__IGND1_2p9__Iload=0mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.5	mA
Min Limit	0.5	mA
krads	0	100
LL	0.500	0.500
Min	1.031	0.902
Average	1.031	0.931
Max	1.031	0.967
UL	1.500	1.500



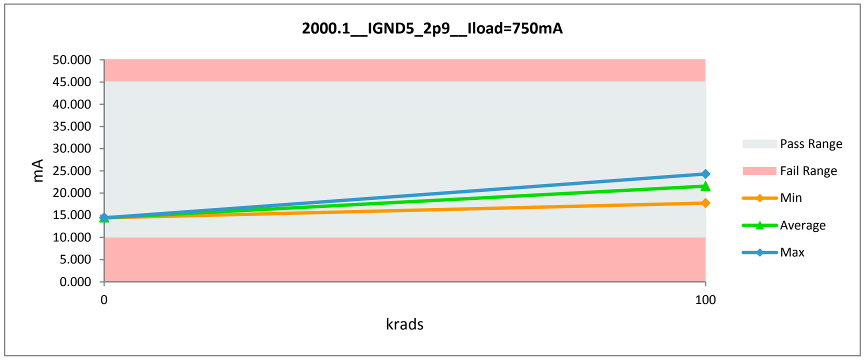
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2000.1__IGND5_2p9__Iload=750mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mA	mA	
Max Limit		45	45	
Min Limit		10	10	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	14.590	14.440	0.150
100	LDR_L1_D18_Bias	14.634	23.740	-9.106
100	LDR_L1_D19_Bias	14.522	23.609	-9.087
100	LDR_L1_D20_Bias	14.514	23.469	-8.955
100	LDR_L2_D20_Bias	16.192	24.302	-8.110
100	LDR_L2_D21_Bias	14.579	22.815	-8.236
100	LDR_L1_D24_Unbias	14.359	17.738	-3.379
100	LDR_L2_D25_Unbias	15.617	18.771	-3.154
100	LDR_L3_D23_Unbias	14.963	19.989	-5.026
100	LDR_L3_D24_Unbias	15.300	21.333	-6.033
100	LDR_L3_D25_Unbias	15.410	19.761	-4.351
	Max	16.192	24.302	0.150
	Average	14.971	20.906	-5.935
	Min	14.359	14.440	-9.106
	Std Dev	0.584	3.096	3.062



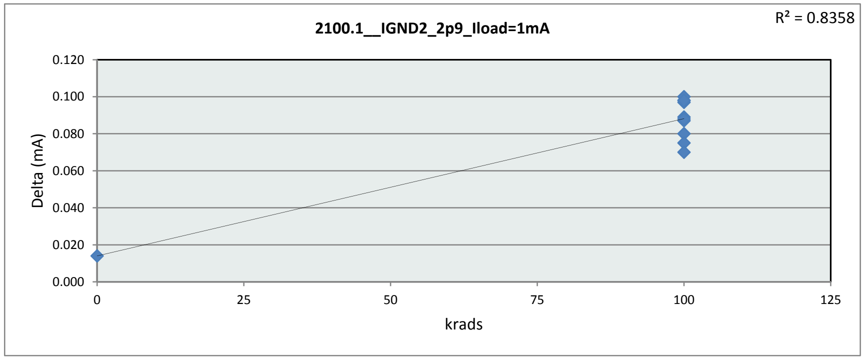
	2000.1__IGND5_2p9__Iload=750mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	45	mA
Min Limit	10	mA
krads	0	100
LL	10.000	10.000
Min	14.440	17.738
Average	14.440	21.553
Max	14.440	24.302
UL	45.000	45.000



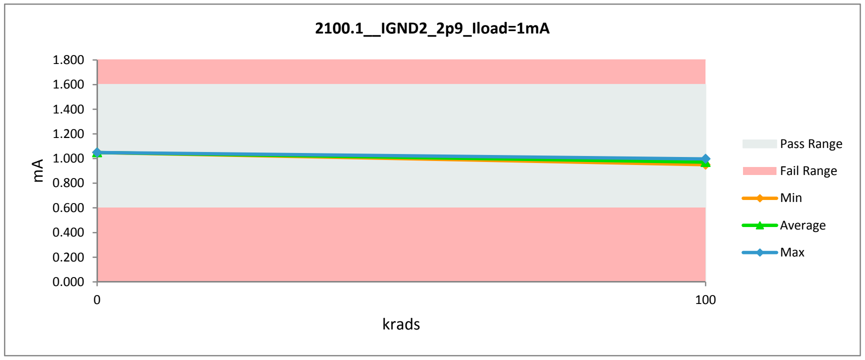
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2100.1__IGND2_2p9_Iload=1mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mA	mA	
Max Limit		1.6	1.6	
Min Limit		0.6	0.6	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	CORR_L1_D25	1.063	1.049	0.014
100	LDR_L1_D18_Bias	1.050	0.950	0.100
100	LDR_L1_D19_Bias	1.065	0.968	0.097
100	LDR_L1_D20_Bias	1.067	0.987	0.080
100	LDR_L2_D20_Bias	1.069	0.982	0.087
100	LDR_L2_D21_Bias	1.056	0.967	0.089
100	LDR_L1_D24_Unbias	1.072	0.997	0.075
100	LDR_L2_D25_Unbias	1.054	0.984	0.070
100	LDR_L3_D23_Unbias	1.066	0.968	0.098
100	LDR_L3_D24_Unbias	1.048	0.950	0.098
100	LDR_L3_D25_Unbias	1.043	0.955	0.088
	Max	1.072	1.049	0.100
	Average	1.059	0.978	0.081
	Min	1.043	0.950	0.014
	Std Dev	0.010	0.028	0.024



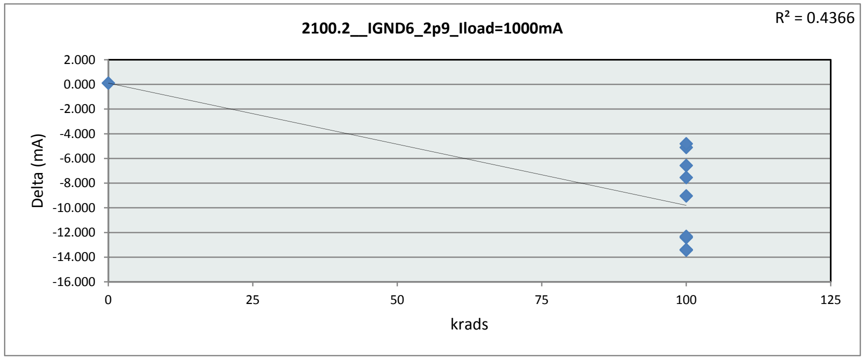
	2100.1__IGND2_2p9_Iload=1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1.6	mA
Min Limit	0.6	mA
krads	0	100
LL	0.600	0.600
Min	1.049	0.950
Average	1.049	0.971
Max	1.049	0.997
UL	1.600	1.600



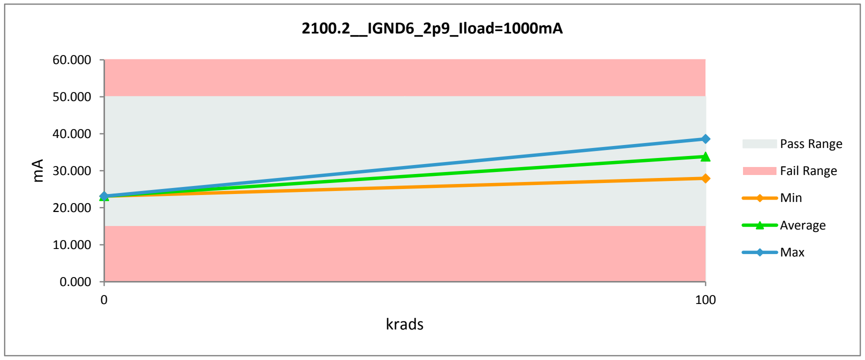
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2100.2__IGND6_2p9_Iload=1000mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	50	50	
	Min Limit	15	15	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	23.227	23.125	0.102
100	LDR_L1_D18_Bias	23.331	36.767	-13.436
100	LDR_L1_D19_Bias	23.148	36.558	-13.410
100	LDR_L1_D20_Bias	23.109	36.503	-13.394
100	LDR_L2_D20_Bias	26.192	38.603	-12.411
100	LDR_L2_D21_Bias	23.305	35.623	-12.318
100	LDR_L1_D24_Unbias	22.839	27.951	-5.112
100	LDR_L2_D25_Unbias	25.036	29.851	-4.815
100	LDR_L3_D23_Unbias	23.968	31.519	-7.551
100	LDR_L3_D24_Unbias	24.642	33.676	-9.034
100	LDR_L3_D25_Unbias	24.663	31.242	-6.579
	Max	26.192	38.603	0.102
	Average	23.951	32.856	-8.905
	Min	22.839	23.125	-13.436
	Std Dev	1.054	4.646	4.521

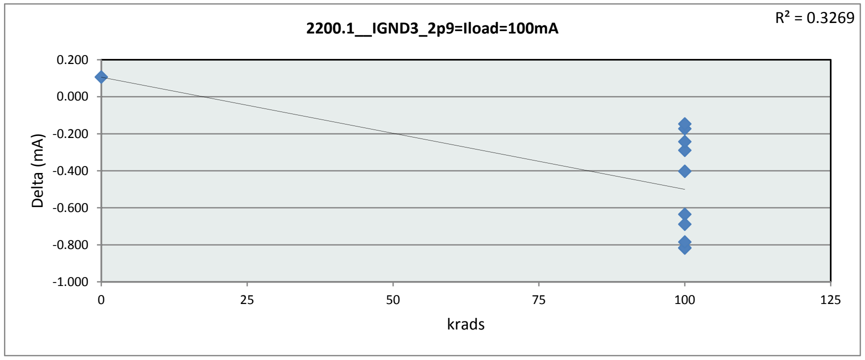


	2100.2__IGND6_2p9_Iload=1000mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	50	mA
Min Limit	15	mA
krads	0	100
LL	15.000	15.000
Min	23.125	27.951
Average	23.125	33.829
Max	23.125	38.603
UL	50.000	50.000

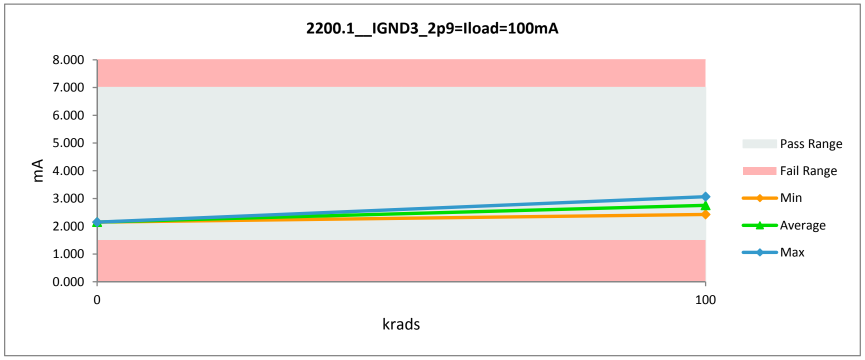


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
		2200.1__IGND3_2p9=Iload=100mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mA	mA	
Max Limit		7	7	
Min Limit		1.5	1.5	
0	_CORR_L1_D25	2.256	2.150	0.106
100	LDR_L1_D18_Bias	2.239	3.057	-0.818
100	LDR_L1_D19_Bias	2.250	3.066	-0.816
100	LDR_L1_D20_Bias	2.254	3.039	-0.785
100	LDR_L2_D20_Bias	2.296	2.931	-0.635
100	LDR_L2_D21_Bias	2.231	2.920	-0.689
100	LDR_L1_D24_Unbias	2.254	2.427	-0.173
100	LDR_L2_D25_Unbias	2.279	2.426	-0.147
100	LDR_L3_D23_Unbias	2.259	2.549	-0.290
100	LDR_L3_D24_Unbias	2.245	2.648	-0.403
100	LDR_L3_D25_Unbias	2.256	2.499	-0.243
	Max	2.296	3.066	0.106
	Average	2.256	2.701	-0.445
	Min	2.231	2.150	-0.818
	Std Dev	0.018	0.316	0.320



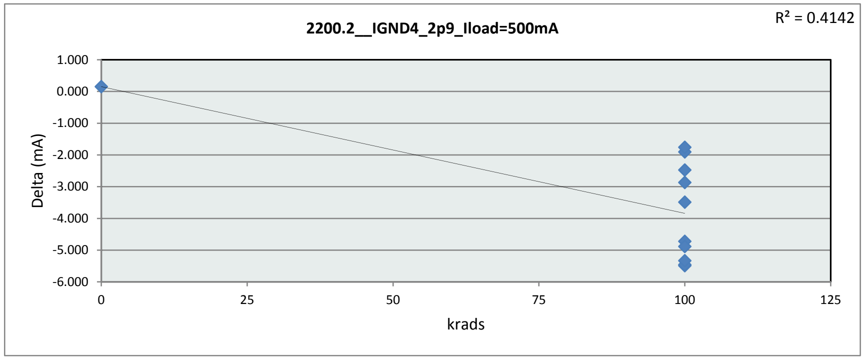
	0	100
	2200.1__IGND3_2p9=Iload=100mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	7	mA
Min Limit	1.5	mA
krads	0	100
LL	1.500	1.500
Min	2.150	2.426
Average	2.150	2.756
Max	2.150	3.066
UL	7.000	7.000



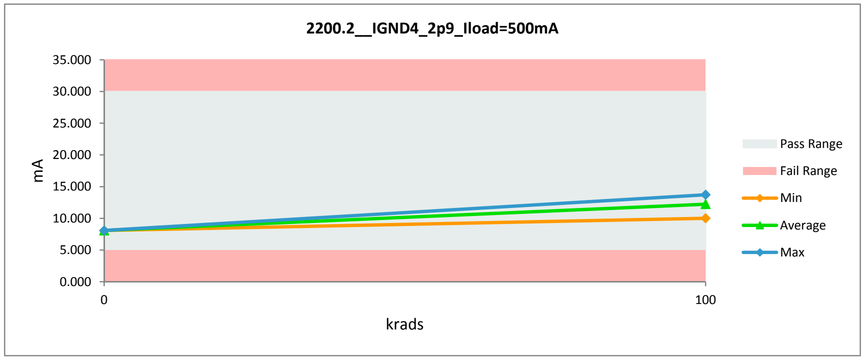
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2200.2__IGND4_2p9_Iload=500mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mA	mA	
Max Limit		30	30	
Min Limit		5	5	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	8.231	8.080	0.151
100	LDR_L1_D18_Bias	8.233	13.726	-5.493
100	LDR_L1_D19_Bias	8.193	13.653	-5.460
100	LDR_L1_D20_Bias	8.186	13.519	-5.333
100	LDR_L2_D20_Bias	8.934	13.656	-4.722
100	LDR_L2_D21_Bias	8.176	13.060	-4.884
100	LDR_L1_D24_Unbias	8.113	10.018	-1.905
100	LDR_L2_D25_Unbias	8.700	10.458	-1.758
100	LDR_L3_D23_Unbias	8.373	11.241	-2.868
100	LDR_L3_D24_Unbias	8.496	11.984	-3.488
100	LDR_L3_D25_Unbias	8.601	11.075	-2.474
	Max	8.934	13.726	0.151
	Average	8.385	11.861	-3.476
	Min	8.113	8.080	-5.493
	Std Dev	0.265	1.865	1.869

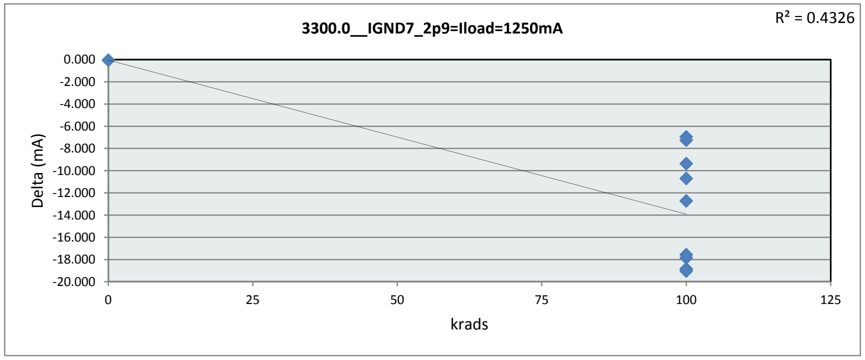


	2200.2__IGND4_2p9_Iload=500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	30	mA
Min Limit	5	mA
krads	0	100
LL	5.000	5.000
Min	8.080	10.018
Average	8.080	12.239
Max	8.080	13.726
UL	30.000	30.000

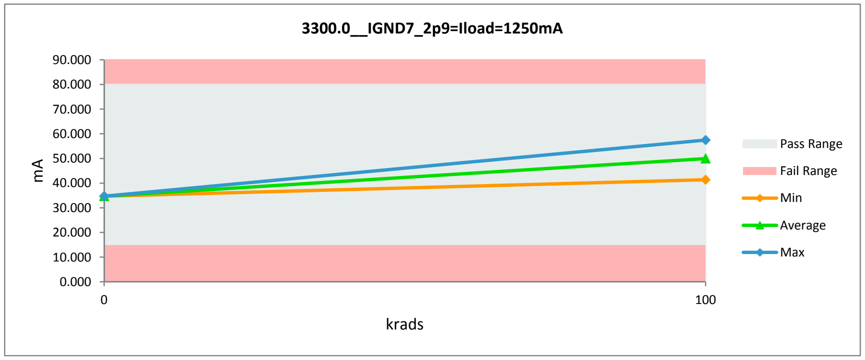


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		3300.0__IGND7_2p9=Iload=1250mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mA	mA	
Max Limit		80	80	
Min Limit		15	15	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	34.657	34.703	-0.046
100	LDR_L1_D18_Bias	34.856	53.731	-18.875
100	LDR_L1_D19_Bias	34.557	53.395	-18.838
100	LDR_L1_D20_Bias	34.512	53.543	-19.031
100	LDR_L2_D20_Bias	39.616	57.459	-17.843
100	LDR_L2_D21_Bias	34.910	52.456	-17.546
100	LDR_L1_D24_Unbias	34.095	41.352	-7.257
100	LDR_L2_D25_Unbias	37.533	44.481	-6.948
100	LDR_L3_D23_Unbias	35.962	46.654	-10.692
100	LDR_L3_D24_Unbias	37.230	49.943	-12.713
100	LDR_L3_D25_Unbias	36.965	46.316	-9.351
	Max	39.616	57.459	-0.046
	Average	35.899	48.548	-12.649
	Min	34.095	34.703	-19.031
	Std Dev	1.732	6.637	6.355



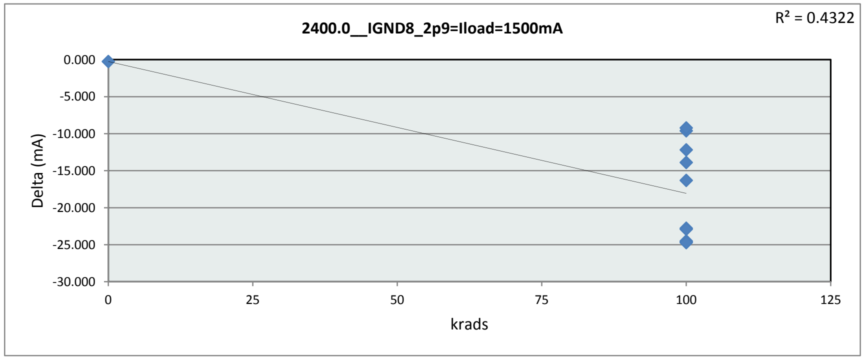
	3300.0__IGND7_2p9=Iload=1250mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	80	mA
Min Limit	15	mA
krads	0	100
LL	15.000	15.000
Min	34.703	41.352
Average	34.703	49.933
Max	34.703	57.459
UL	80.000	80.000



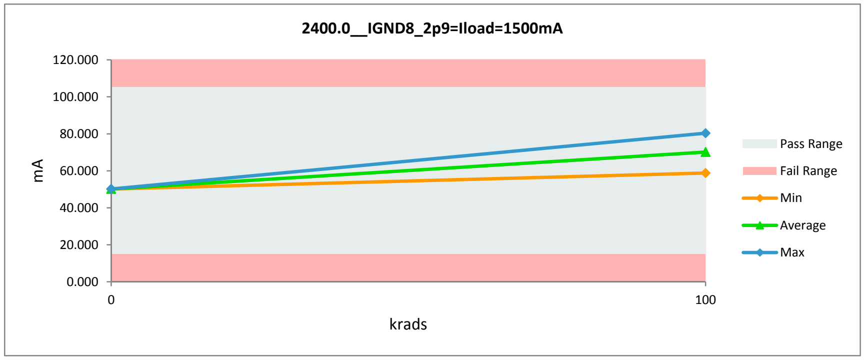
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2400.0__IGND8_2p9=Iload=1500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	105	105	
	Min Limit	15	15	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	49.905	50.157	-0.252
100	LDR_L1_D18_Bias	50.286	74.877	-24.591
100	LDR_L1_D19_Bias	49.826	74.307	-24.481
100	LDR_L1_D20_Bias	49.793	74.498	-24.705
100	LDR_L2_D20_Bias	57.588	80.356	-22.768
100	LDR_L2_D21_Bias	50.461	73.351	-22.890
100	LDR_L1_D24_Unbias	49.186	58.783	-9.597
100	LDR_L2_D25_Unbias	54.251	63.467	-9.216
100	LDR_L3_D23_Unbias	52.027	65.907	-13.880
100	LDR_L3_D24_Unbias	54.150	70.447	-16.297
100	LDR_L3_D25_Unbias	53.386	65.551	-12.165
	Max	57.588	80.356	-0.252
	Average	51.896	68.336	-16.440
	Min	49.186	50.157	-24.705
	Std Dev	2.644	8.658	8.167



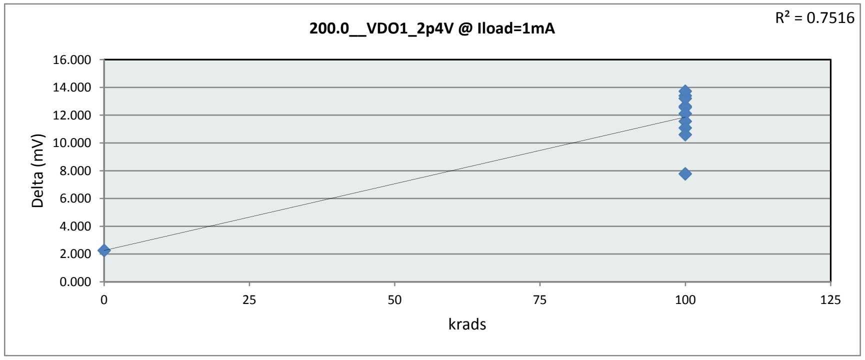
	2400.0__IGND8_2p9=Iload=1500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	105	mA
Min Limit	15	mA
krads	0	100
LL	15.000	15.000
Min	50.157	58.783
Average	50.157	70.154
Max	50.157	80.356
UL	105.000	105.000



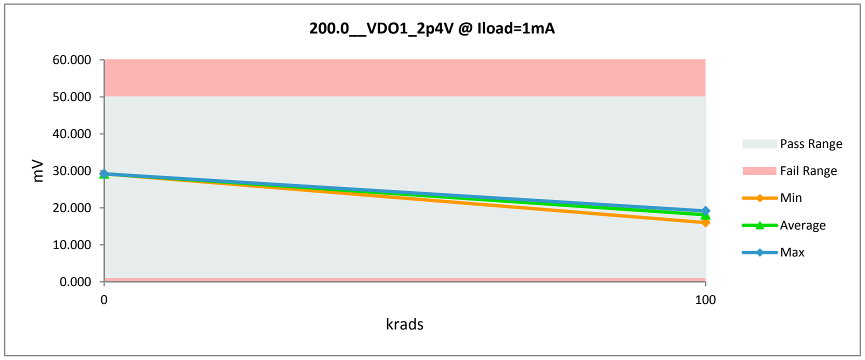
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		200.0__VDO1_2p4V @ Iload=1mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		50	50	
Min Limit		1	1	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	31.457	29.199	2.258
100	LDR_L1_D18_Bias	31.210	17.811	13.399
100	LDR_L1_D19_Bias	30.760	18.116	12.644
100	LDR_L1_D20_Bias	30.724	19.163	11.561
100	LDR_L2_D20_Bias	24.917	17.139	7.778
100	LDR_L2_D21_Bias	31.730	19.172	12.558
100	LDR_L1_D24_Unbias	30.113	19.031	11.082
100	LDR_L2_D25_Unbias	29.295	18.691	10.604
100	LDR_L3_D23_Unbias	31.489	18.285	13.204
100	LDR_L3_D24_Unbias	29.745	16.025	13.720
100	LDR_L3_D25_Unbias	30.028	17.918	12.110
	Max	31.730	29.199	13.720
	Average	30.133	19.141	10.993
	Min	24.917	16.025	2.258
	Std Dev	1.900	3.466	3.341

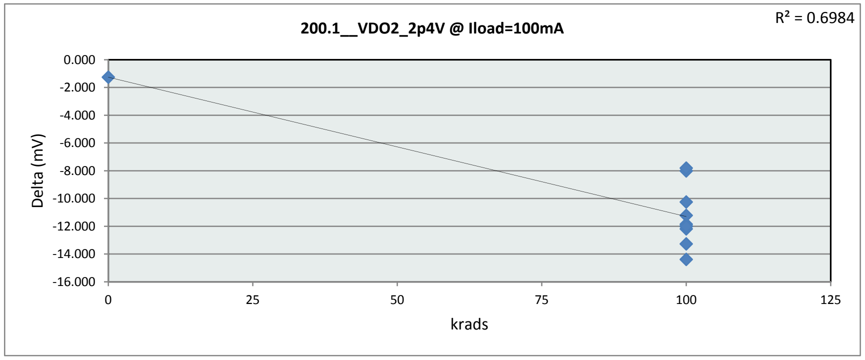


	200.0__VDO1_2p4V @ Iload=1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	50	mV
Min Limit	1	mV
krads	0	100
LL	1.000	1.000
Min	29.199	16.025
Average	29.199	18.135
Max	29.199	19.172
UL	50.000	50.000

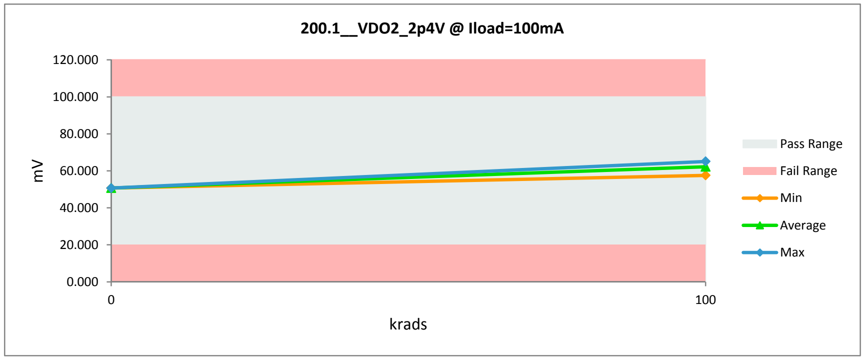


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		200.1__VDO2_2p4V @ Iload=100mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		100	100	
Min Limit		20	20	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	49.452	50.715	-1.263
100	LDR_L1_D18_Bias	49.371	61.227	-11.856
100	LDR_L1_D19_Bias	49.754	61.937	-12.183
100	LDR_L1_D20_Bias	49.592	63.974	-14.382
100	LDR_L2_D20_Bias	53.107	65.082	-11.975
100	LDR_L2_D21_Bias	49.827	63.099	-13.272
100	LDR_L1_D24_Unbias	49.541	57.560	-8.019
100	LDR_L2_D25_Unbias	51.101	58.906	-7.805
100	LDR_L3_D23_Unbias	51.660	62.872	-11.212
100	LDR_L3_D24_Unbias	52.724	64.733	-12.009
100	LDR_L3_D25_Unbias	52.183	62.435	-10.252
	Max	53.107	65.082	-1.263
	Average	50.756	61.140	-10.384
	Min	49.371	50.715	-14.382
	Std Dev	1.438	4.149	3.620

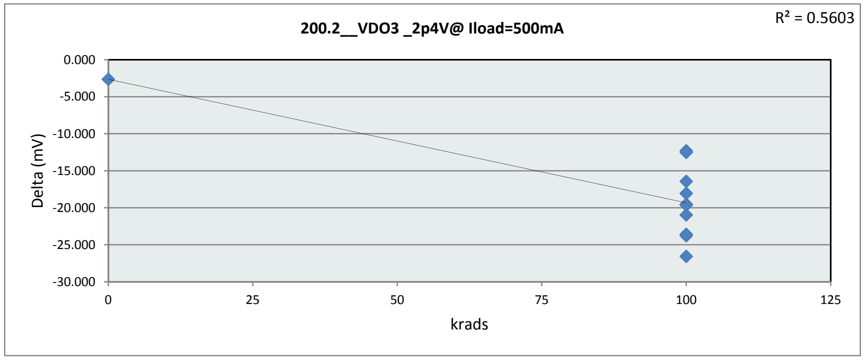


	200.1__VDO2_2p4V @ Iload=100mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	100	mV
Min Limit	20	mV
krads	0	100
LL	20.000	20.000
Min	50.715	57.560
Average	50.715	62.183
Max	50.715	65.082
UL	100.000	100.000

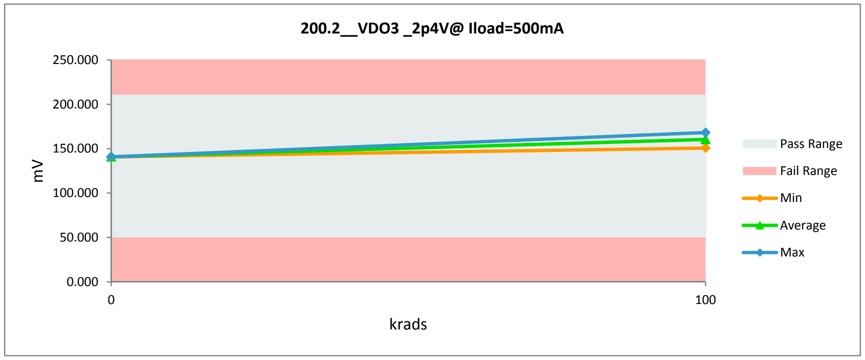


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		200.2__VDO3 _2p4V@ Iload=500mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		210	210	
Min Limit		50	50	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	138.230	140.879	-2.649
100	LDR_L1_D18_Bias	138.568	158.082	-19.514
100	LDR_L1_D19_Bias	138.876	159.838	-20.962
100	LDR_L1_D20_Bias	138.765	165.320	-26.555
100	LDR_L2_D20_Bias	144.401	168.186	-23.785
100	LDR_L2_D21_Bias	139.400	162.978	-23.578
100	LDR_L1_D24_Unbias	138.421	150.735	-12.314
100	LDR_L2_D25_Unbias	141.287	153.798	-12.511
100	LDR_L3_D23_Unbias	142.562	160.615	-18.053
100	LDR_L3_D24_Unbias	144.958	164.584	-19.626
100	LDR_L3_D25_Unbias	143.200	159.634	-16.434
	Max	144.958	168.186	-2.649
	Average	140.788	158.604	-17.816
	Min	138.230	140.879	-26.555
	Std Dev	2.577	7.732	6.721

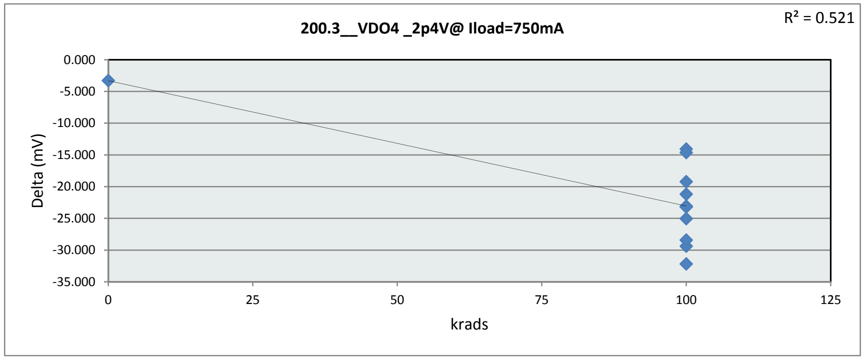


	200.2__VDO3 _2p4V@ Iload=500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	210	mV
Min Limit	50	mV
krads	0	100
LL	50.000	50.000
Min	140.879	150.735
Average	140.879	160.377
Max	140.879	168.186
UL	210.000	210.000

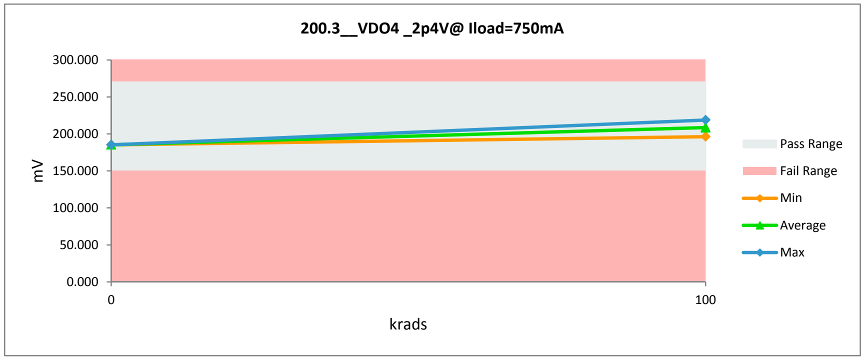


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		200.3__VDO4 _2p4V@ Iload=750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	270	270	
	Min Limit	150	150	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	181.986	185.288	-3.302
100	LDR_L1_D18_Bias	182.683	205.757	-23.074
100	LDR_L1_D19_Bias	182.831	207.875	-25.044
100	LDR_L1_D20_Bias	182.823	215.006	-32.183
100	LDR_L2_D20_Bias	189.424	218.792	-29.368
100	LDR_L2_D21_Bias	183.489	211.910	-28.421
100	LDR_L1_D24_Unbias	182.244	196.321	-14.077
100	LDR_L2_D25_Unbias	185.823	200.454	-14.631
100	LDR_L3_D23_Unbias	187.276	208.471	-21.195
100	LDR_L3_D24_Unbias	190.409	213.614	-23.205
100	LDR_L3_D25_Unbias	187.967	207.189	-19.222
	Max	190.409	218.792	-3.302
	Average	185.178	206.425	-21.247
	Min	181.986	185.288	-32.183
	Std Dev	3.113	9.488	8.246



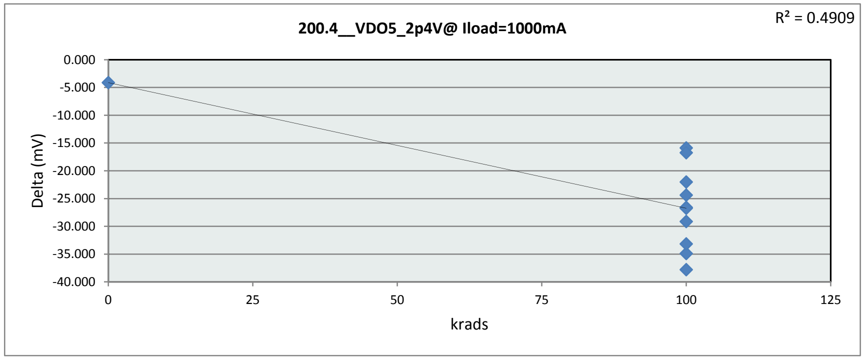
	200.3__VDO4 _2p4V@ Iload=750mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	270	mV
Min Limit	150	mV
krads	0	100
LL	150.000	150.000
Min	185.288	196.321
Average	185.288	208.539
Max	185.288	218.792
UL	270.000	270.000



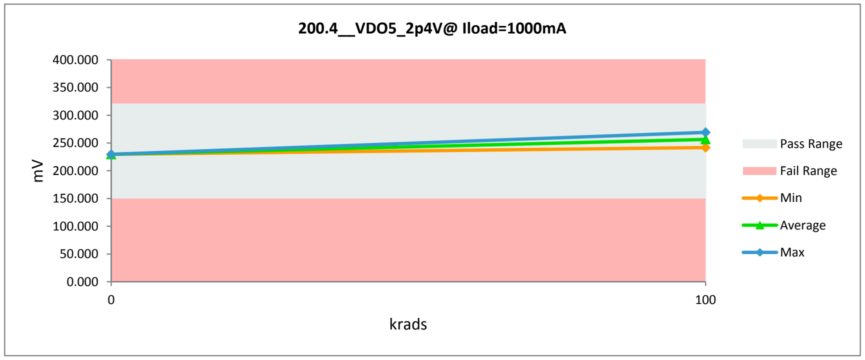
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		200.4__VDO5_2p4V@ Iload=1000mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	320	320	
	Min Limit	150	150	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	225.423	229.560	-4.137
100	LDR_L1_D18_Bias	226.598	253.203	-26.605
100	LDR_L1_D19_Bias	226.507	255.638	-29.131
100	LDR_L1_D20_Bias	226.614	264.425	-37.811
100	LDR_L2_D20_Bias	234.344	269.250	-34.906
100	LDR_L2_D21_Bias	227.424	260.592	-33.168
100	LDR_L1_D24_Unbias	225.841	241.735	-15.894
100	LDR_L2_D25_Unbias	230.228	246.977	-16.749
100	LDR_L3_D23_Unbias	231.841	256.214	-24.373
100	LDR_L3_D24_Unbias	235.766	262.508	-26.742
100	LDR_L3_D25_Unbias	232.512	254.525	-22.013
	Max	235.766	269.250	-4.137
	Average	229.373	254.057	-24.684
	Min	225.423	229.560	-37.811
	Std Dev	3.710	11.237	9.727

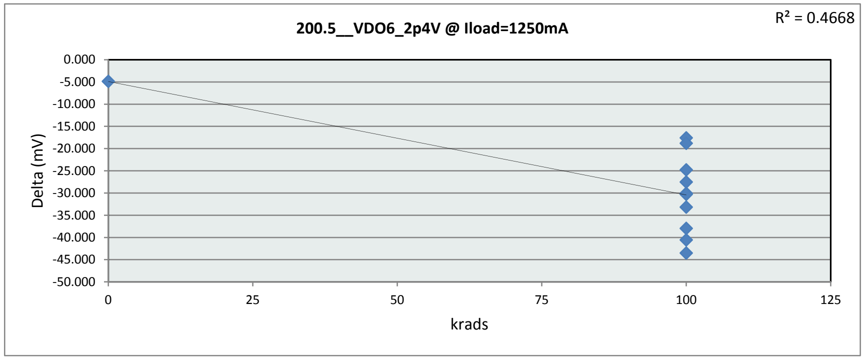


	200.4__VDO5_2p4V@ Iload=1000mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	320	mV
Min Limit	150	mV
krads	0	100
LL	150.000	150.000
Min	229.560	241.735
Average	229.560	256.507
Max	229.560	269.250
UL	320.000	320.000

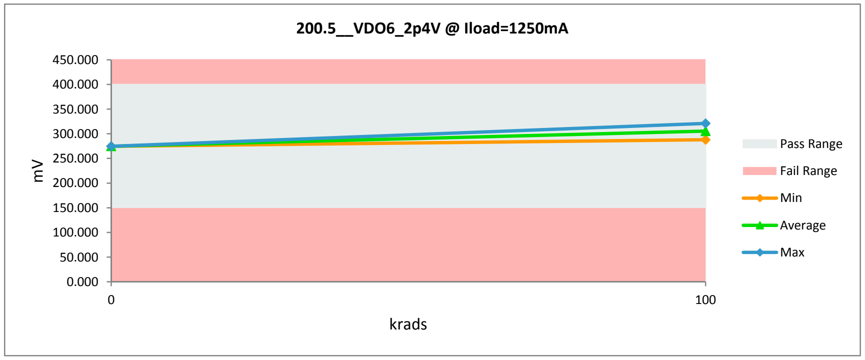


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		200.5__VDO6_2p4V @ Iload=1250mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		400	400	
Min Limit		150	150	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	269.770	274.665	-4.895
100	LDR_L1_D18_Bias	271.497	301.593	-30.096
100	LDR_L1_D19_Bias	271.144	304.338	-33.194
100	LDR_L1_D20_Bias	271.407	314.913	-43.506
100	LDR_L2_D20_Bias	280.390	320.951	-40.561
100	LDR_L2_D21_Bias	272.372	310.330	-37.958
100	LDR_L1_D24_Unbias	270.375	287.959	-17.584
100	LDR_L2_D25_Unbias	275.699	294.532	-18.833
100	LDR_L3_D23_Unbias	277.499	305.045	-27.546
100	LDR_L3_D24_Unbias	282.335	312.626	-30.291
100	LDR_L3_D25_Unbias	278.073	302.875	-24.802
	Max	282.335	320.951	-4.895
	Average	274.596	302.712	-28.115
	Min	269.770	274.665	-43.506
	Std Dev	4.392	13.109	11.272

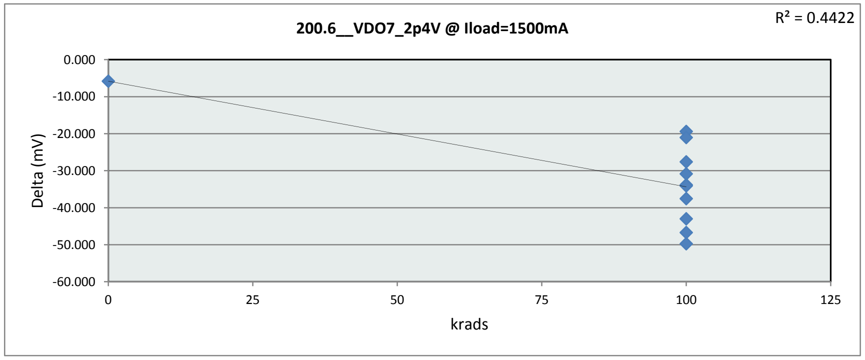


	200.5__VDO6_2p4V @ Iload=1250mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	400	mV
Min Limit	150	mV
krads	0	100
LL	150.000	150.000
Min	274.665	287.959
Average	274.665	305.516
Max	274.665	320.951
UL	400.000	400.000

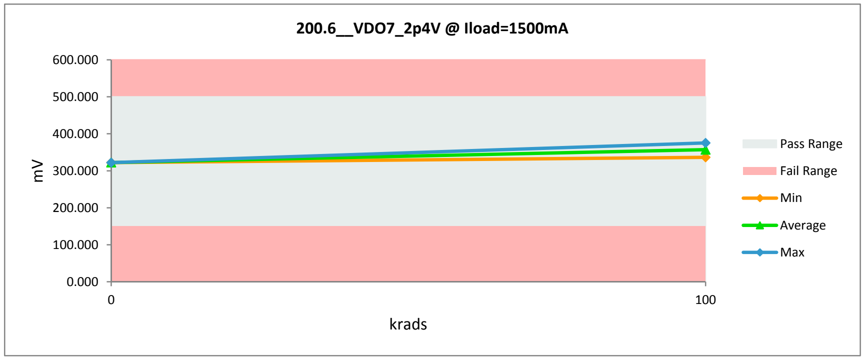


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		200.6__VDO7_2p4V @ Iload=1500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	500	500	
	Min Limit	150	150	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	316.169	321.991	-5.822
100	LDR_L1_D18_Bias	318.516	352.350	-33.834
100	LDR_L1_D19_Bias	317.843	355.388	-37.545
100	LDR_L1_D20_Bias	318.303	368.022	-49.719
100	LDR_L2_D20_Bias	328.782	375.462	-46.680
100	LDR_L2_D21_Bias	319.530	362.494	-42.964
100	LDR_L1_D24_Unbias	316.982	336.349	-19.367
100	LDR_L2_D25_Unbias	323.423	344.439	-21.016
100	LDR_L3_D23_Unbias	325.441	356.265	-30.824
100	LDR_L3_D24_Unbias	331.304	365.355	-34.051
100	LDR_L3_D25_Unbias	325.857	353.430	-27.573
	Max	331.304	375.462	-5.822
	Average	322.014	353.777	-31.763
	Min	316.169	321.991	-49.719
	Std Dev	5.193	15.151	12.938



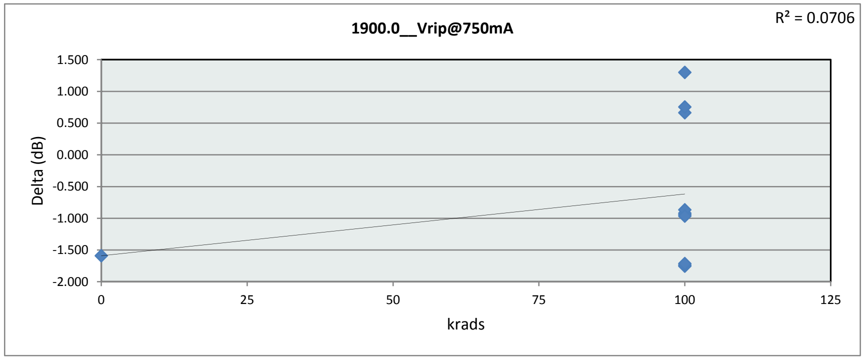
	200.6__VDO7_2p4V @ Iload=1500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	500	mV
Min Limit	150	mV
krads	0	100
LL	150.000	150.000
Min	321.991	336.349
Average	321.991	356.955
Max	321.991	375.462
UL	500.000	500.000



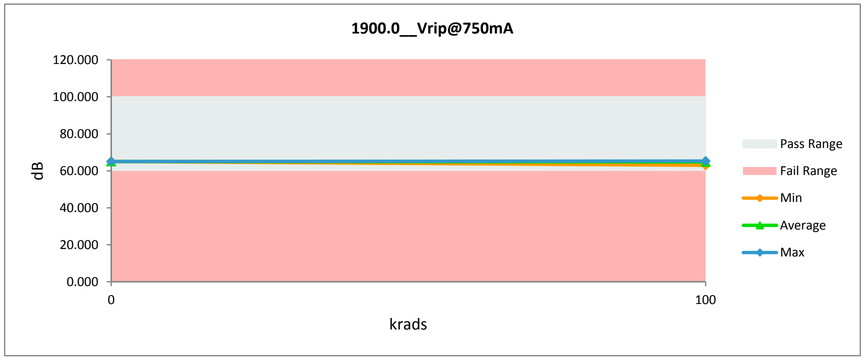
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		1900.0__Vrip@750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	dB	dB	
	Max Limit	100	100	
	Min Limit	60	60	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	63.476	65.066	-1.590
100	LDR_L1_D18_Bias	63.474	65.226	-1.752
100	LDR_L1_D19_Bias	65.066	64.402	0.664
100	LDR_L1_D20_Bias	65.981	65.225	0.756
100	LDR_L2_D20_Bias	63.541	65.277	-1.736
100	LDR_L2_D21_Bias	63.478	64.396	-0.918
100	LDR_L1_D24_Unbias	64.246	65.187	-0.941
100	LDR_L2_D25_Unbias	63.499	64.365	-0.866
100	LDR_L3_D23_Unbias	64.235	65.200	-0.965
100	LDR_L3_D24_Unbias	64.252	62.952	1.300
100	LDR_L3_D25_Unbias	63.495	65.208	-1.713
	Max	65.981	65.277	1.300
	Average	64.068	64.773	-0.706
	Min	63.474	62.952	-1.752
	Std Dev	0.820	0.711	1.104

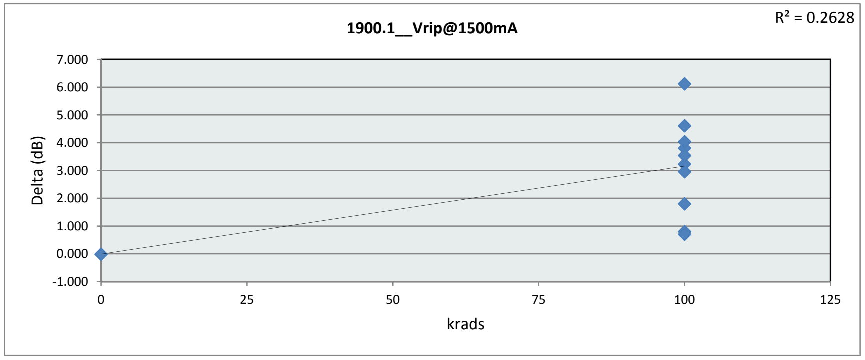


	1900.0__Vrip@750mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	100	dB
Min Limit	60	dB
krads	0	100
LL	60.000	60.000
Min	65.066	62.952
Average	65.066	64.744
Max	65.066	65.277
UL	100.000	100.000

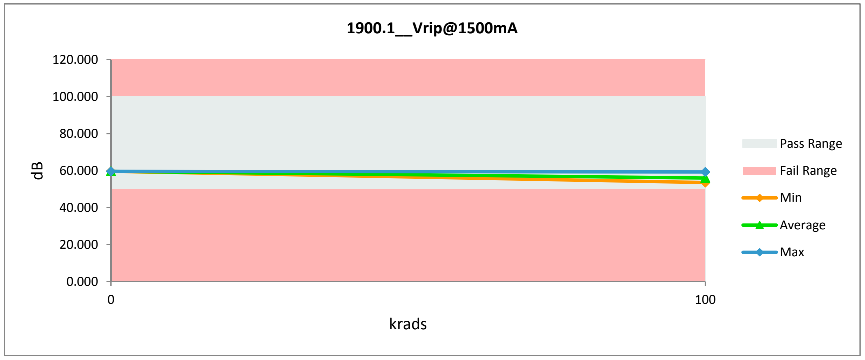


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		1900.1__Vrip@1500mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		dB	dB	
Max Limit		100	100	
Min Limit		50	50	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	59.557	59.571	-0.014
100	LDR_L1_D18_Bias	59.554	55.749	3.805
100	LDR_L1_D19_Bias	58.692	55.465	3.227
100	LDR_L1_D20_Bias	58.287	53.675	4.612
100	LDR_L2_D20_Bias	59.626	53.507	6.119
100	LDR_L2_D21_Bias	58.689	54.655	4.034
100	LDR_L1_D24_Unbias	60.039	59.244	0.795
100	LDR_L2_D25_Unbias	59.138	58.430	0.708
100	LDR_L3_D23_Unbias	59.558	56.018	3.540
100	LDR_L3_D24_Unbias	58.708	55.752	2.956
100	LDR_L3_D25_Unbias	59.131	57.329	1.802
	Max	60.039	59.571	6.119
	Average	59.180	56.309	2.871
	Min	58.287	53.507	-0.014
	Std Dev	0.535	2.091	1.867



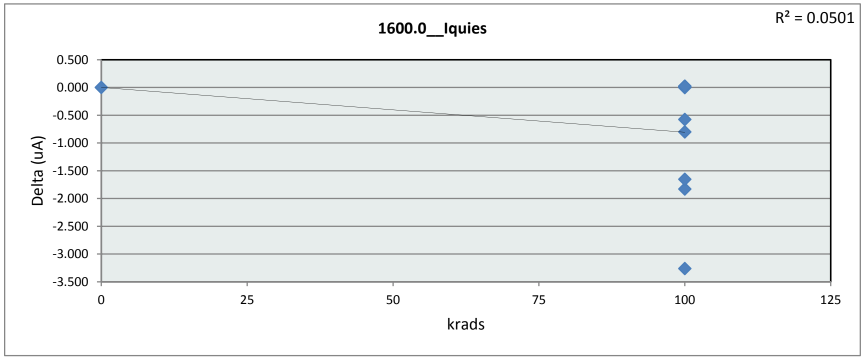
	1900.1__Vrip@1500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	100	dB
Min Limit	50	dB
krads	0	100
LL	50.000	50.000
Min	59.571	53.507
Average	59.571	55.982
Max	59.571	59.244
UL	100.000	100.000



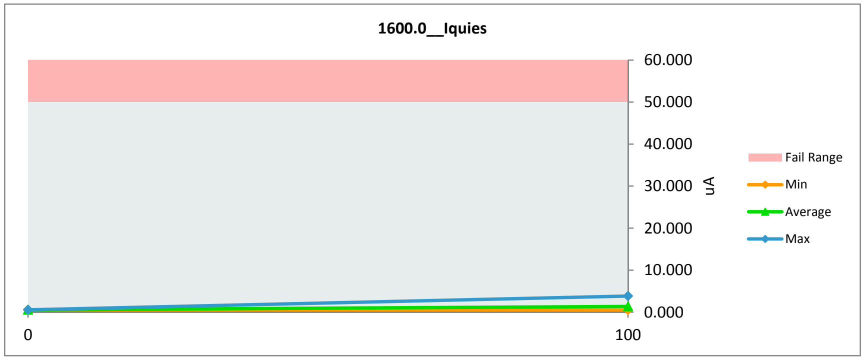
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		1600.0__Iquies		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		uA	uA	
Max Limit		50	50	
Min Limit				
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	0.553	0.552	0.001
100	LDR_L1_D18_Bias	0.573	1.148	-0.575
100	LDR_L1_D19_Bias	0.558	1.359	-0.801
100	LDR_L1_D20_Bias	0.541	2.371	-1.830
100	LDR_L2_D20_Bias	0.552	3.814	-3.262
100	LDR_L2_D21_Bias	0.550	2.204	-1.654
100	LDR_L1_D24_Unbias	0.546	0.537	0.009
100	LDR_L2_D25_Unbias	0.547	0.549	-0.002
100	LDR_L3_D23_Unbias	0.555	0.536	0.019
100	LDR_L3_D24_Unbias	0.551	0.529	0.022
100	LDR_L3_D25_Unbias	0.550	0.530	0.020
	Max	0.573	3.814	0.022
	Average	0.552	1.284	-0.732
	Min	0.541	0.529	-3.262
	Std Dev	0.008	1.086	1.086

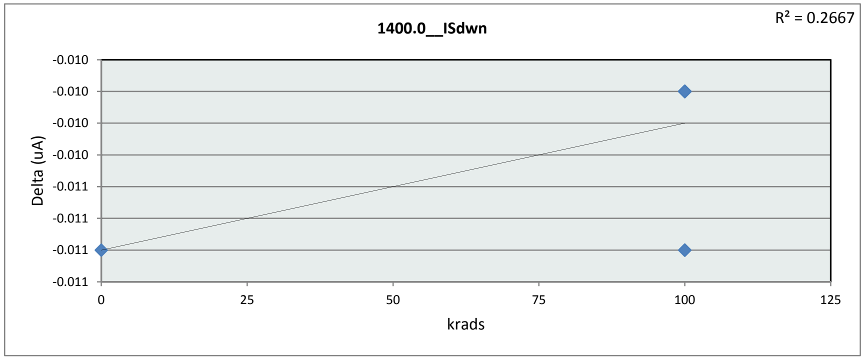


	1600.0__Iquies	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	50	uA
Min Limit		uA
krads	0	100
LL		
Min	0.552	0.529
Average	0.552	1.358
Max	0.552	3.814
UL	50.000	50.000

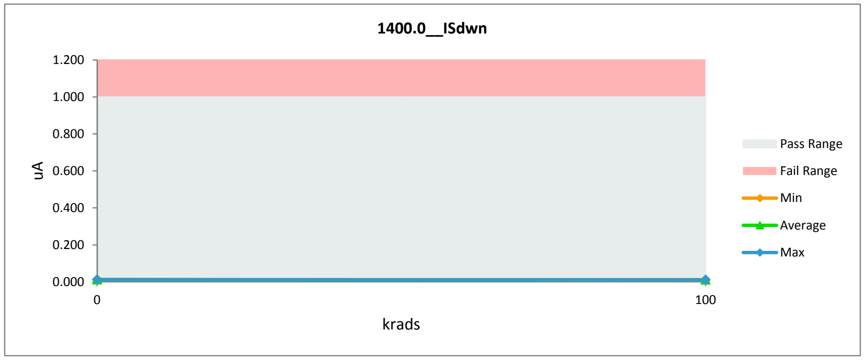


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		1400.0__ISdwn		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		uA	uA	
Max Limit		1	1	
Min Limit		0	0	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	0.001	0.012	-0.011
100	LDR_L1_D18_Bias	0.001	0.011	-0.010
100	LDR_L1_D19_Bias	0.001	0.011	-0.010
100	LDR_L1_D20_Bias	0.001	0.011	-0.010
100	LDR_L2_D20_Bias	0.000	0.010	-0.010
100	LDR_L2_D21_Bias	0.001	0.011	-0.010
100	LDR_L1_D24_Unbias	0.000	0.011	-0.011
100	LDR_L2_D25_Unbias	0.001	0.011	-0.010
100	LDR_L3_D23_Unbias	0.001	0.011	-0.010
100	LDR_L3_D24_Unbias	0.000	0.011	-0.011
100	LDR_L3_D25_Unbias	0.001	0.011	-0.010
	Max	0.001	0.012	-0.010
	Average	0.001	0.011	-0.010
	Min	0.000	0.010	-0.011
	Std Dev	0.000	0.000	0.000



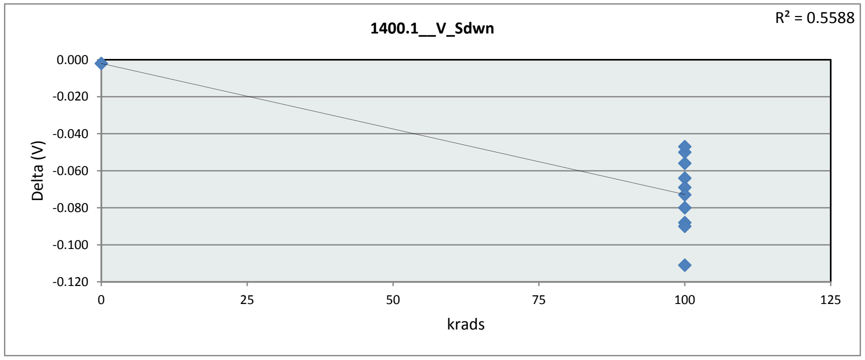
	1400.0__ISdwn	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	1	uA
Min Limit	0	uA
krads	0	100
LL	0.000	0.000
Min	0.012	0.010
Average	0.012	0.011
Max	0.012	0.011
UL	1.000	1.000



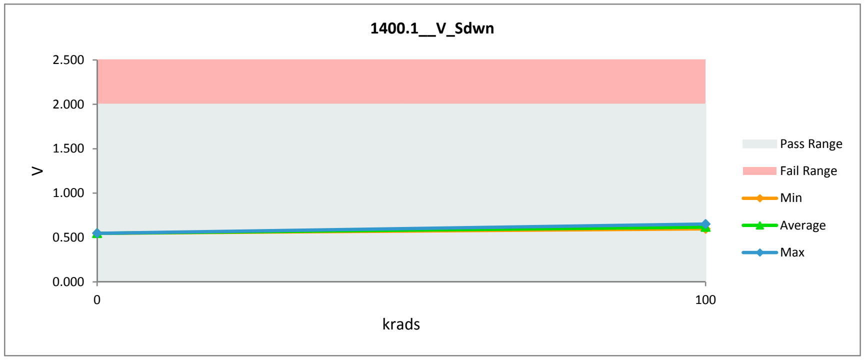
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		1400.1__V_Sdwn		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	V	V	
	Max Limit	2	2	
	Min Limit	0	0	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	0.545	0.547	-0.002
100	LDR_L1_D18_Bias	0.548	0.636	-0.088
100	LDR_L1_D19_Bias	0.546	0.626	-0.080
100	LDR_L1_D20_Bias	0.547	0.597	-0.050
100	LDR_L2_D20_Bias	0.552	0.599	-0.047
100	LDR_L2_D21_Bias	0.542	0.606	-0.064
100	LDR_L1_D24_Unbias	0.544	0.613	-0.069
100	LDR_L2_D25_Unbias	0.550	0.606	-0.056
100	LDR_L3_D23_Unbias	0.538	0.628	-0.090
100	LDR_L3_D24_Unbias	0.540	0.651	-0.111
100	LDR_L3_D25_Unbias	0.540	0.613	-0.073
	Max	0.552	0.651	-0.002
	Average	0.545	0.611	-0.066
	Min	0.538	0.547	-0.111
	Std Dev	0.004	0.027	0.029



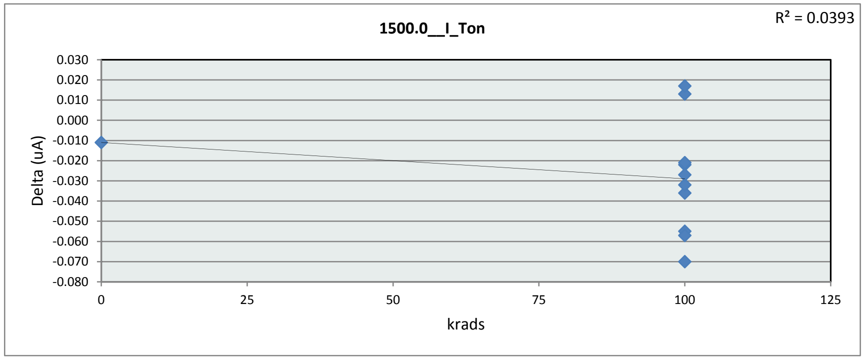
	1400.1__V_Sdwn	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	2	V
Min Limit	0	V
krads	0	100
LL	0.000	0.000
Min	0.547	0.597
Average	0.547	0.618
Max	0.547	0.651
UL	2.000	2.000



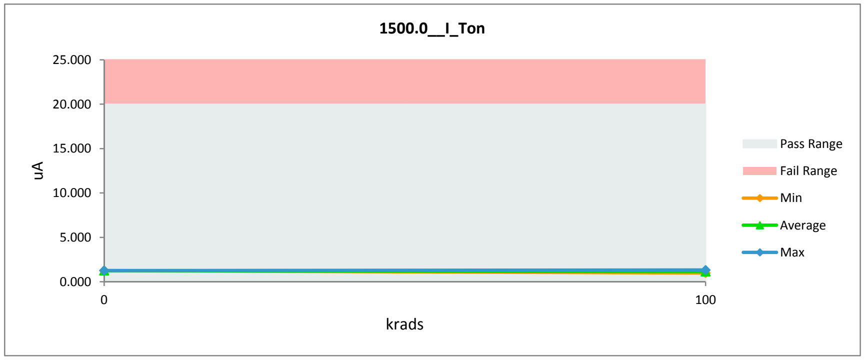
TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

	1500.0__I_Ton	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	uA	uA
Max Limit	20	20
Min Limit	0	0

krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	1.245	1.256	-0.011
100	LDR_L1_D18_Bias	1.123	1.193	-0.070
100	LDR_L1_D19_Bias	1.217	1.272	-0.055
100	LDR_L1_D20_Bias	1.196	1.183	0.013
100	LDR_L2_D20_Bias	1.212	1.195	0.017
100	LDR_L2_D21_Bias	1.001	1.023	-0.022
100	LDR_L1_D24_Unbias	1.259	1.316	-0.057
100	LDR_L2_D25_Unbias	1.248	1.284	-0.036
100	LDR_L3_D23_Unbias	1.039	1.071	-0.032
100	LDR_L3_D24_Unbias	0.958	0.985	-0.027
100	LDR_L3_D25_Unbias	0.976	0.997	-0.021
	Max	1.259	1.316	0.017
	Average	1.134	1.161	-0.027
	Min	0.958	0.985	-0.070
	Std Dev	0.119	0.122	0.027



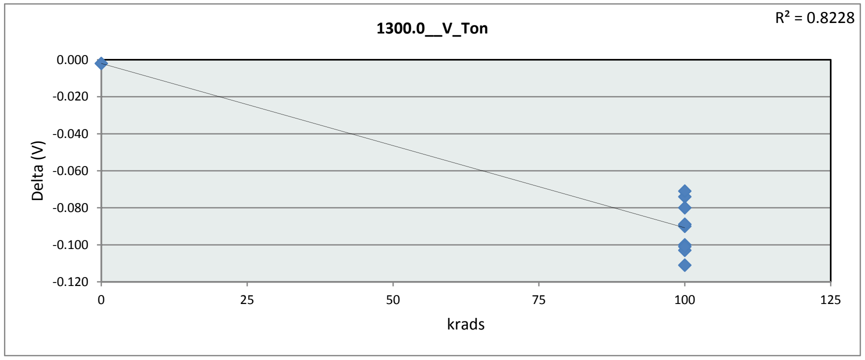
	1500.0__I_Ton	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	20	uA
Min Limit	0	uA
krads	0	100
LL	0.000	0.000
Min	1.256	0.985
Average	1.256	1.152
Max	1.256	1.316
UL	20.000	20.000



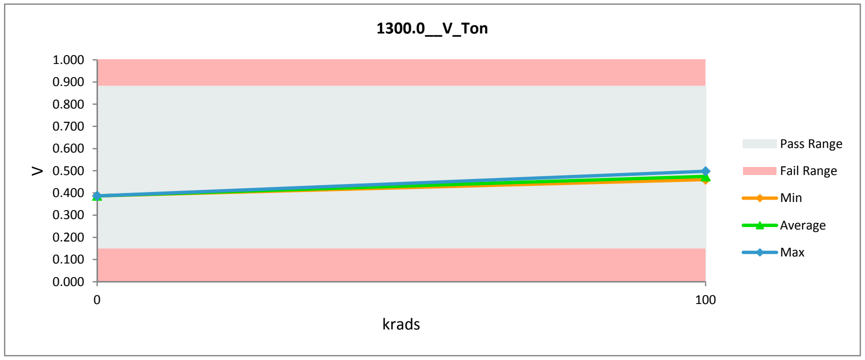
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		1300.0__V_Ton		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		V	V	
Max Limit		0.88	0.88	
Min Limit		0.15	0.15	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	0.385	0.387	-0.002
100	LDR_L1_D18_Bias	0.387	0.498	-0.111
100	LDR_L1_D19_Bias	0.386	0.489	-0.103
100	LDR_L1_D20_Bias	0.386	0.460	-0.074
100	LDR_L2_D20_Bias	0.390	0.461	-0.071
100	LDR_L2_D21_Bias	0.381	0.470	-0.089
100	LDR_L1_D24_Unbias	0.384	0.474	-0.090
100	LDR_L2_D25_Unbias	0.388	0.468	-0.080
100	LDR_L3_D23_Unbias	0.377	0.477	-0.100
100	LDR_L3_D24_Unbias	0.378	0.479	-0.101
100	LDR_L3_D25_Unbias	0.379	0.468	-0.089
	Max	0.390	0.498	-0.002
	Average	0.384	0.466	-0.083
	Min	0.377	0.387	-0.111
	Std Dev	0.004	0.029	0.030



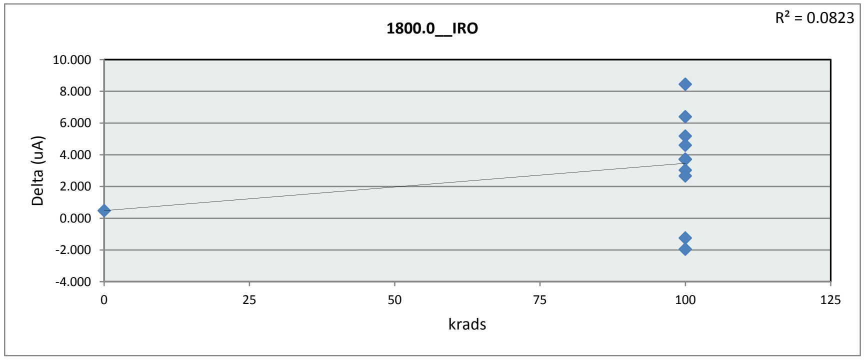
	1300.0__V_Ton	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	0.88	V
Min Limit	0.15	V
krads	0	100
LL	0.150	0.150
Min	0.387	0.460
Average	0.387	0.474
Max	0.387	0.498
UL	0.880	0.880



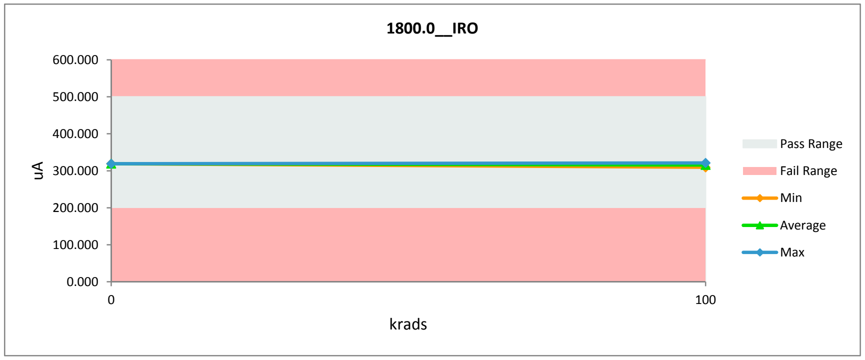
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		1800.0__IRO		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	uA	uA	
	Max Limit	500	500	
	Min Limit	200	200	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	319.450	318.967	0.483
100	LDR_L1_D18_Bias	317.805	309.355	8.450
100	LDR_L1_D19_Bias	319.147	312.744	6.403
100	LDR_L1_D20_Bias	319.891	321.126	-1.235
100	LDR_L2_D20_Bias	319.035	320.976	-1.941
100	LDR_L2_D21_Bias	320.990	317.957	3.033
100	LDR_L1_D24_Unbias	319.107	313.923	5.184
100	LDR_L2_D25_Unbias	316.861	313.145	3.716
100	LDR_L3_D23_Unbias	322.674	318.067	4.607
100	LDR_L3_D24_Unbias	318.097	314.364	3.733
100	LDR_L3_D25_Unbias	315.757	313.078	2.679
	Max	322.674	321.126	8.450
	Average	318.983	315.791	3.192
	Min	315.757	309.355	-1.941
	Std Dev	1.893	3.820	3.132



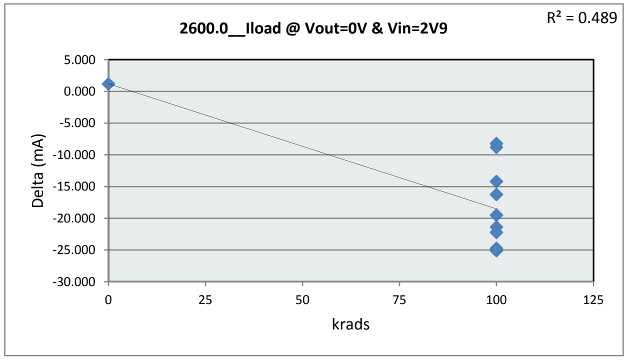
	1800.0__IRO	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	500	uA
Min Limit	200	uA
krads	0	100
LL	200.000	200.000
Min	318.967	309.355
Average	318.967	315.474
Max	318.967	321.126
UL	500.000	500.000



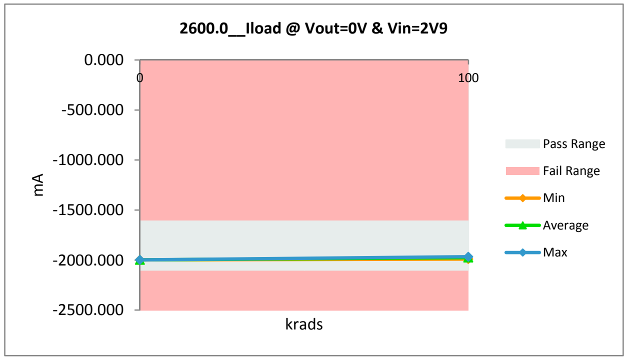
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2600.0__Iload @ Vout=0V & Vin=2V9		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mA	mA	
	Max Limit	-1600	-1600	
	Min Limit	-2100	-2100	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	-1997.223	-1998.413	1.190
100	LDR_L1_D18_Bias	-1996.802	-1971.730	-25.072
100	LDR_L1_D19_Bias	-1997.492	-1972.770	-24.722
100	LDR_L1_D20_Bias	-1997.625	-1972.734	-24.891
100	LDR_L2_D20_Bias	-1987.975	-1966.595	-21.380
100	LDR_L2_D21_Bias	-1996.687	-1974.471	-22.216
100	LDR_L1_D24_Unbias	-1998.644	-1989.854	-8.790
100	LDR_L2_D25_Unbias	-1991.623	-1983.394	-8.229
100	LDR_L3_D23_Unbias	-1994.785	-1980.586	-14.199
100	LDR_L3_D24_Unbias	-1992.237	-1972.746	-19.491
100	LDR_L3_D25_Unbias	-1992.518	-1976.273	-16.245
	Max	-1987.975	-1966.595	1.190
	Average	-1994.874	-1978.142	-16.731
	Min	-1998.644	-1998.413	-25.072
	Std Dev	3.344	9.275	8.500



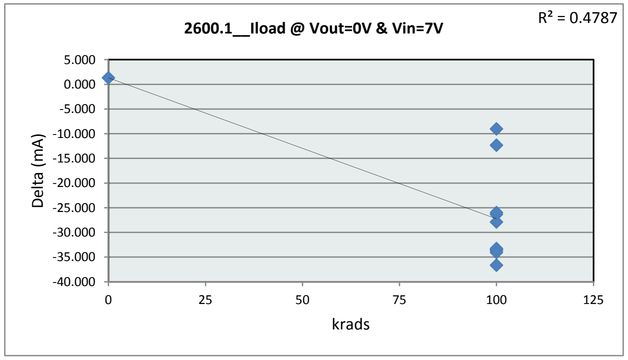
	2600.0__Iload @ Vout=0V & Vin=2V9	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	-1600	mA
Min Limit	-2100	mA
krads	0	100
LL	-2100.000	-2100.000
Min	-1998.413	-1989.854
Average	-1998.413	-1976.115
Max	-1998.413	-1966.595
UL	-1600.000	-1600.000



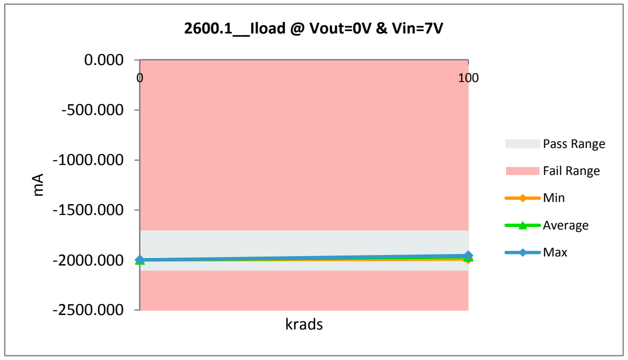
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2600.1__Iload @ Vout=0V & Vin=7V		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mA	mA	
Max Limit		-1700	-1700	
Min Limit		-2100	-2100	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	-1997.141	-1998.458	1.317
100	LDR_L1_D18_Bias	-1996.721	-1970.404	-26.317
100	LDR_L1_D19_Bias	-1997.414	-1971.450	-25.964
100	LDR_L1_D20_Bias	-1997.521	-1963.858	-33.663
100	LDR_L2_D20_Bias	-1987.905	-1954.463	-33.442
100	LDR_L2_D21_Bias	-1996.507	-1963.260	-33.247
100	LDR_L1_D24_Unbias	-1998.510	-1989.509	-9.001
100	LDR_L2_D25_Unbias	-1991.439	-1979.111	-12.328
100	LDR_L3_D23_Unbias	-1994.666	-1966.786	-27.880
100	LDR_L3_D24_Unbias	-1992.165	-1955.539	-36.626
100	LDR_L3_D25_Unbias	-1992.429	-1958.387	-34.042
	Max	-1987.905	-1954.463	1.317
	Average	-1994.765	-1970.111	-24.654
	Min	-1998.510	-1998.458	-36.626
	Std Dev	3.339	13.980	12.450



	2600.1__Iload @ Vout=0V & Vin=7V	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	-1700	mA
Min Limit	-2100	mA
krads	0	100
LL	-2100.000	-2100.000
Min	-1998.458	-1989.509
Average	-1998.458	-1967.277
Max	-1998.458	-1954.463
UL	-1700.000	-1700.000

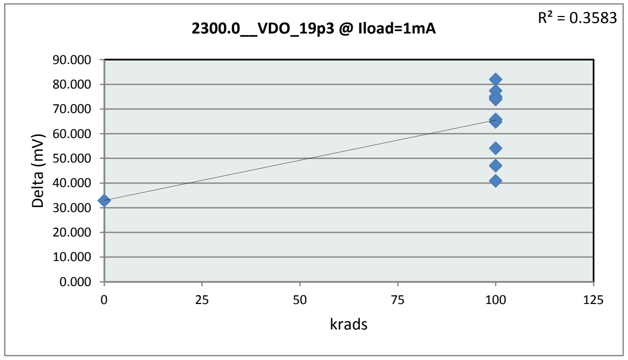


TPS7A4501-RHA

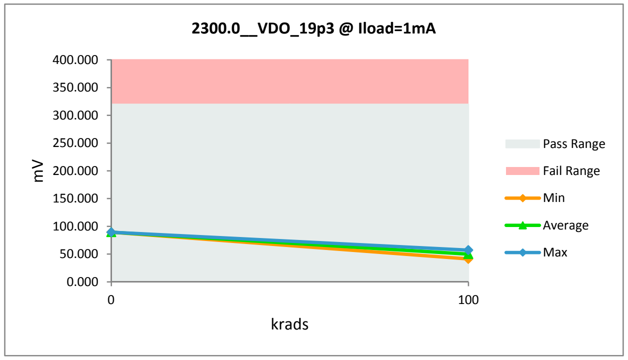
All units passed SMD specification limits up to 100kRAD LDR.

	2300.0__VDO_19p3 @ Iload=1mA	
Test Site	CLAB	CLAB
Tester	ETS#3	ETS#3
Test Number	EF556000	EF556000
Unit	mV	mV
Max Limit	320	320
Min Limit	1	1

krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	122.321	89.373	32.948
100	LDR_L1_D18_Bias	126.275	44.276	81.999
100	LDR_L1_D19_Bias	119.929	44.888	75.041
100	LDR_L1_D20_Bias	124.466	50.547	73.919
100	LDR_L2_D20_Bias	82.116	41.184	40.932
100	LDR_L2_D21_Bias	127.732	50.367	77.365
100	LDR_L1_D24_Unbias	110.113	56.020	54.093
100	LDR_L2_D25_Unbias	104.155	57.119	47.036
100	LDR_L3_D23_Unbias	129.373	54.946	74.427
100	LDR_L3_D24_Unbias	112.564	47.731	64.833
100	LDR_L3_D25_Unbias	118.566	52.784	65.782
	Max	129.373	89.373	81.999
	Average	116.146	53.567	62.580
	Min	82.116	41.184	32.948
	Std Dev	13.749	12.929	16.418



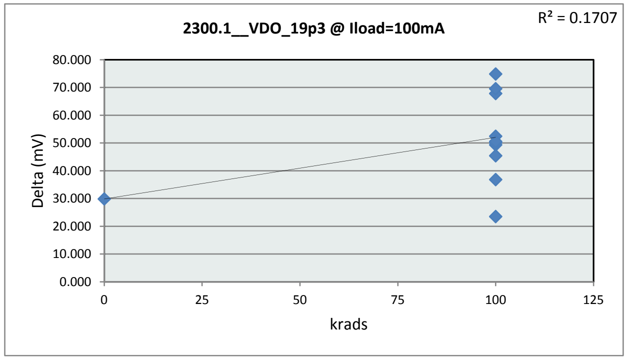
	2300.0__VDO_19p3 @ Iload=1mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	320	mV
Min Limit	1	mV
krads	0	100
LL	1.000	1.000
Min	89.373	41.184
Average	89.373	49.986
Max	89.373	57.119
UL	320.000	320.000



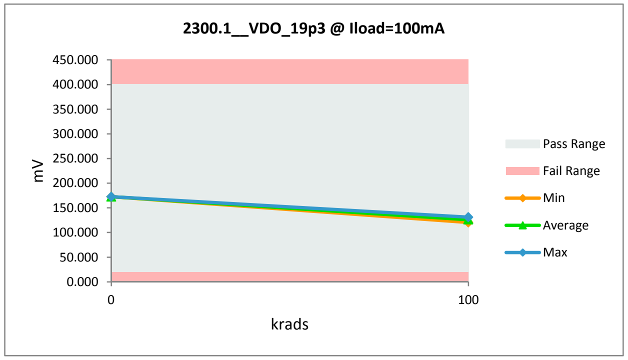
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2300.1__VDO_19p3 @ Iload=100mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		400	400	
Min Limit		20	20	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	202.490	172.672	29.818
100	LDR_L1_D18_Bias	188.264	120.443	67.821
100	LDR_L1_D19_Bias	174.006	121.582	52.424
100	LDR_L1_D20_Bias	166.290	129.494	36.796
100	LDR_L2_D20_Bias	146.153	122.648	23.505
100	LDR_L2_D21_Bias	203.314	128.491	74.823
100	LDR_L1_D24_Unbias	173.020	123.711	49.309
100	LDR_L2_D25_Unbias	178.086	128.005	50.081
100	LDR_L3_D23_Unbias	200.584	131.039	69.545
100	LDR_L3_D24_Unbias	176.609	126.066	50.543
100	LDR_L3_D25_Unbias	174.481	129.063	45.418
	Max	203.314	172.672	74.823
	Average	180.300	130.292	50.008
	Min	146.153	120.443	23.505
	Std Dev	17.333	14.490	16.208



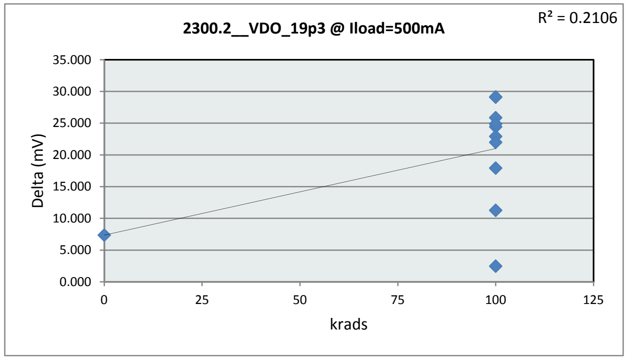
	2300.1__VDO_19p3 @ Iload=100mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	400	mV
Min Limit	20	mV
krads	0	100
LL	20.000	20.000
Min	172.672	120.443
Average	172.672	126.054
Max	172.672	131.039
UL	400.000	400.000



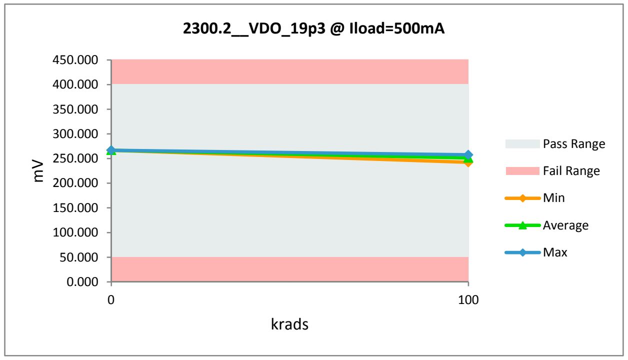
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2300.2__VDO_19p3 @ Iload=500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	50	50	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	274.225	266.872	7.353
100	LDR_L1_D18_Bias	273.699	244.577	29.122
100	LDR_L1_D19_Bias	271.465	247.040	24.425
100	LDR_L1_D20_Bias	268.915	257.646	11.269
100	LDR_L2_D20_Bias	257.233	254.758	2.475
100	LDR_L2_D21_Bias	278.925	256.021	22.904
100	LDR_L1_D24_Unbias	268.257	242.401	25.856
100	LDR_L2_D25_Unbias	273.500	248.611	24.889
100	LDR_L3_D23_Unbias	283.556	254.450	29.106
100	LDR_L3_D24_Unbias	275.919	253.942	21.977
100	LDR_L3_D25_Unbias	271.359	253.448	17.911
	Max	283.556	266.872	29.122
	Average	272.459	252.706	19.753
	Min	257.233	242.401	2.475
	Std Dev	6.685	6.830	8.962



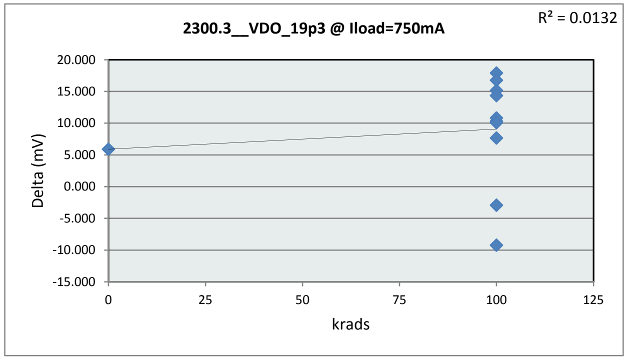
	2300.2__VDO_19p3 @ Iload=500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	400	mV
Min Limit	50	mV
krads	0	100
LL	50.000	50.000
Min	266.872	242.401
Average	266.872	251.289
Max	266.872	257.646
UL	400.000	400.000



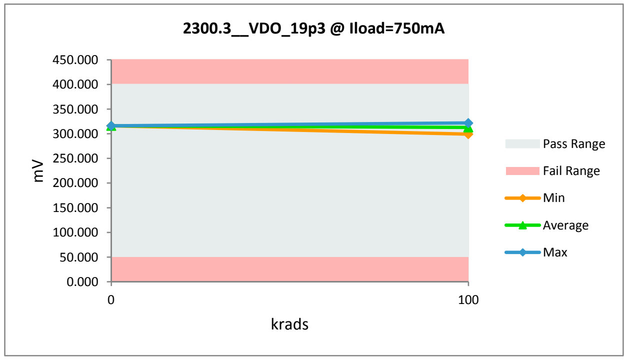
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2300.3__VDO_19p3 @ Iload=750mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	400	400	
	Min Limit	50	50	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	322.060	316.160	5.900
100	LDR_L1_D18_Bias	321.947	306.795	15.152
100	LDR_L1_D19_Bias	319.675	309.369	10.306
100	LDR_L1_D20_Bias	318.919	321.841	-2.922
100	LDR_L2_D20_Bias	311.589	320.824	-9.235
100	LDR_L2_D21_Bias	326.796	319.144	7.652
100	LDR_L1_D24_Unbias	317.243	299.348	17.895
100	LDR_L2_D25_Unbias	321.413	307.080	14.333
100	LDR_L3_D23_Unbias	331.284	314.515	16.769
100	LDR_L3_D24_Unbias	327.036	316.230	10.806
100	LDR_L3_D25_Unbias	323.107	313.027	10.080
	Max	331.284	321.841	17.895
	Average	321.915	313.121	8.794
	Min	311.589	299.348	-9.235
	Std Dev	5.310	6.876	8.352



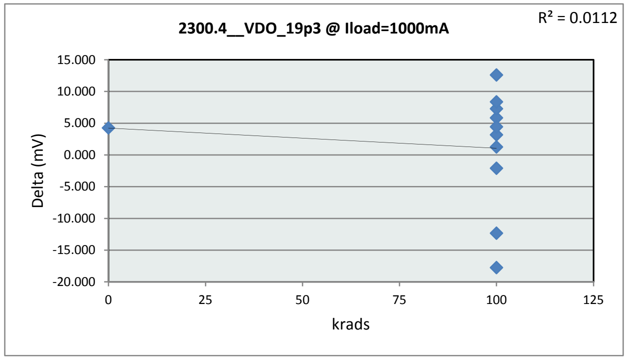
	2300.3__VDO_19p3 @ Iload=750mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	400	mV
Min Limit	50	mV
krads	0	100
LL	50.000	50.000
Min	316.160	299.348
Average	316.160	312.817
Max	316.160	321.841
UL	400.000	400.000



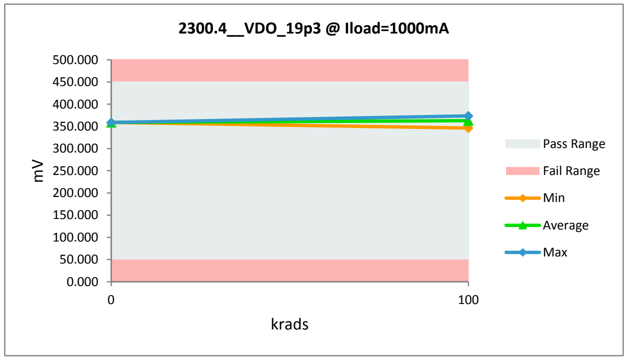
TPS7A4501-RHA

All units passed SMD specification limits up to 100kRAD LDR.

		2300.4__VDO_19p3 @ Iload=1000mA		
Test Site		CLAB	CLAB	
Tester		ETS#3	ETS#3	
Test Number		EF556000	EF556000	
Unit		mV	mV	
Max Limit		450	450	
Min Limit		50	50	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	362.945	358.700	4.245
100	LDR_L1_D18_Bias	362.811	356.985	5.826
100	LDR_L1_D19_Bias	360.882	359.637	1.245
100	LDR_L1_D20_Bias	360.749	373.082	-12.333
100	LDR_L2_D20_Bias	355.747	373.497	-17.750
100	LDR_L2_D21_Bias	367.259	369.356	-2.097
100	LDR_L1_D24_Unbias	358.841	346.244	12.597
100	LDR_L2_D25_Unbias	361.923	354.661	7.262
100	LDR_L3_D23_Unbias	372.036	363.668	8.368
100	LDR_L3_D24_Unbias	370.310	367.152	3.158
100	LDR_L3_D25_Unbias	366.527	362.109	4.418
	Max	372.036	373.497	12.597
	Average	363.639	362.281	1.358
	Min	355.747	346.244	-17.750
	Std Dev	4.918	8.254	9.032

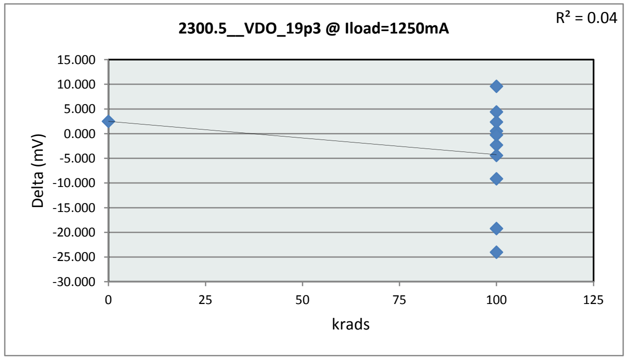


	2300.4__VDO_19p3 @ Iload=1000mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	450	mV
Min Limit	50	mV
krads	0	100
LL	50.000	50.000
Min	358.700	346.244
Average	358.700	362.639
Max	358.700	373.497
UL	450.000	450.000

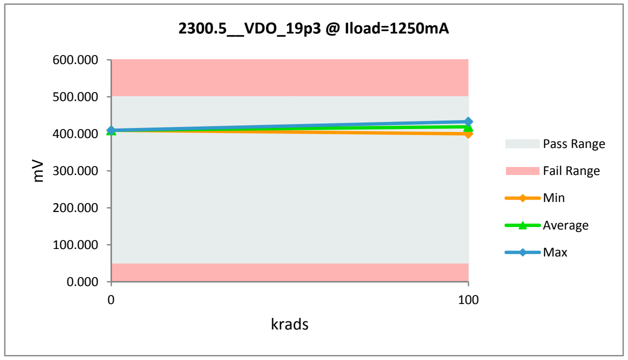


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		2300.5__VDO_19p3 @ Iload=1250mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	500	500	
	Min Limit	50	50	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	_CORR_L1_D25	412.036	409.538	2.498
100	LDR_L1_D18_Bias	413.168	412.654	0.514
100	LDR_L1_D19_Bias	411.286	415.698	-4.412
100	LDR_L1_D20_Bias	411.838	431.039	-19.201
100	LDR_L2_D20_Bias	408.720	432.731	-24.011
100	LDR_L2_D21_Bias	417.188	426.310	-9.122
100	LDR_L1_D24_Unbias	409.402	399.790	9.612
100	LDR_L2_D25_Unbias	413.939	409.530	4.409
100	LDR_L3_D23_Unbias	422.160	419.796	2.364
100	LDR_L3_D24_Unbias	422.382	424.683	-2.301
100	LDR_L3_D25_Unbias	417.566	417.801	-0.235
	Max	422.382	432.731	9.612
	Average	414.517	418.143	-3.626
	Min	408.720	399.790	-24.011
	Std Dev	4.716	10.063	10.161

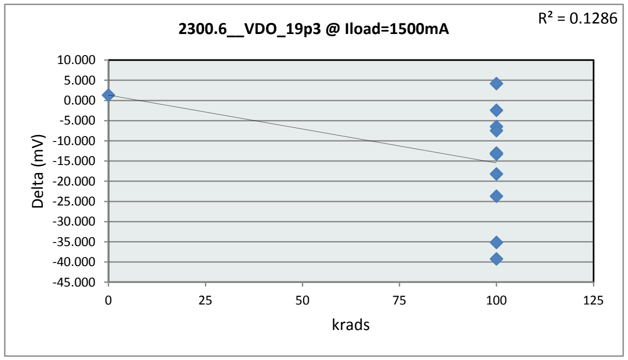


	2300.5__VDO_19p3 @ Iload=1250mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	500	mV
Min Limit	50	mV
krads	0	100
LL	50.000	50.000
Min	409.538	399.790
Average	409.538	419.003
Max	409.538	432.731
UL	500.000	500.000

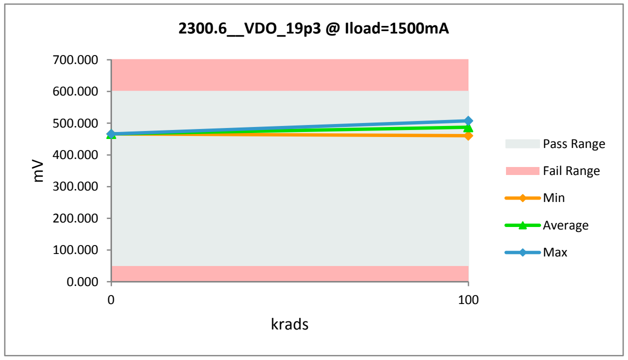


TPS7A4501-RHA
All units passed SMD specification limits up to 100kRAD LDR.

		2300.6__VDO_19p3 @ Iload=1500mA		
	Test Site	CLAB	CLAB	
	Tester	ETS#3	ETS#3	
	Test Number	EF556000	EF556000	
	Unit	mV	mV	
	Max Limit	600	600	
	Min Limit	50	50	
krads	Serial #	PreRad_LDR_100K	PostRad_LDR_100K	Delta
0	CORR_L1_D25	467.319	465.980	1.339
100	LDR_L1_D18_Bias	468.886	482.141	-13.255
100	LDR_L1_D19_Bias	466.891	485.088	-18.197
100	LDR_L1_D20_Bias	467.714	502.867	-35.153
100	LDR_L2_D20_Bias	468.420	507.649	-39.229
100	LDR_L2_D21_Bias	473.506	497.180	-23.674
100	LDR_L1_D24_Unbias	464.938	460.756	4.182
100	LDR_L2_D25_Unbias	470.920	473.338	-2.418
100	LDR_L3_D23_Unbias	479.273	485.721	-6.448
100	LDR_L3_D24_Unbias	480.892	493.869	-12.977
100	LDR_L3_D25_Unbias	475.327	482.795	-7.468
	Max	480.892	507.649	4.182
	Average	471.281	485.217	-13.936
	Min	464.938	460.756	-39.229
	Std Dev	5.287	14.689	14.129



	2300.6__VDO_19p3 @ Iload=1500mA	
Test Site	CLAB	
Tester	ETS#3	
Test Number	EF556000	
Max Limit	600	mV
Min Limit	50	mV
krads	0	100
LL	50.000	50.000
Min	465.980	460.756
Average	465.980	487.140
Max	465.980	507.649
UL	600.000	600.000



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